



The 1st Space Science School Payload Design - An Example of Advanced Ionospheric Probe

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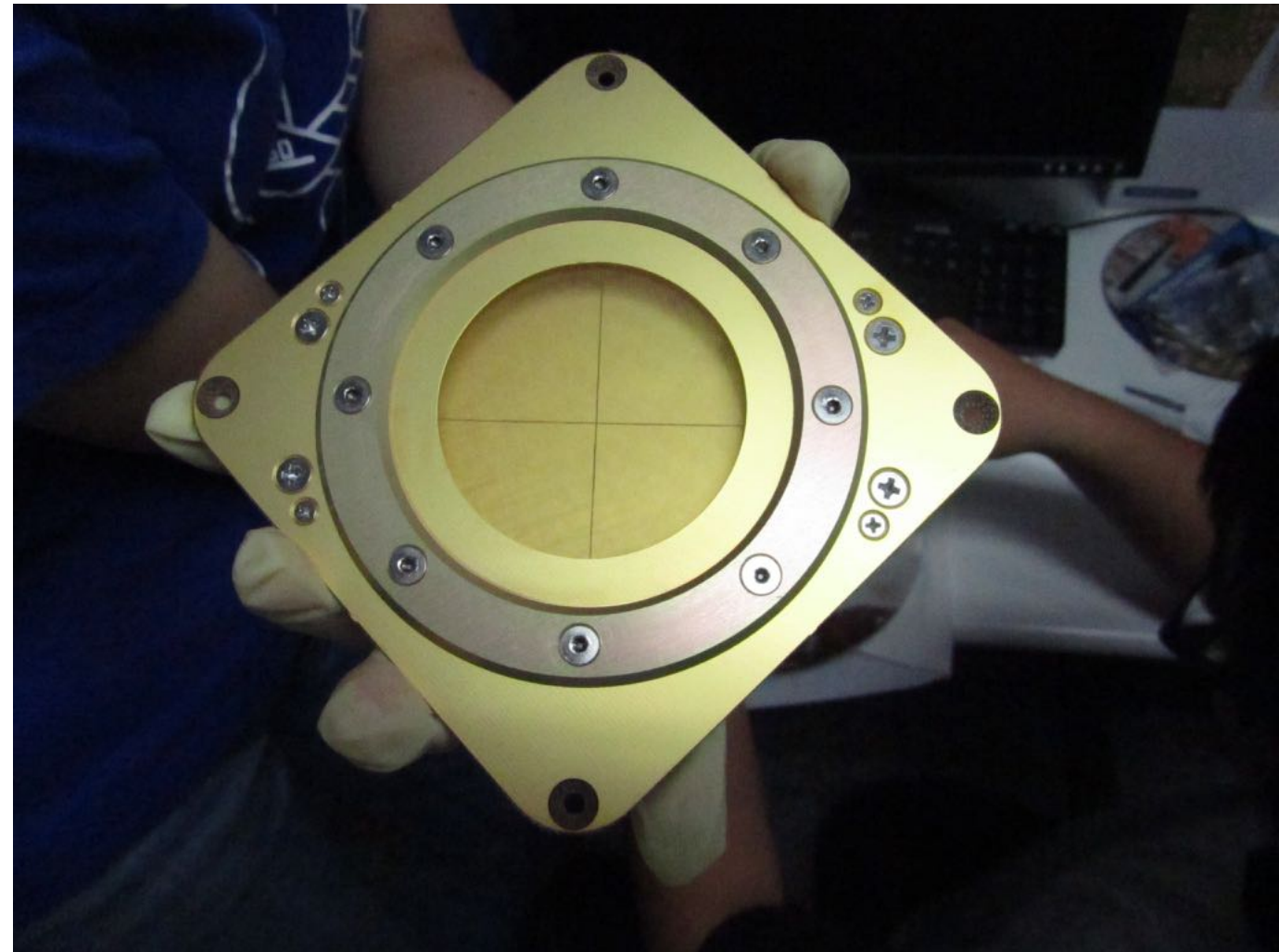
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October 24, 2016

Outline - the 1st hour

- Requirements
- Science objectives
- Principles of measurement
- Designs
- Verifications
- Future works



FS-5 to P/L interface requirements

- System
- Mechanical interface requirements
- Electrical interface requirements
- Environmental test requirements





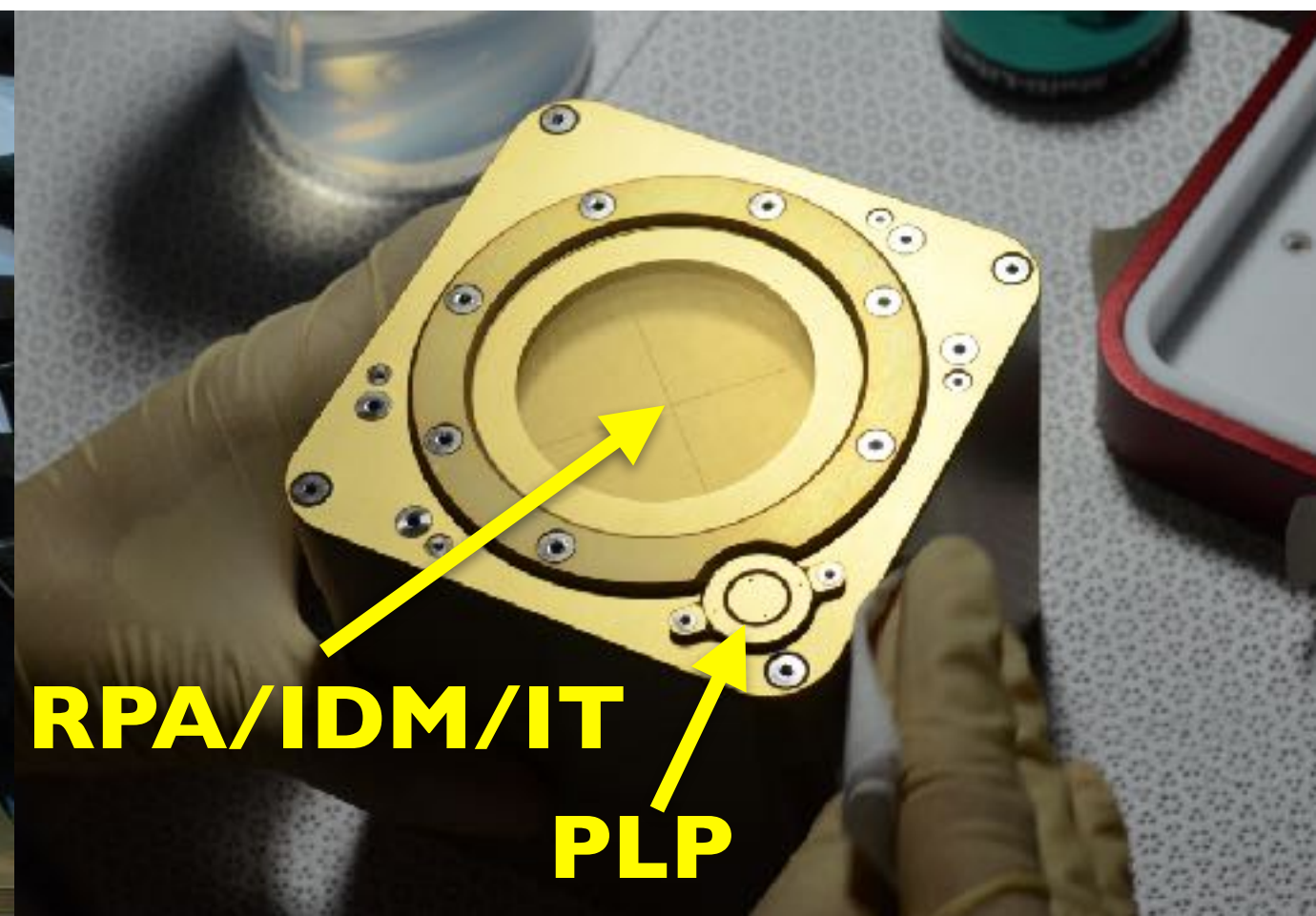
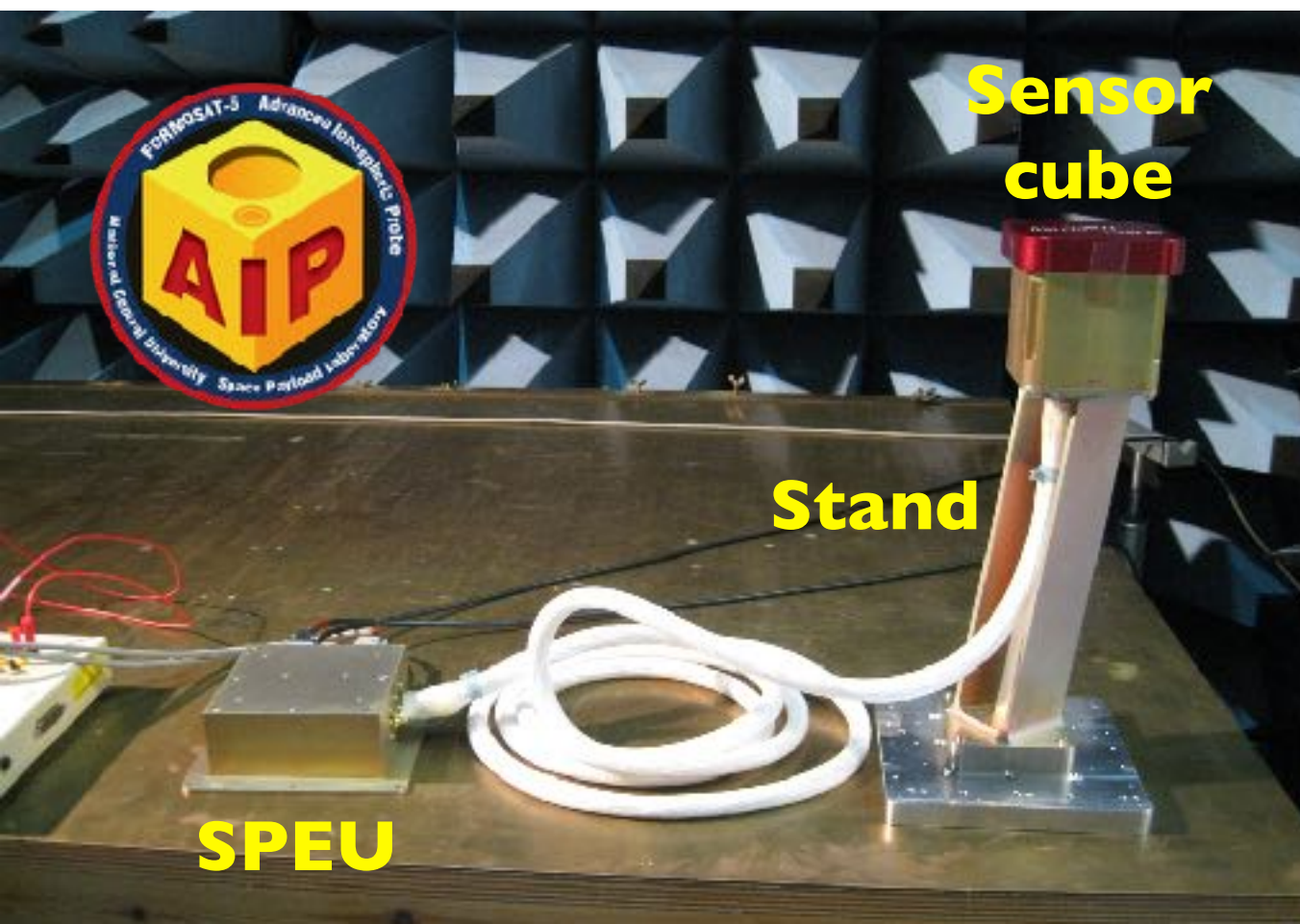
FORMOSAT-5 satellite

The **FORMOSAT-5** (FS-5) is a **remote sensing satellite** and currently scheduled to be launched by SpaceX in **October 2016**. The FS-5 is anticipated to fly in a **98.28°** inclination **sun-synchronous circular orbit** at **720 km** altitude in the **1030/2230 LT** sectors. The primary payload is **Remote Sensing Instrument (RSI)** organized by NSPO. In addition, a scientific instrument, **Advanced Ionospheric Probe (AIP)** developed by National Central University, has been chosen as the secondary payload.

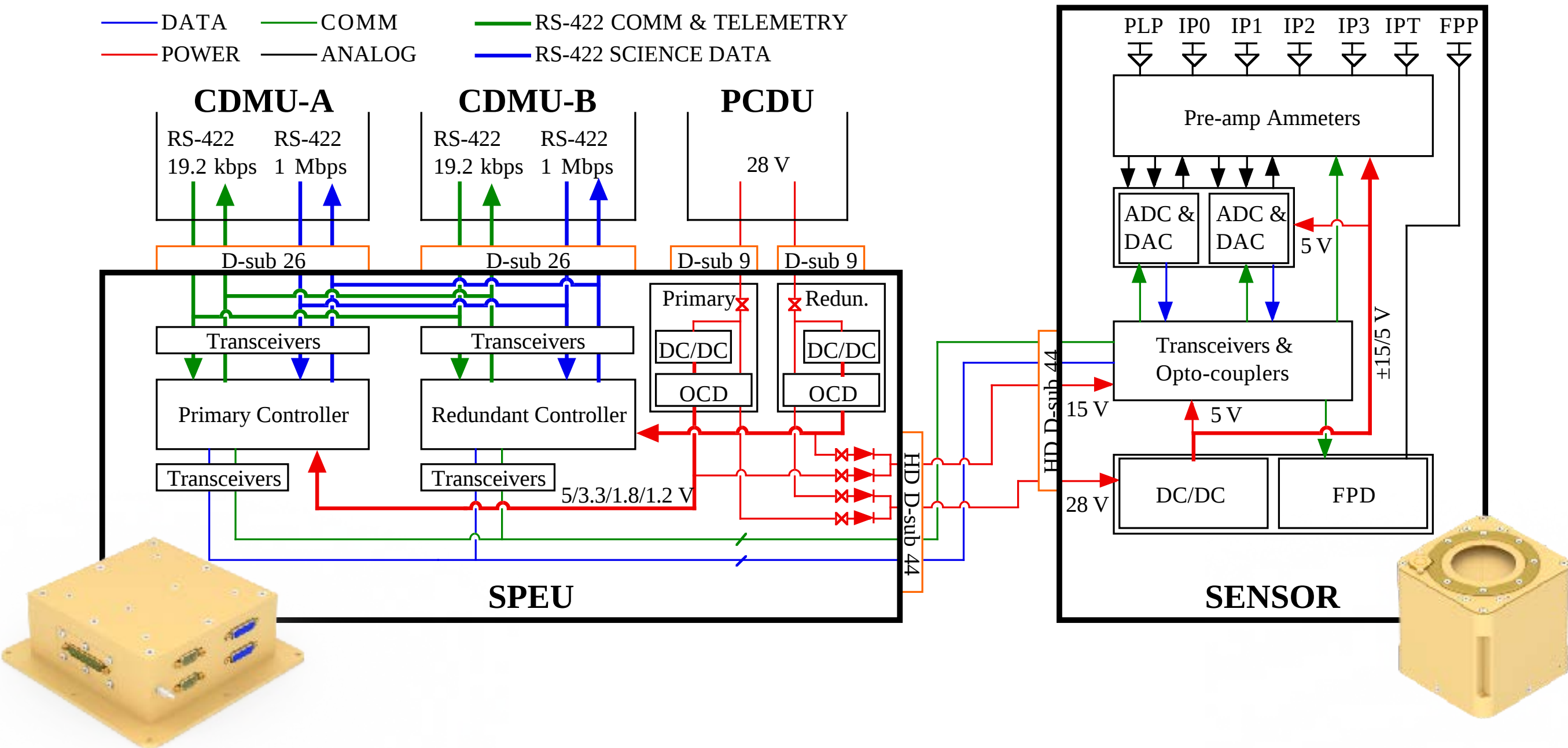


Configuration of AIP

The AIP consists of a sensor unit (a **sensor cube** mounted on a stand to enlarge its field of view) located on a top panel of the FORMOSAT-5 satellite, a **Science Payload Electronics Unit (SPEU)** housed on a side panel, and an interconnection cable between the two units.



Functional diagram

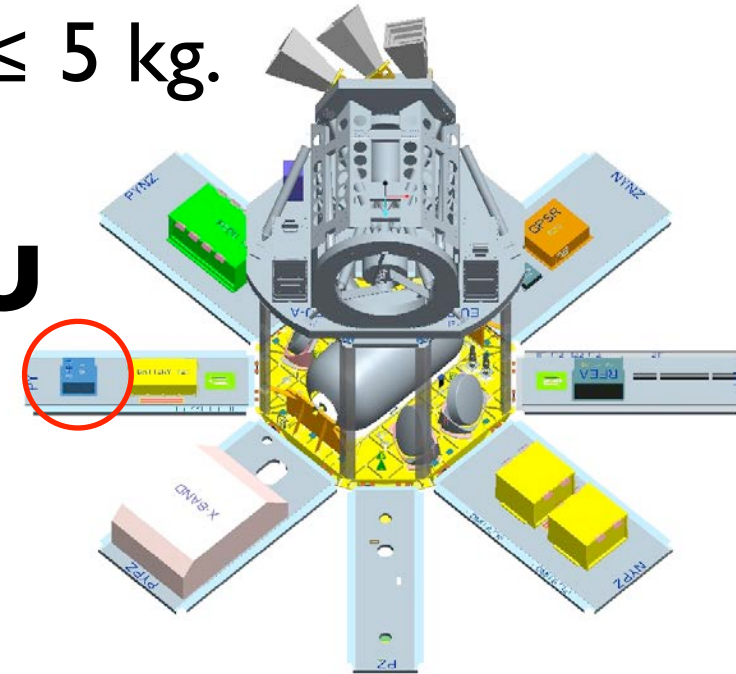


Redundant design on controllers, transceivers, powers, ADC/DAC, ammeters, etc.

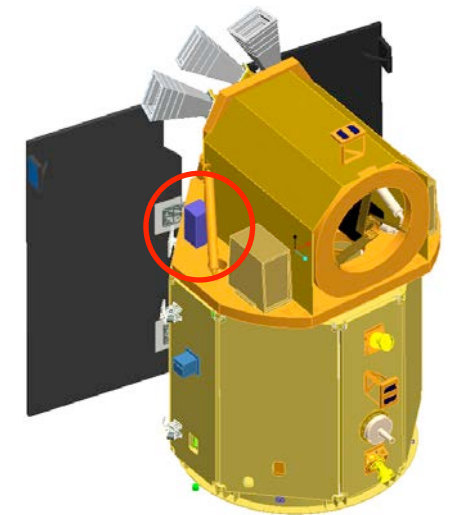
Mechanical interface requirements

- Mass: sensor ≤ 1 kg, SPEU ≤ 4 kg, and total mass ≤ 5 kg.
- Natural frequency of the sensor: > 120 Hz.
- Load factors
 - Out of plane: > 20 G.
 - In-plane: > 20 G.
- Margin of safety (MS)
 - Ultimate: > 0 .
 - Yield: > 0 .
- Buckling safety margin (MS_B): > 0 .
- Sinusoidal vibration (no collision during vibration)
 - 9G in-plane.
 - 10-300 Hz.

SPEU

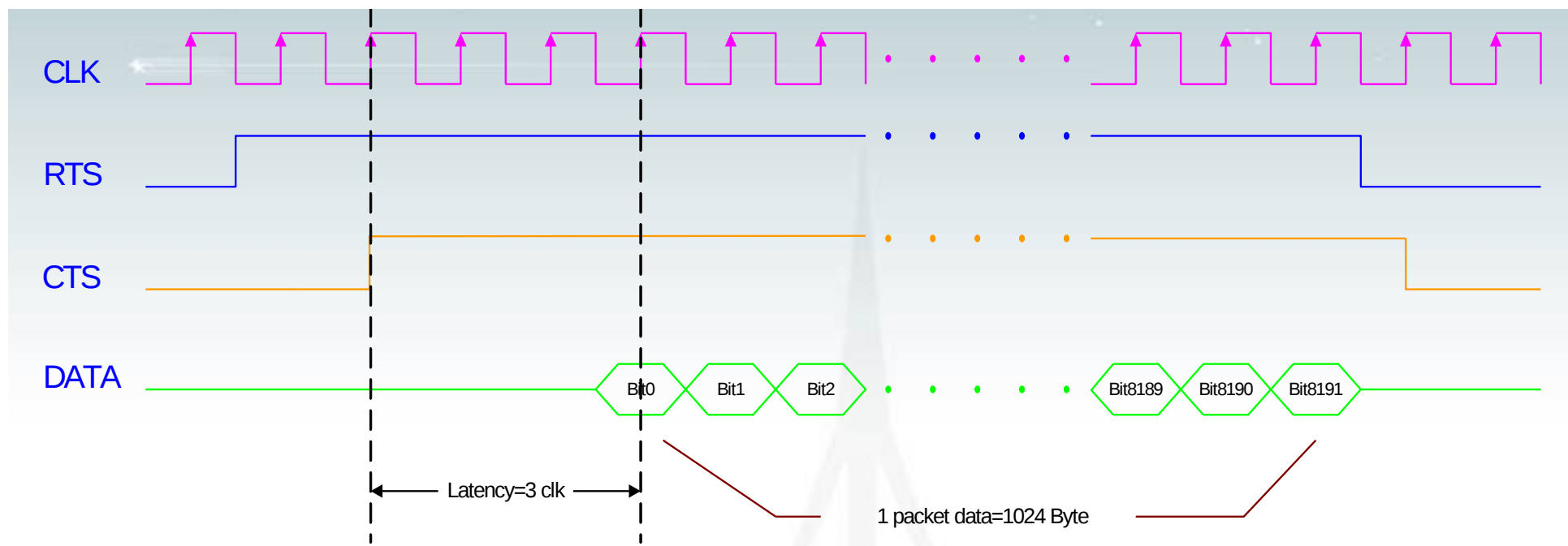


Sensor



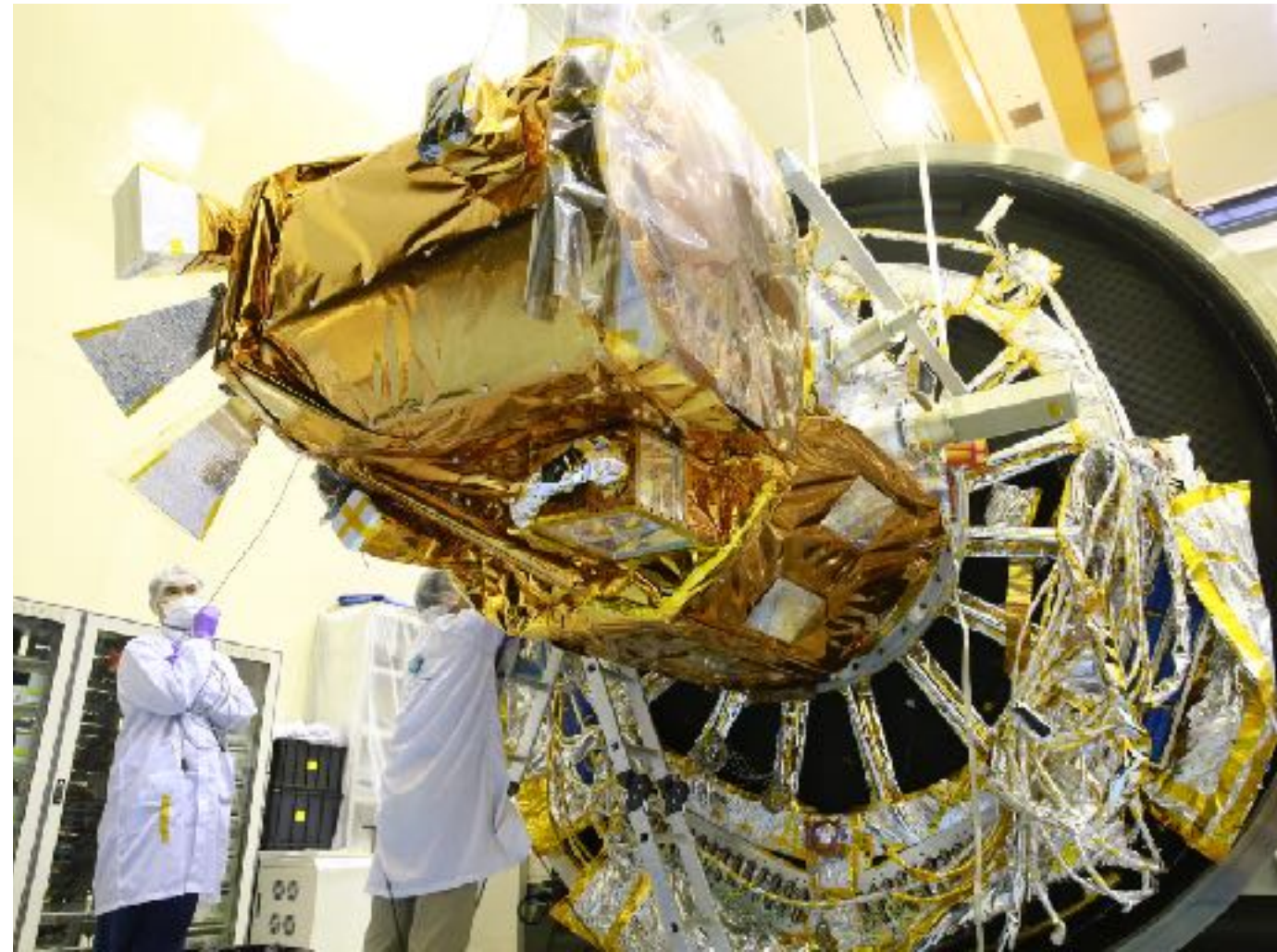
Electrical interface requirements

- Power: $\leq 5W$ average power per orbit, $\leq 2 A$ with 26V to 34V input voltage, and over-current-protection is required (1.75x max op. current with time duration $> 1ms$) to prevent from SEL.
- Command and telemetry interface (RS-422, 19.2 kbps, ASYN, bi-directional).
- Science data interface (RS-422, 1 Mbps, SYNC, only from SPEU to CDMU in a 1,024-byte science data packet).



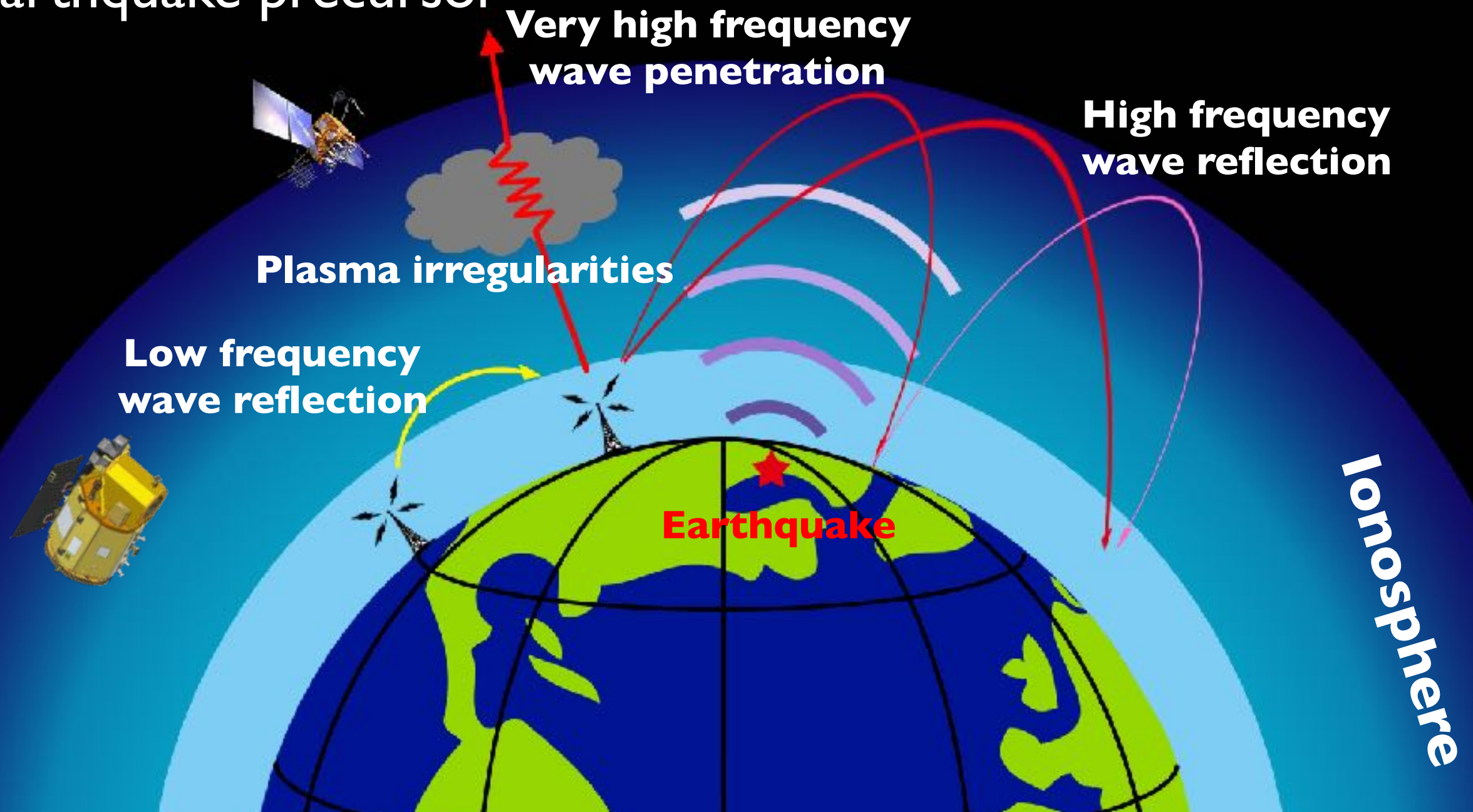
Environmental test requirements

- Sine vibration
- Random vibration
- Shock
- Thermal vacuum
- EMC

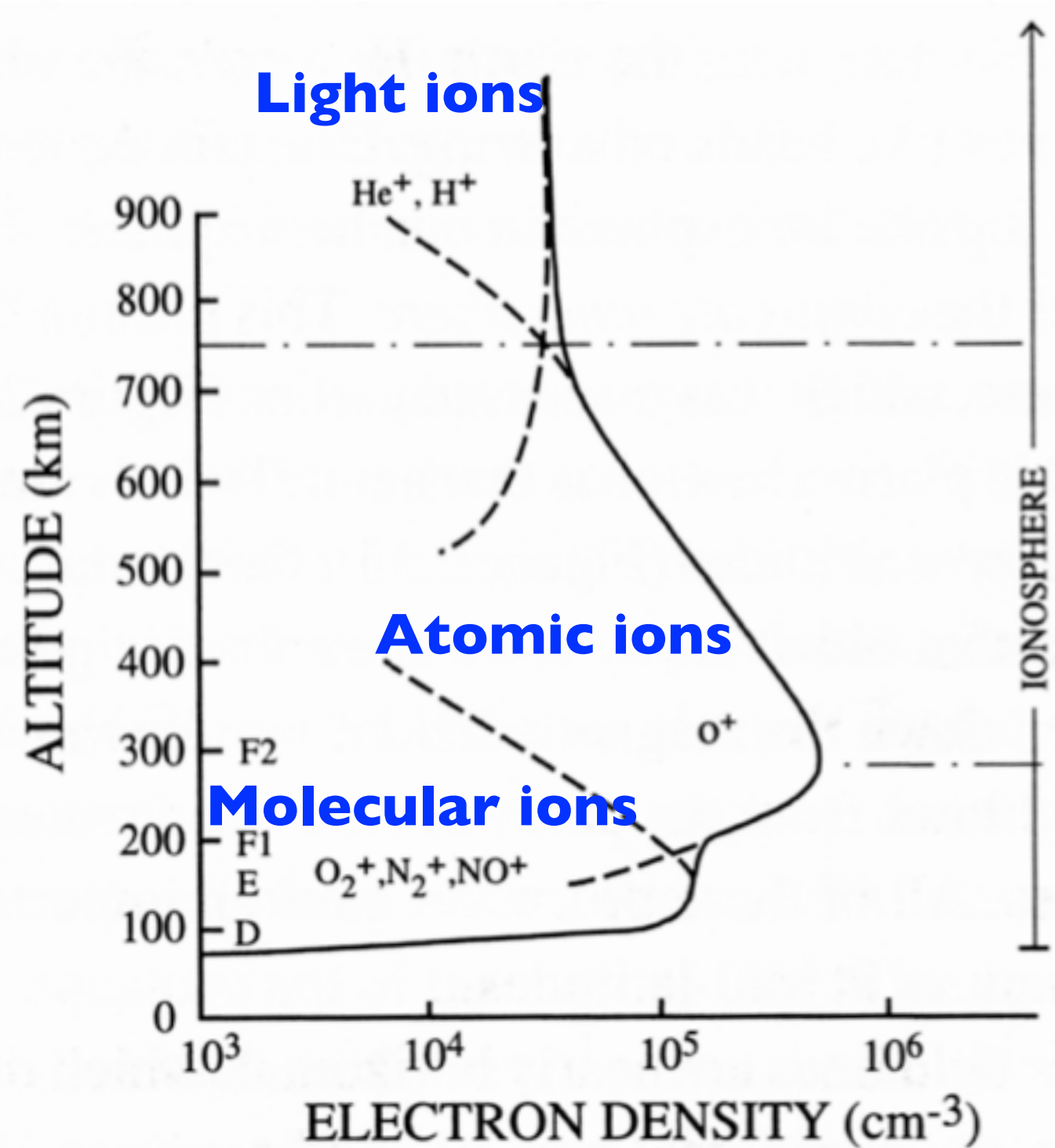
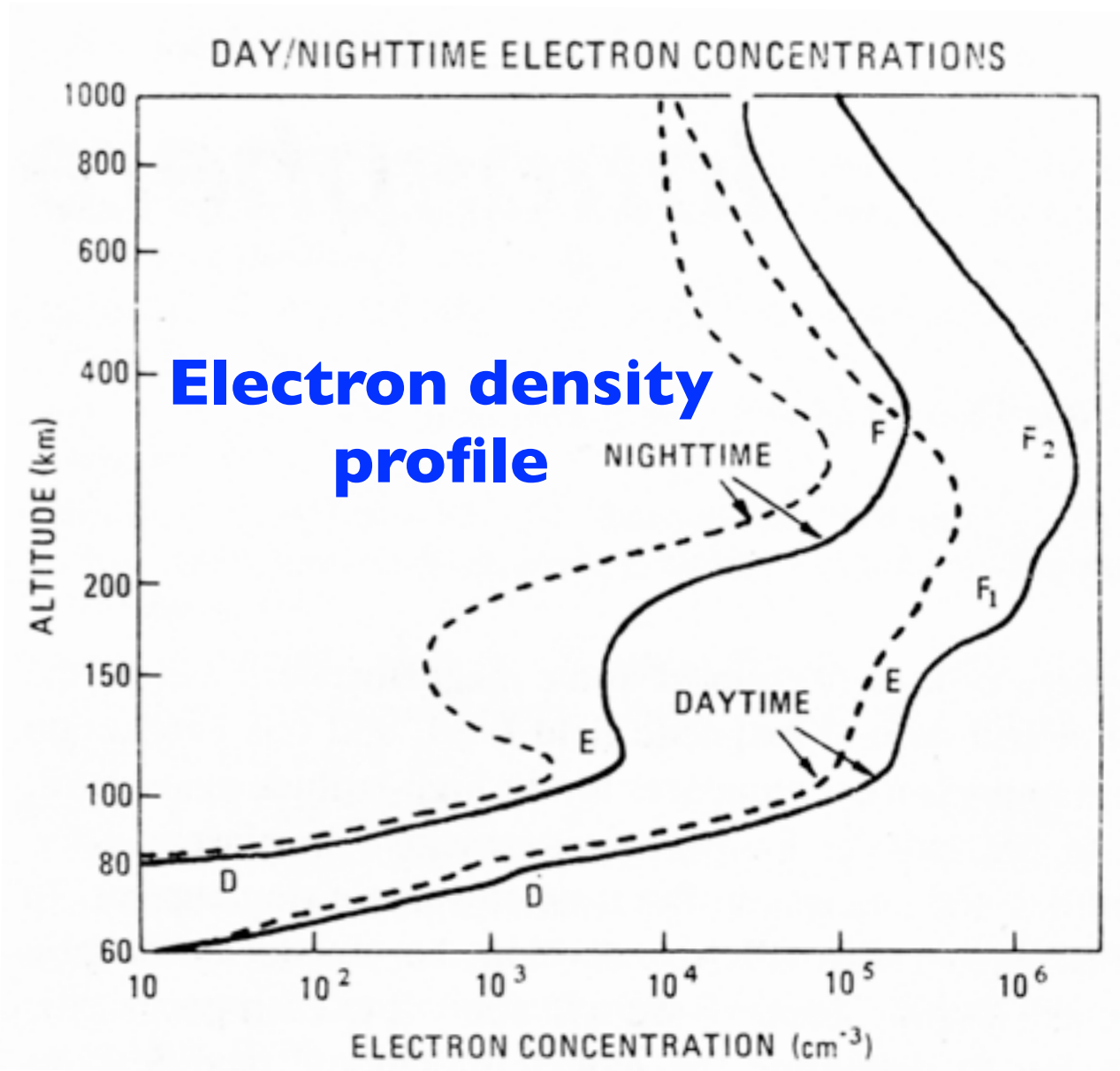


Scientific objectives

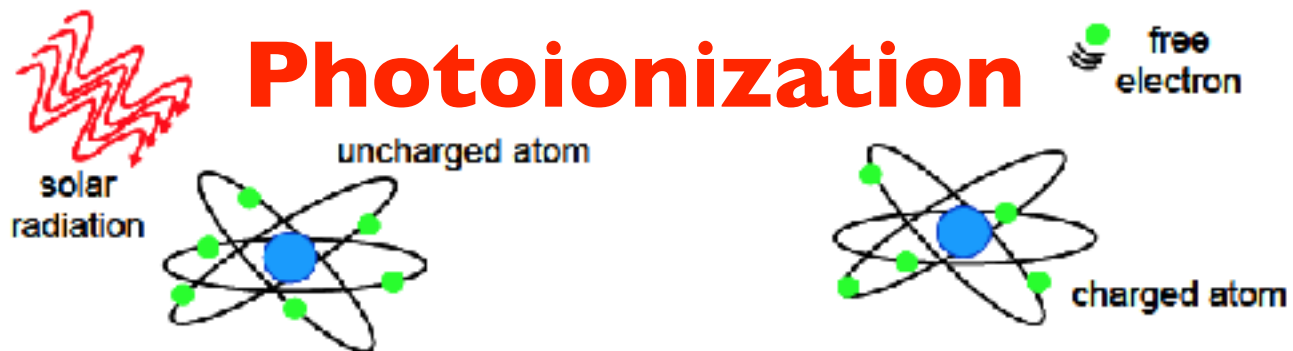
- Space weather and climate
- Earthquake precursor



Ionosphere

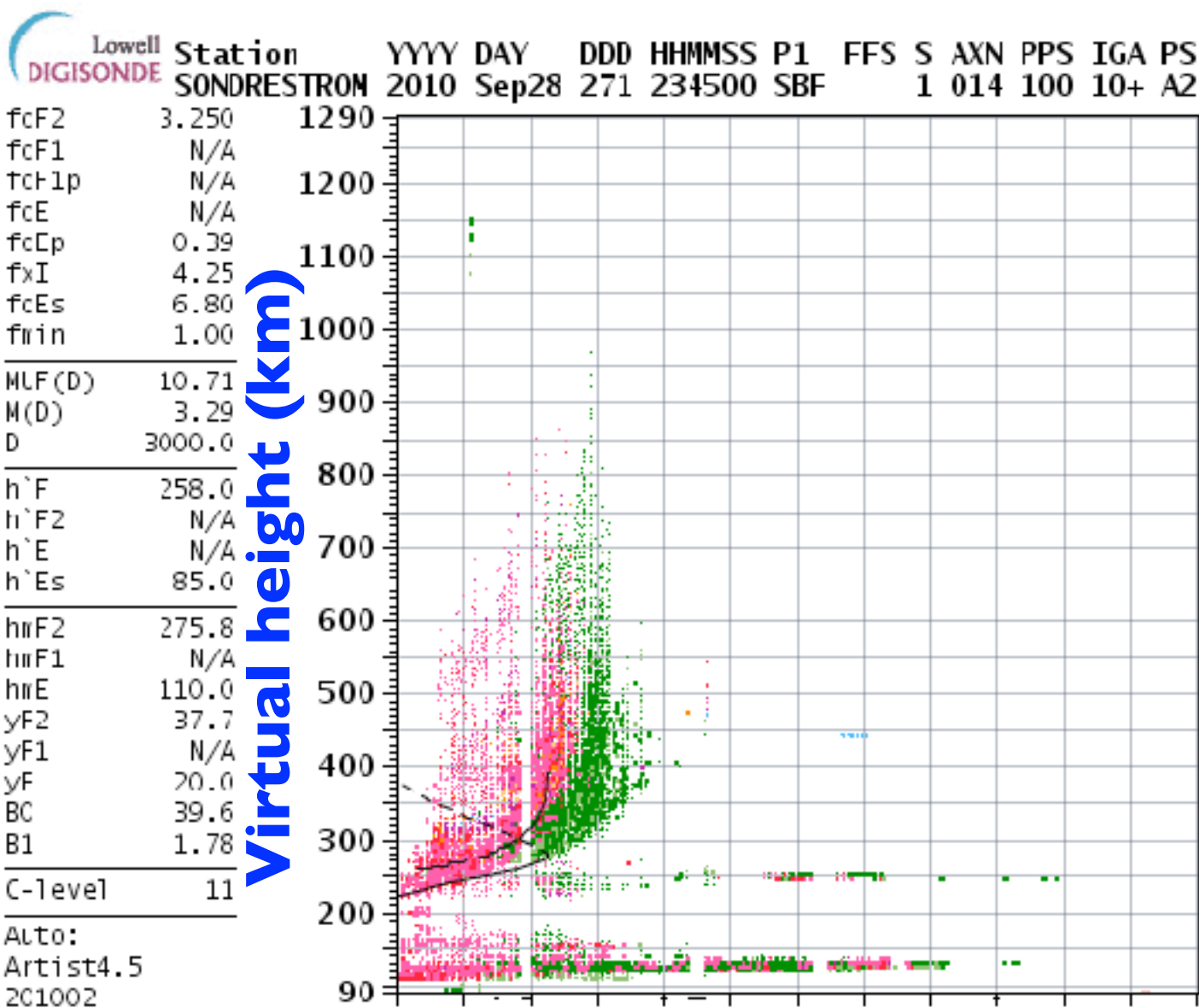


Photoionization



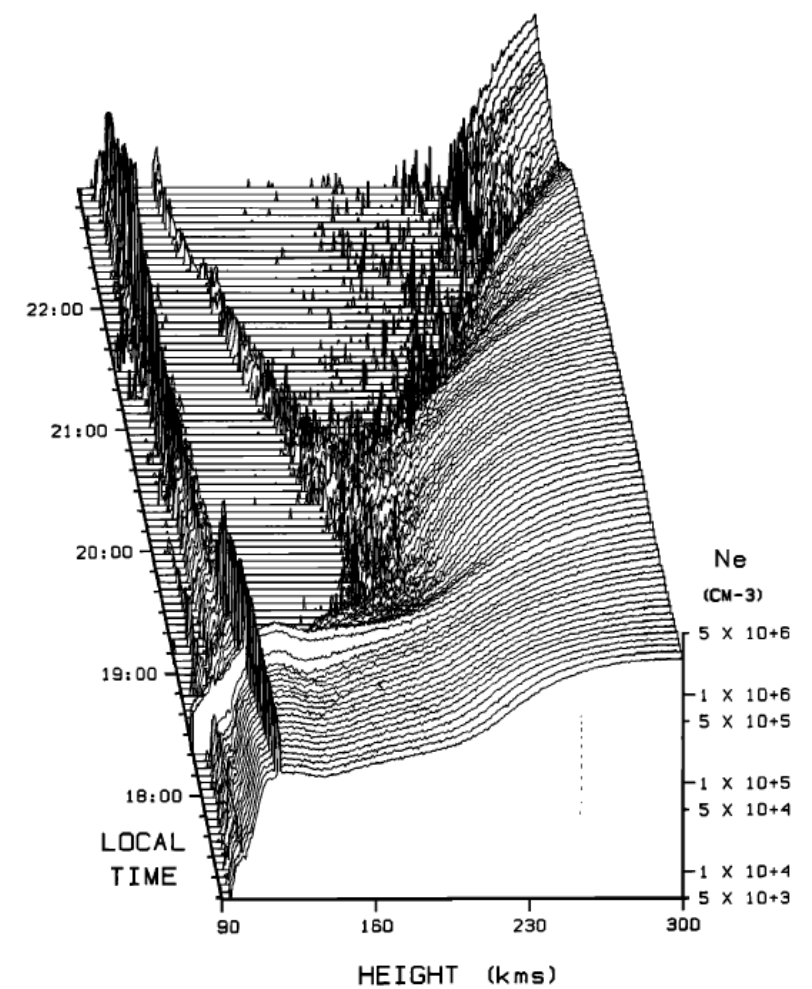


Ionosonde

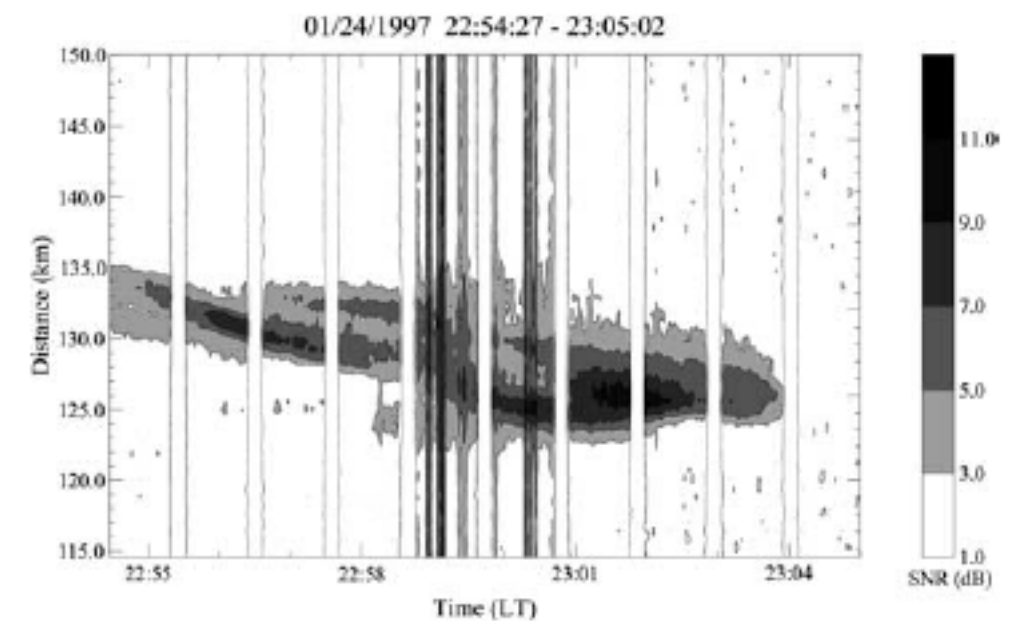


Sounding radio frequency

D 100 200 400 600 800 1000 1500 3000 [km]
 MLF 3.9 4.0 4.1 4.4 4.8 5.3 5.8 10.7 [MHz]
 82961441.tmp / 240fx255h 50 kHz 5.0 km / D²S-4 5M367 067 / 67.0 N 309.1 E
 ShowIonogram v 1.0



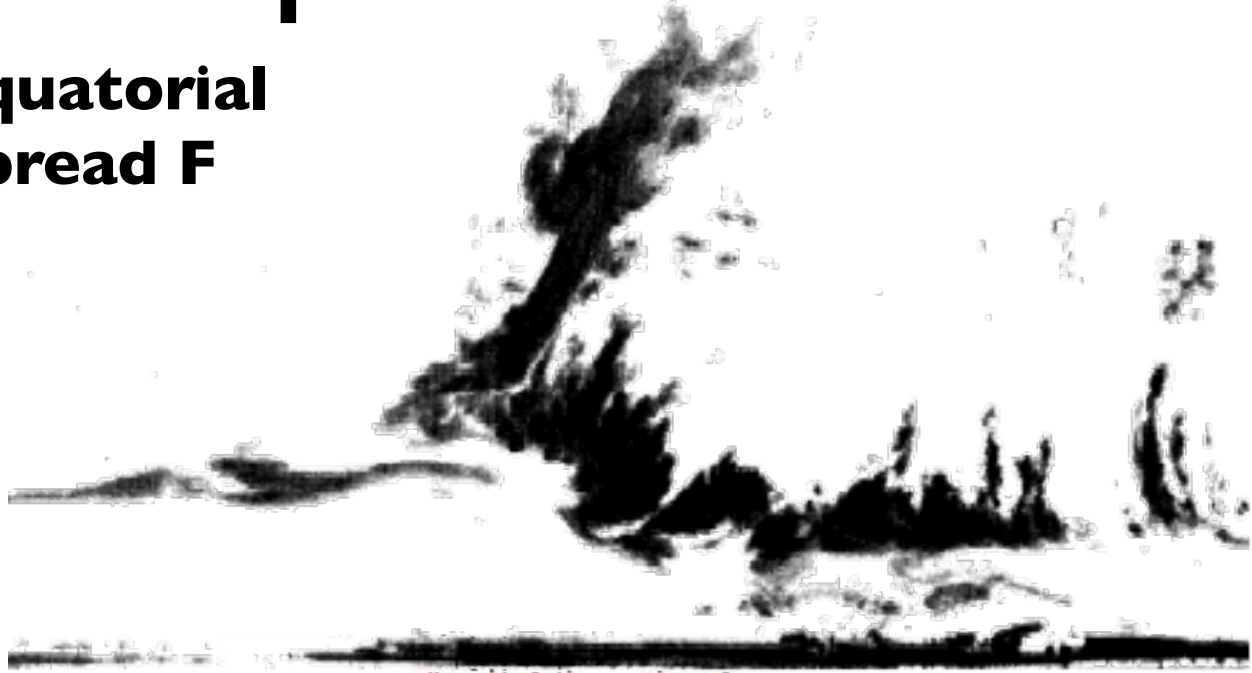
Incoherent scatter radar



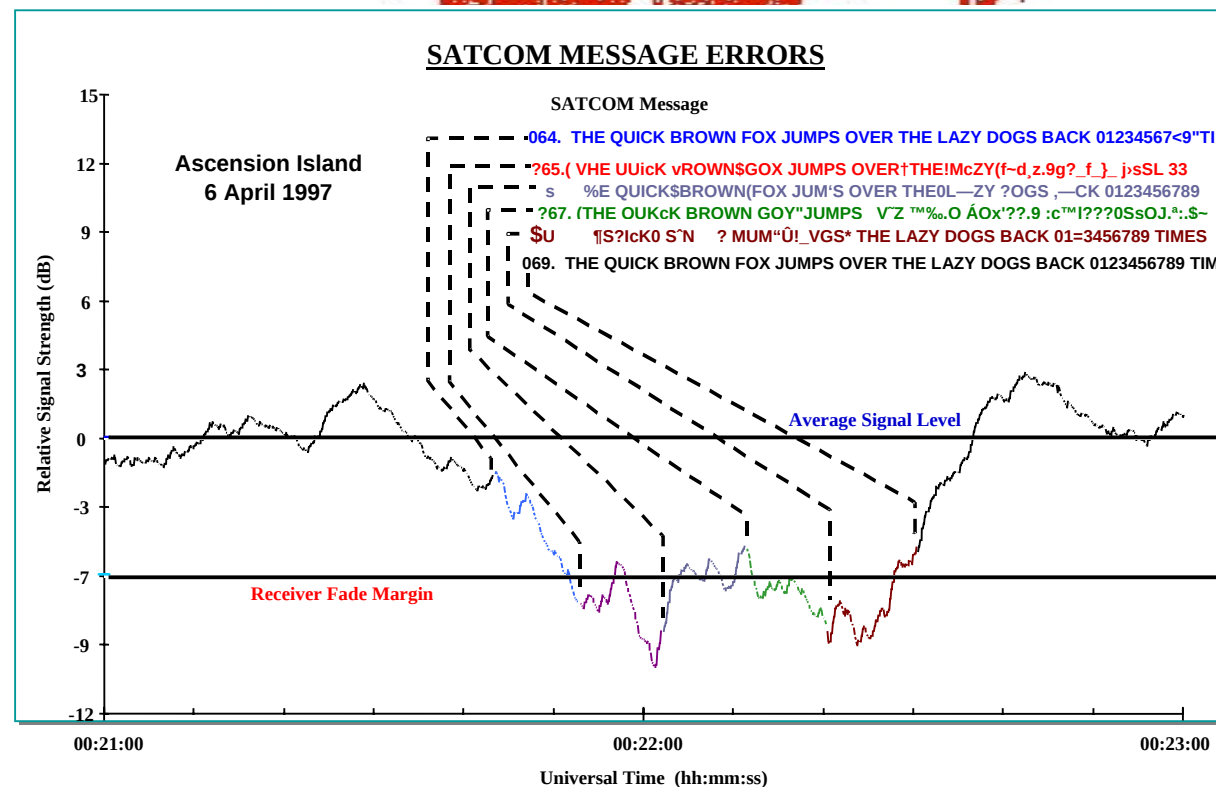
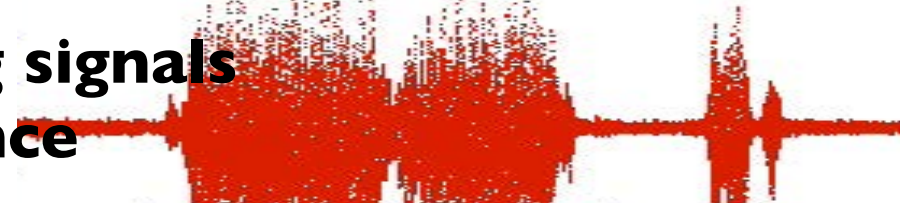
Coherent scatter radar

Space communication anomaly

**Equatorial
Spread F**



**Receiving signals
disturbance**

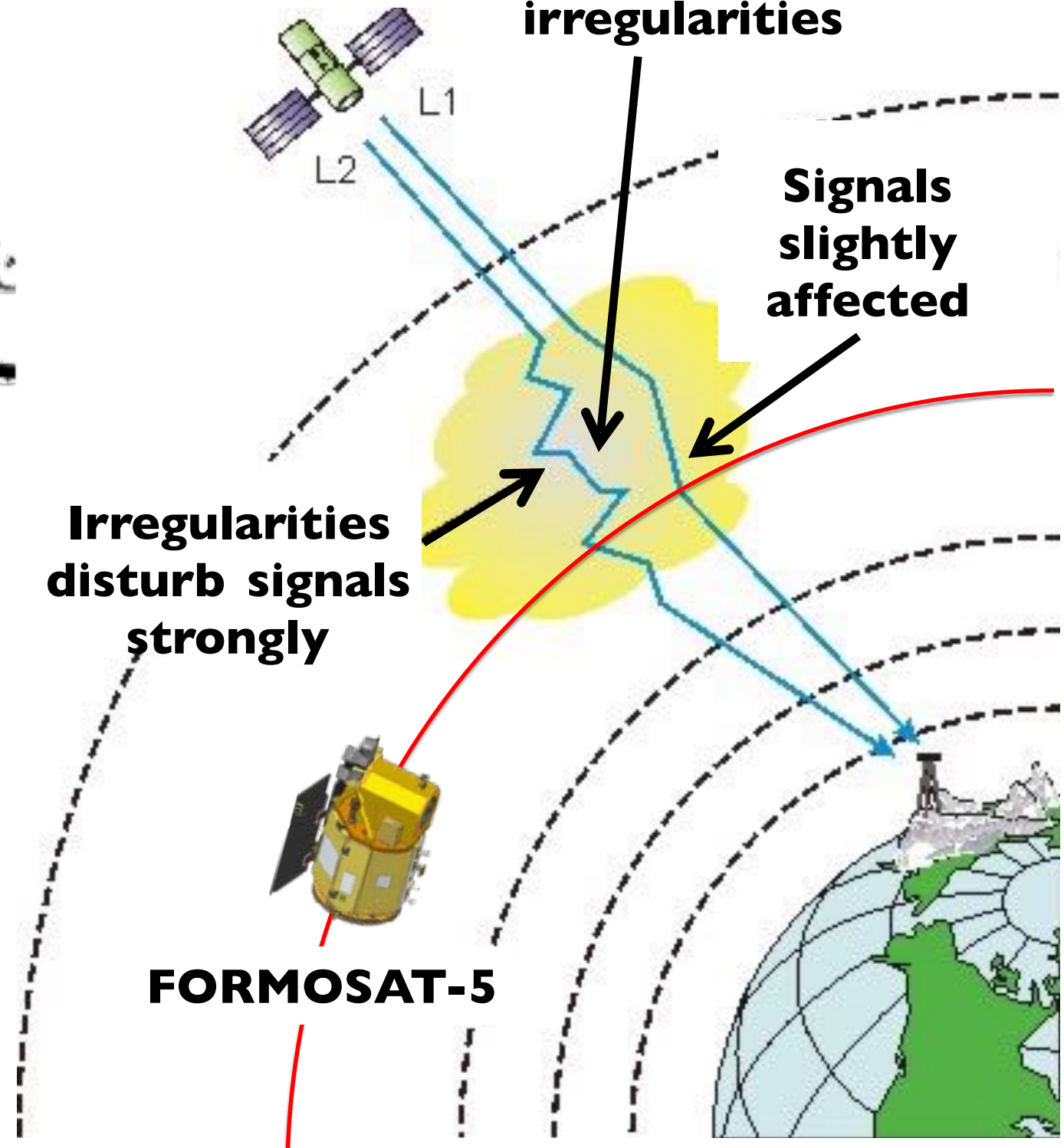


**Plasma
irregularities**

**Signals
slightly
affected**

**Irregularities
disturb signals
strongly**

FORMOSAT-5



Fine structures of the equatorial plasma irregularities

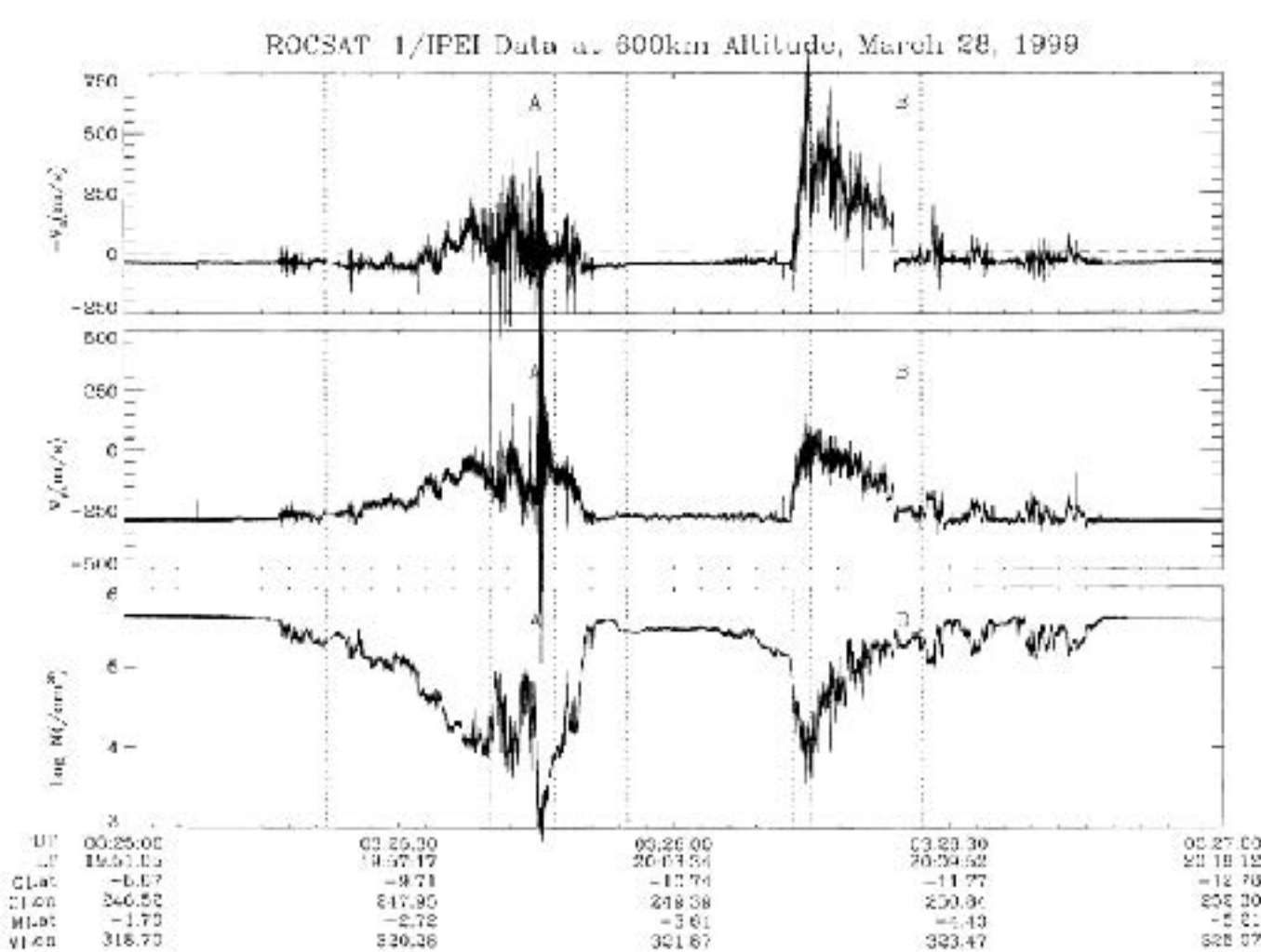


Figure 2. The expanded plot of Figure 1 for the time period 0325-0327 UT for bubble A and bubble B near the magnetic equator. The corotation component in V_z has been removed. Vertical dotted lines indicate the locations of sampled 1-s power spectra plotted in Figure 3.

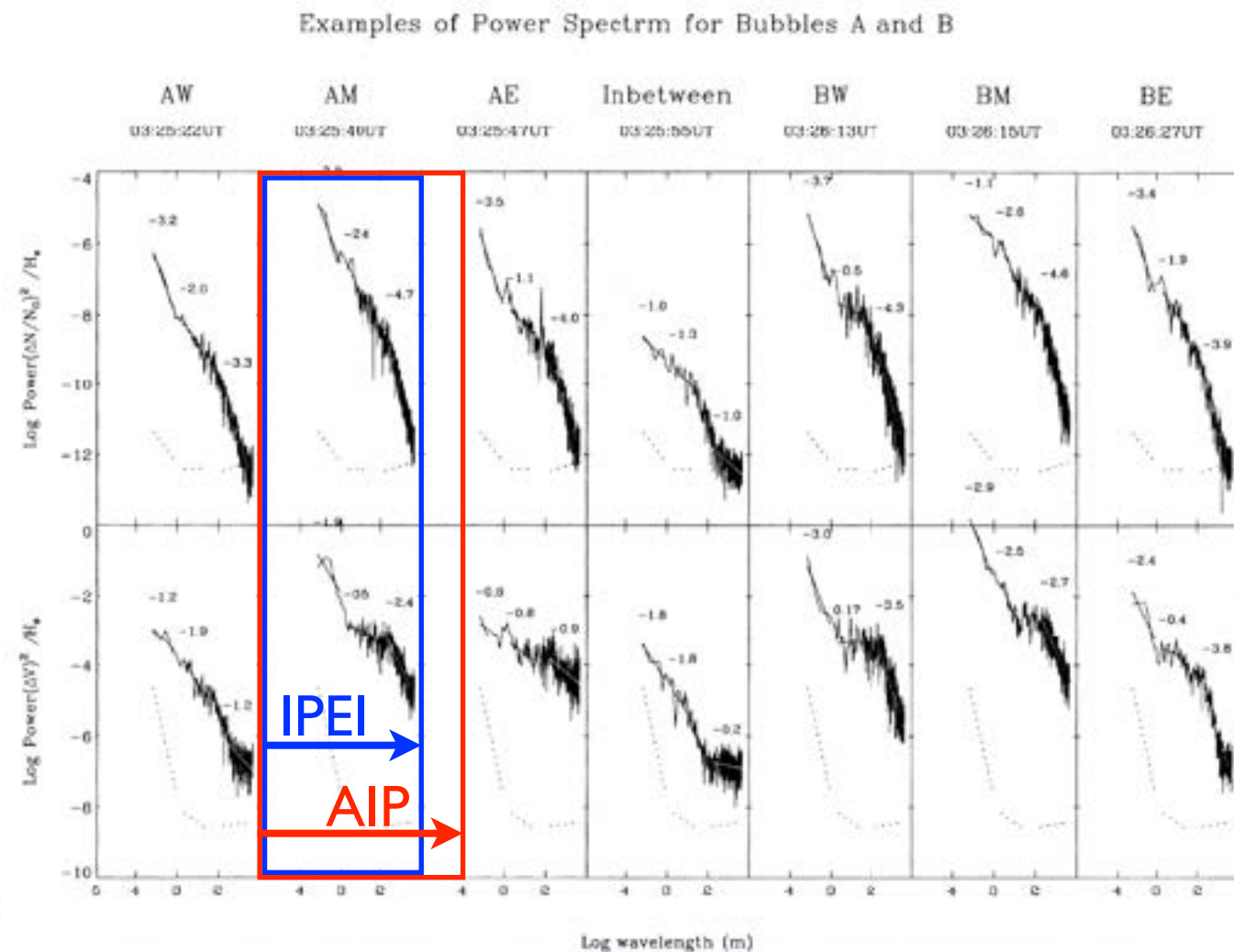
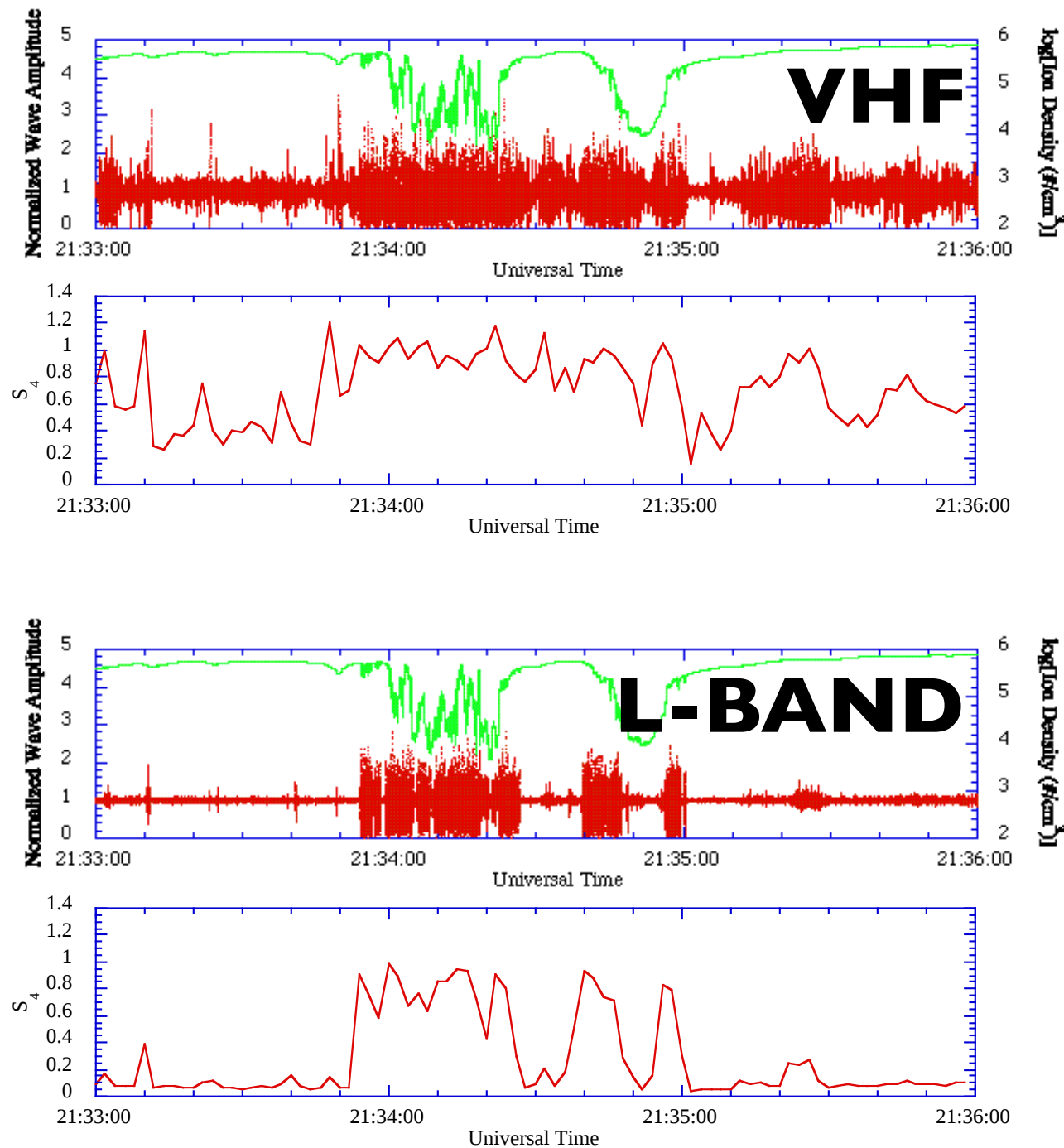


Figure 3. Examples of power spectra for $(\Delta N/N_0)$ and ΔF_z fluctuations at various parts of the bubbles as indicated by vertical lines in bubbles A and B in Figure 2.

Su et al., 2001, *JGR*

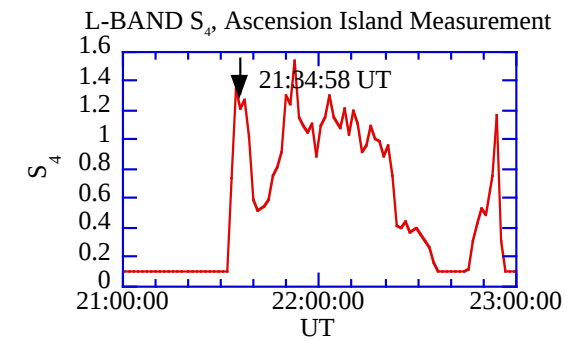
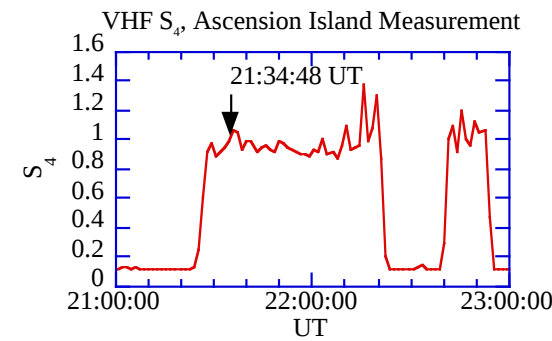
The AIP can explore 8 x finer scale fluctuations than those measured by ROCSAT-1/IPEI.

Propagation simulation

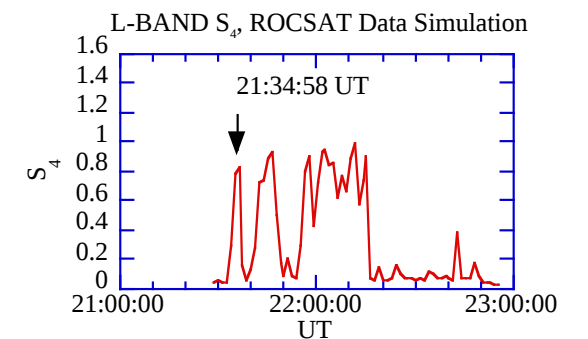
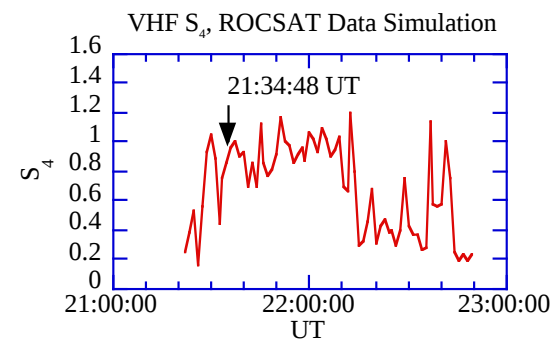


Simulation vs. ground data

Ground data



Simulation



VHF

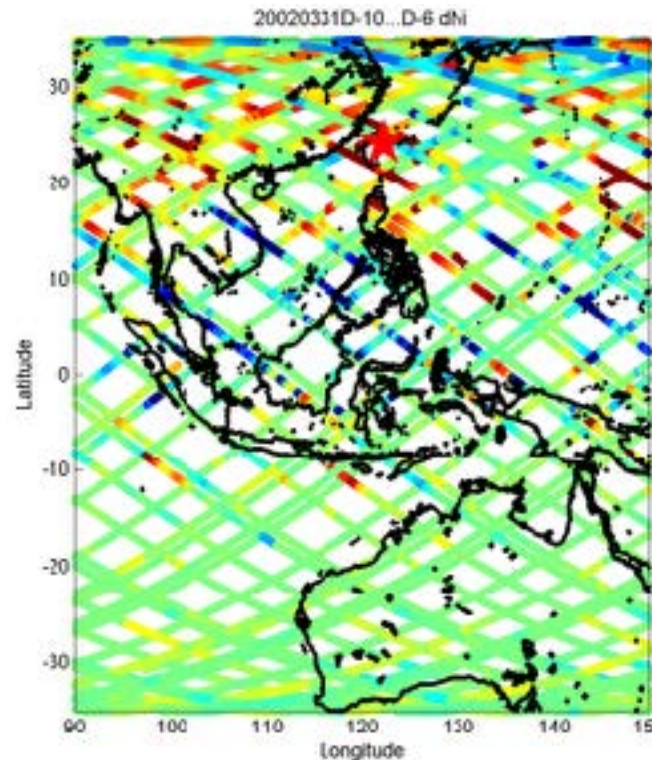
L-BAND

Liu et al., 2012, *Radio Sci.*

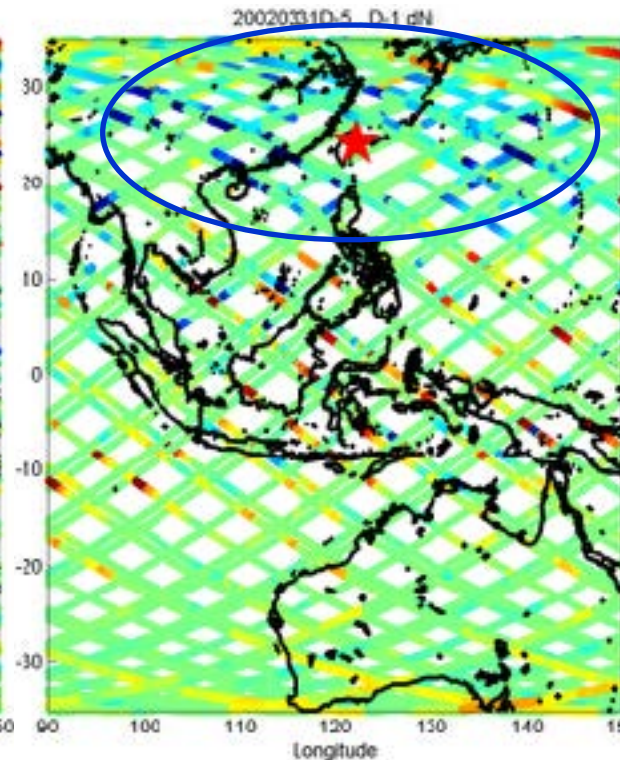
AIP can measure N_i structures to compare to RF signals at ground equivalent to 100 Hz samples for ionospheric scintillation study if eastward drift of the equatorial plasma irregularities is $\sim 100 \text{ ms}^{-1}$.

Ionospheric earthquake precursor

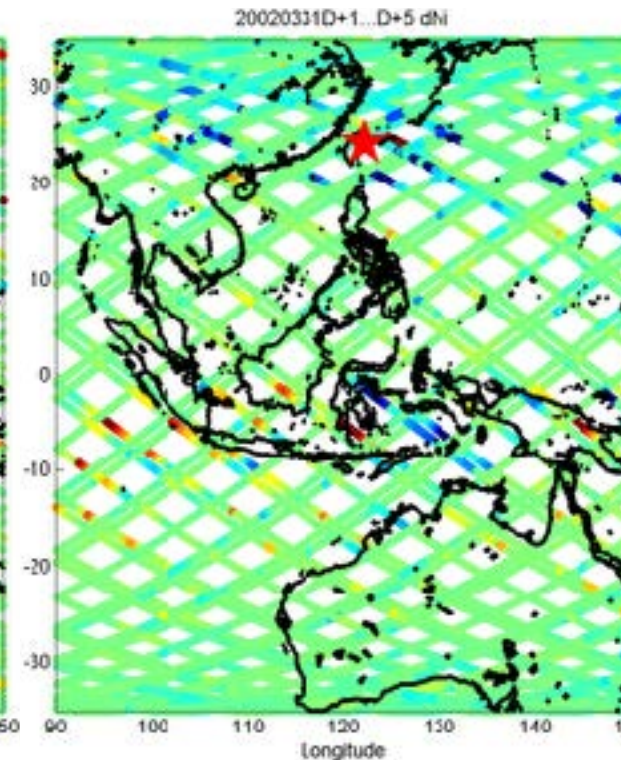
6-10 days before the EQ



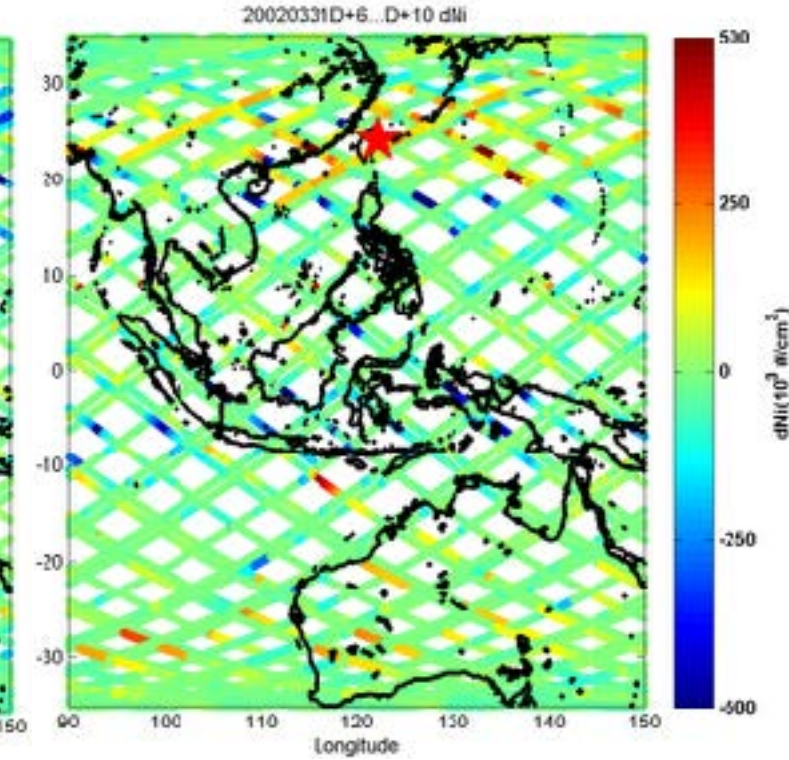
1-5 days before the EQ



1-5 days after the EQ



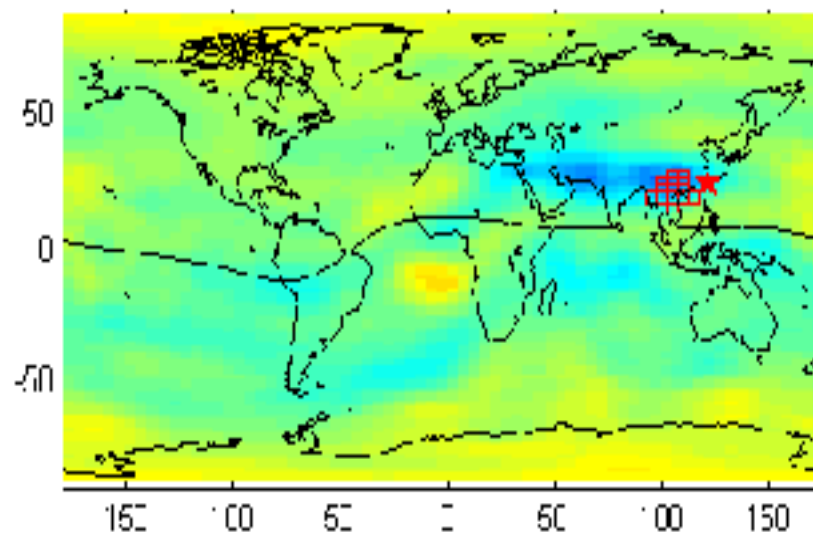
6-510 days after the EQ



Total ion concentration detected by ROCSAT-I satellite is abnormally reduced 1-5 days before the Yilan earthquake, M6.8, on 3/31/2002.

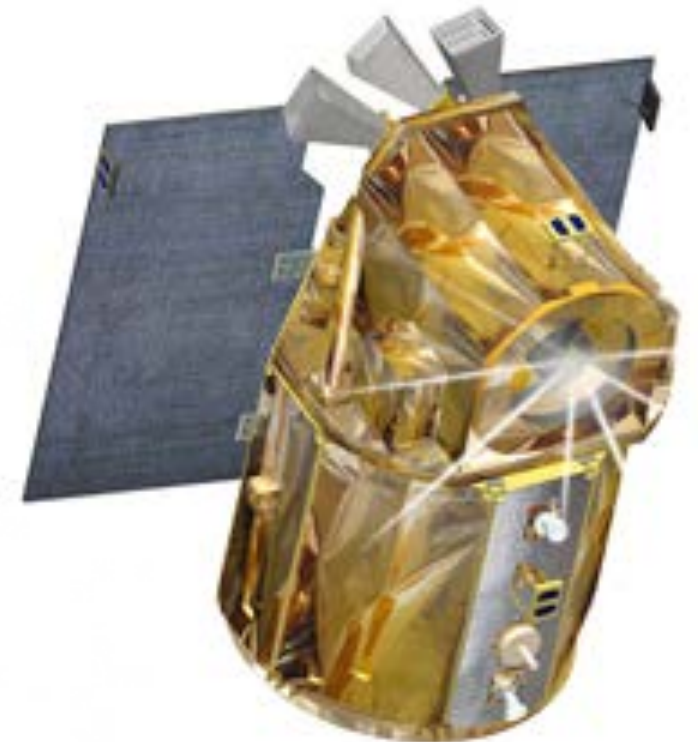
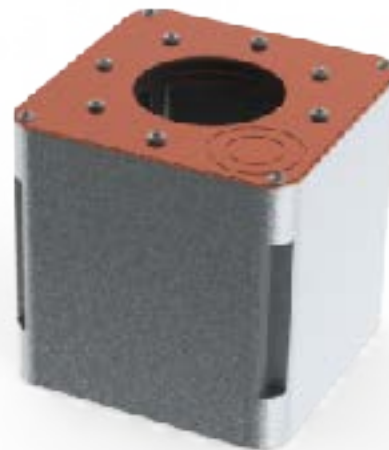
Total Electron Content (TEC) by GPS are greatly reduced 2 days before the earthquake.

20020329 continuous anomaly L U to 12



Requirements for geophysical parameters

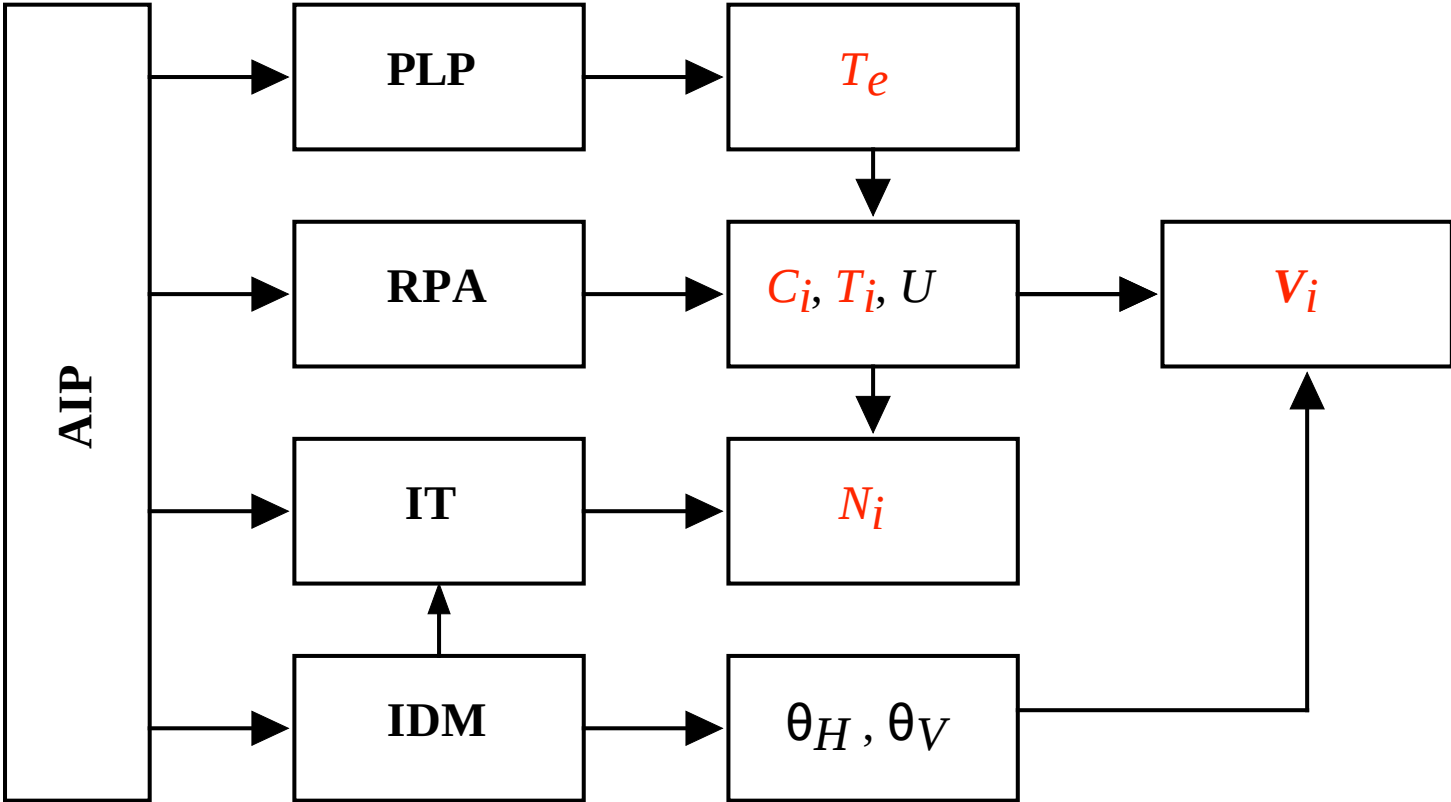
- The FORMOSAT-5 mission orbit is at 720 km altitude with inclination 98.28° as a sun-synchronous orbit at 1030/2230 LT sector.
- Derived from International Reference Ionosphere - 2001.
- Parameter ranges (according to day & night, seasons, and solar fluxes):
 - N_e (or N_i): 5.13×10^3 to $2.61 \times 10^5 \text{ \# cm}^{-3}$.
 - T_e : 910 to 3,100 K.
 - T_i : 770 to 2,370 K.



Requirements

Parameters	Range	Accuracy
C_i	5% to 100%	10%
N_i	10^3 to $5 \times 10^6 \text{ cm}^{-3}$	10%
$\mathbf{V}_i$ (w.r.t ground)	$\pm 2 \text{ km s}^{-1}$ (cross track) $\pm 2 \text{ km s}^{-1}$ (ram)	$\pm 50 \text{ m s}^{-1}$ $\pm 200 \text{ m s}^{-1}$
T_i	750 to 5,000 K	$\pm 200 \text{ K}$
T_e	750 to 5,000 K	$\pm 200 \text{ K}$

Data availabilities



Mode	N_i	Transverse components of the ion velocity	Others
NORMAL	128 Hz	32 Hz	1 Hz
FAST	1,024 Hz	256 Hz	1 Hz
BURST	8,192 Hz	2,048 Hz	1 Hz

Parameters	Range	Sensitivity	Accuracy
C_i	3% to 100%	1%	10%
N_i	10^3 to 10^6 cm ⁻³	1%	10%
V_i (w.r.t satellite)	± 2.5 km s ⁻¹ 7.5 ± 1 km s ⁻¹ (ram)	± 10 m s ⁻¹ ± 100 m s ⁻¹	± 50 m s ⁻¹ ± 200 m s ⁻¹
T_i	500 to 5,000 K	± 50 K	± 200 K
T_e	500 to 5,000 K	± 50 K	± 200 K

Principles of measurement

- Distribution function for a steady state condition
- Langmuir probe
- Retarding potential analyzer
- Ion drift meter



Integration of constant

Assuming a collision-less, electrostatic and no external magnetic field condition, the **Vlasov equation** can be rewritten as

$$\frac{\partial f_j}{\partial t} + \mathbf{v} \cdot \frac{\partial f_j}{\partial \mathbf{x}} + \frac{q_j}{m_j} \left(\mathbf{E} + \frac{\mathbf{v} \times \mathbf{B}}{c} \right) \cdot \frac{\partial f_j}{\partial \mathbf{v}} = 0$$

The phase space distribution function will be conserved if follows a dynamical trajectory described as

$$\frac{dx}{v_x} = \frac{dy}{v_y} = \frac{dz}{v_z} = \frac{dv_x}{-\frac{q_j}{m_j} \frac{\partial V}{\partial x}} = \frac{dv_y}{-\frac{q_j}{m_j} \frac{\partial V}{\partial y}} = \frac{dv_z}{-\frac{q_j}{m_j} \frac{\partial V}{\partial z}}$$

An integration of constant (**conservation law of total energy**) can be obtained as

$$\frac{m_j v^2}{2} + q_j V = \text{const}$$

Maxwell-Boltzmann distribution function

Any function with the energy conservation form will be accepted as a solution of the Vlasov equation, so the distribution function can be described as

$$f(\mathbf{x}, \mathbf{v}) = f\left(\frac{mv^2}{2} + qV(\mathbf{x})\right)$$

In our application, a satellite flows through the ionosphere horizontally with a supersonic speed, a three-dimensional Maxwell-Boltzmann distribution function **with drift velocity U** is applied to obtain the **steady flux** collected within the retarding potential analyzer as

$$f(\mathbf{x}, \mathbf{v}) = n_o \left(\frac{m}{2\pi\kappa T}\right)^{\frac{3}{2}} \exp\left[-\left(\sqrt{\frac{mv^2}{2\kappa T} + \frac{qV(\mathbf{x})}{\kappa T}} - \sqrt{\frac{mU^2}{2\kappa T}}\right)^2\right]$$

~~$$f(\mathbf{x}, \mathbf{v}) = n_o \left(\frac{m}{2\pi\kappa T}\right)^{\frac{3}{2}} \exp\left[-\left(\frac{m(v-U)^2}{2\kappa T} + \frac{qV(\mathbf{x})}{\kappa T}\right)\right]$$~~

The moment equations

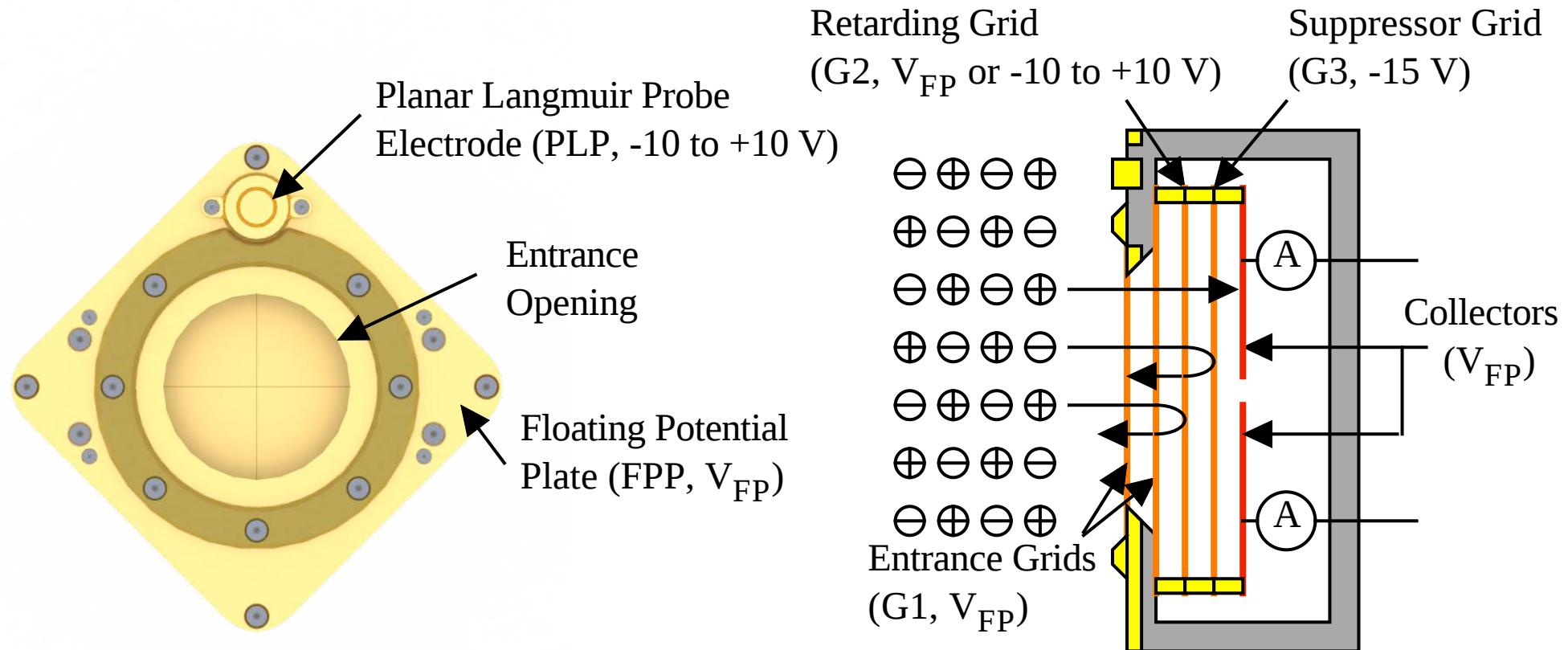
The particle number density n and flux Φ are defined by integrating the phase space distribution function over velocity space as

$$n(\mathbf{x}) \equiv \int f(\mathbf{x}, \mathbf{v}) d\mathbf{v}$$

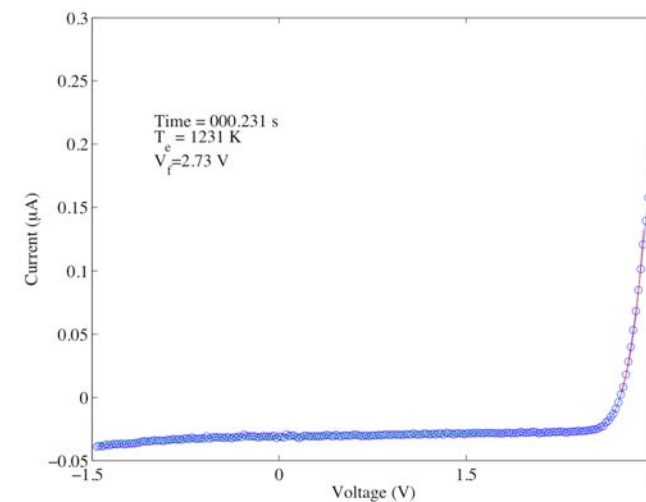
$$\Phi(\mathbf{x}) \equiv n(\mathbf{x})\mathbf{u}(\mathbf{x}) \equiv \int f(\mathbf{x}, \mathbf{v}) \mathbf{v} d\mathbf{v}$$

where $\mathbf{u}(\mathbf{x})$ is the average velocity of incoming plasma at position $\mathbf{x}$. It is noted that lower and upper velocity limits become important in deriving these macroscopic density and flux for different boundary conditions.

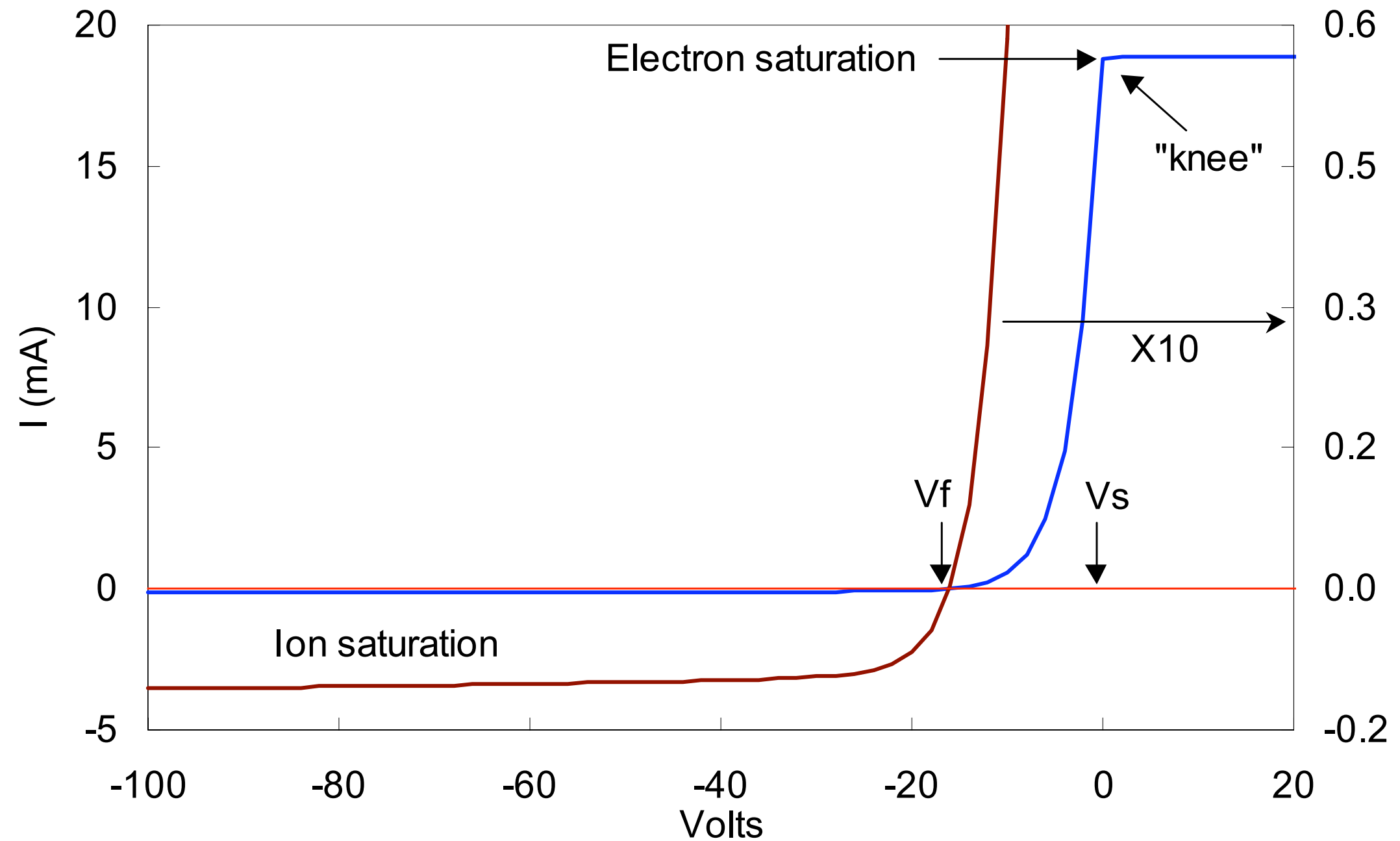
Planar Langmuir Probe (PLP)



$$\frac{\kappa T_e}{e} = \frac{1}{\frac{d}{dV}[\ln(I)]}$$



I-V curve



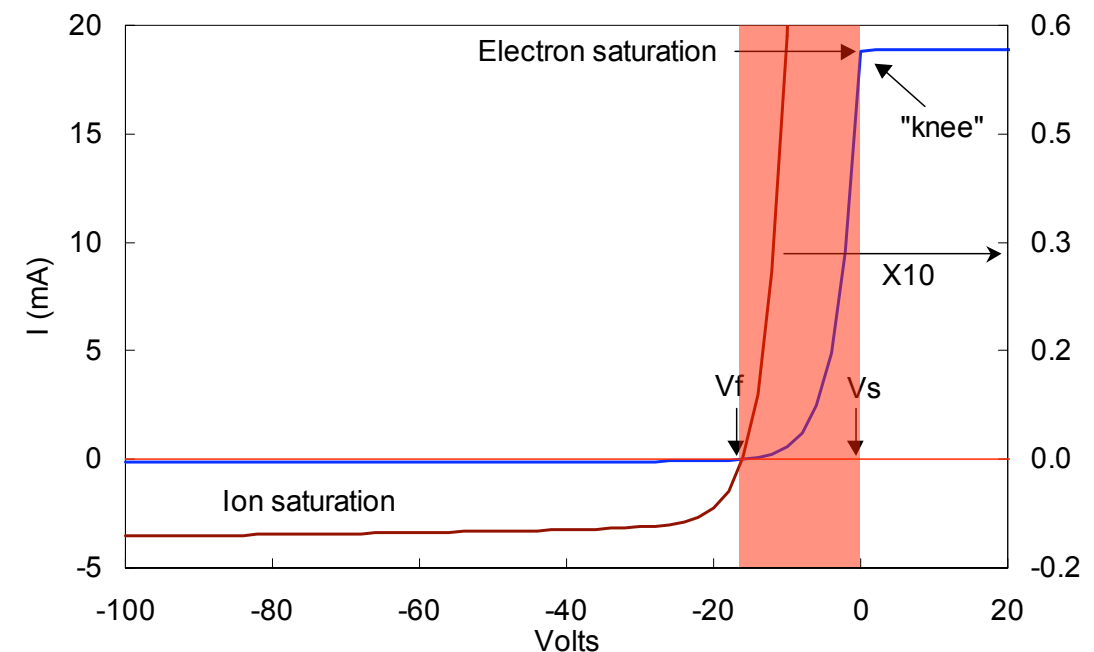
$$I = I_e - I_i$$

Transition region

If the probe voltage is made negative relative to plasma potential, the probe begins to repel electrons and accelerate ions.

Because the fraction of electrons with velocities sufficient for overcoming the decelerating field diminished, the electron current falls as probe voltage decreases, which we shall call the transition region or retarding-field region of the characteristic.

If the electron distribution were Maxwellian, the shape of the curve, after the contribution of ions is subtracted, would be exponential.



For $V < 0$, the lowest limit for a free electron to hit on probe surface is zero.

$$\int_0^{\infty} v \exp(-\alpha v^2) dv = \frac{\exp(-\alpha \omega^2)}{2\alpha}$$

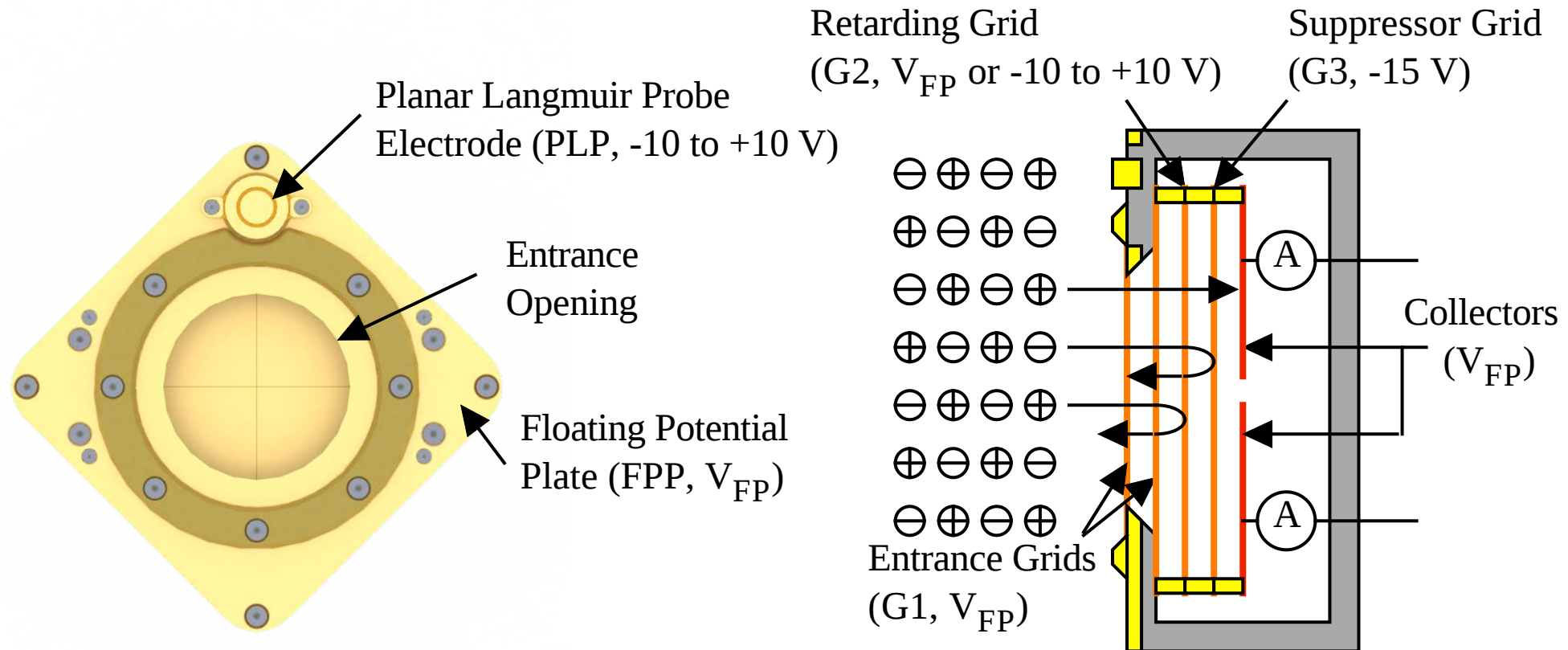
$$\begin{aligned} \Phi(V) &= \int_{-\infty}^{\infty} \int_{-\infty}^{\infty} \int_0^{\infty} n_o \sqrt{\left(\frac{m_e}{2\pi\kappa T_e}\right)^3} \exp\left[-\left(\frac{m_e(v_x^2 + v_y^2 + v_z^2) - 2eV}{2\kappa T_e}\right)\right] v_x dv_x dv_y dv_z \\ &= n_o \exp\left(\frac{eV}{\kappa T_e}\right) \left[\int_{-\infty}^{\infty} \sqrt{\frac{m_e}{2\pi\kappa T_e}} \exp\left(-\frac{m_e v_y^2}{2\kappa T_e}\right) dv_y \right] \left[\int_{-\infty}^{\infty} \sqrt{\frac{m_e}{2\pi\kappa T_e}} \exp\left(-\frac{m_e v_z^2}{2\kappa T_e}\right) dv_z \right] \\ &\quad \left[\int_0^{\infty} \sqrt{\frac{m_e}{2\pi\kappa T_e}} v_x \exp\left(-\frac{m_e v_x^2}{2\kappa T_e}\right) dv_x \right] = n_o \exp\left(\frac{eV}{\kappa T_e}\right) \frac{\sqrt{\frac{m_e}{2\pi\kappa T_e}}}{2 \frac{m_e}{2\kappa T_e}} = \frac{1}{4} n_o \sqrt{\frac{8\kappa T_e}{\pi m_e}} \exp\left(\frac{eV}{\kappa T_e}\right) \end{aligned}$$

$$I(V) = qA\Phi(V) = I_e = A(-e)n_o \exp\left(\frac{eV}{\kappa T_e}\right) \sqrt{\frac{\kappa T_e}{2\pi m_e}}$$

$$\rightarrow \ln(I) = \ln\left[A(-e)n_o \exp\left(\frac{eV}{\kappa T_e}\right) \sqrt{\frac{\kappa T_e}{2\pi m_e}}\right] = \ln\left[A(-e)n_o \sqrt{\frac{\kappa T_e}{2\pi m_e}}\right] + \frac{eV}{\kappa T_e}$$

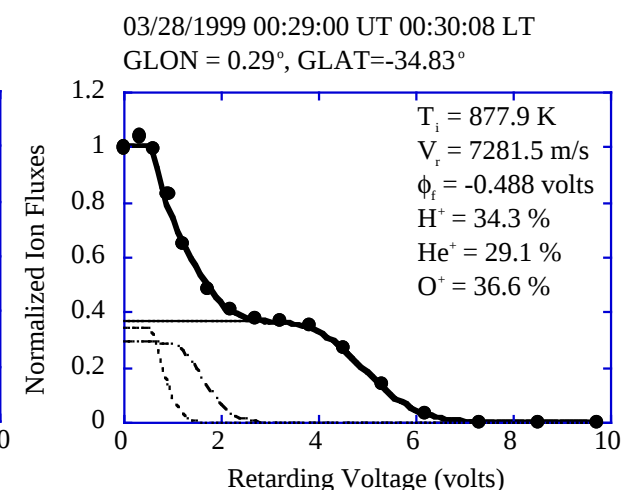
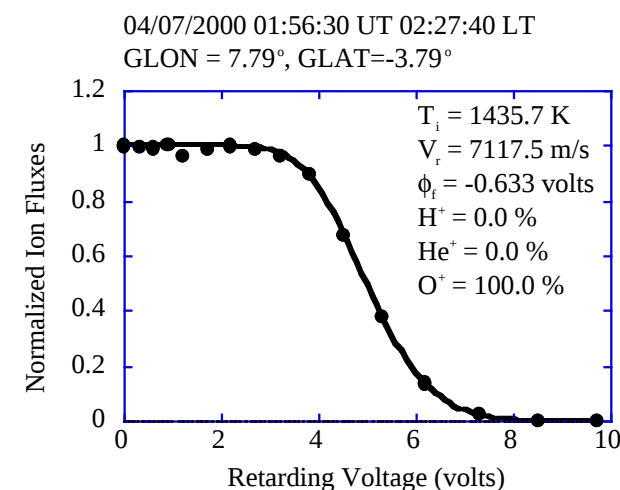
$$\rightarrow \frac{d}{dV}[\ln(I)] = \frac{e}{\kappa T_e} \rightarrow T_e = \frac{e}{\kappa} \frac{1}{\frac{d}{dV}[\ln(I)]}$$

Retarding Potential Analyzer (RPA)



$$I = CA \sum_s q_s n_{s0} U_s \left\{ \frac{1}{2} \left[1 + \operatorname{erf}(\beta_s F_s) + \frac{\exp(-\beta_s^2 F_s^2)}{\sqrt{\pi} \beta_s U_s} \right] \right\}$$

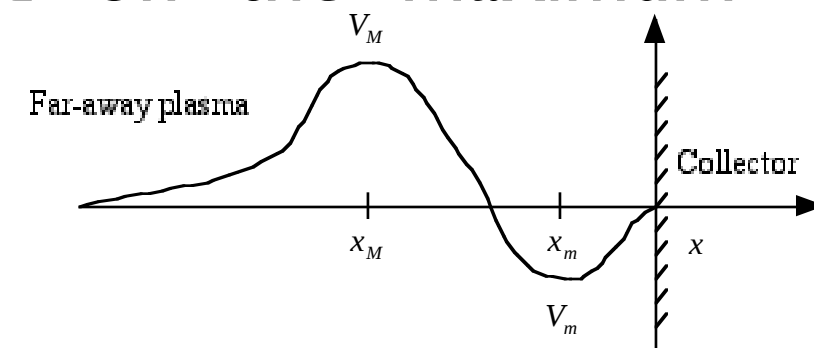
$$\beta_s = \sqrt{\frac{m_s}{2\kappa T_s}}, \quad \beta_s F_s = U_s / \sqrt{\frac{2\kappa T_s}{m_s}} - \sqrt{\frac{q_s V_{G2}}{\kappa T_s}}$$



The lower velocity limit

To derive the ion flux within the RPA, several assumptions are made here. We set electric potential to zero for plasma far away from collector. In a fixed frame of a satellite rigid body, positive ions can stream with about satellite velocity from outside the RPA into the collector. Based on the conservation of energy, the retarding potential structure inside the RPA will prevent the low energy positive ions from reaching the collector. The lower velocity limit v_L for integration is depended on the maximum potential V_M along the streaming path and its location

$$v_L = \pm \sqrt{\frac{2q[V_M - V(x)]}{M}}$$



where M is the ion mass. The positive sign indicates that the distribution has overcome the maximum potential barrier (between the retarding grid and the collector, i.e., $x > x_M$) and the negative sign indicates that the distribution has return particles (between the far away space and retarding grid, i.e., $x < x_M$).

The ion flux equation

The flux for a single species can be integrated as

$$\Phi(x) = \int_{v_L}^{\infty} f v dv = \int_{\pm \sqrt{\frac{2q[V_M - V(x)]}{M}}}^{\infty} n_o \sqrt{\frac{M}{2\pi\kappa T}} \exp \left[- \left(\sqrt{\frac{Mv^2}{2\kappa T} + \frac{qV}{\kappa T}} - \sqrt{\frac{MU^2}{2\kappa T}} \right)^2 \right] v dv$$

Let's define the variable α and substitute it into the flux equation

$$\alpha = \sqrt{\frac{Mv^2}{2\kappa T} + \frac{qV}{\kappa T}} - \sqrt{\frac{MU^2}{2\kappa T}} \rightarrow v dv = \frac{\alpha + \sqrt{\frac{MU^2}{2\kappa T}}}{\left(\frac{M}{2\kappa T} \right)} d\alpha$$

The lower limit of the integration is not a function of position any more and can be changed to

$$\alpha_L = \sqrt{\frac{qV_M}{\kappa T}} - \sqrt{\frac{MU^2}{2\kappa T}}$$

The ion flux equation (cont.)

The flux can be modified as

$$\Phi = \int_{\sqrt{\frac{qV_M}{\kappa T}} - \sqrt{\frac{MU^2}{2\kappa T}}}^{\infty} n_o \sqrt{\frac{M}{2\pi\kappa T}} \exp[-\alpha^2] \left(\alpha + \sqrt{\frac{MU^2}{2\kappa T}} \right) \frac{d\alpha}{\left(\frac{M}{2\kappa T} \right)}$$

Using these definite integrals from mathematical handbook

$$\int_x^{\infty} \exp[-\alpha^2] d\alpha = \frac{\sqrt{\pi}}{2} [1 - \operatorname{erf}(x)]$$

$$\int_x^{\infty} \exp[-\alpha^2] \alpha d\alpha = \frac{\exp[-x^2]}{2}$$

The flux equation can be derived as

$$\Phi(V_M) = n_o U \left\{ \frac{1}{2} \left[1 + \operatorname{erf}(\beta F) + \frac{\exp[-(\beta F)^2]}{\sqrt{\pi} \beta U} \right] \right\}$$

, where

$$\beta = \sqrt{\frac{M}{2\kappa T}} \quad F = U - \sqrt{\frac{2qV_M}{M}}$$

$$\beta F = \frac{U}{\sqrt{\frac{2\kappa T}{M}}} - \sqrt{\frac{qV_M}{\kappa T}}$$

High ram velocity

From the ion flux equation for multiple species, the ion flux at far away plasma (the electric potential is set to zero) is expressed as

$$\Phi(0) = \sum_i \Phi_i(0) = \sum_i n_{oi} U_i \left\{ \frac{1}{2} \left[1 + \operatorname{erf}(\beta_i U_i) + \frac{\exp[-(\beta_i U_i)^2]}{\sqrt{\pi} \beta_i U_i} \right] \right\}$$

For ROCSAT observation, the **ion ram velocities U_i** ($\sim$ satellite velocity) are **larger than the ion thermal speeds**, i.e.:

$$\beta_i U_i = U_i / \sqrt{\frac{2\kappa T_i}{M_i}} \gg 1$$

The error function can be expanded for large $\beta_i U_i$ and the ion flux at zero electric potential can be reduced to

$$\Phi(0) = \sum_i \Phi_i(0) \sim \sum_i n_{oi} U_i \left\{ \frac{1}{2} \left[1 + 1 - \frac{\exp[-(\beta_i U_i)^2]}{\sqrt{\pi} \beta_i U_i} \left(1 - \frac{1}{2\beta_i^2 U_i^2} + \dots \right) + \frac{\exp[-(\beta_i U_i)^2]}{\sqrt{\pi} \beta_i U_i} \right] \right\} \sim \sum_i n_{oi} U_i$$

Cut-off potential

We can define a cut-off electric potential V_{ci} for species i to make $\beta_i F_i = 0$. It is similar to zero point of the second derivative of the I-V curve with respect to the potential mentioned by *Greenspan et al.* [1986]. Such the cut-off potential can be written as

$$V_{ci} \equiv \frac{M_i U_i^2}{2q_i}$$

The **cut-off potential** was defined [*Chao and Su, 1999*] as the potential that prevents the mean flow of a specific species from reaching the collector plate. The ion fluxes can be written as

$$\Phi_j(V_{ci}) \sim \begin{cases} 0, & \text{if } i > j \\ \Phi_i(0) \left\{ \frac{1}{2} \left[1 + \frac{1}{\sqrt{\pi} \sqrt{\frac{q_i V_{ci}}{\kappa T_i}}} \right] \right\} = \Phi_i(0) \left\{ \frac{1}{2} \left[1 + \frac{1}{\sqrt{\pi} \sqrt{\frac{M_i U_i^2}{2\kappa T_i}}} \right] \right\}, & \text{if } i = j \\ \Phi_j(0), & \text{if } i < j \end{cases}$$

Half current approximation

Considering the ROCSAT flying speed and the ionospheric environment at 600 km altitude, most of cases that we study indicate $M_i U_i^2 / 2 > \kappa T_i$.

Therefore the total ion flux $\Phi(V_{ci})$ can be approximated as

Half current at cut-off potential

$$\Phi(V_{ci}) = \sum_j \Phi_j(V_{ci}) \sim \frac{\Phi_i(0)}{2} + \sum_{i < j} \Phi_j(0)$$

Once the $\Phi(V_{ci})$ are estimated, the cut-off potentials V_{ci} can be searched from the I-V data measured by the RPA through interpolation methods and are expressed as

$$V_{ci} \sim V \left(\Phi = \frac{1}{2} \Phi_i(0) + \sum_{i < j} \Phi_j(0) \right)$$

The ram velocity and the ion density for each species can be derived from

$$U_i = \sqrt{\frac{2q_i V_{ci}}{M_i}}$$

$$n_{oi} = \frac{\Phi_i(0)}{U_i \left\{ \frac{1}{2} \left[1 + \operatorname{erf}(\beta_i U_i) + \frac{\exp[-(\beta_i U_i)^2]}{\sqrt{\pi} \beta_i U_i} \right] \right\}} \sim \frac{\Phi_i(0)}{U_i}$$

Half current approximation (cont.)

To derive the ion temperature, we can differentiate the ion flux equation for species i with electric potential

$$\frac{d\Phi_i}{dV} = \frac{q_i n_{oi}}{\sqrt{2\pi}} \frac{\exp\left[-(\beta_i F_i)^2\right]}{\sqrt{M_i \kappa T_i}}$$

The slope of j -ion flux at V_{ci} can be approximated as

$$\frac{d\Phi_j}{dV}(V_{ci}) \sim \begin{cases} 0, & \text{if } i \neq j \\ -\frac{q_i \Phi_i(0)}{U_i \sqrt{2\pi M_i \kappa T_i}}, & \text{if } i = j \end{cases}$$

Therefore the slope of the total ion flux at V_{ci} can be estimated as

$$\frac{d\Phi}{dV}(V_{ci}) = \sum_j \frac{d\Phi_j}{dV}(V_{ci}) = -\frac{q_i \Phi_i(0)}{U_i \sqrt{2\pi M_i \kappa T_i}}$$

Half current approximation (cont.)

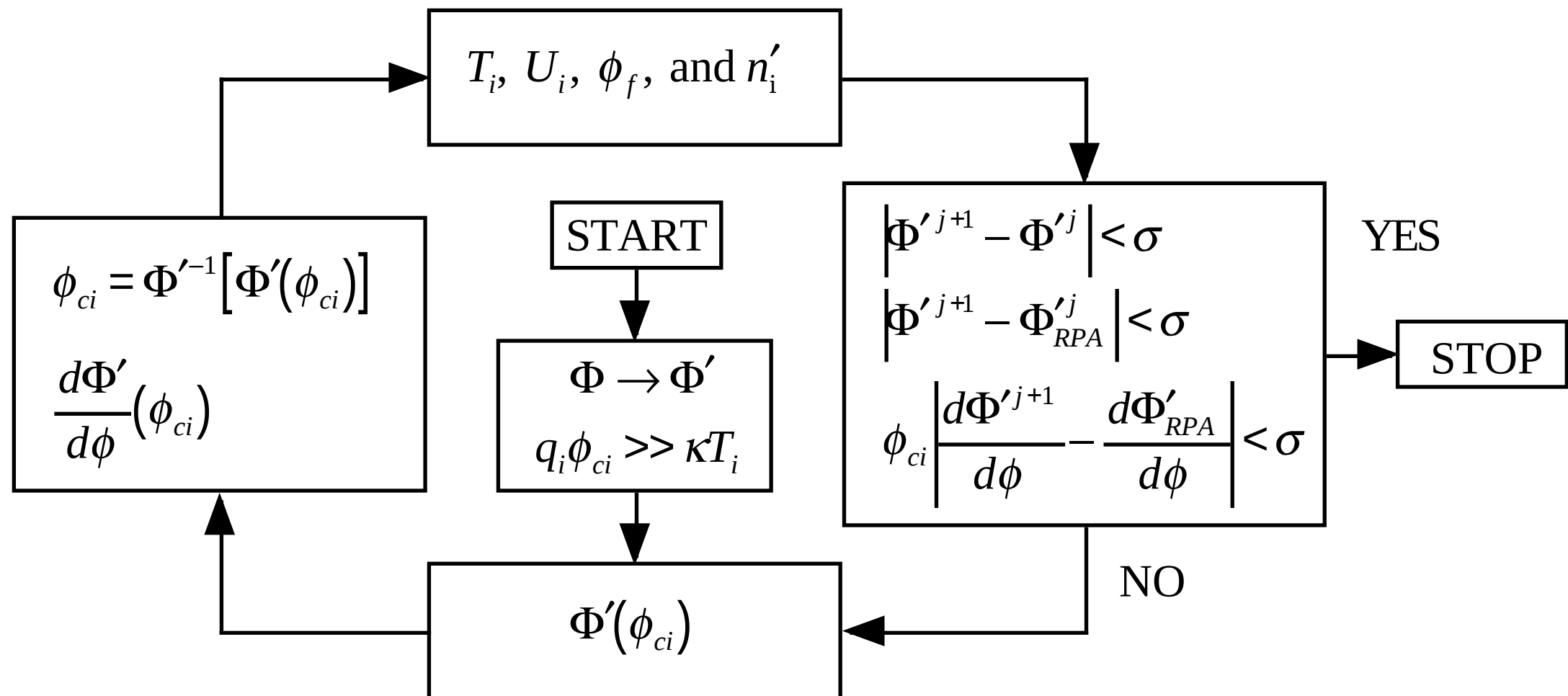
Once the $d\Phi(V_{ci})/dV$ is known (also available from the interpolation of the I-V data), the ion temperature for species i can then be calculated as

$$\kappa T_i = \frac{q_i^2 \Phi_i^2(0)}{2\pi M_i U_i^2 \left[\frac{d\Phi}{dV}(V_{ci}) \right]^2} = \frac{q_i \Phi_i^2(0)}{4\pi V_{ci} \left[\frac{d\Phi}{dV}(V_{ci}) \right]^2}$$

Hence the half-current approximation can obtain the ion ram velocity, ion density and ion temperature for each species. These results can be served as initial guesses for a more sophisticate regression fit.

Half current method

The half-current method is composed by the half-current approximation and a variety of numerical schemes.



Grid search method

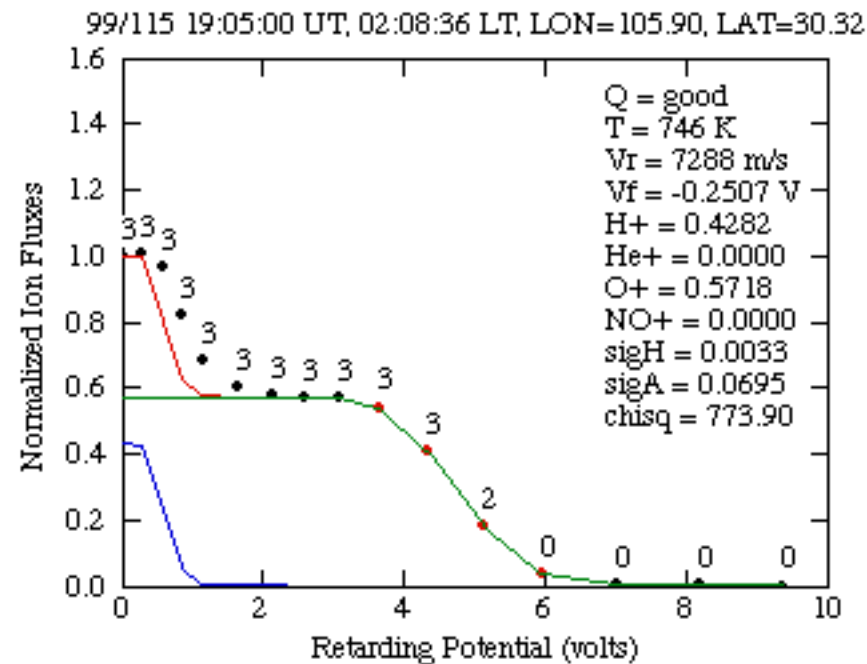
In most statistic textbooks, χ^2 has been recognized as a measure of goodness of fit [Bevington, 2002],

$$\chi^2 \equiv \sum_i \left\{ \frac{[\Phi'_i - \Phi'(V_i)]^2}{\sigma_i^2} \right\}$$

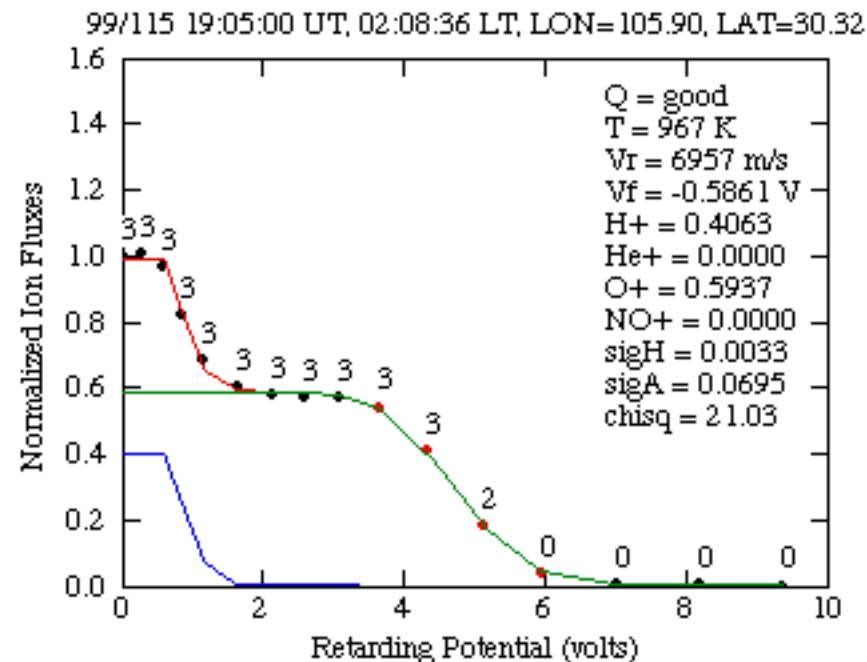
where i is the subscript for different data points and the σ_i are the uncertainties in the normalized data points Φ'_i . The analytical values are the normalized ion fluxes calculated at the potentials V_i from the derived parameters. **One of the easiest methods to find out the minimum of the χ^2 is to use a grid search method.** The minimum of the χ^2 can be derived from the derivative of the χ^2 with respect to each parameter as

$$\frac{\partial \chi^2}{\partial \alpha_k} = \frac{\partial}{\partial \alpha_k} \sum_i \left\{ \frac{[\Phi'_i - \Phi'(V_i)]^2}{\sigma_i^2} \right\} = 0$$

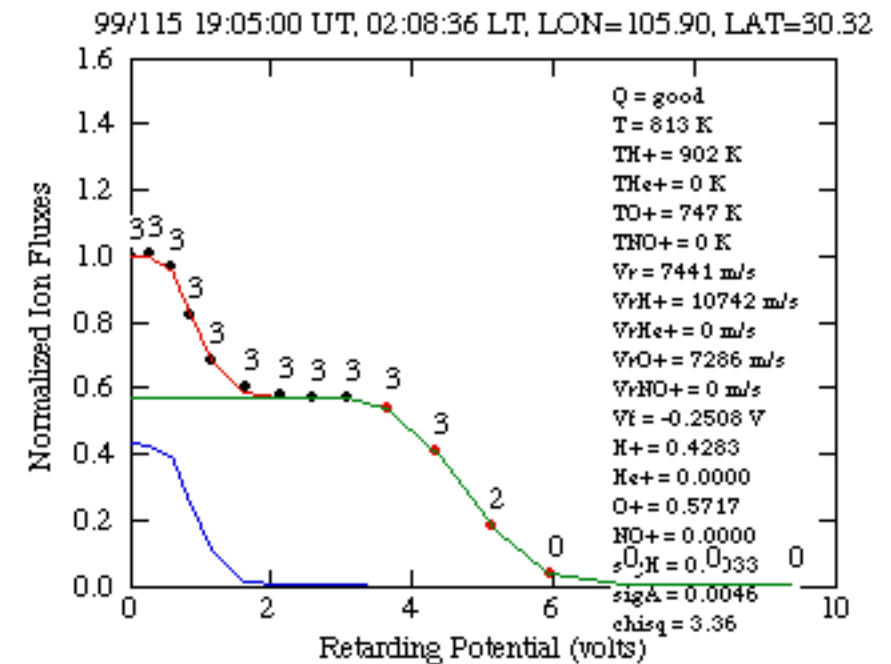
Half-current method only single species



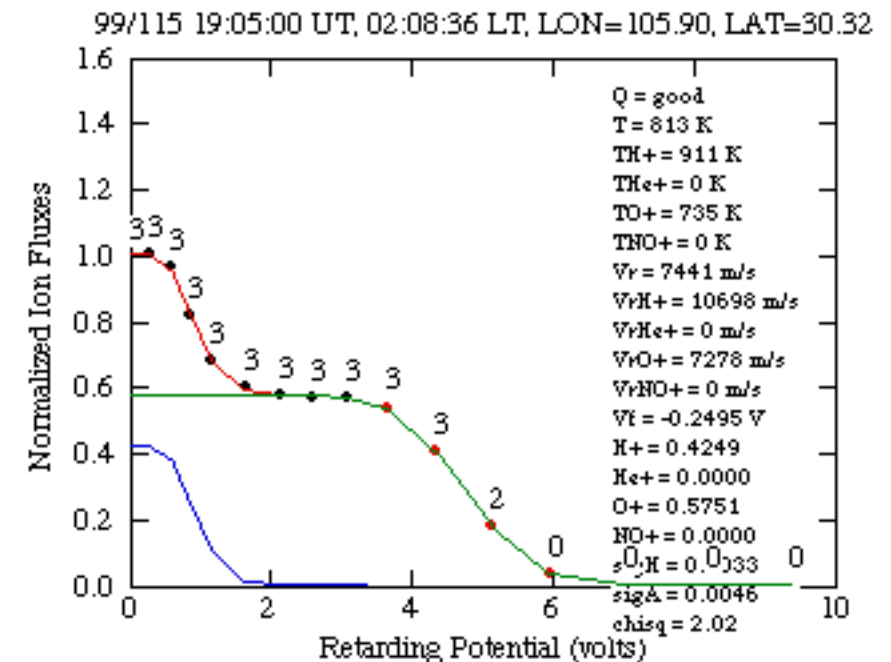
Least-squares fit single species



Half-current method only multiple species



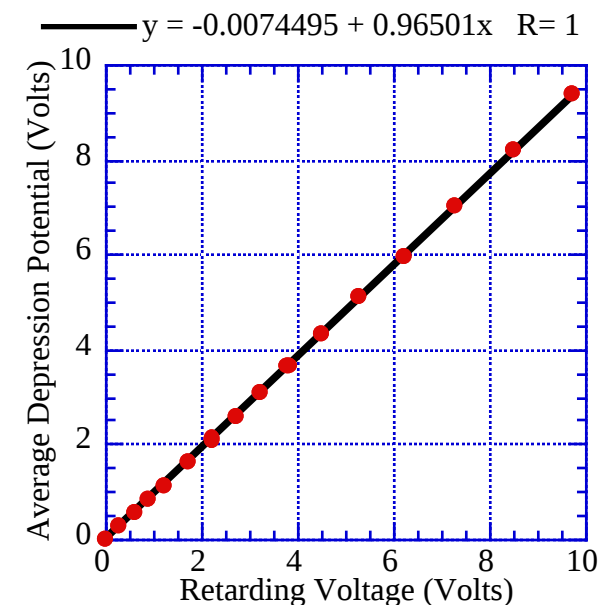
Least-squares fit multiple species



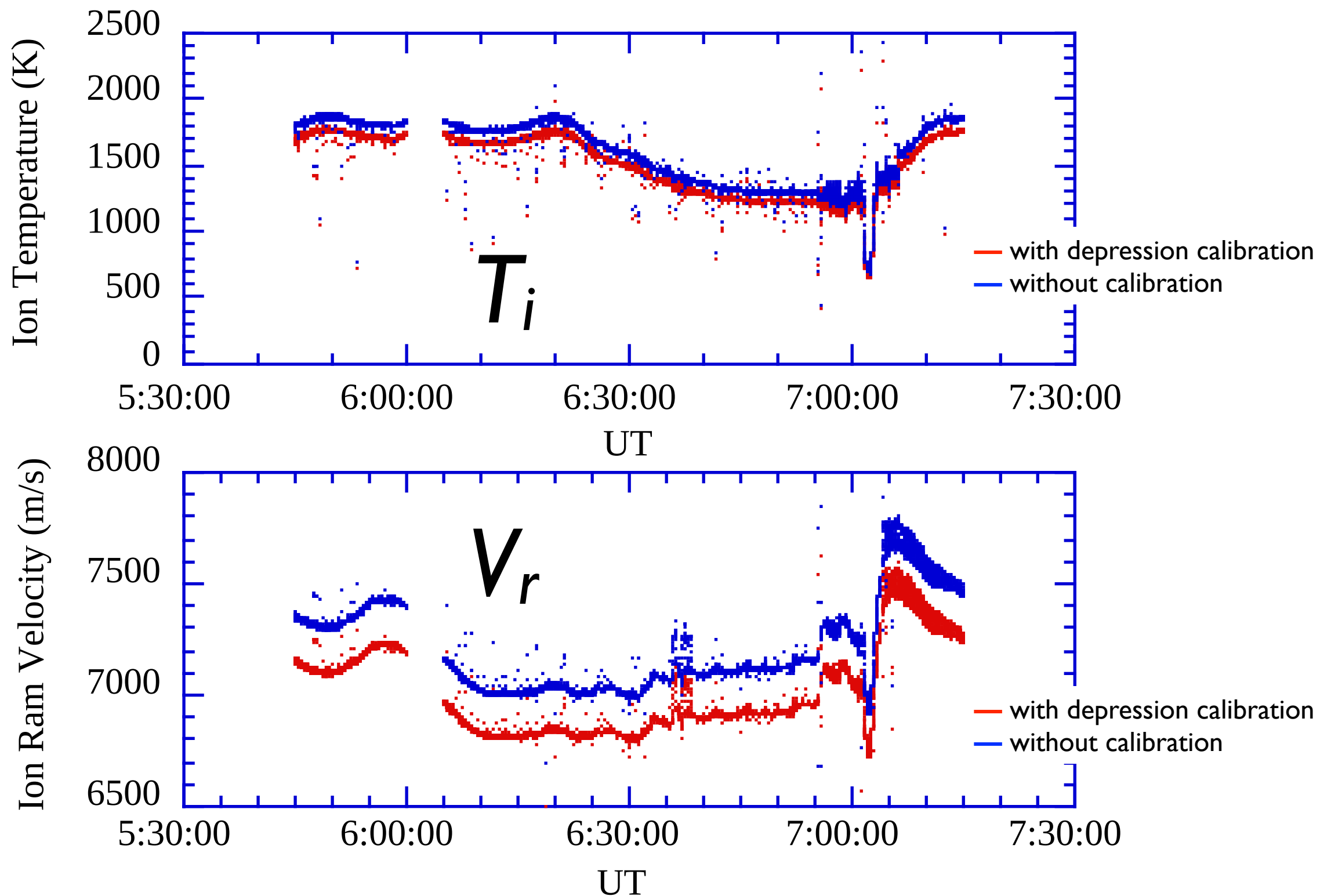
Grid potential depression

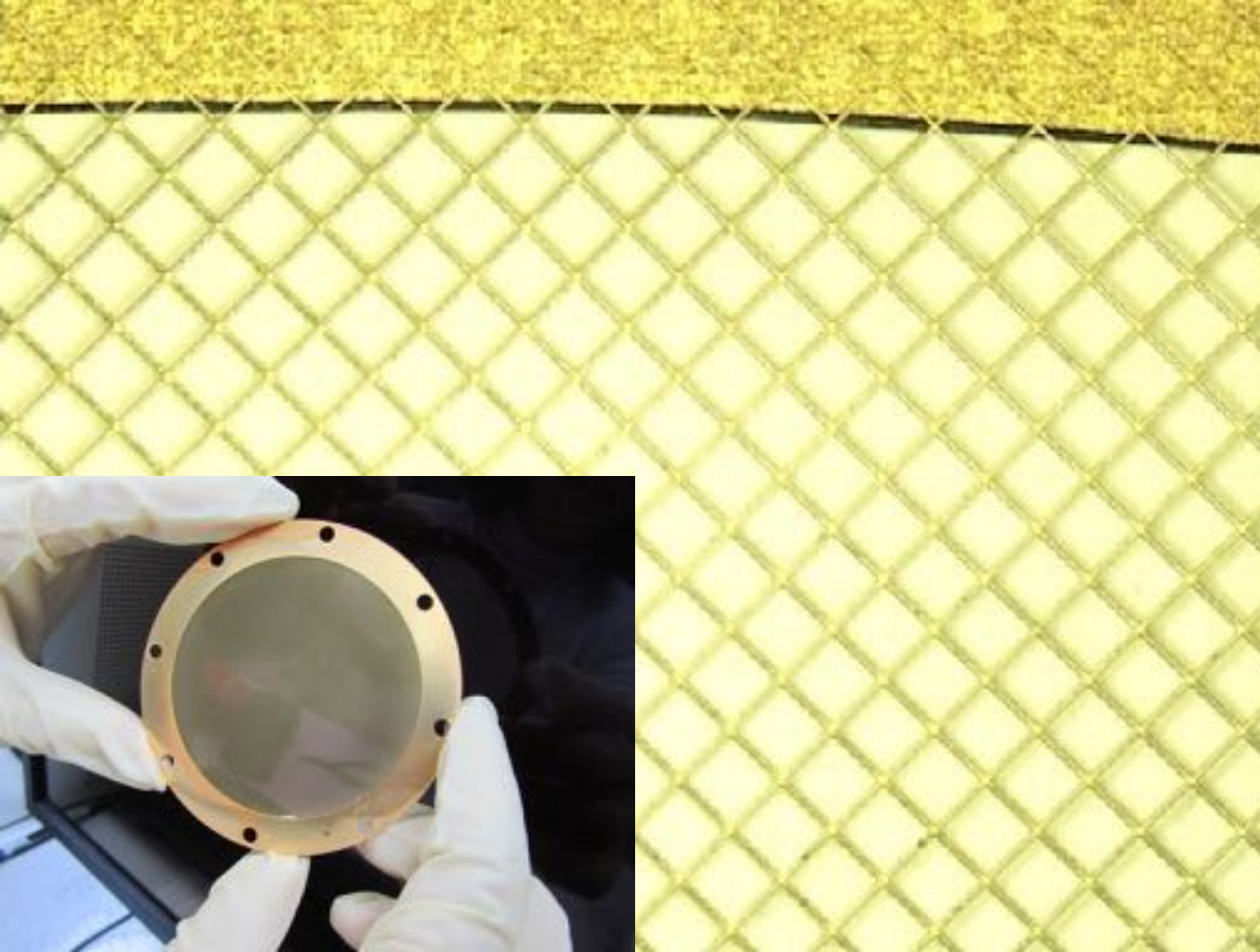
Since the retarding grid cannot provide a uniform electric potential perfectly, there is some calibration on the retarding potential. The suppressor and dual aperture grids are both possible to reduce the potential on a saddle point of the retarding grids. Thus particles with energies smaller than the retarding voltage could pass through these potential depressions on the retarding grid planes to reach the collector.

According to the simulation results shown in the figure, the **potential depression factor for the IPEI/RPA configuration is about 0.96501** [Chao et al., 2003]. That means the retarding potential will be used by the input retarding voltage multiplied by the depression factor.



Effects on ion T_i and U_r





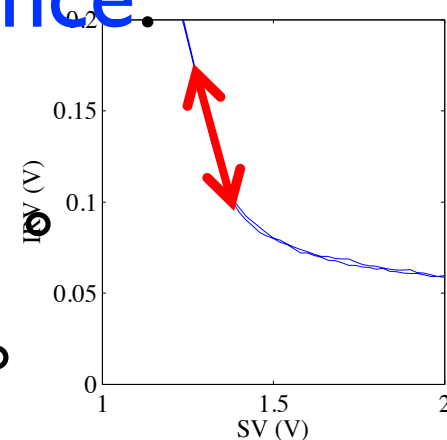
Electro-formed grids (AIP)

99.98% gold grid, good equal potential surface, reduced I-V hysteresis, poor resilience.

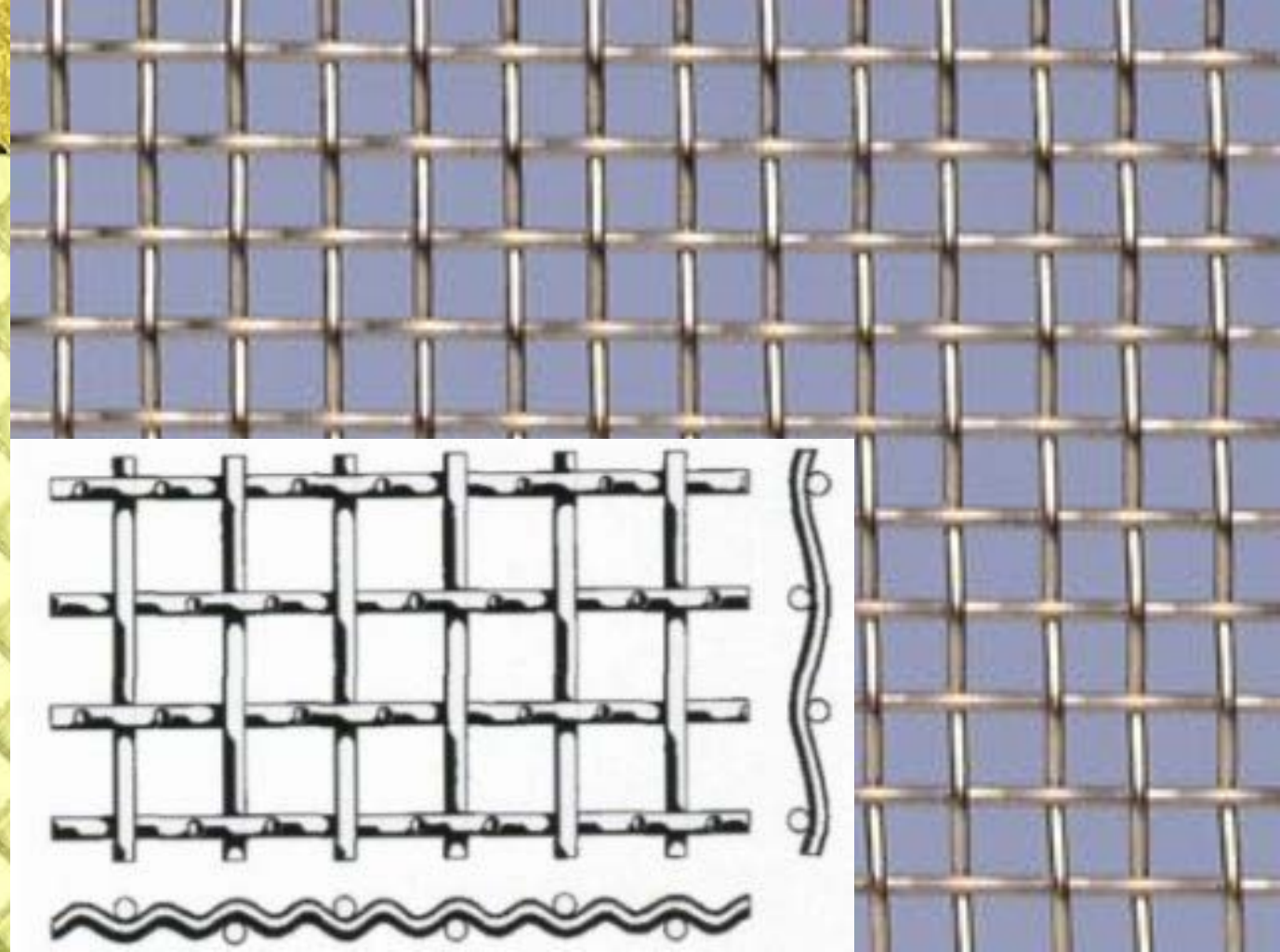
Mesh density: 100 LPI.

Grid diameter: 0.5 mil

Transparency: 0.9025



1 mil (10^{-3} inch = 25.4 μm) and diameter of a human hair ~ 4 mil.



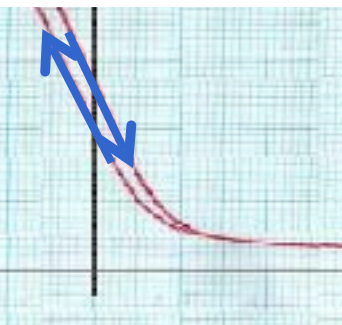
Weaved grids (IPEI)

Stainless steel grid coated in gold, bad equal potential surface, apparent I-V hysteresis, good resilience.

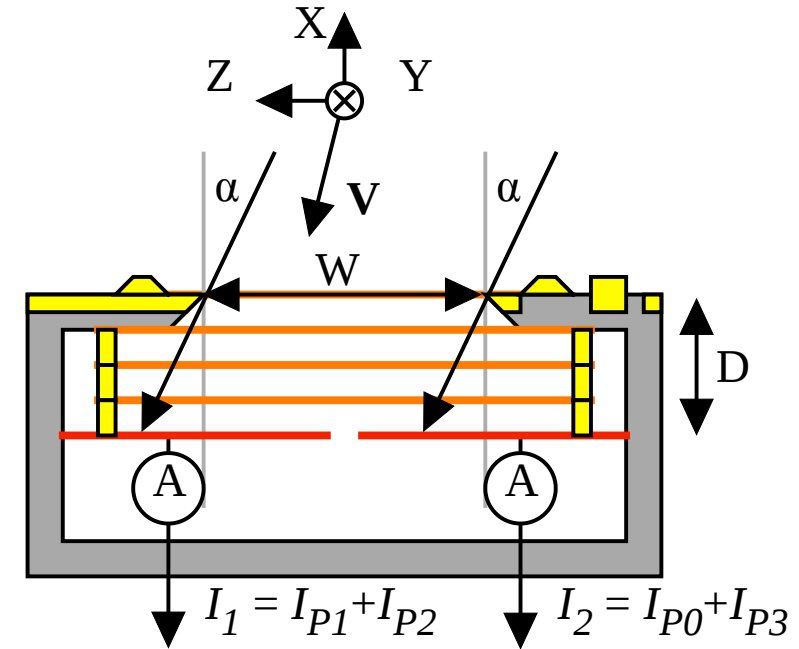
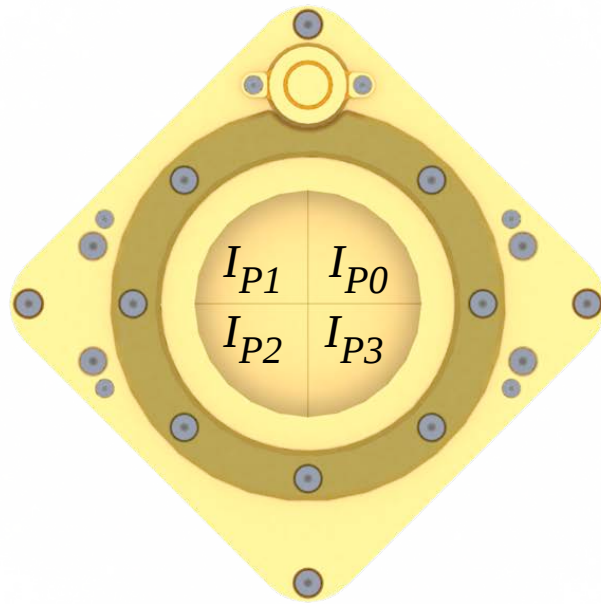
Mesh density: 50/100 LPI.

Grid diameter: 1 mil.

Transparency: 0.9025/0.81.



Ion Drift Meter (IDM)

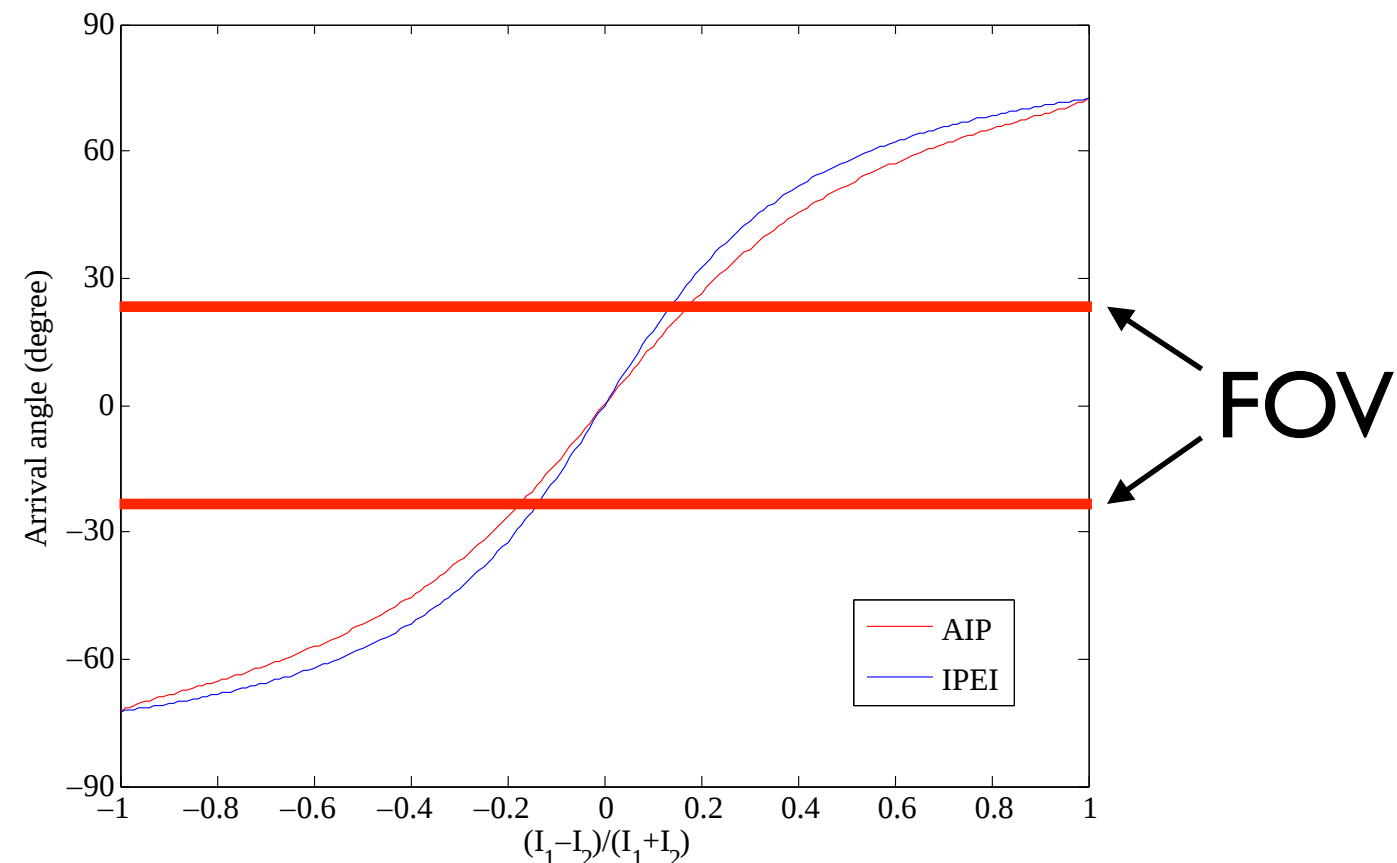


For a circular aperture in AIP

$$\tan \alpha = \frac{W}{2D} \cos \frac{\theta}{2}, \quad \theta = \sin^{-1} \left(\frac{I_1 - I_2}{I_1 + I_2} \right) \pi$$

For a square aperture in IPEI

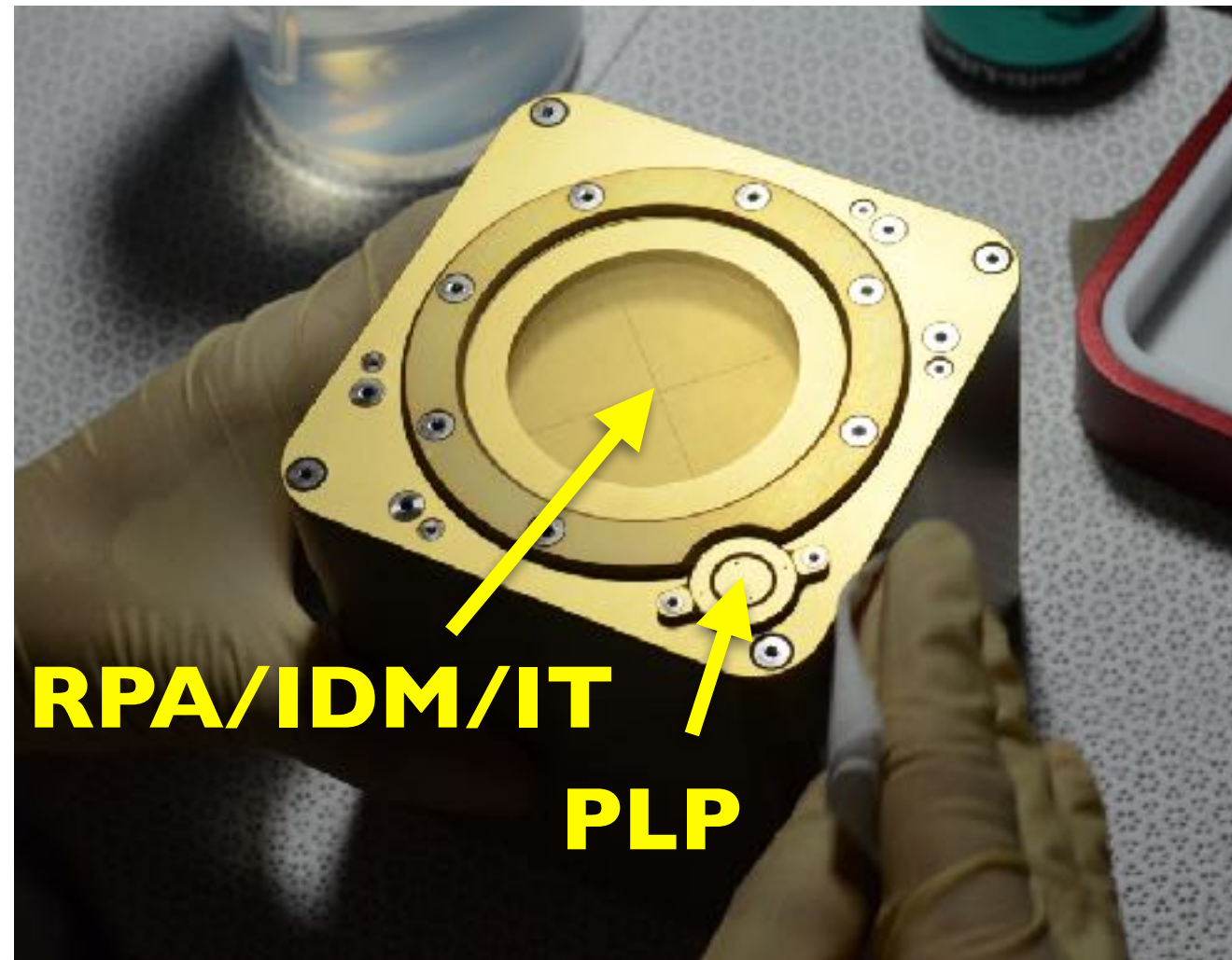
$$\tan \alpha = \frac{W}{2D} \left(\frac{I_1 - I_2}{I_1 + I_2} \right)$$



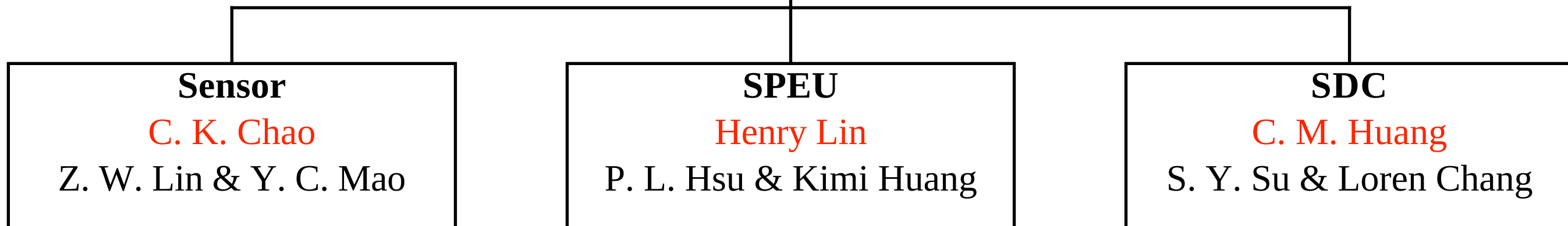
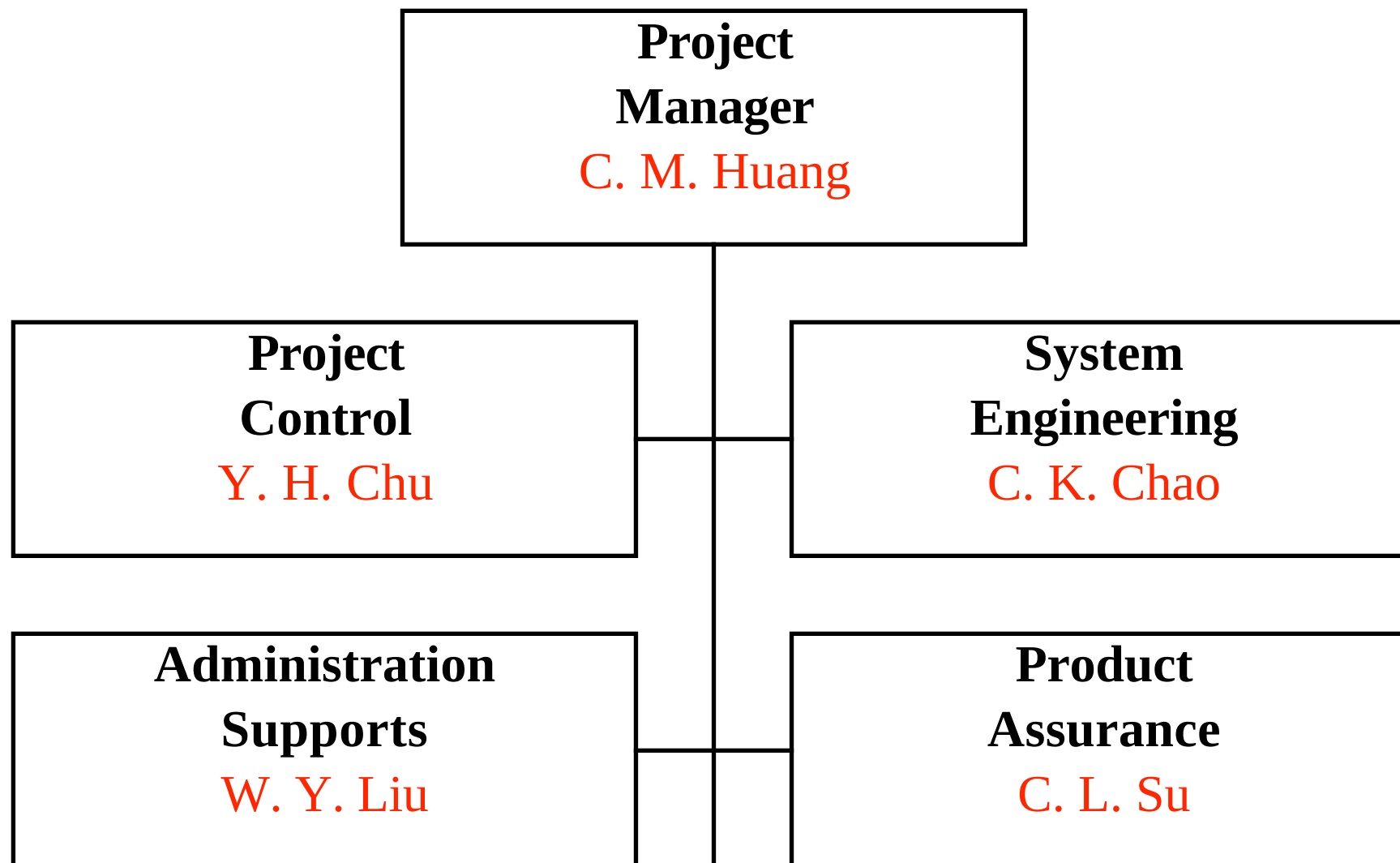
Advanced Ionospheric Probe

Advanced Ionospheric Probe (AIP) is an **all-in-one thermal plasma sensor** to measure ionospheric plasma concentrations (N_i), velocities (V_i), and temperatures (T_i and T_e) in a time sharing way to play Ion Trap (IT), Ion Drift Meter (IDM), Retarding Potential Analyzer (RPA), and Planar Langmuir Probe (PLP).

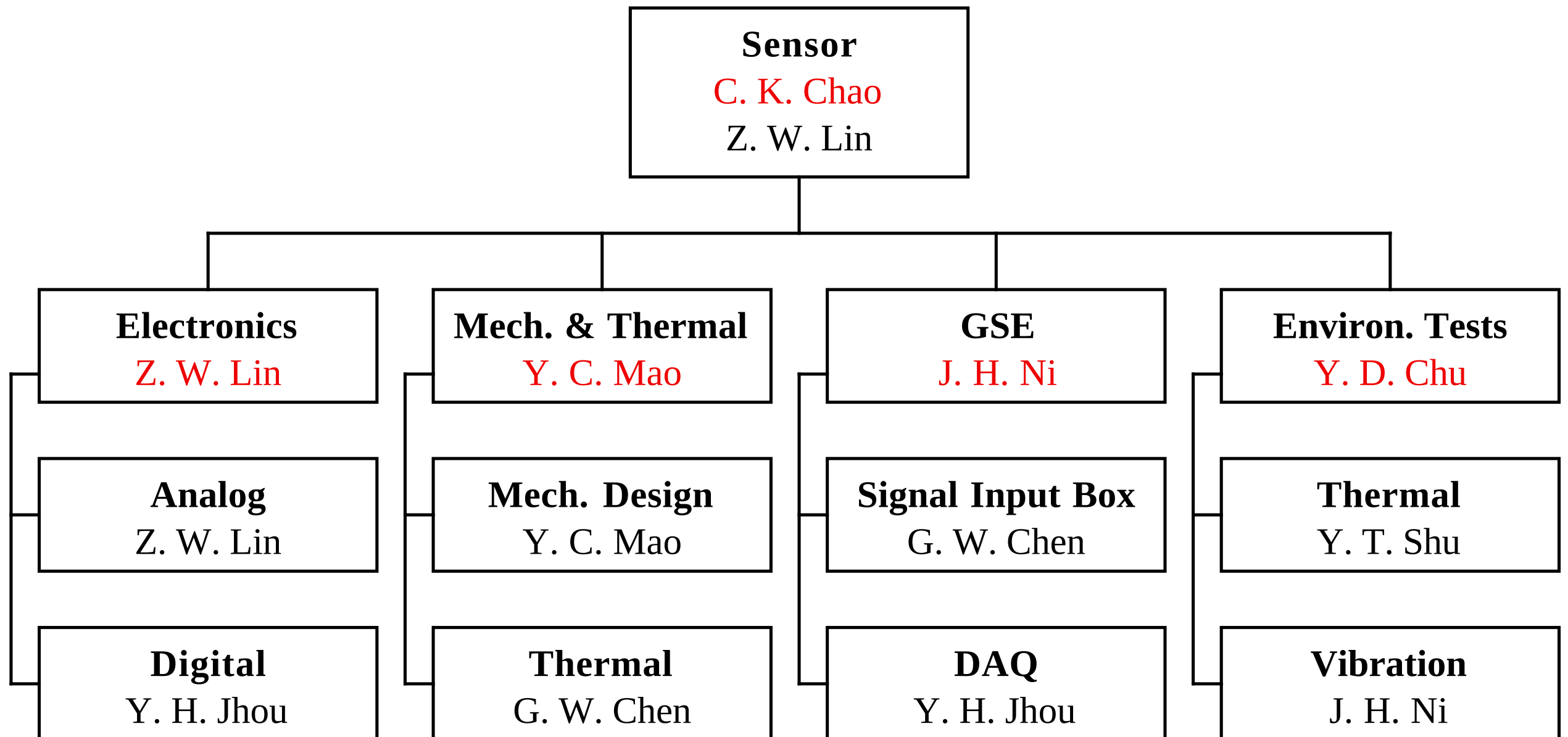
The AIP is capable of measuring **ionospheric plasma irregularities** with sampling rate up to **8,192 Hz**. **Electro-formed gold grids** used in the AIP can reduce quasi-hysteresis effect on I-V curves and approximate ideal electrical potential surfaces for **accurate geophysical parameters**.



AIP organization



Sensor organization

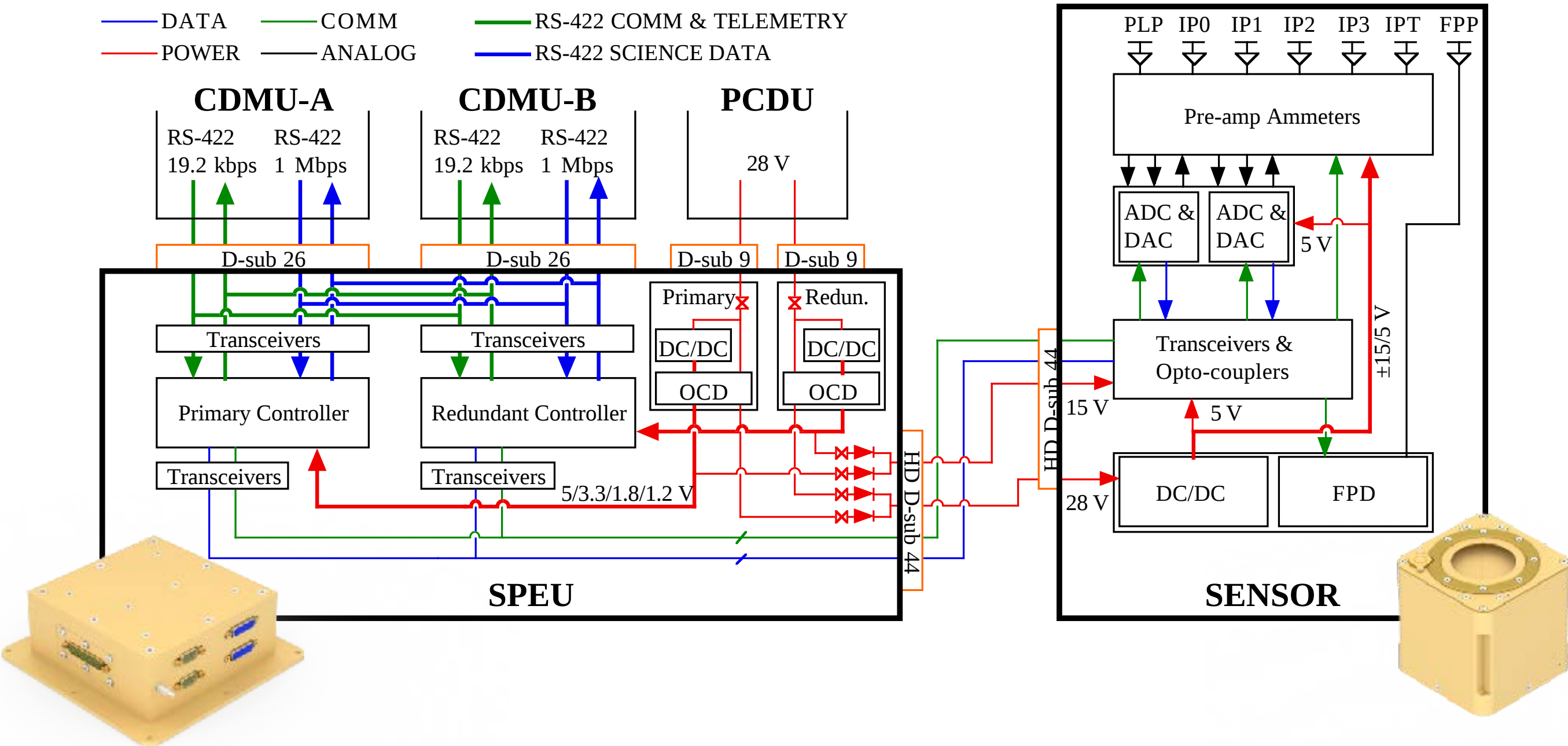




Satellites	DMSP	DEMETER	FORMOSAT-5
Nations	US	France	Taiwan
Sun-synchronous Orbits	840 km	715 km	720 km
Solar activity	All	Low	Low
Thermal plasma sensors	SSI/ES-3: IT + DM + RPA + LP.	RPA + IDM + LP.	AIP: PLP, RPA, or IDM/IT.
Sampling rates	24 S/s (N_i) 2.5 S/s (others)	160 S/s (N_i) 3 S/s (others)	128 - 8,192 S/s (N_i) 32 - 2,048 S/s ($V_{y,z}$) 1 S/s (others)
Sensor functions	Fixed	Fixed	Software programmable

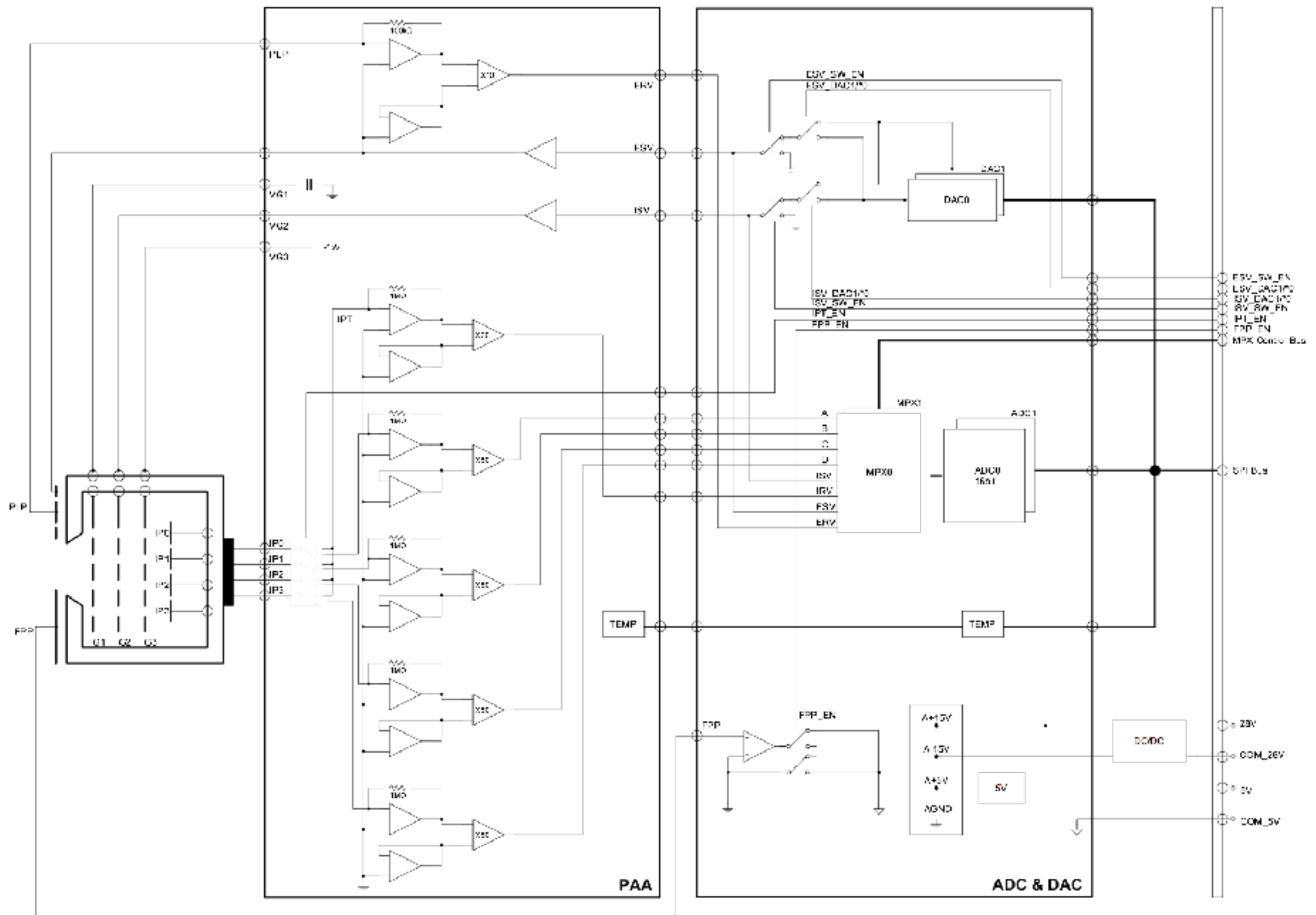
Schedule	WSD
38 months	2012/01/13 to 2015/03/12
Milestone	Due
MDR / SDR	2012/03/12 (WSD + 2m)
PDR	2012/05/12 (WSD + 4m)
ISD	2012/07/12 (WSD + 6m)
CDR	2012/09/12 (WSD + 8m)
DRR	2013/01/12 (WSD + 12m)
PAR	2013/08/12 (WSD + 19m)
SMRR	2014/07/12 (WSD + 30m)
ITR	2014/07/12 (WSD + 30m)
PSR	2014/08/12 (WSD + 31m)
IOCR	2015/03/12 (WSD + 38m)
FR	2015/03/12 (WSD + 38m)

Functional diagram

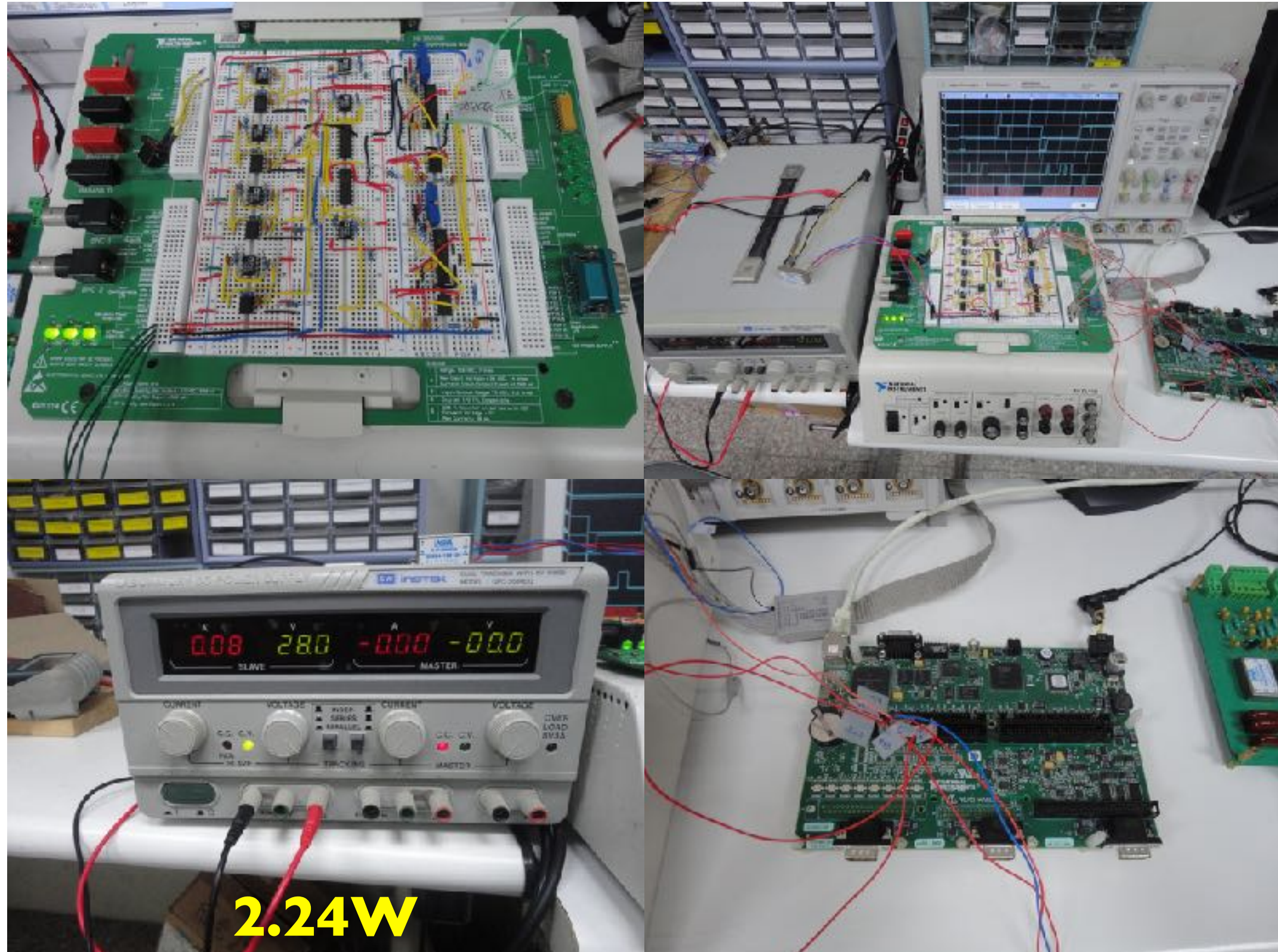


Redundant design on controllers, transceivers, powers, ADC/DAC, ammeters, etc.

Block diagram of the sensor



Power consumption - sensor only



Ammeters

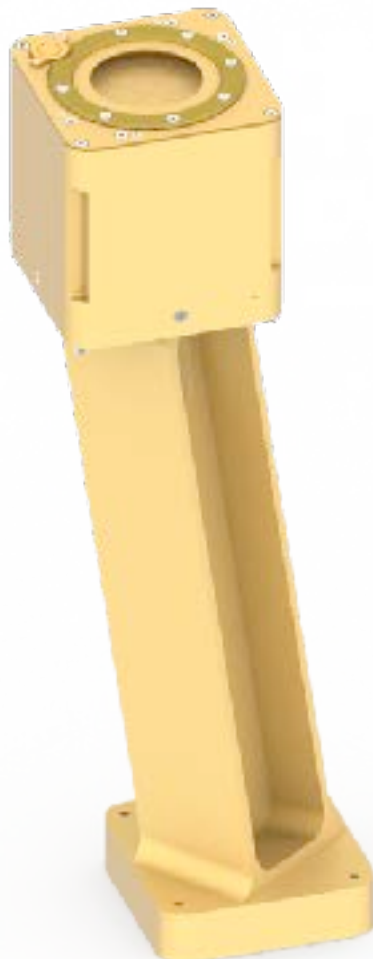
Sensor	Range	Sensitivity	Rate	If noise level is 1 mV
IP0, IP1, IP2, and IP3	$\pm 1.25 \mu\text{A}$	$\pm 38.1 \text{ pA}$	$0.5 \mu\text{A/V}$ or 2.0 mV/nA	0.5 nA $\rightarrow 10^3 \text{ cm}^{-3}$
IPT and PLP	$\pm 2.5 \mu\text{A}$	$\pm 76.3 \text{ pA}$	$1.0 \mu\text{A/V}$ or 1.0 mV/nA	1 nA $\rightarrow 10^3 \text{ cm}^{-3}$

Geophysical parameters

Parameters	Range	Sensitivity	Accuracy
C_i	3% to 100%	1%	10%
N_i (or N_e)	10^3 to 10^6 cm ⁻³	1%	10%
V_i	± 2.5 km s⁻¹ (cross track) 7.5 ± 1 km s⁻¹ (ram)	± 10 m s ⁻¹ ± 100 m s ⁻¹	± 50 m s ⁻¹ ± 200 m s ⁻¹
T_i	500 to 5,000 K	± 50 K	± 200 K
T_e	500 to 5,000 K	± 50 K	± 200 K

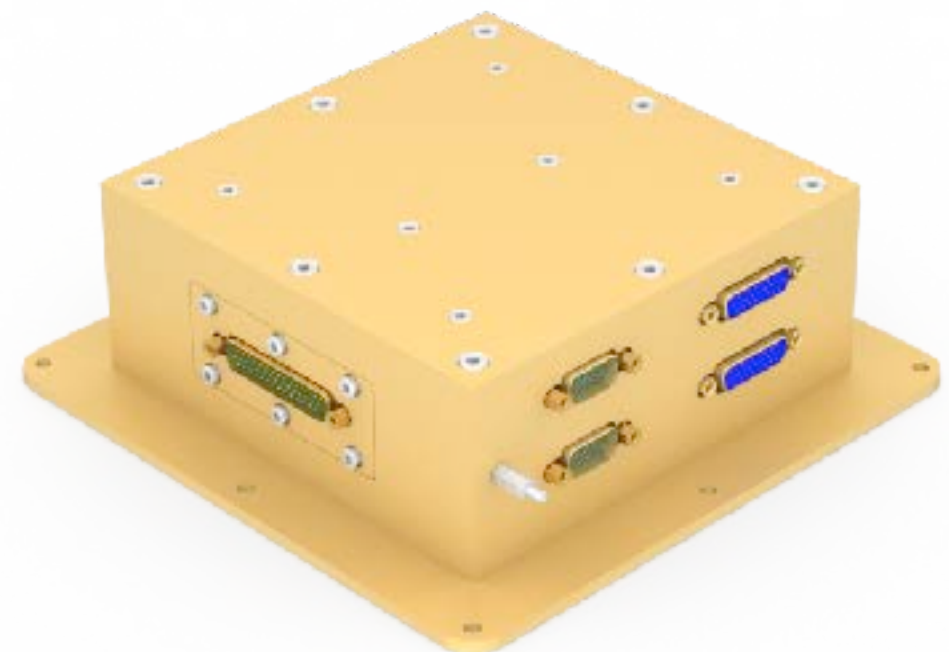
Mechanical specifications

- Sensor: **2.046** kg (shall be less than 1.0 kg) and installed on the top panel with field of view (FOV) **46.4°** ($\geq 45^\circ$).
- Head:
 - Material: 6061-T6 with chromate coating.
 - Dimension: 100 (L) x 100 (W) x **100.6** mm (H).
 - Mass: **0.8617** kg (**3 mm thickness**).
- Stand:
 - Material: 7075-T6 with chromate coating.
 - Dimension: 140 (L) x 130 (W) x **300** mm (H).
 - Footprint: 100 (L) x 100 mm (W).
 - Mass: **1.184** kg.



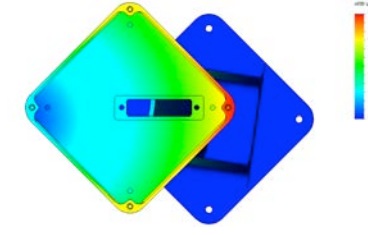
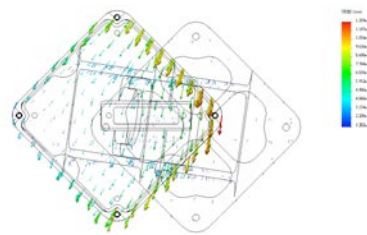
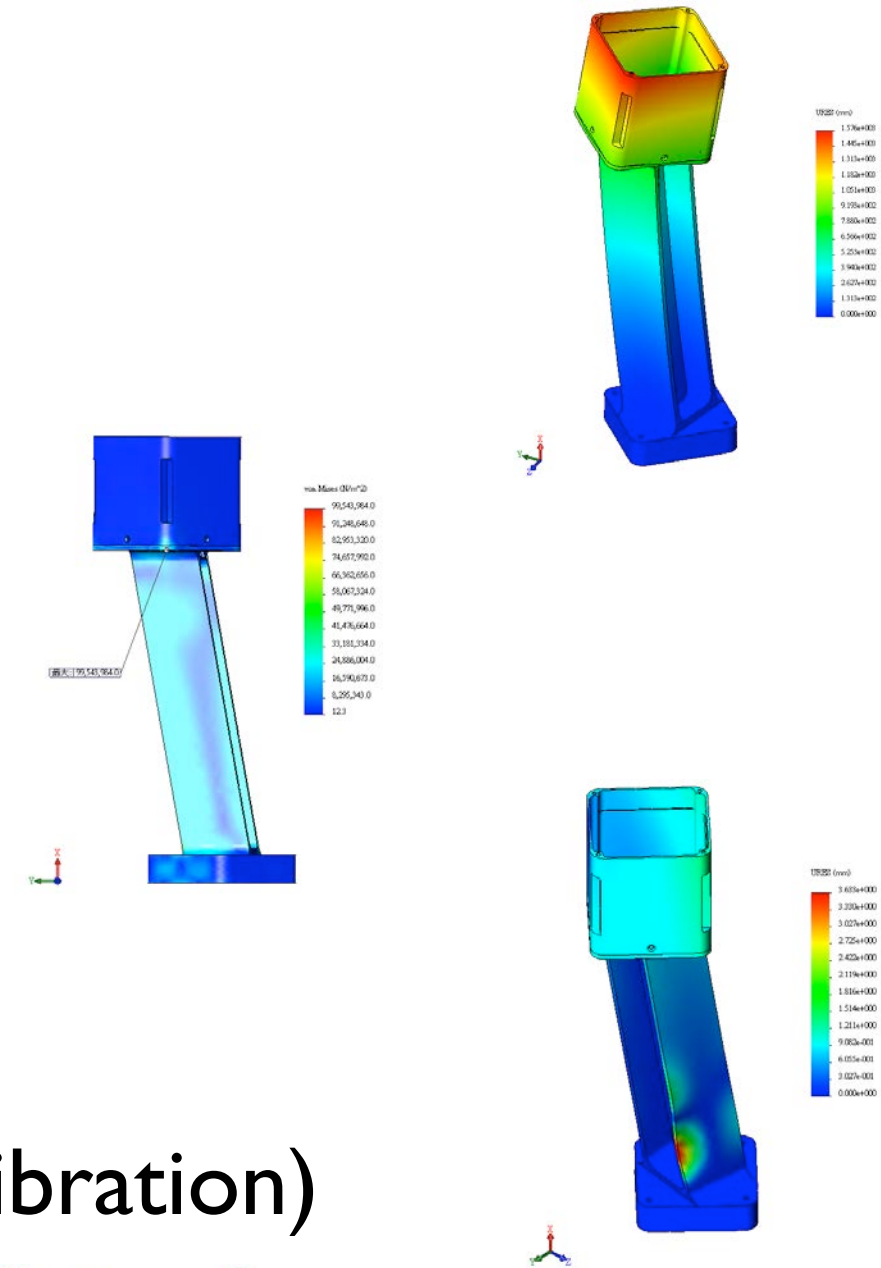
Mechanical specifications (cont.)

- SPEU: installed inside S/C.
- Material: 6061-T6 with chromate coating.
- Dimension: 180 mm (L) x 180 mm (W) x 60 mm (H).
- Mass: **1.761** kg.
- Harness between SPEU & sensor: **1.747** kg and **3.8** m.
- Total mass: **5.554** kg (shall be less than 5.0 kg).



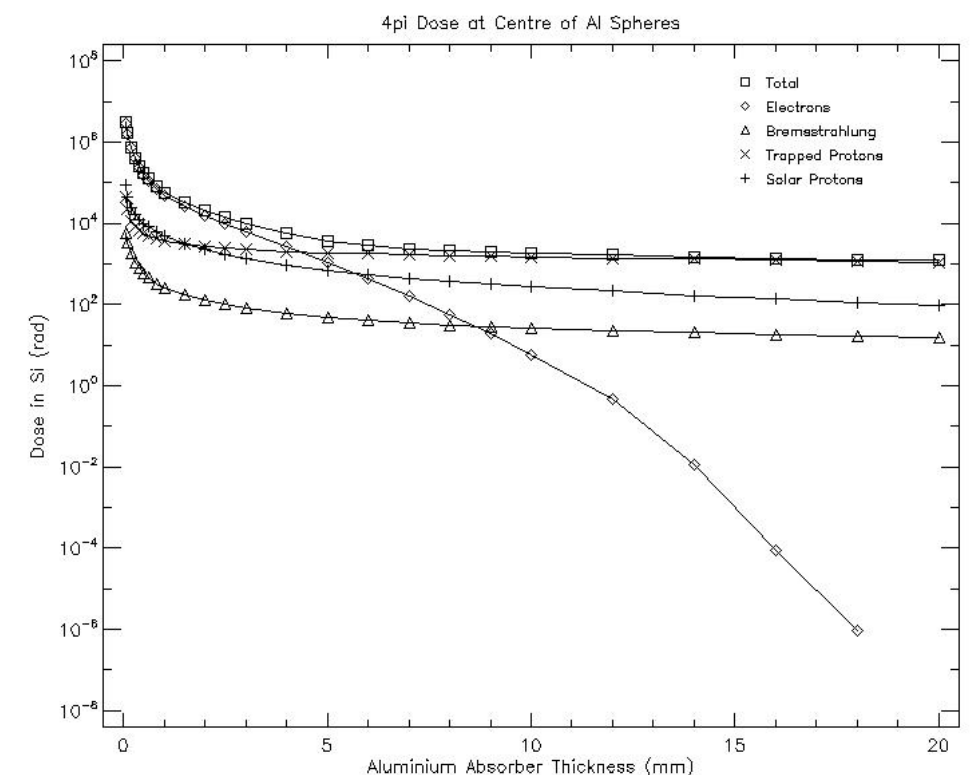
Structure analysis for sensor

- Ref. to FS-5 AIP Mechanical Structure Analysis Report, FS5SPL-MECH-ANLYS.
- Natural frequency: **130.4** Hz (> 120 Hz).
- Load factors
 - Out of plane: **61.9** G (> 20 G).
 - In-plane: **46.4** G (> 20 G).
- Margin of safety (MS)
 - Ultimate: **1.27** (> 0).
 - Yield: **1.42** (> 0).
- Buckling safety margin (MS_B): **44.7** (> 0).
- Sinusoidal vibration (no collision during vibration)
 - 9G in-plane.
 - 10-300 Hz.



Total ionizing dose

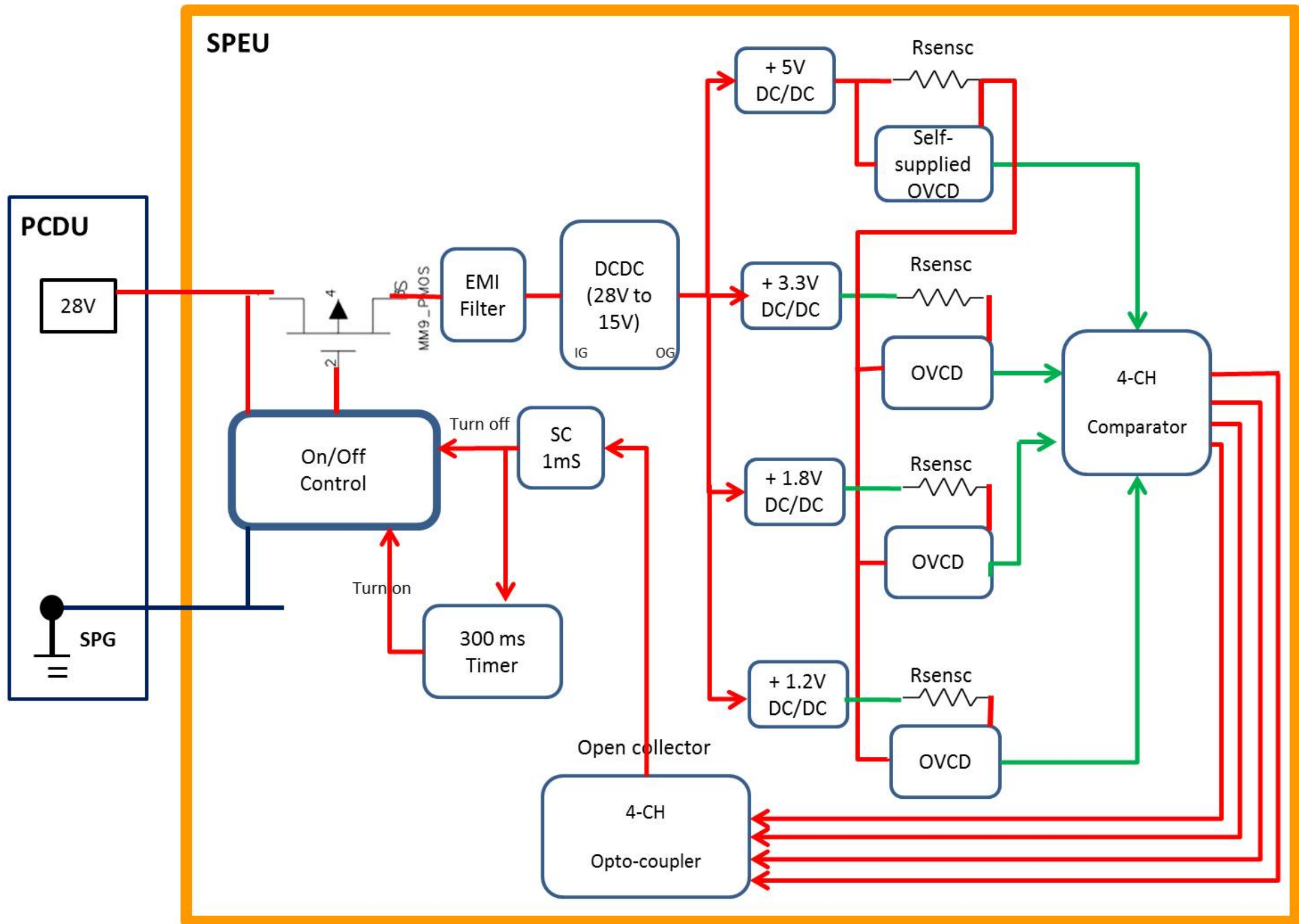
- For a 3 mm thickness of 6061-T6 sensor cube, the requirement of total ionizing dose for a two-year mission life time is **3.6 krad (Si)**.
- It is lower than **5 krad (Si)** for untested COTS EEE parts (ref. IAC-02-IAA.6.3.04, In-orbit Monitoring of “Space Weather” and Its Effects on Commercial-Off-The-Shelf, COTS, Electronics - A Decade of Research Using Micro-Satellites)



Electrical specifications

- Input voltage: **28 ± 6** VDC (wider than +26 V to +34 V).
- Power on: 23.8 to 26.9 W and 0.85 to **0.96 A** (≤ 1.3 A, limited by PCDU) for +28 V.
- Operation: **11.9 W** in average.
 - Sensor: **7.11 W** (< 11.3 W in analysis), 0.12 A for +28 V and 0.25 A for +15 V.
 - SPEU (without sensor load): **4.76 W** (< 8.15 W in analysis), 0.17 A for +28 V.
- Average power per orbit: can be reduced to 5 W if the duty cycle of ALP can be reduced to **42 %** (≥ 30 %).
- Single event latch-up (over-current) protection.

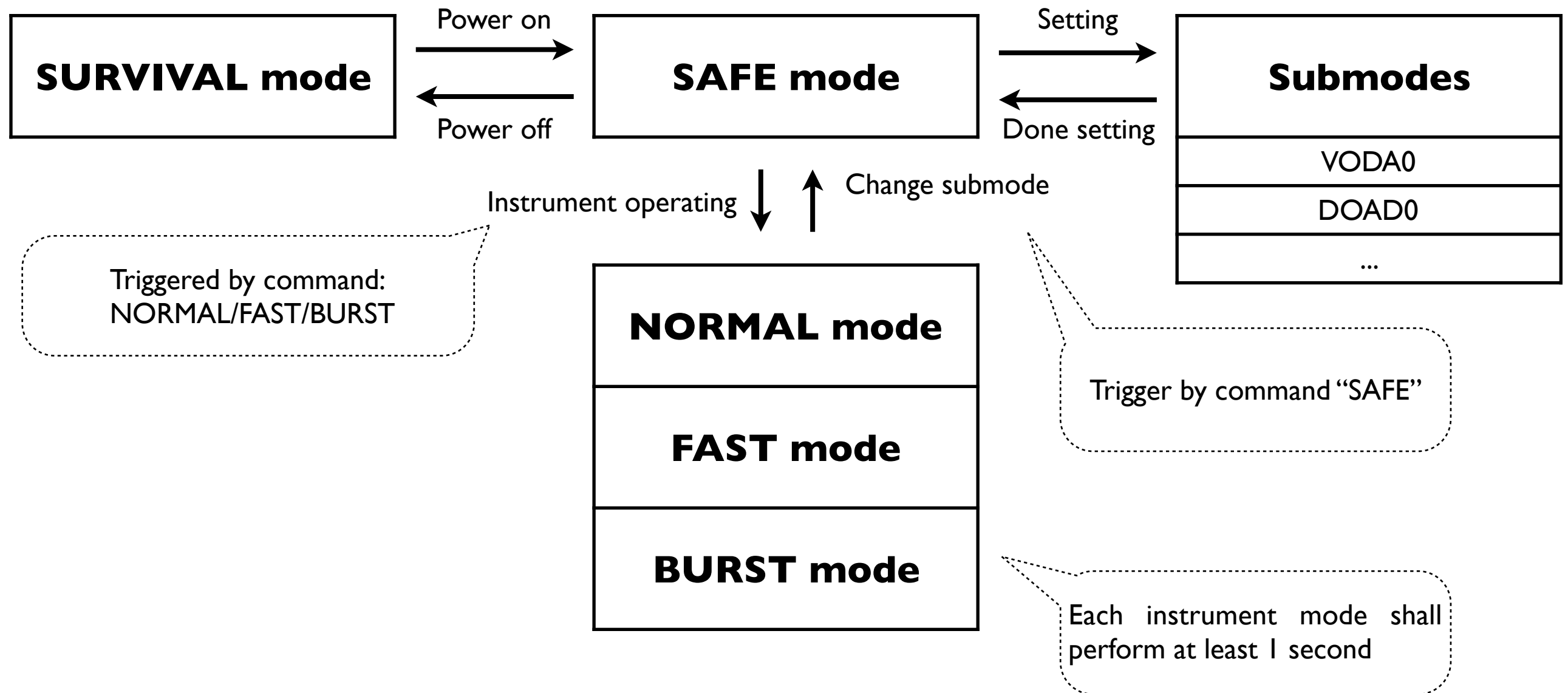
Single event latch-up protection



Commands and telemetry

- Command and telemetry interface (RS-422, 19.2 kbps, ASYN)
 - From CDMU to SPEU
 - Command: 1 command (3 bytes) in a 6-byte command packet. The command packet is sent every 1s.
 - Ancillary data: 64-byte ancillary data in a 68-byte ancillary data packet. The ancillary data packet is sent every 1s.
 - From SPEU to CDMU
 - Status of health (SOH): a 19-byte SOH in a 22-byte SOH packet. The SOH packet is sent every 1s.
- Science data interface (RS-422, 1 Mbps, SYNC)
 - Only from SPEU to CDMU: 3 sets of science data in a 1024-byte science data packet.

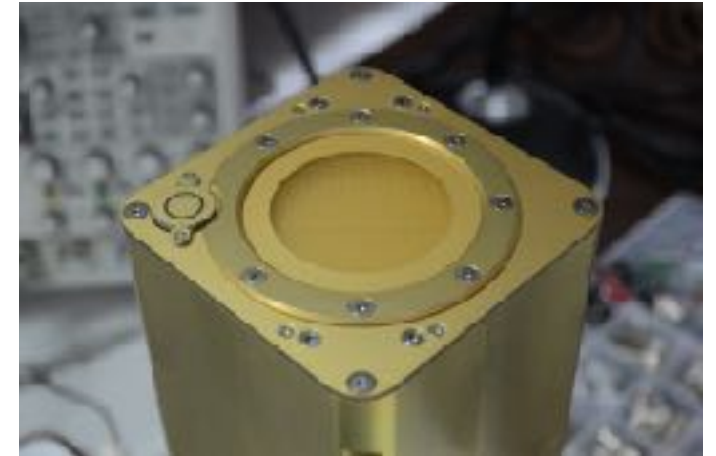
Mode operation



When turning on SPEU (SAFE mode), the submode is setting to default value. To change the submode setting, the instrument shall go to SAFE mode first and then change the submodes according to the commands received from CDMU. After the setting is done, the instrument can start measuring as NORMAL, FAST, or BURST mode.

Fabrications

- Mechanical components
 - Sensor cube and stand.
 - Bonded meshes.
 - PLP electrodes, aperture, insulator rings, collector, etc.
- Electrical components
 - Harness
 - PCB fabrication
 - Components assembly
- Final assembly
 - Sensor by NCU
 - SPEU by T&C

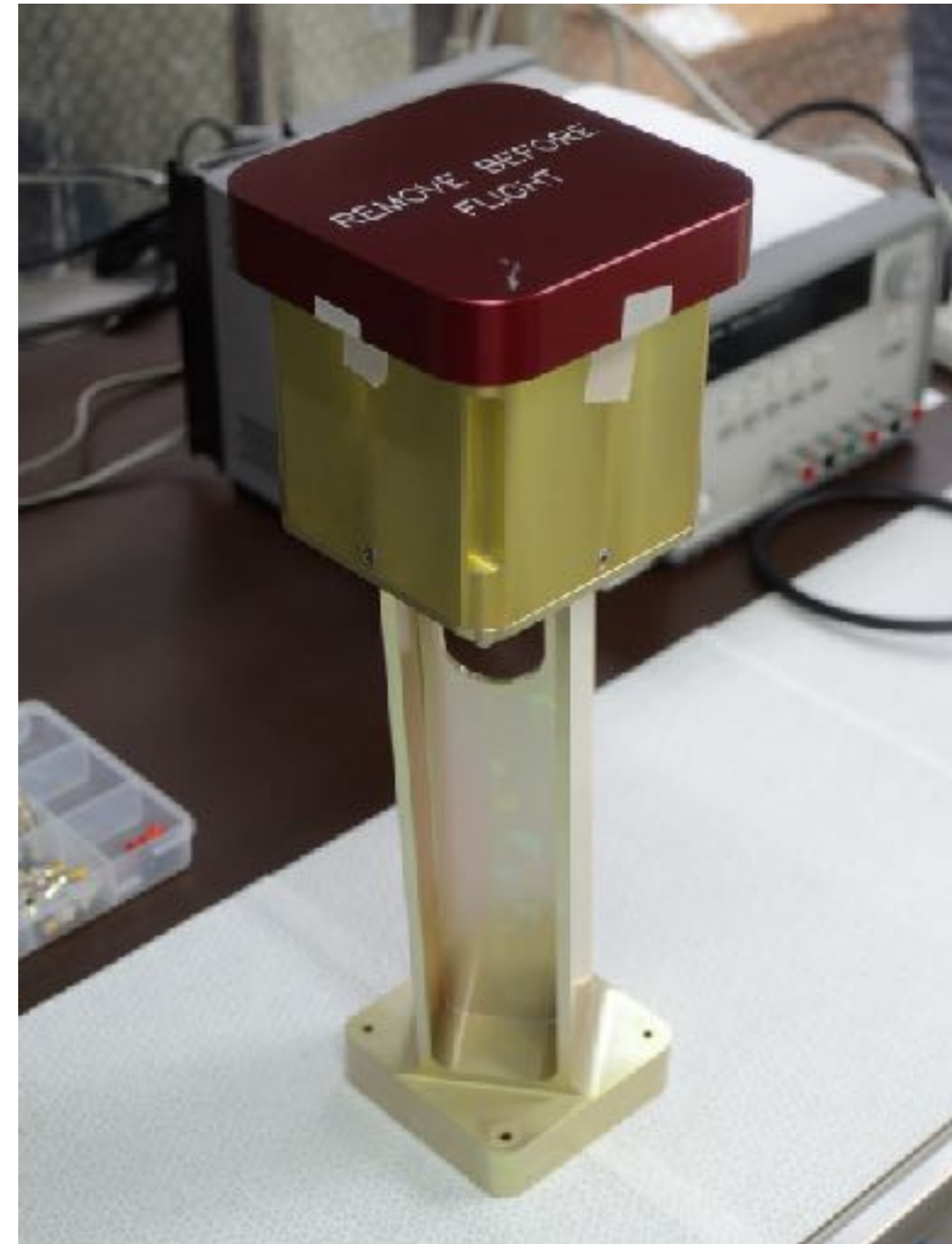


Sub-contractors

- SPEU: T&C Technologies Inc.
- Component acquisition: BUY-A Technology Corp. and Bentech Computer Corp.
- Bonded meshes: Precision Eforming LLC.
- Aperture and collector construction:
- Gold-coating: ATI.
- PCB and coating: BoardTek Electronics Corp.
- Assembly: EMTT Systems Corp.
- ISD: National Instruments Corp.
- Vibration and shock test: CSIST.

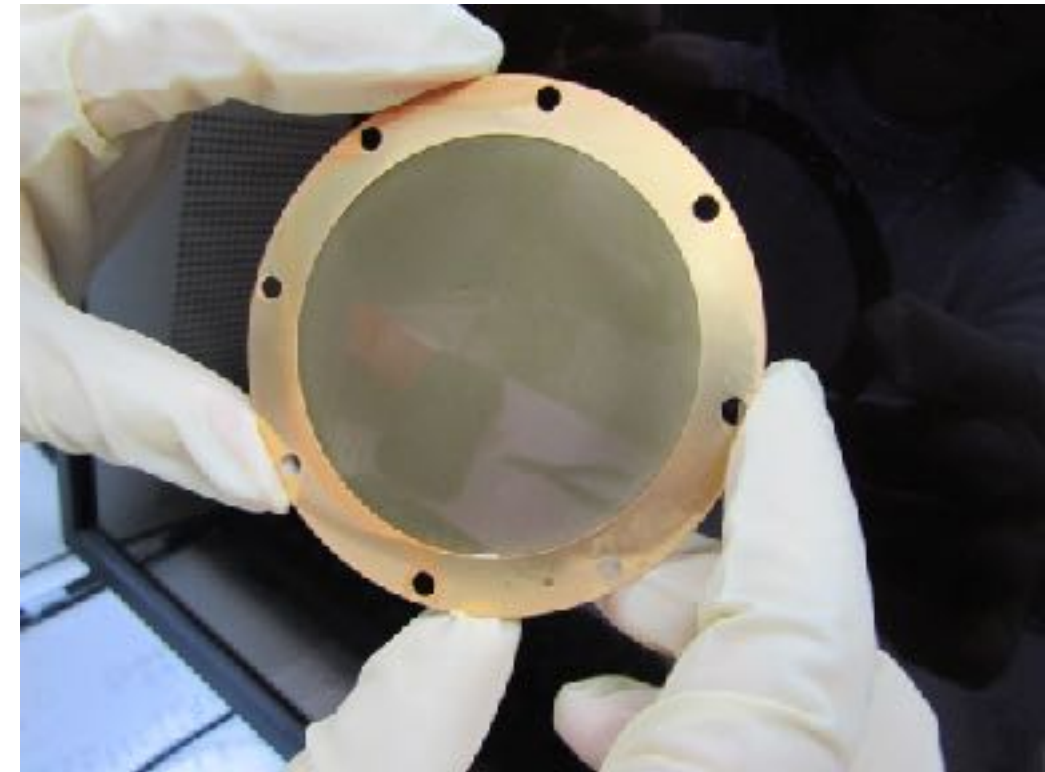
Sensor cube and stand

- Manufactured by BCV Tech. and Min-Wang Co.
- Head:
 - Material: **6061-T6** with chromate coating.
- Stand:
 - Material: **7075-T6** with chromate coating.
- Bolts and nuts: manufactured by Bulten Stainless.
- Material: Bumax 88 (S31603) and Bumax A4 (S31600).



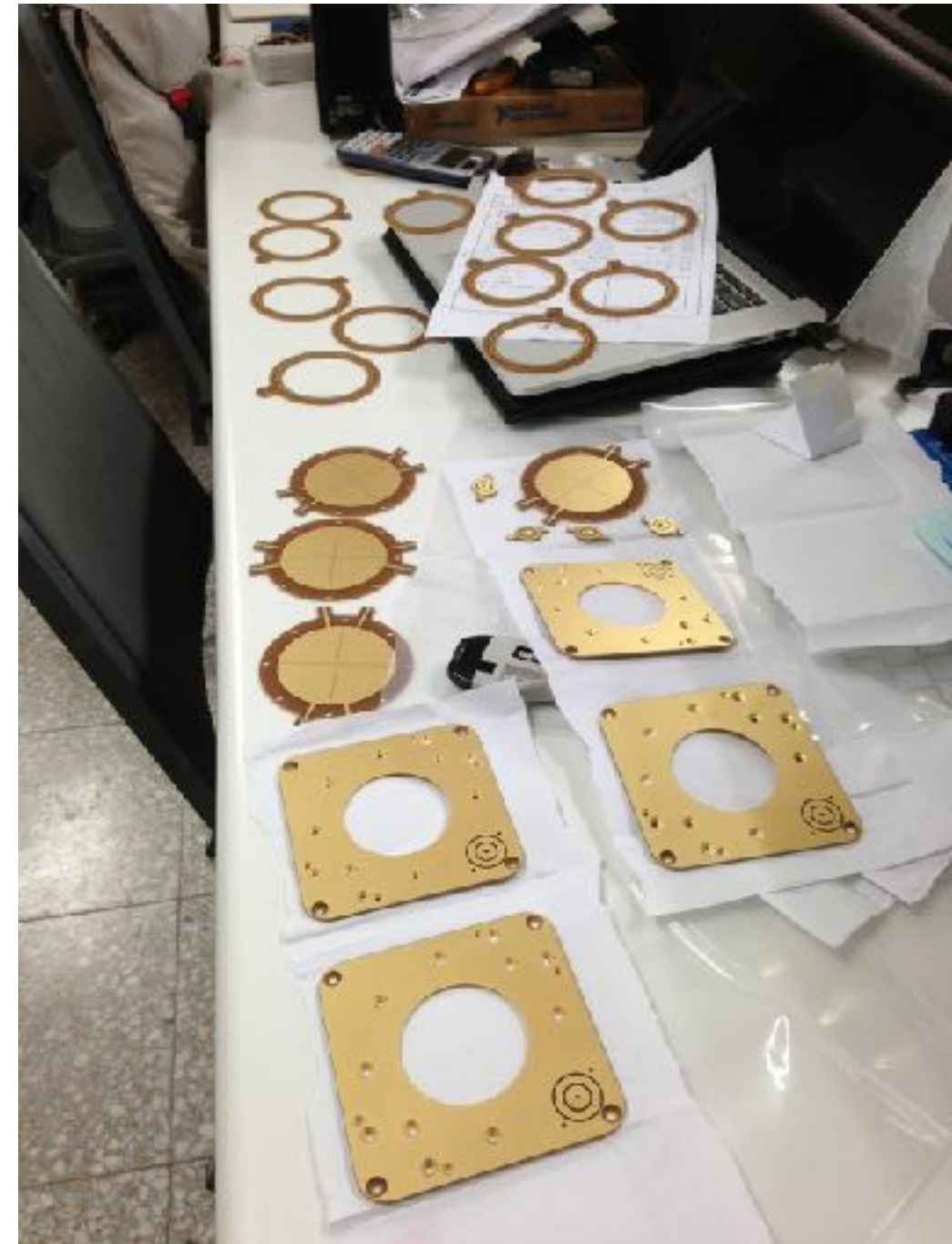
Bonded meshes

- Electroformed bonded gold mesh manufactured by Precision Eforming LLC.
- Material:
 - Stainless steel 304 frame and coated in gold.
 - **99.98% pure gold mesh.**
- Mesh density: 100 LPI.
- Mesh thickness: 0.5 mil.
- Transparency: **0.9025.**



PLP electrodes, aperture, insulator rings, and collector

- Manufactured by Ting Ann Enterprises Co., Ltd. and Advantic Tech. Inc.
- Material: **ARLON 85N PCB** and coated in gold.
 - PCB thickness: 1.6 mm.
 - Copper thickness: 0.5 Oz.
- Structuring and through-hole plating.
- All coppers are coated in gold with **50 μ -inch.**



Harness

- Manufactured by Rosnol RF/
Microwave Technology
- Length: **3.8 m.**
- Connectors: **ITT Cannon**
DBMA44PNMBK52 and
DBMA44SNMBK52.
- Twist-pair cables: Super-Temp M27500
24 RC 2 S06.
- Kyner heat shrink tubing: AWC
M23053/8.
- Expandable sleeving: Techflex Techon
PFA.



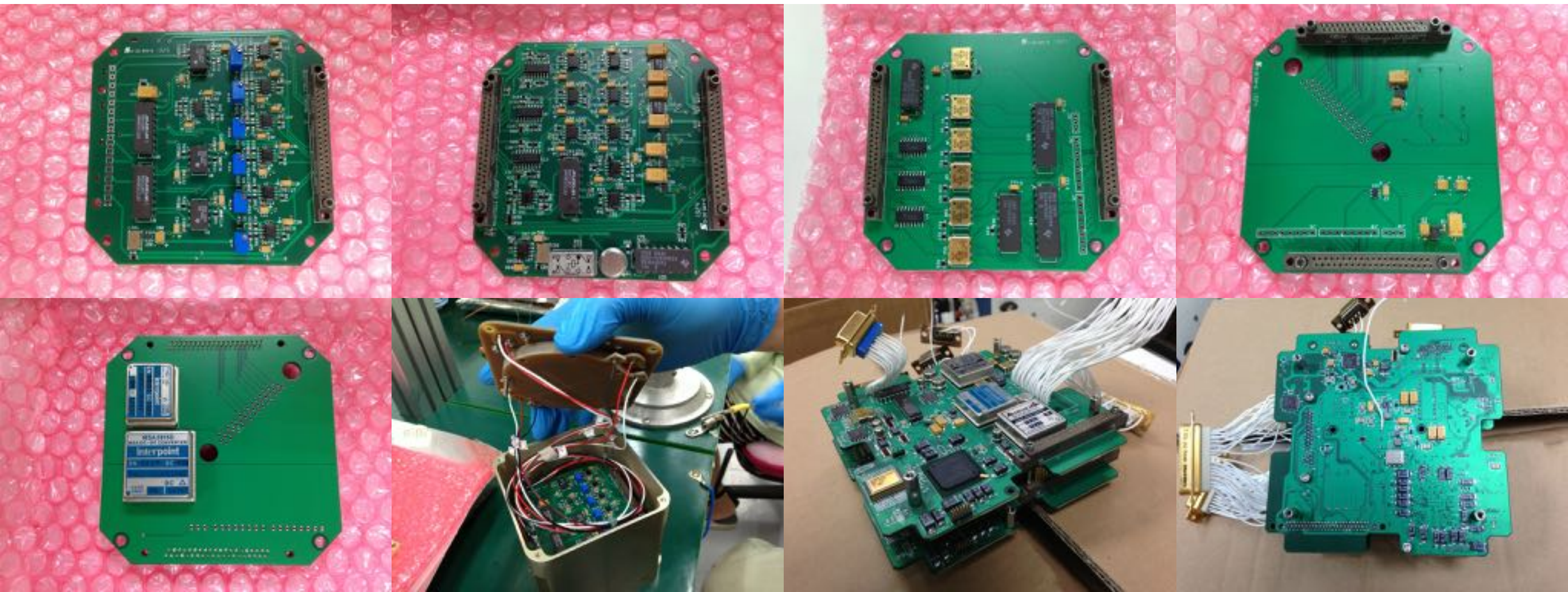
PCB fabrication

- Manufactured by Speedy Circuits Co. Ltd.
- Material: **ARLON 85N PCB**.
 - Layer count: 2 for sensor and 4 for SPEU.
 - Thickness: 1.6 mm.
 - Copper thickness: 0.5 Oz for sensor and 1.0 Oz for SPEU.
- Solder mask: TAIYO PSR-4000 MP.
- Inkjet legend ink: TAIYO IJR-4000 MW300.
- Surface finish: Hot-Air Solder Leveling (HASL) with tin/lead.



Components assembly

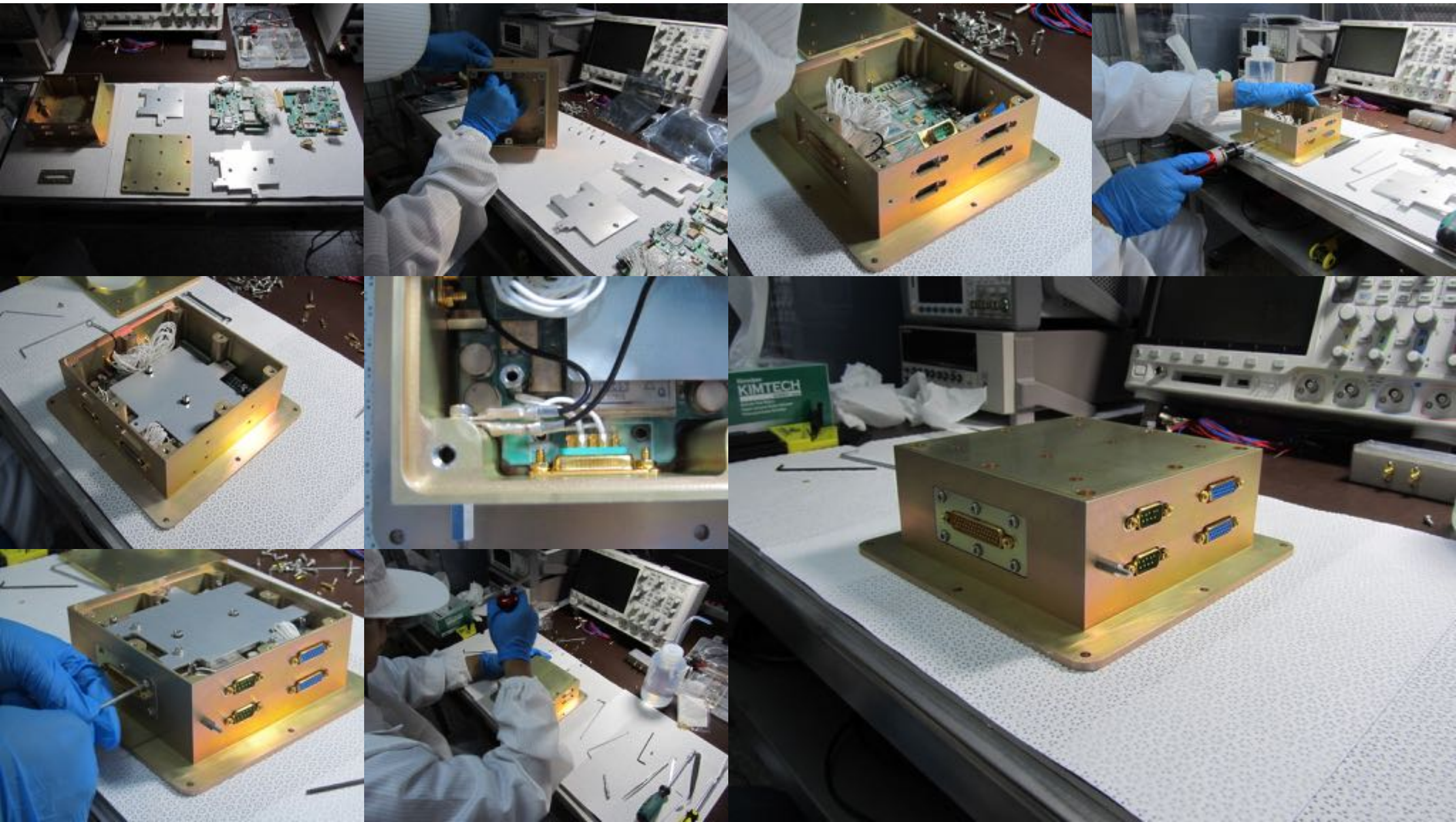
- Soldering by EMMT Systems Corp.



Sensor assembly by students



SPEU assembly by T&C





The 1st Space Science School Payload Design - An Example of Advanced Ionospheric Probe

Chi-Kuang Chao

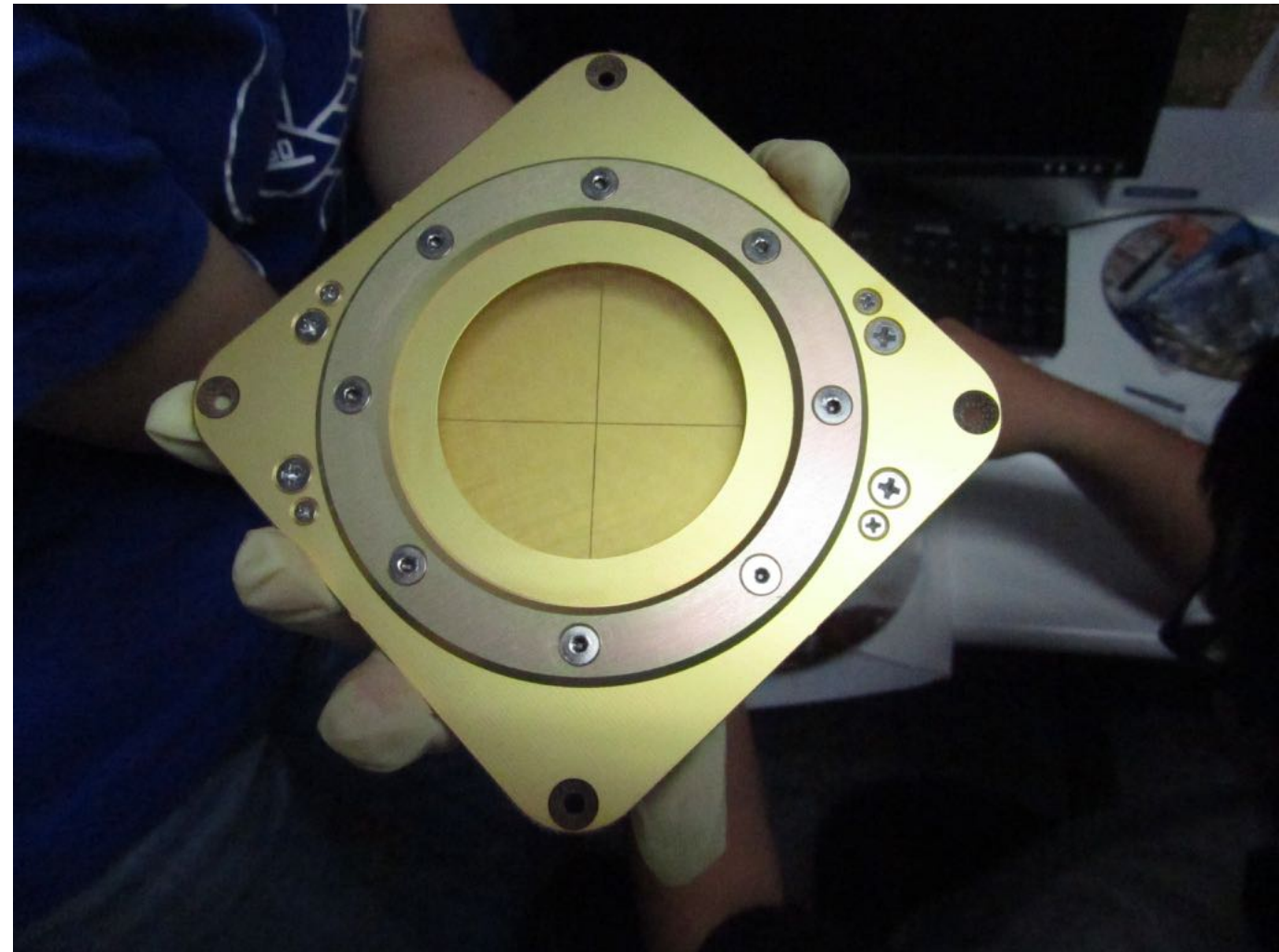
Graduate Institute of Space Science, National Central University

Space Krenovation Park, Sri Racha, Chonburi, Thailand

October 24, 2016

Outline - the 2nd hour

- Requirements
- Science objectives
- Principles of measurement
- Designs
- **Verifications**
- **Future works**



Verifications

- The payload design shall be verified by the following methods:
- **Inspection** is the process of physically **measuring, examining or comparing** an article to the design drawings, schematics, or other records to assure requirements compliance.
- **Analysis** can be performed through **systems engineering analysis, statistics & qualitative analysis**, and **computer & hardware simulations** to be used in reliability assessment, life, storage, failure analysis, safety, interchangeability, and other performance requirements which are difficult or impractical to test.
- **Test** requires the **precise measurement of performance parameters** relative to functional, electrical, mechanical, and environmental requirements imposed on an article.

19 documents submitted for PAR

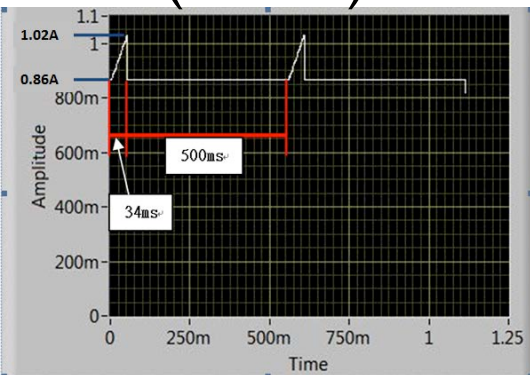
- **FS5SPL-CDRL-1014**: PAR presentation.
- **FS5SPL-CDRL-1015**: P/L test report, 1st draft.
- **FS5SPL-FUNC-PROC/RPT**: functional test procedure/report.
 - **FS5SPL-CPT-PROC/RPT**: circuit protection test procedure/report.
 - **FS5SPL-PIT-PROC/RPT**: plasma injection test procedure/report.
 - **FS5SPL-PMT-PROC/RPT**: power measurement test procedure/report.
 - **FS5SPL-CIT-PROC/RPT**: current injection test procedure/report.
 - **FS5SPL-CT-PROC/RPT**: communication test procedure/report.
- **FS5SPL-SINE-PROC/RPT**: sine vibration test procedure/report.
- **FS5SPL-RAND-PROC/RPT**: random vibration test procedure/report.
- **FS5SPL-SHOCK-PROC/RPT**: shock test procedure/report.
- **FS5SPL-TVT-PROC/RPT**: thermal vacuum test procedure/report.
- **FS5SPL-CEMC-PROC/RPT**: conducted EMC test procedure/report.
- **FS5SPL-REMC-PROC/RPT**: radiated EMC test procedure/report.
- **FS5SPL-CDRL-1016**: EIDP (End-item Data Package) for P/L flight module.
- **FS5SPL-DM-PACK**: Design and manufacturing package.
- **FS5SPL-VQA-PACK**: Verification and quality assurance package.
- **FS5SPL-CDRL-1017**: P/L system operation handbook, 1st draft.
- **FS5SPL-CDRL-1018**: P/L verification control document, 2nd draft.

Functional tests

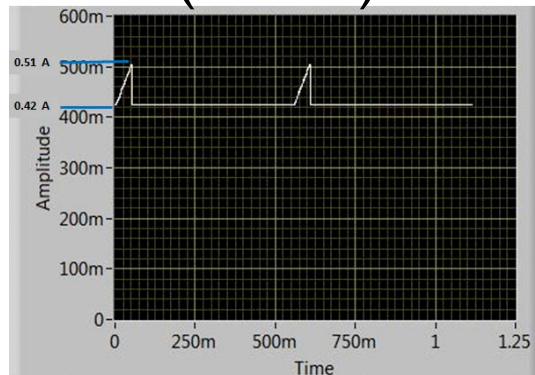
- **Circuit protection test** (T&C, 8/13/2013): FS5SPL-CPT-PROC/RPT.
- **Plasma injection test** (NCU, 8/14/2013 to 8/15/2013): FS5SPL-PIT-PROC/RPT.
- **Power measurement** (NCU, 8/22/2013): FS5SPL-PMT-PROC/RPT.
- **Current injection test** (NCU, 8/27/2013): FS5SPL-CIT-PROC/RPT.
- **Communication test** (NCU, 9/11/2013): FS5SPL-CT-PROC/RPT.

Circuit protection test

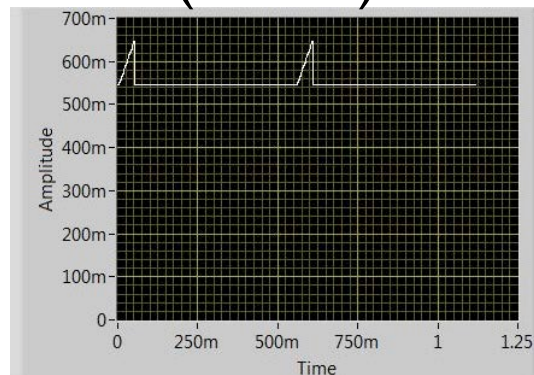
28 V to sensor
(0.98 A)



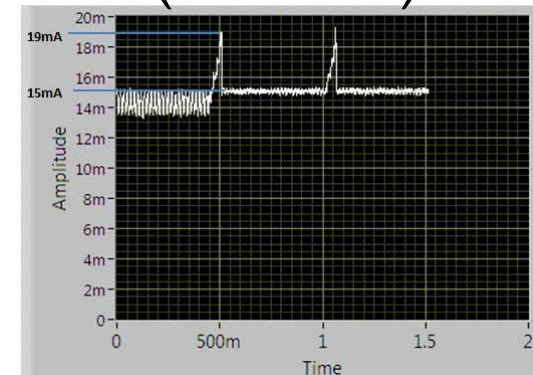
15 V to sensor
(0.49 A)



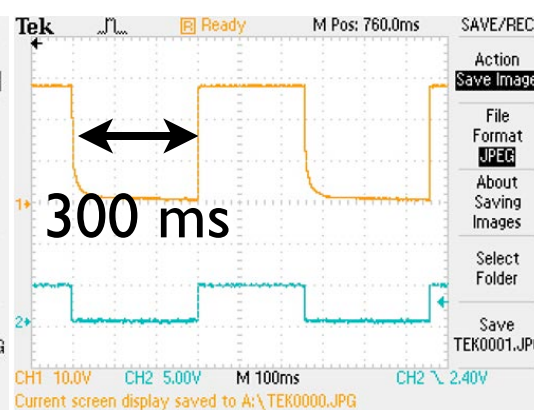
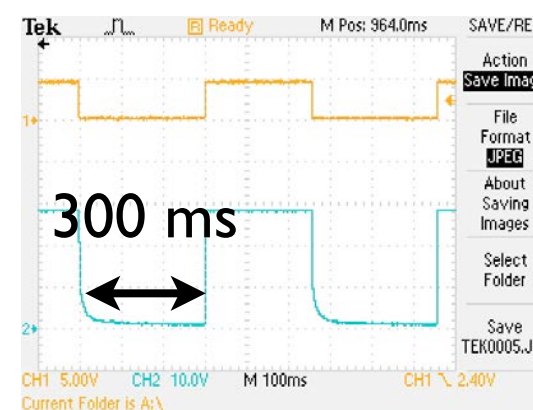
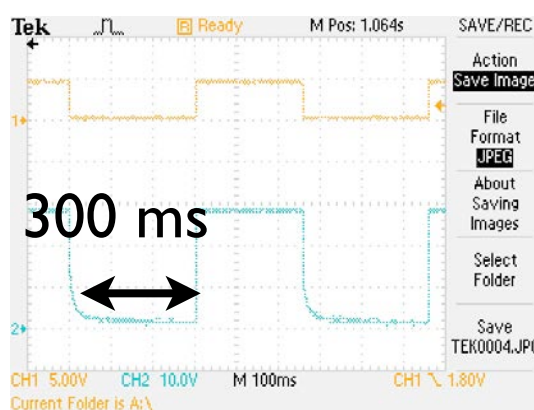
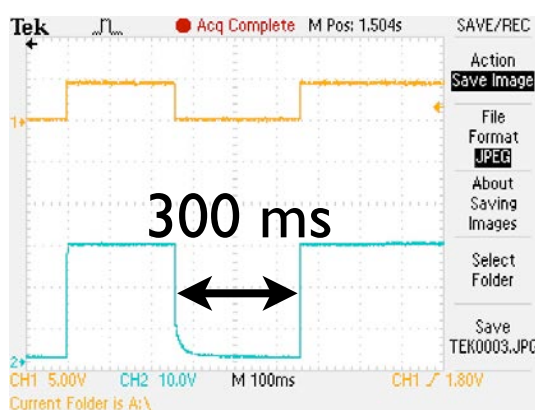
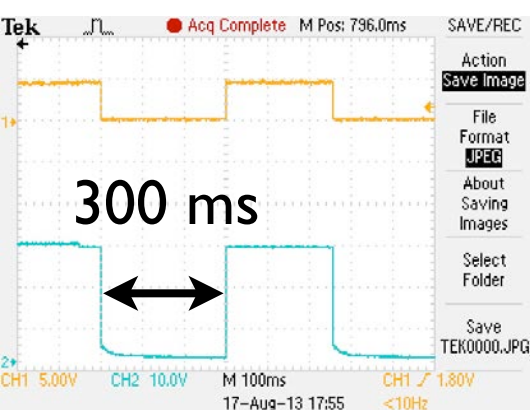
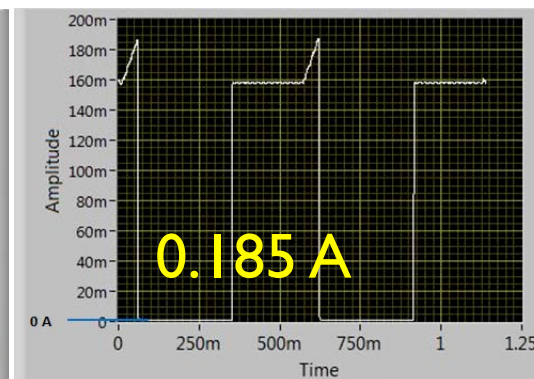
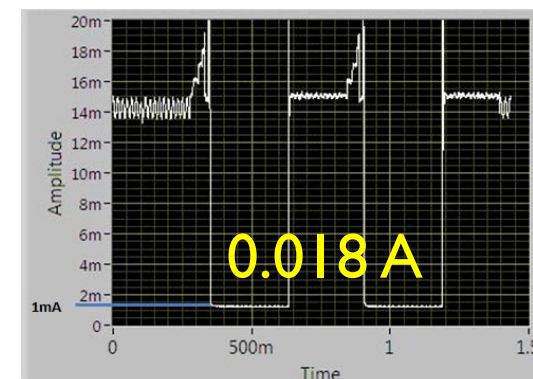
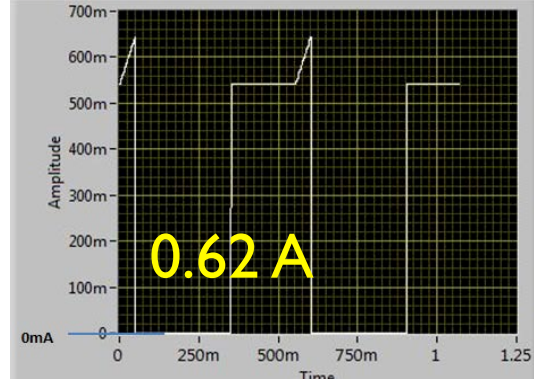
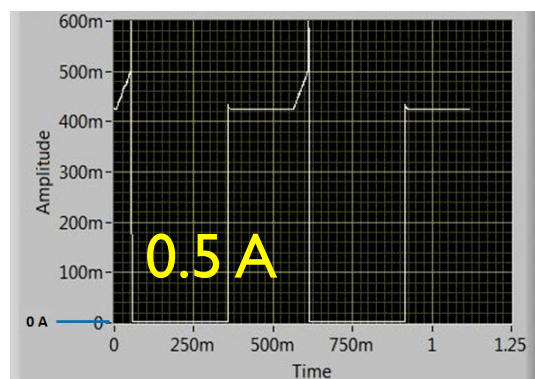
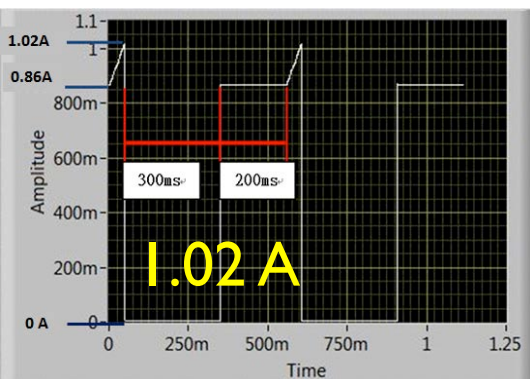
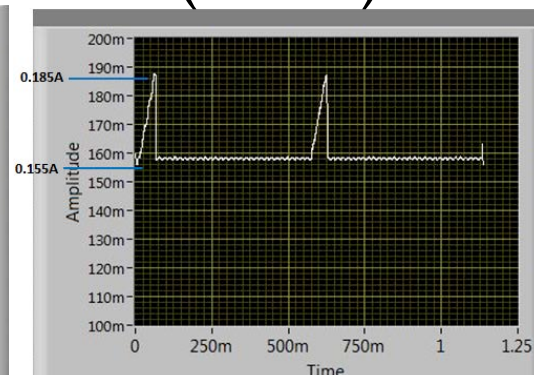
3.3 V to FPGA
(0.62 A)



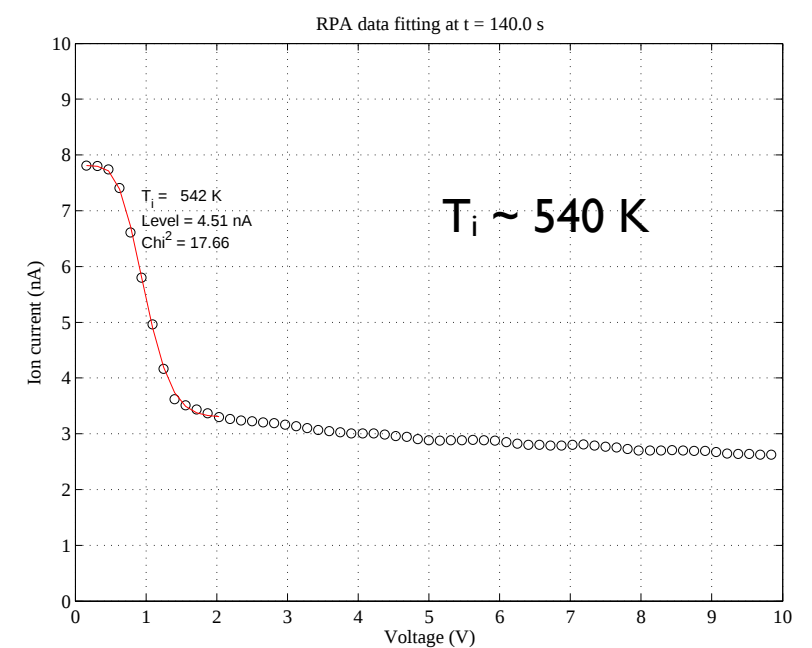
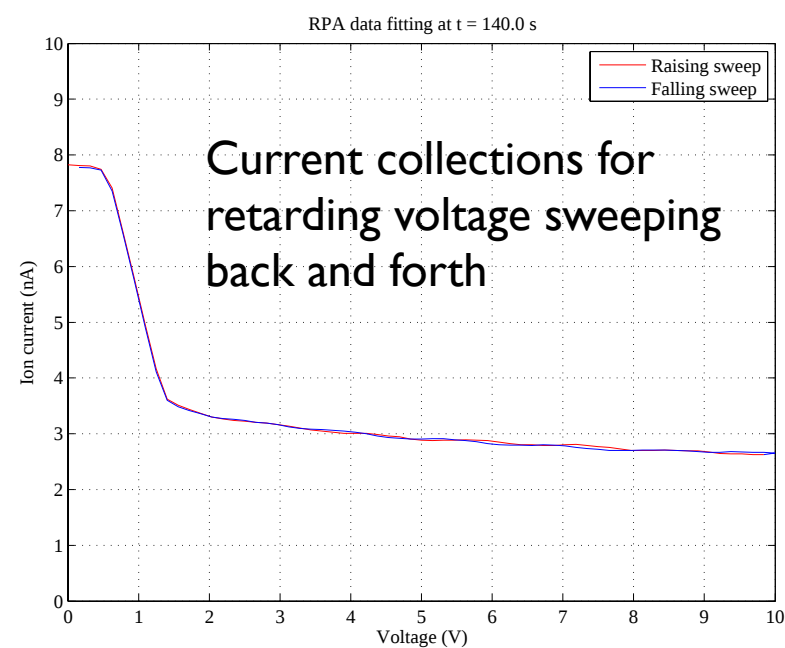
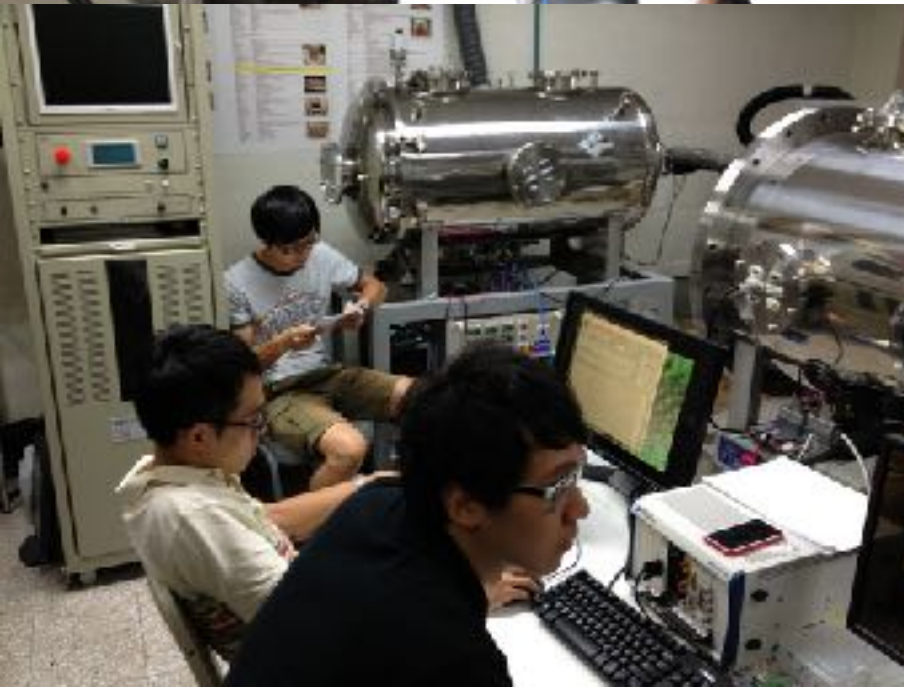
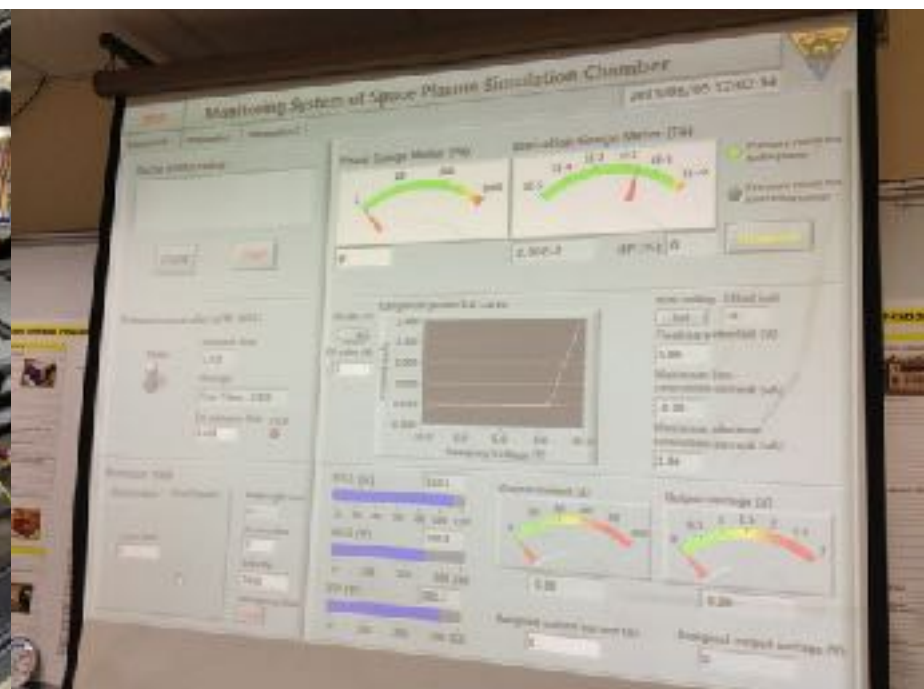
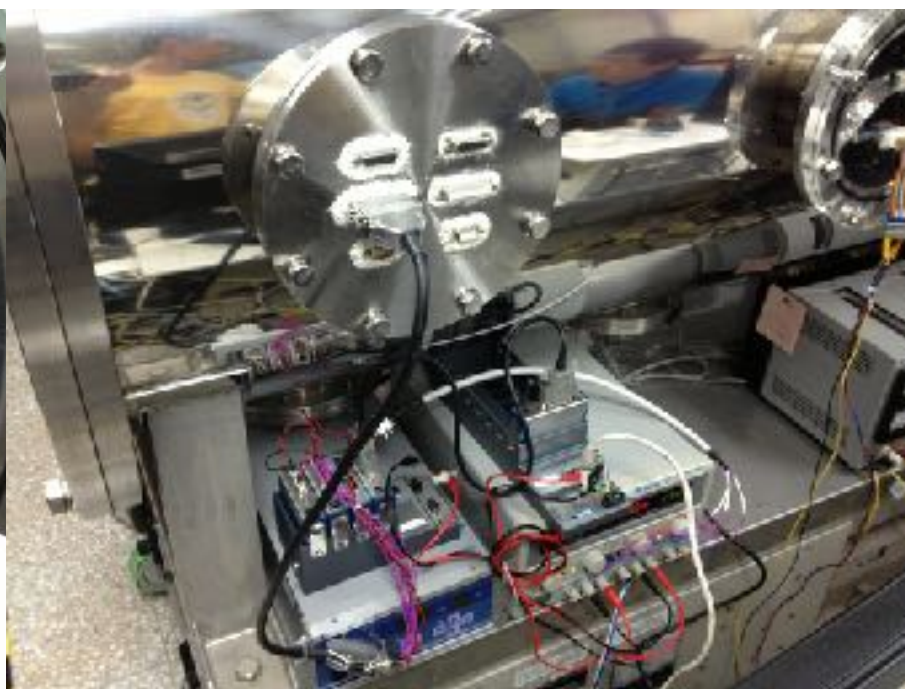
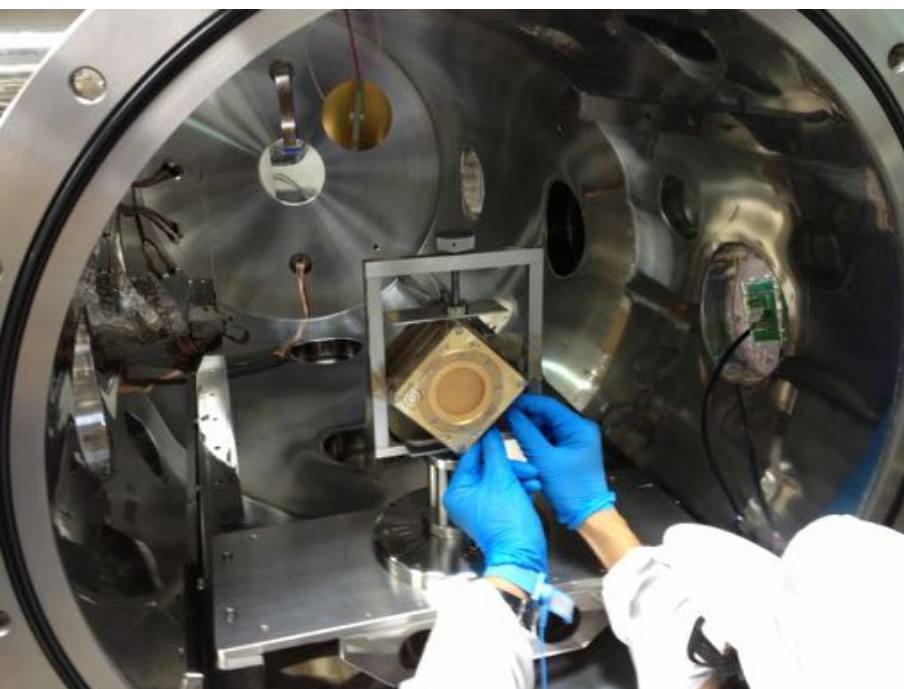
3.3 V to FLASH
(0.0175 A)



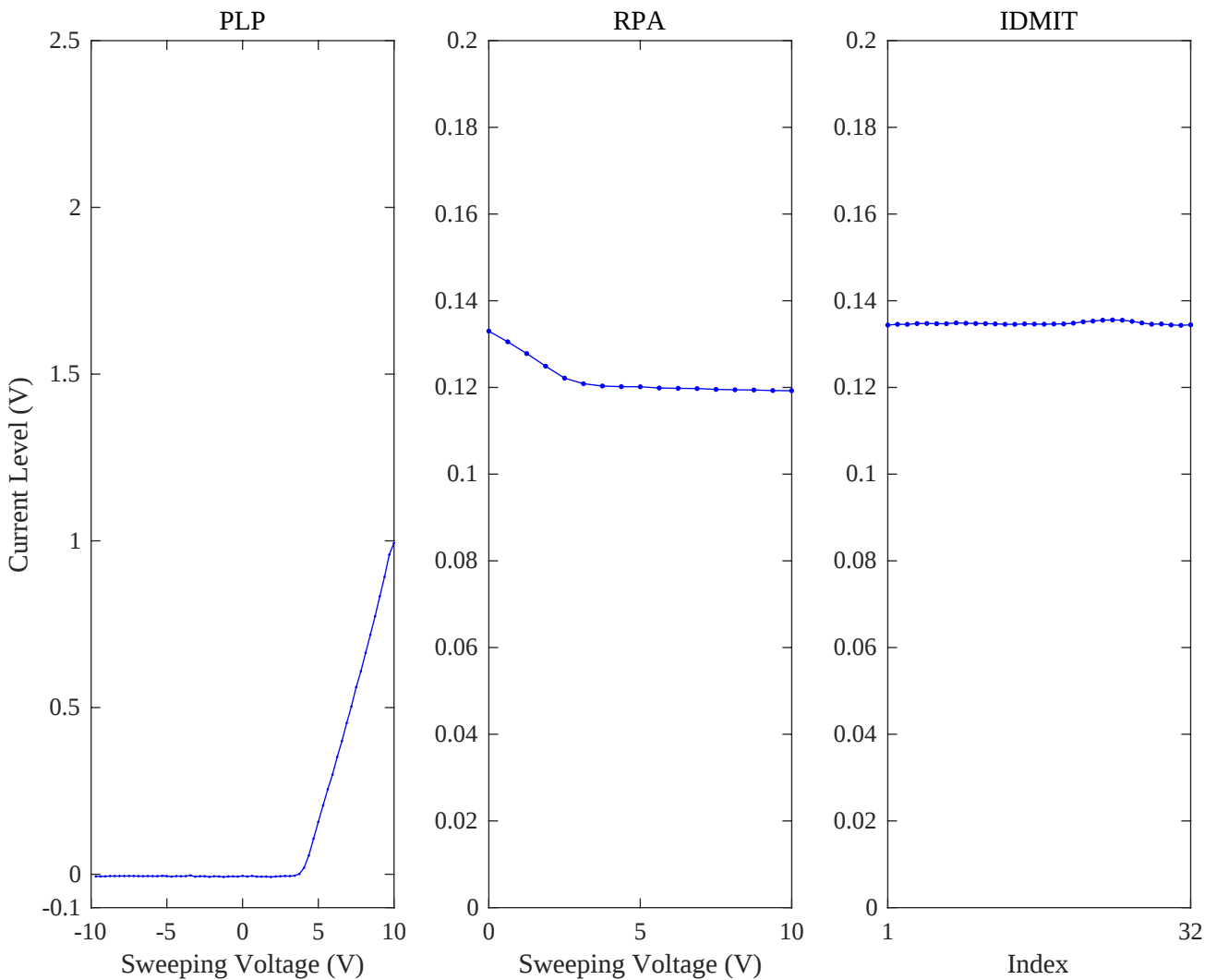
1.2 V to FPGA
(0.18 A)



Plasma injection test

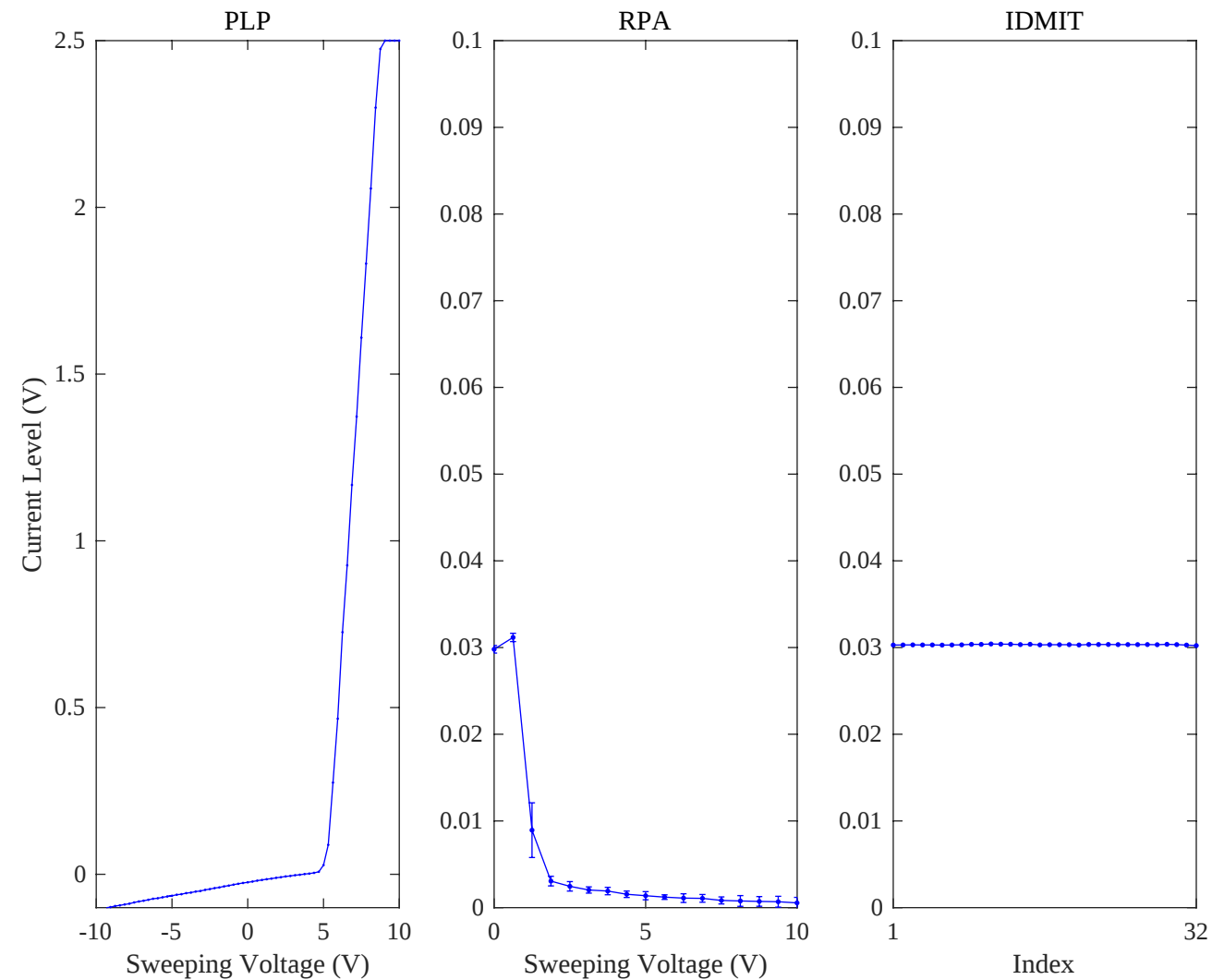


Plasma injection test on Jun. 1, 2016



NORMAL mode

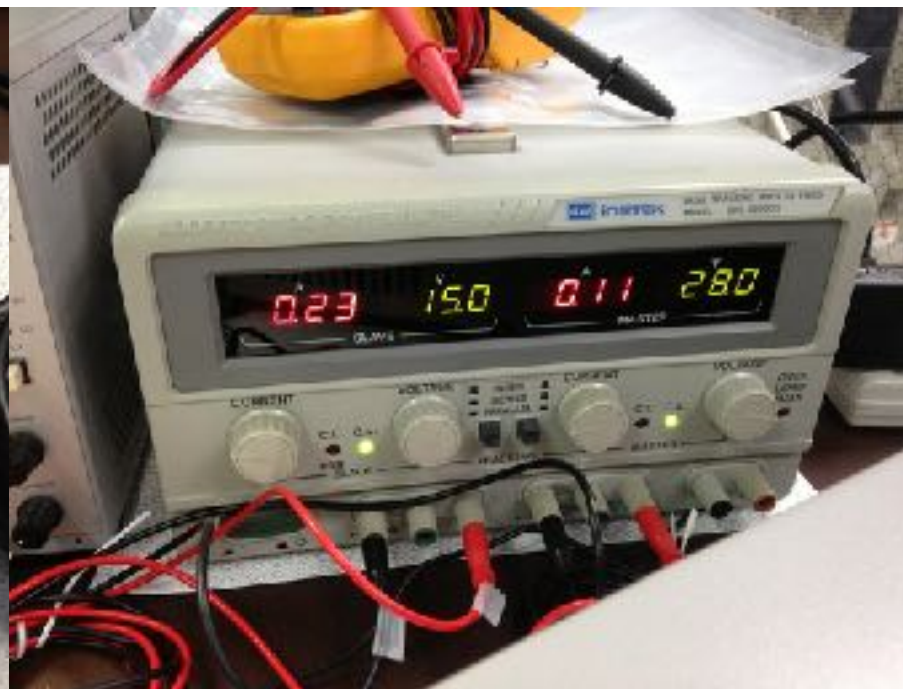
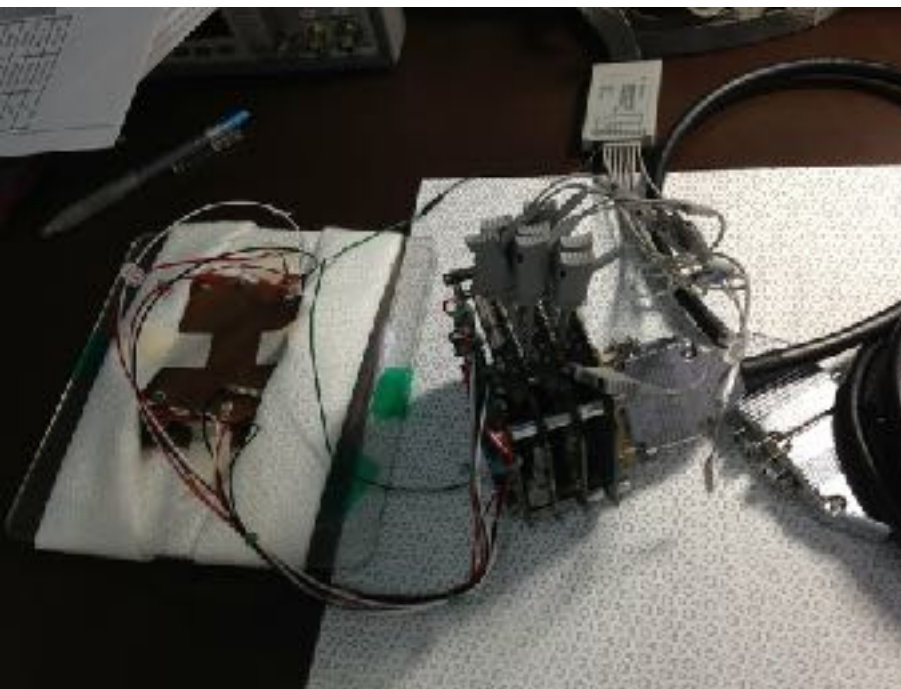
sensor is faced to plasma source



FAST mode

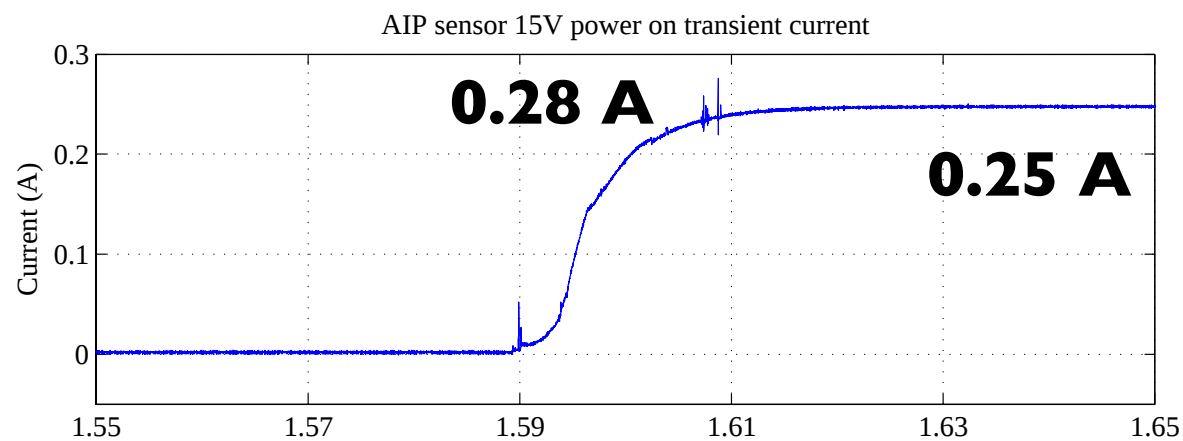
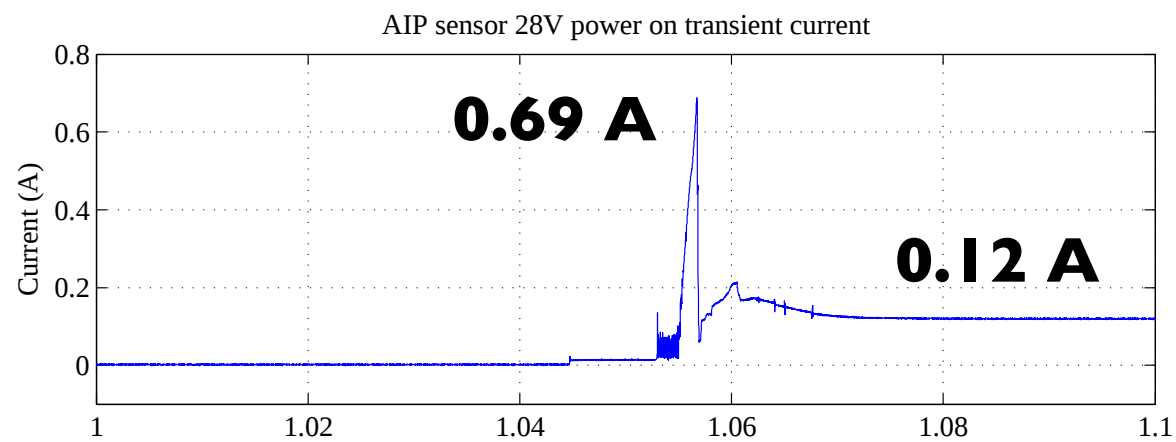
sensor is perpendicular to plasma source

Power measurement

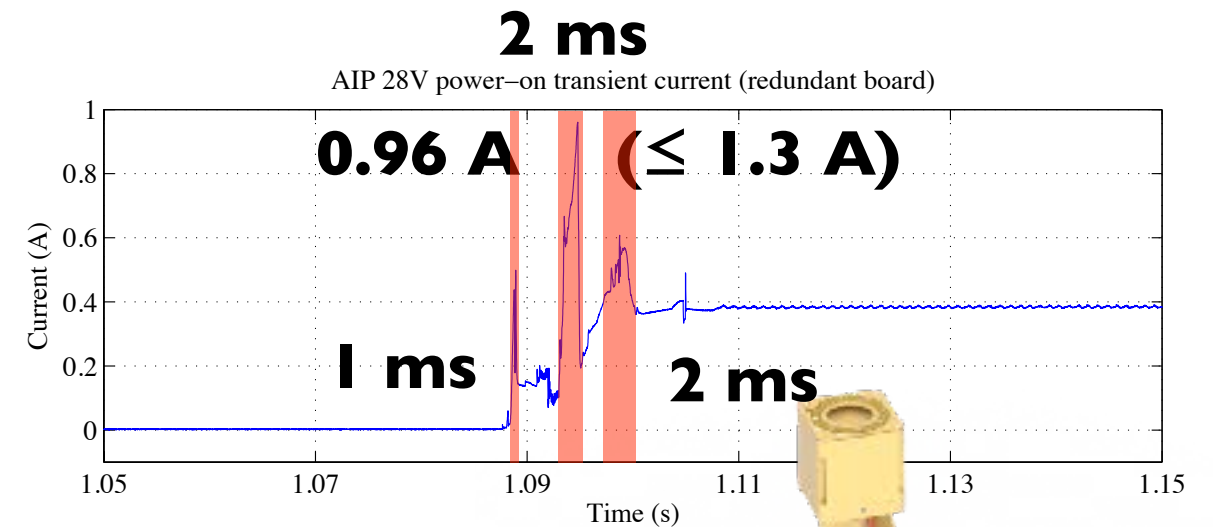
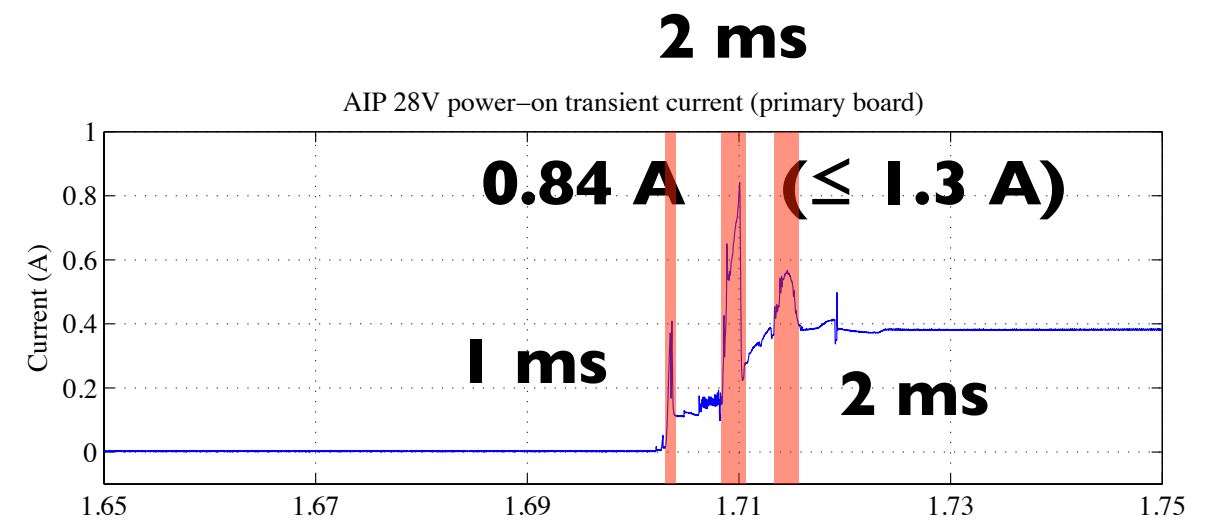


Power measurement (cont.)

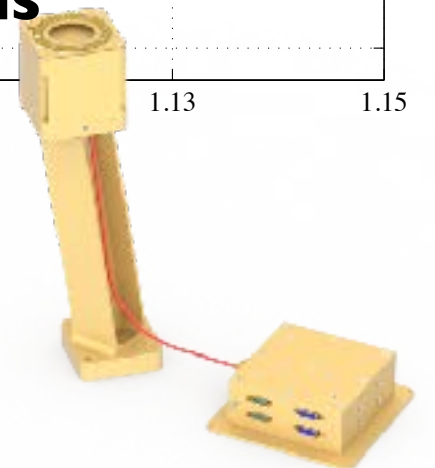
The switch-on current shall return to nominal current level within 5 ms.



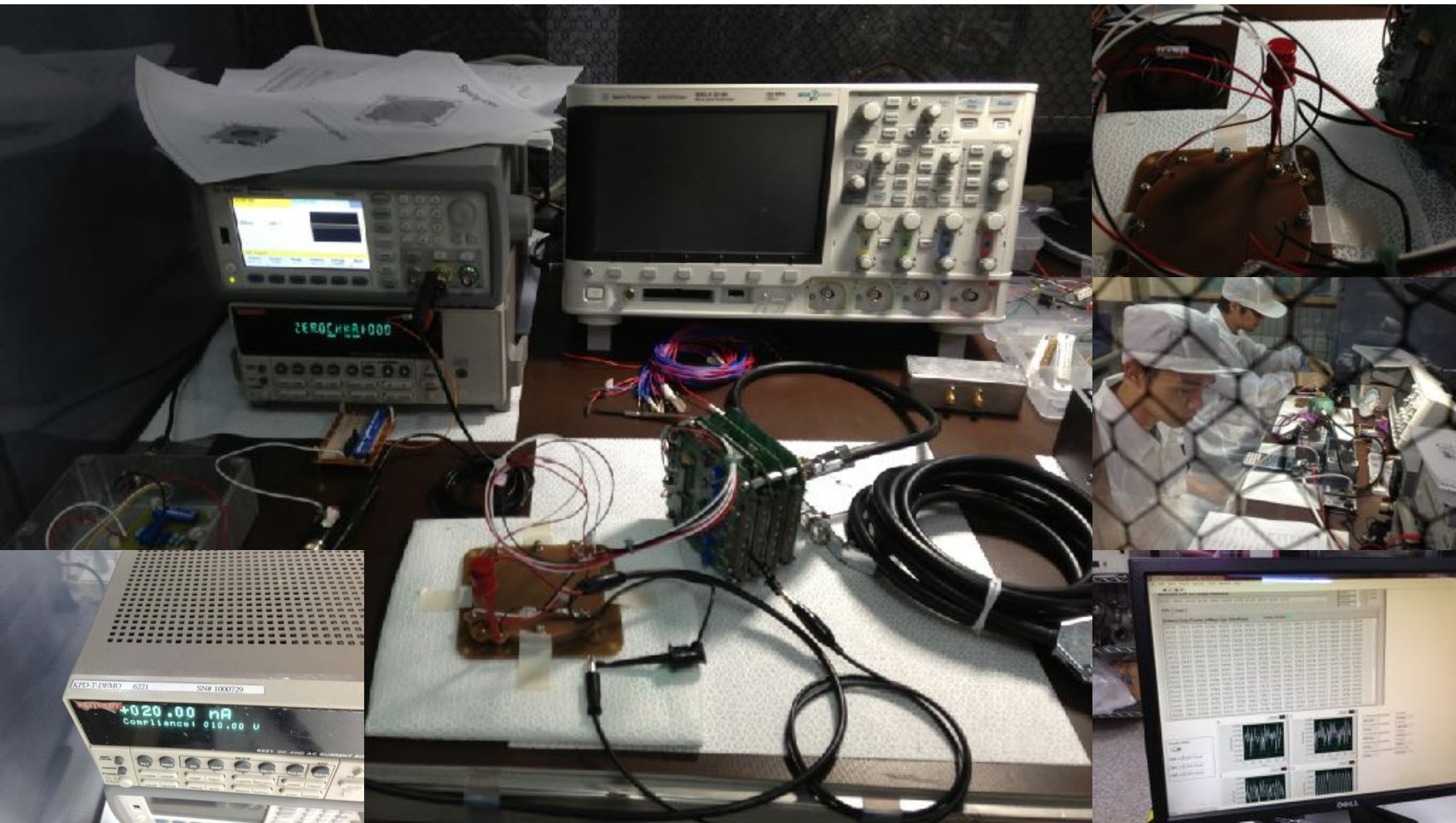
Sensor



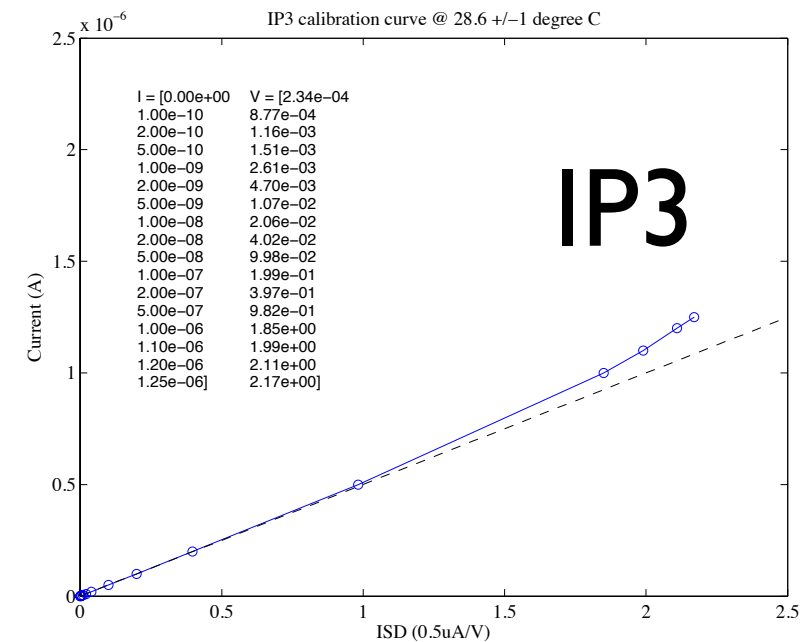
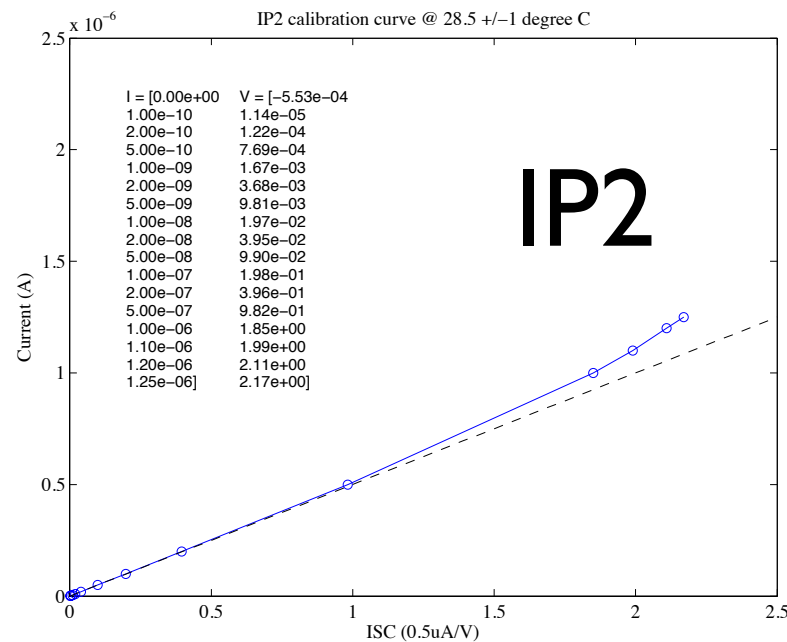
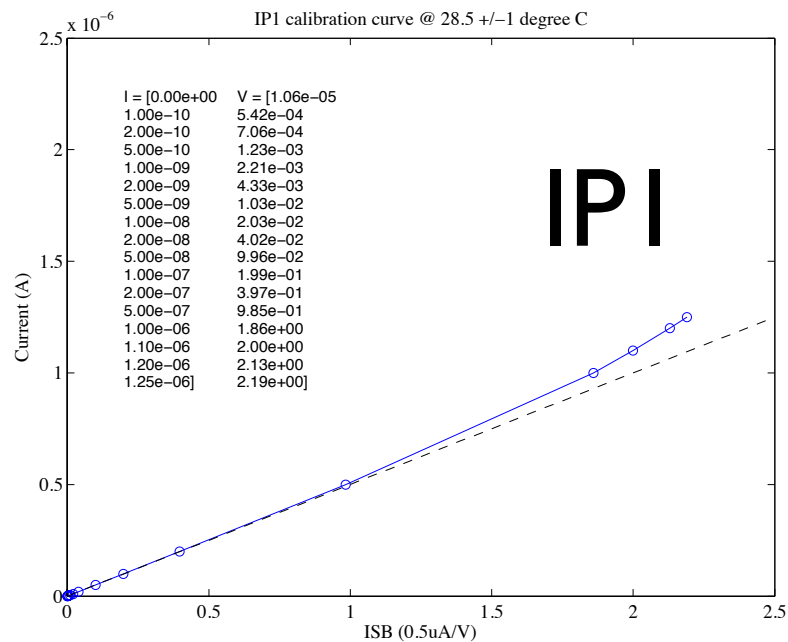
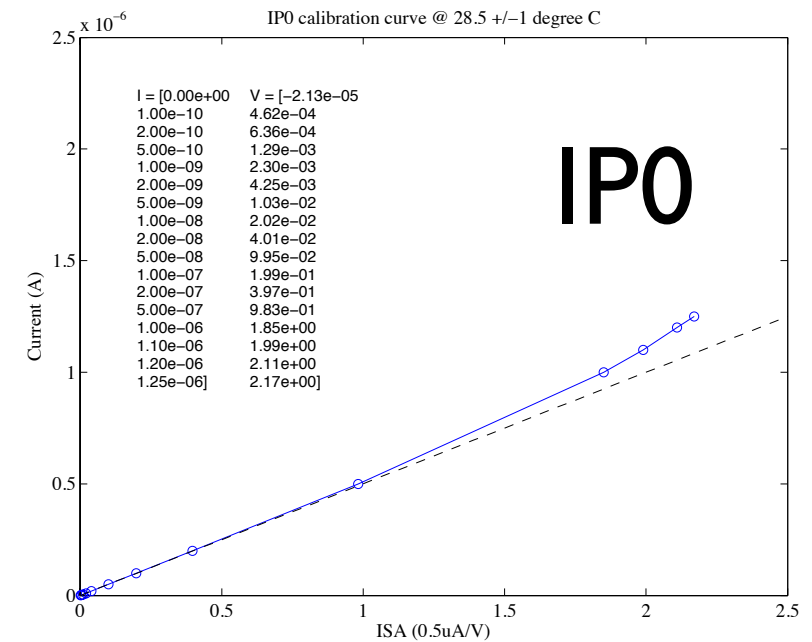
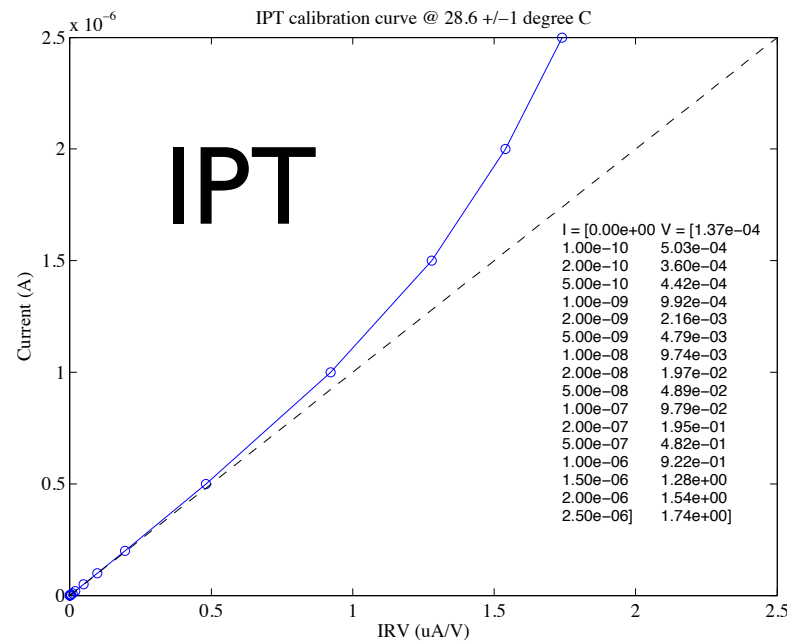
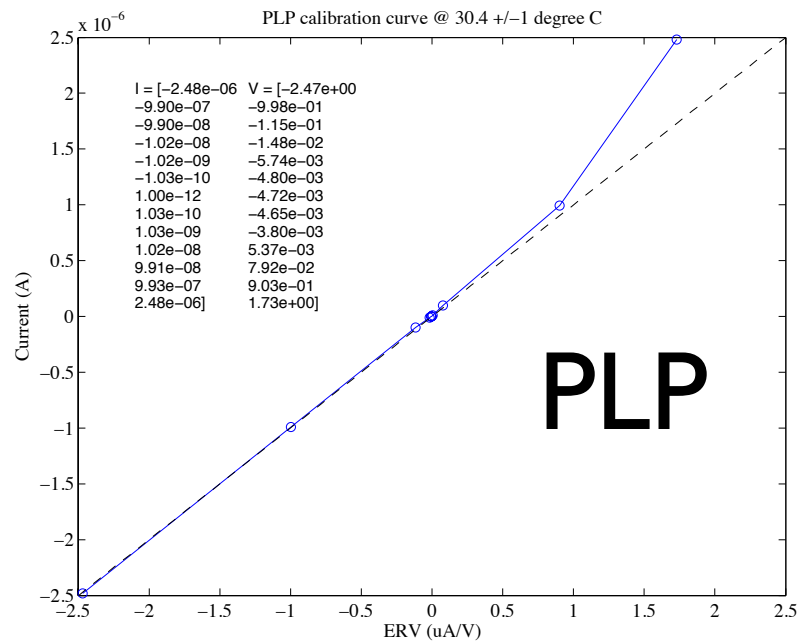
AIP



Current injection test



Current injection test (cont.)



A zener diode is placed in front of an ADC to suppress input voltage smaller than 5 V and can prevent the ADC from damage. It results a non-linear voltage trend (above 1 V) for high current measurement.

Communication test

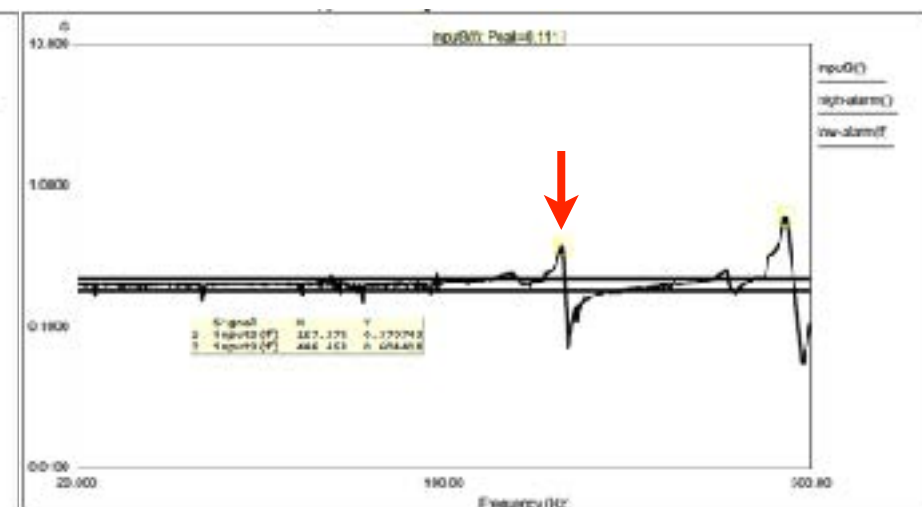
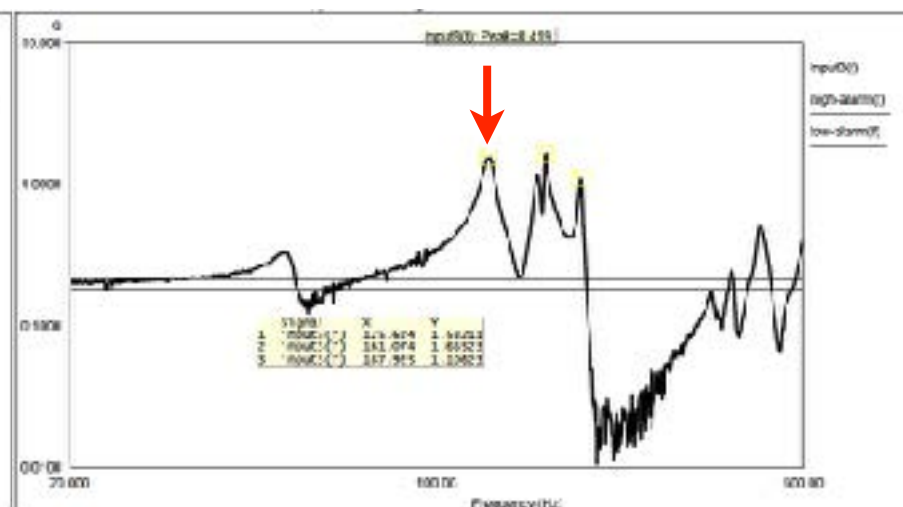
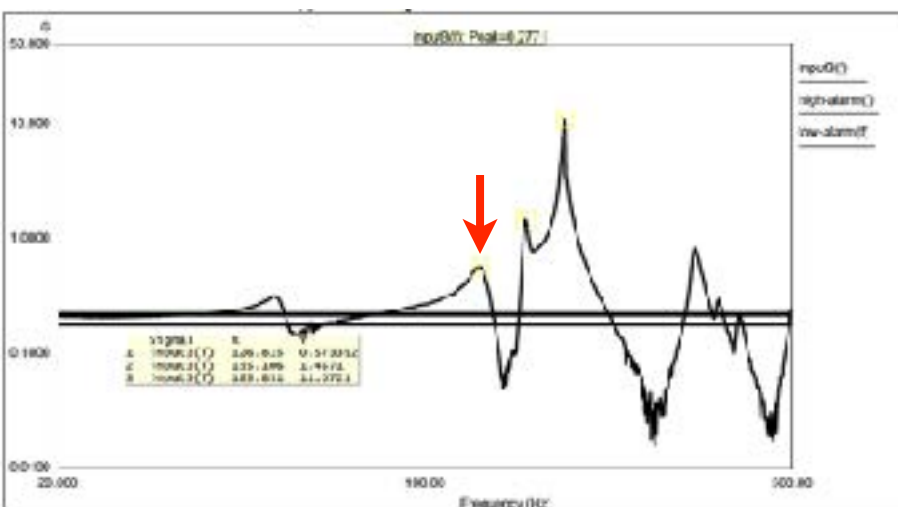
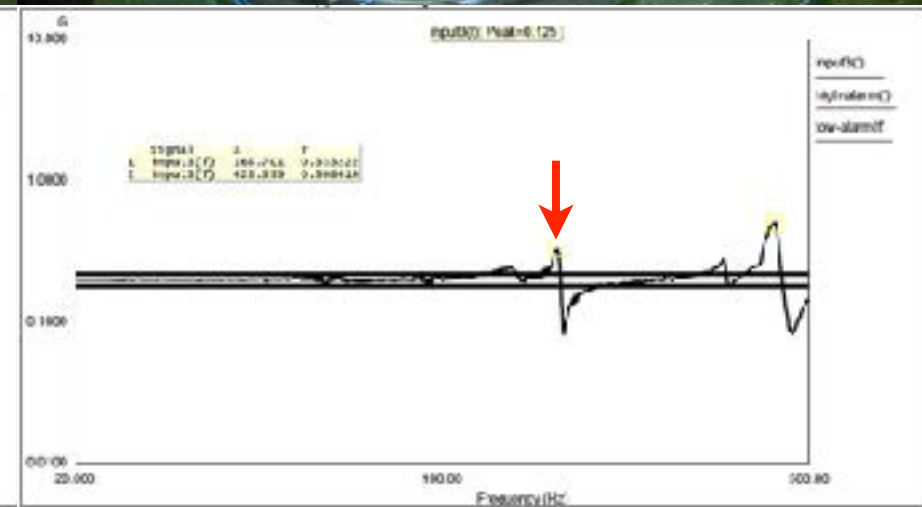
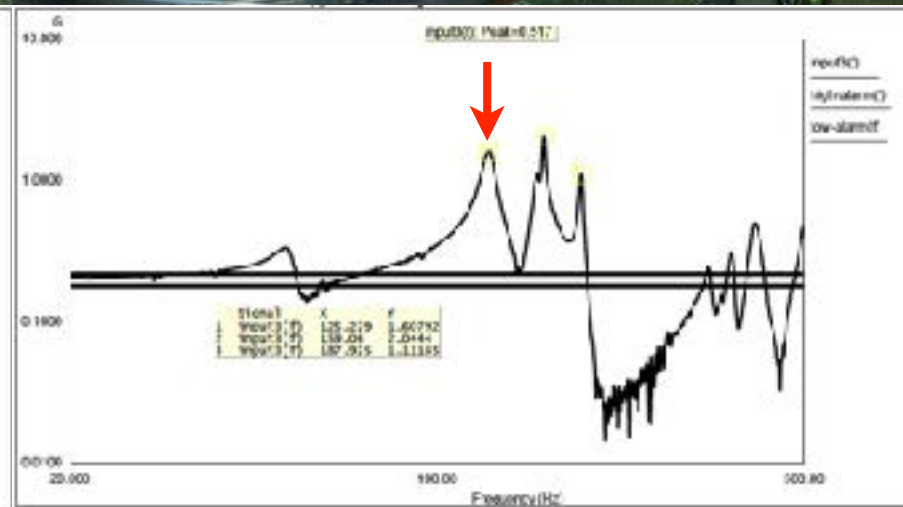
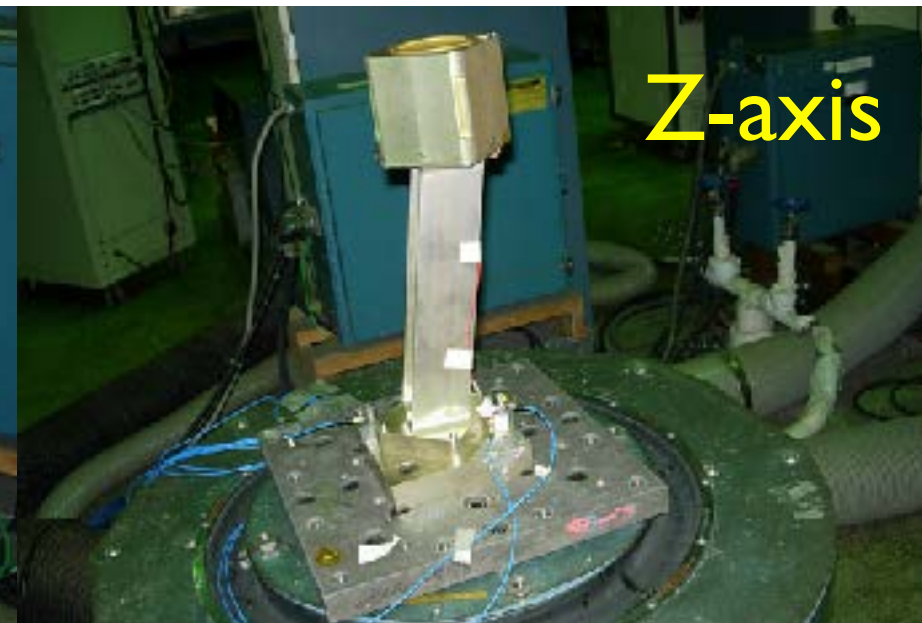
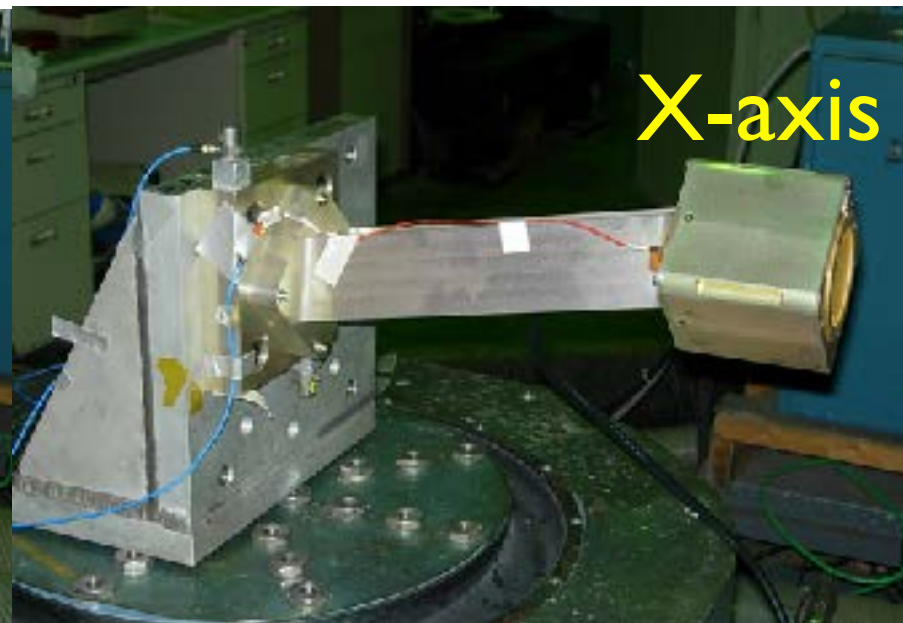


	Sensor only	SPEU only	AIP
EGSE	SPEU & CDMU simulator	CDMU simulator	CDMU simulator
Command	✓	✓	✓
SOH	✓	✓	✓
Ancillary	N/A	✓	✓
Science data	✓ (TESTOFF)	✓ (TESTON)	✓ (TESTOFF)

Environmental tests

- **Sine vibration test** (CSIST, 8/8/2013 & 8/29/2013): FS5SPL-SINE-PROC/RPT.
- **Random vibration test** (CSIST, 8/8/2013 & 8/29/2013): FS5SPL-RAND-PROC/RPT.
- **Shock test** (CSIST, 8/8/2013 & 8/29/2013): FS5SPL-SHOCK-PROC/RPT.
- **Thermal vacuum test** (NCU, 9/4/2013 to 9/11/2013): FS5SPL-TVT-PROC/RPT.
- **EMC test** (NSPO, 9/16/2013 to 9/18/2013 & 9/23/2013 to 9/27/2013): FS5SPL-CEMC-PROC/RPT and FS5SPL-REMC-PROC/RPT.

Structure measurement for sensor



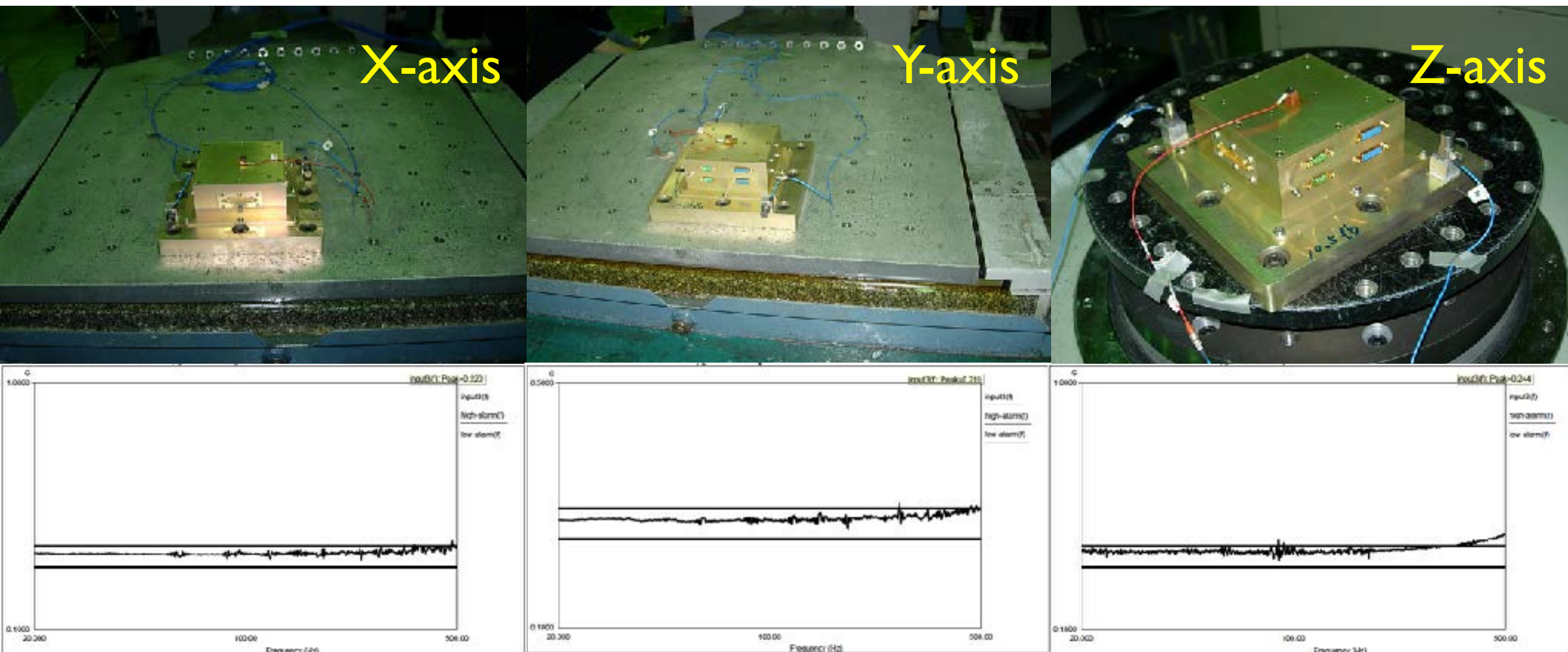
1st mode natural frequency

145.6 Hz estimated by SolidWorks and 136.1 Hz measured by NCU.

CSIST	Y-axis	X-axis	Z-axis
Before	128.4 Hz (x2.71)	125.2 Hz (x8.04)	165.7 Hz (x1.67)
After	126.8 Hz (x2.87)	125.6 Hz (x7.91)	167.3 Hz (x1.85)

All 1st mode natural frequencies measured by NCSIST are higher than 120 Hz.

Structure measurement for SPEU

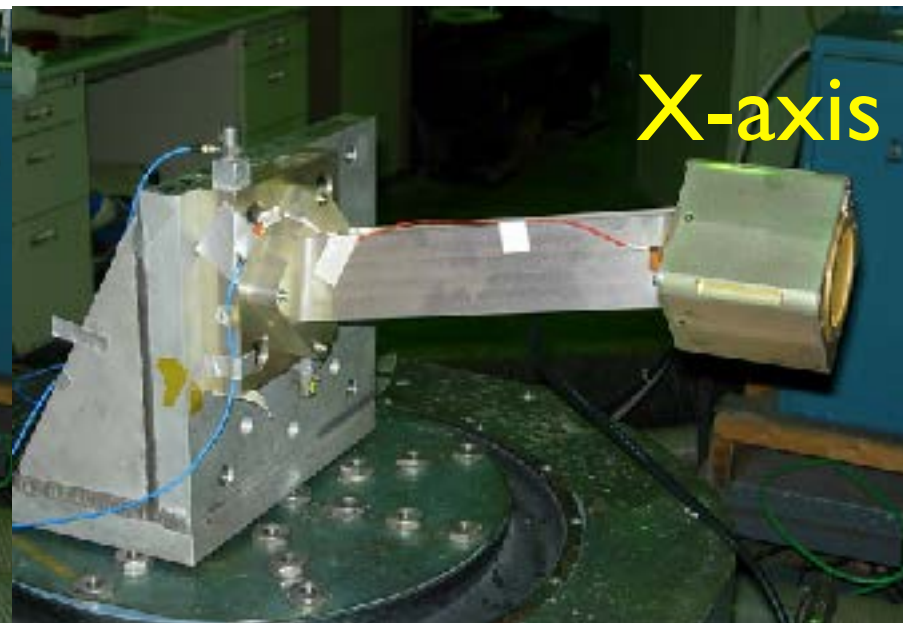


No significant natural frequencies are detected within the measurement range (20 to 500 Hz) in three different orientations.

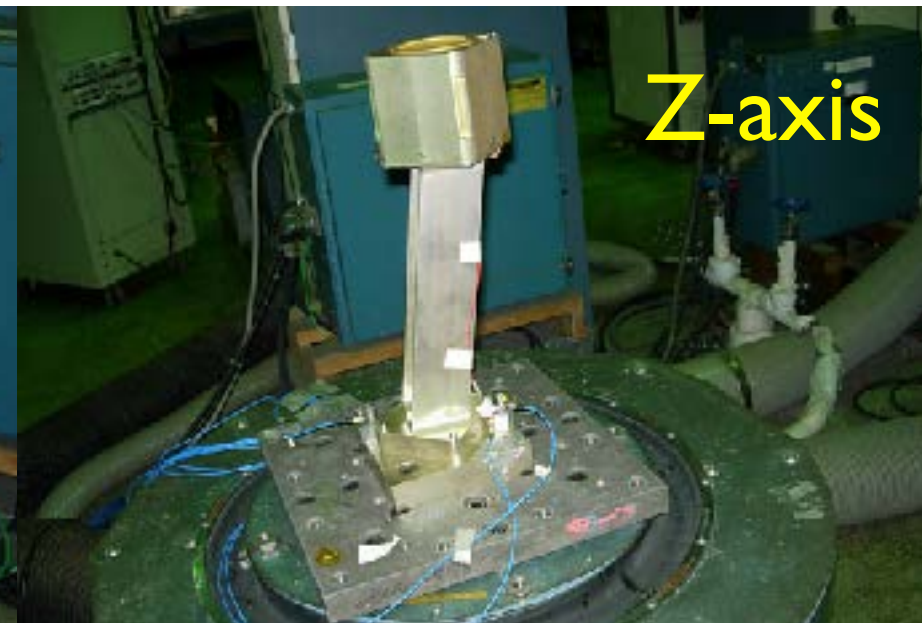
Vibration test for sensor



Y-axis



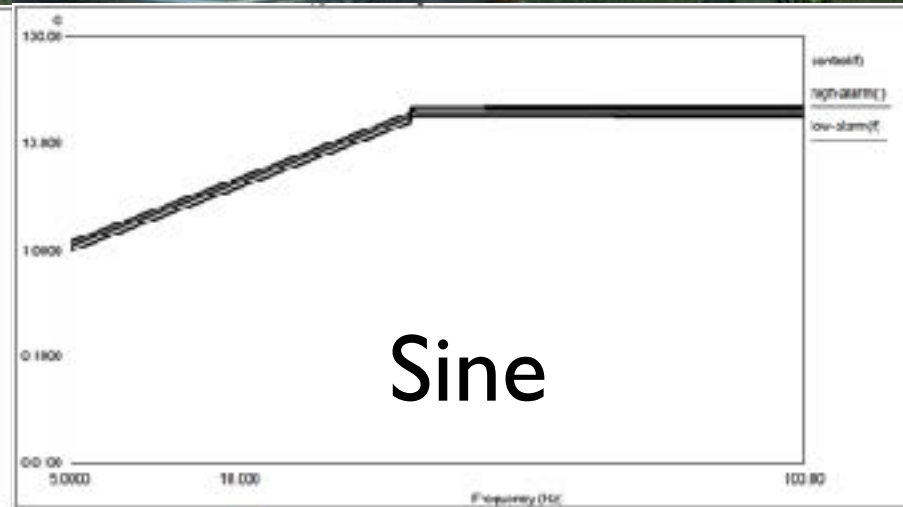
X-axis



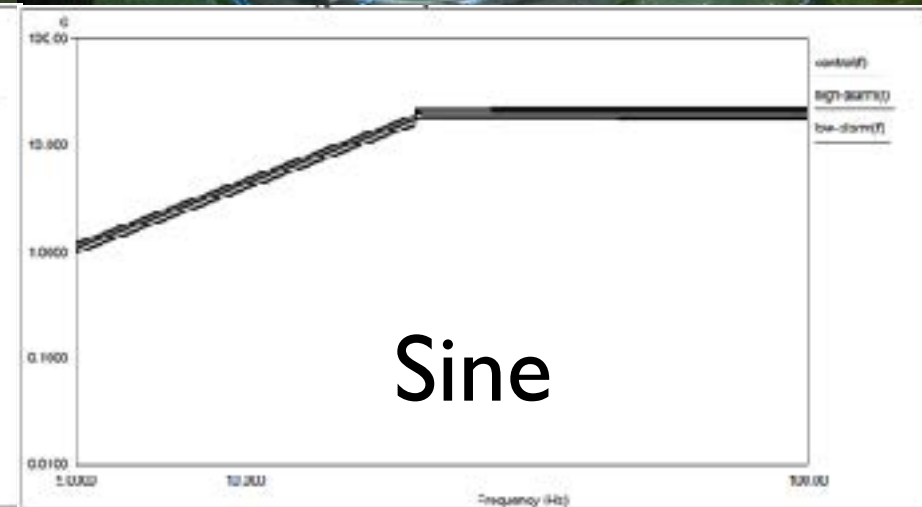
Z-axis



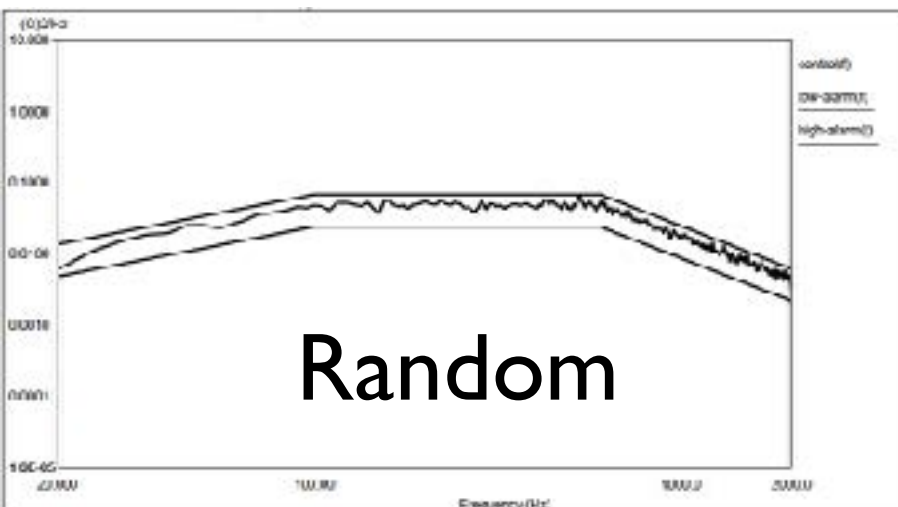
Sine



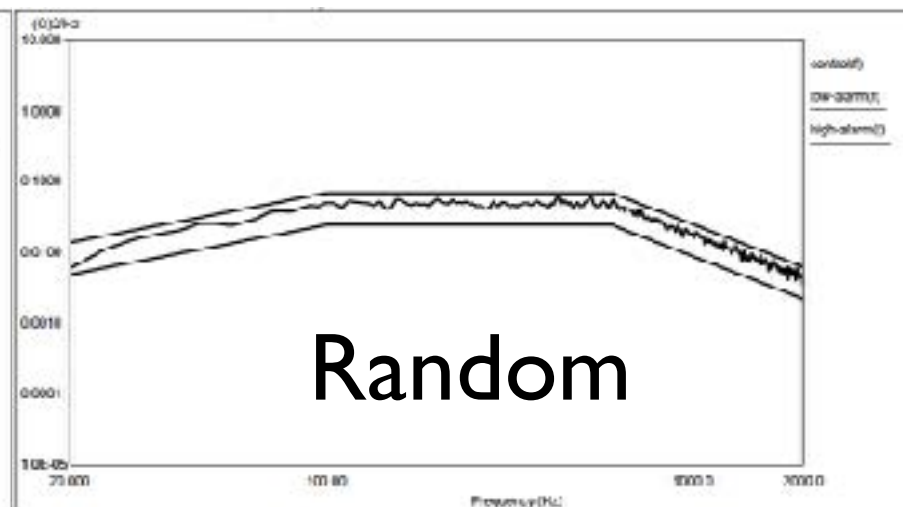
Sine



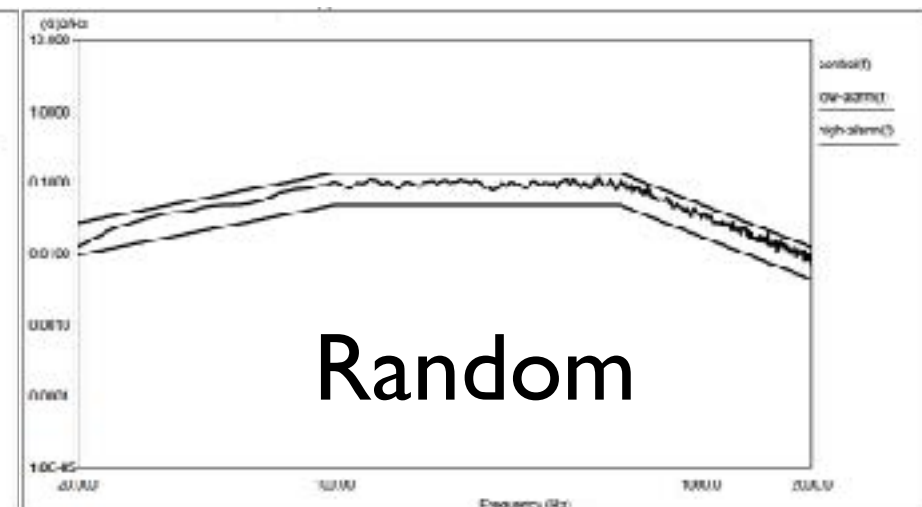
Sine



Random

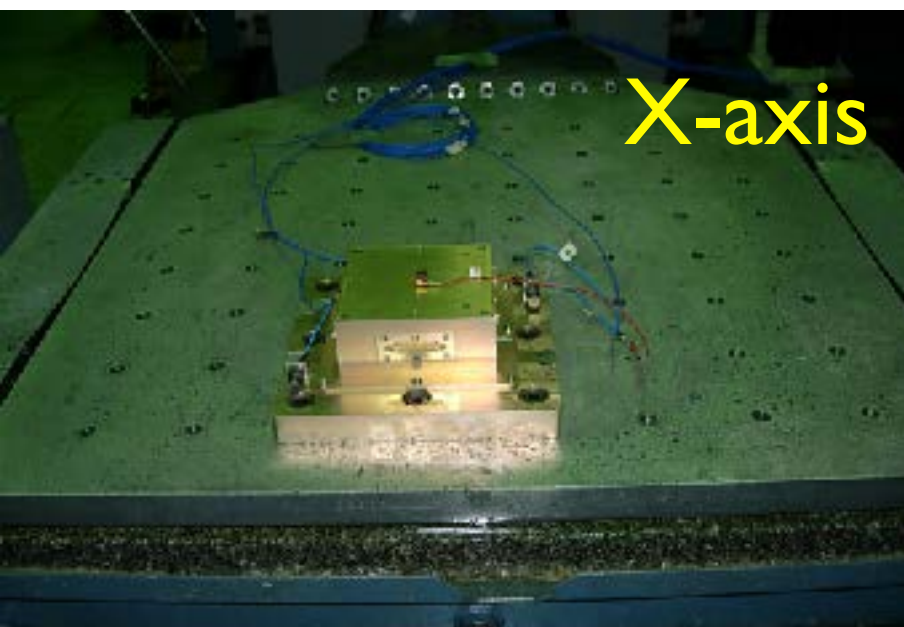


Random



Random

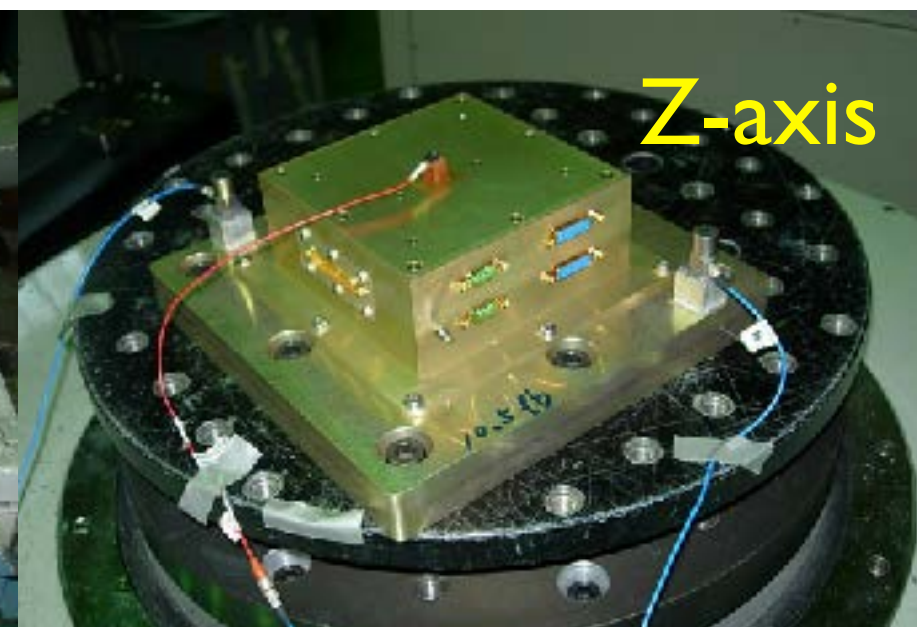
Vibration test for SPEU



X-axis



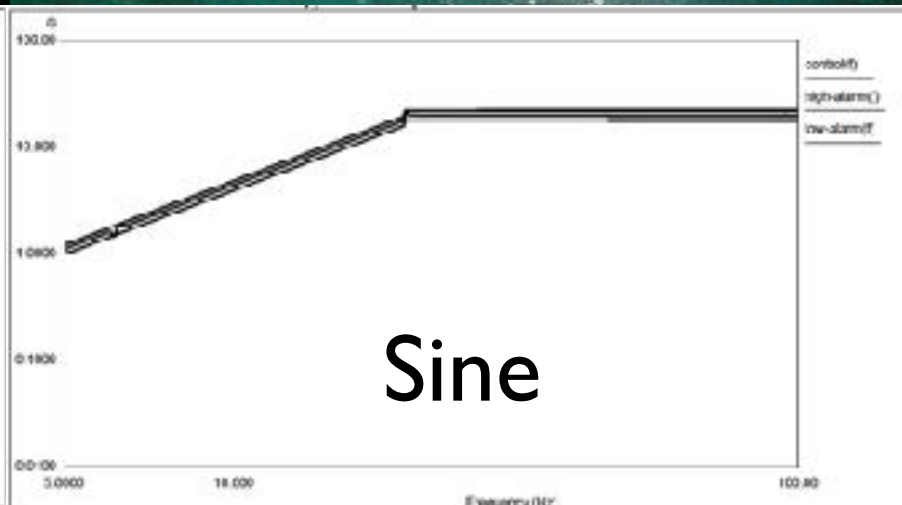
Y-axis



Z-axis



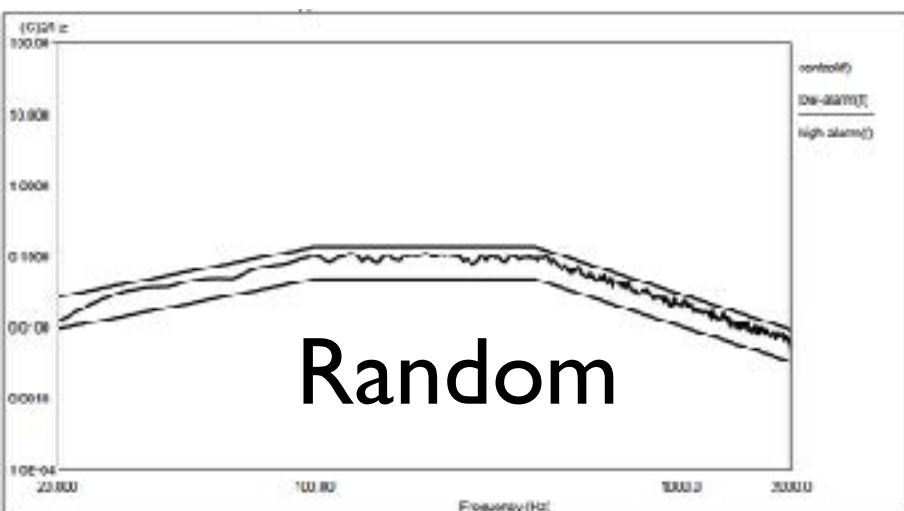
Sine



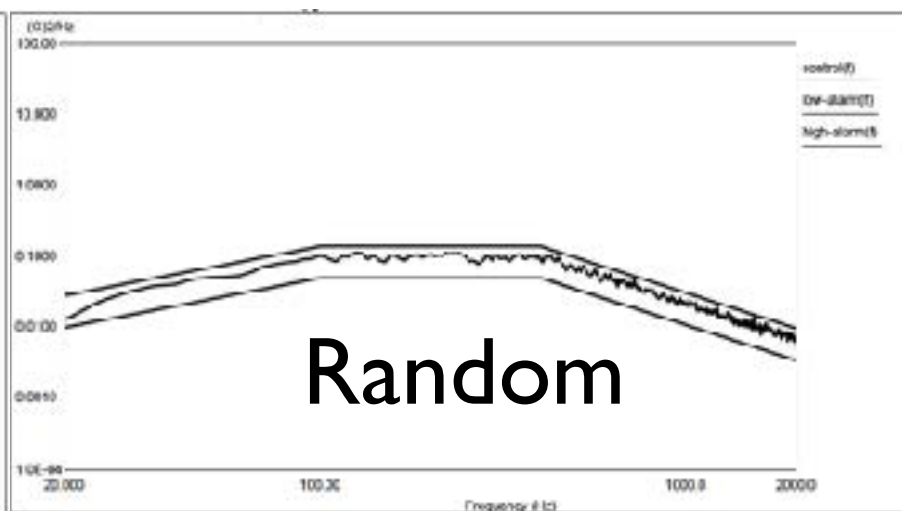
Sine



Sine



Random



Random

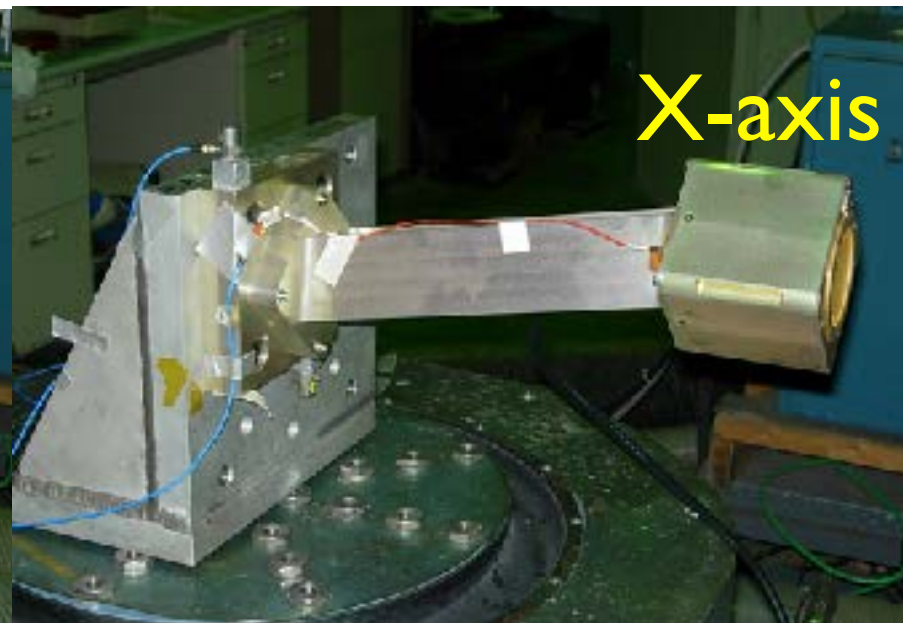


Random

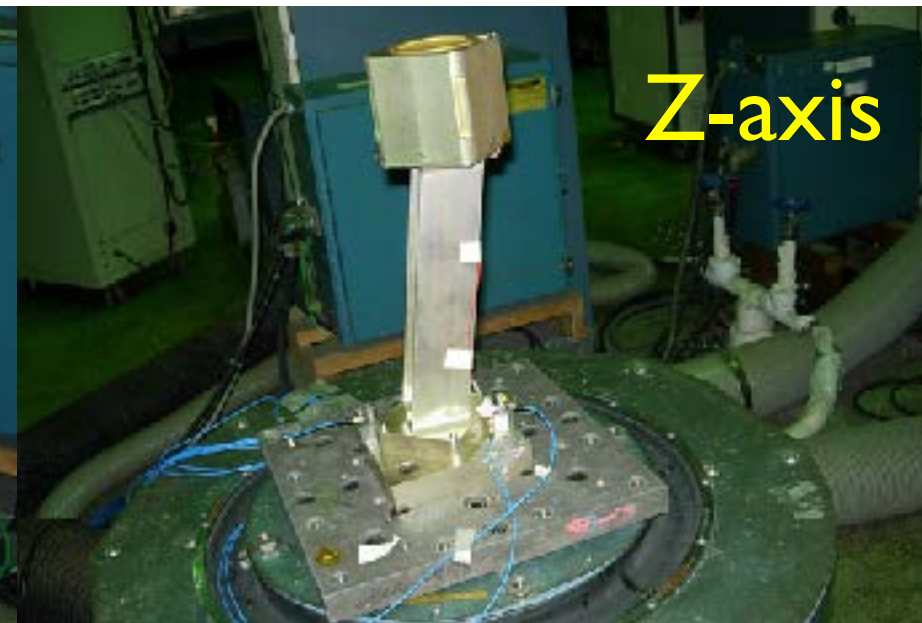
Shock test for sensor



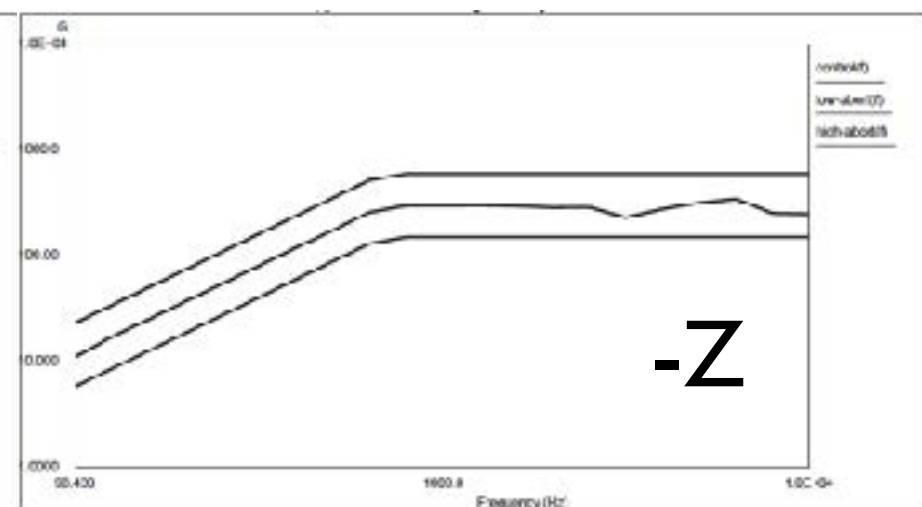
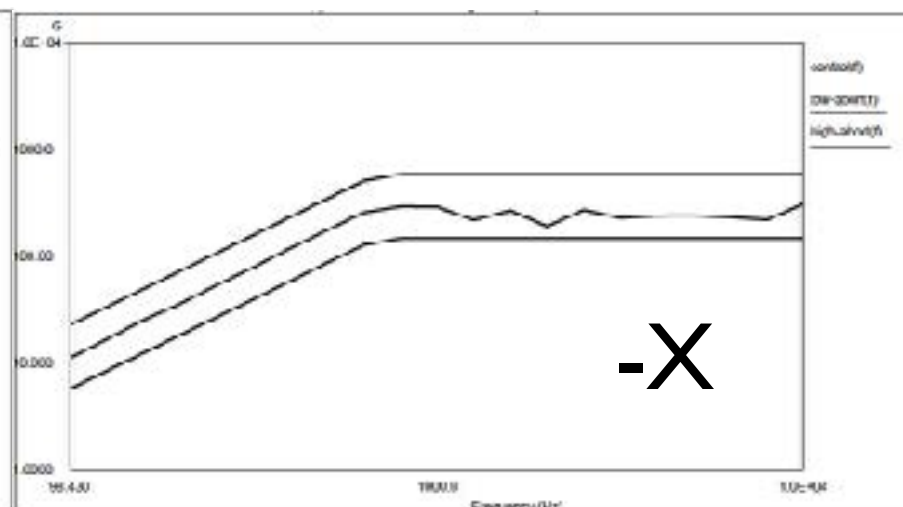
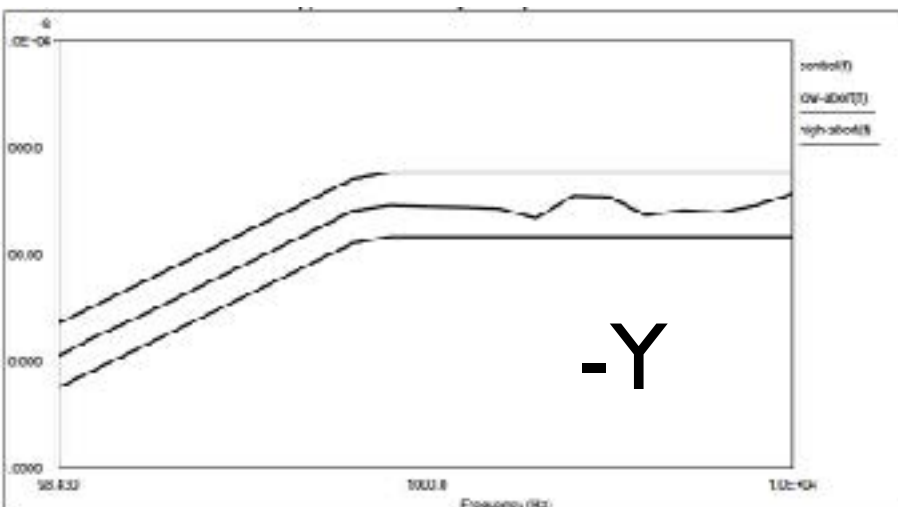
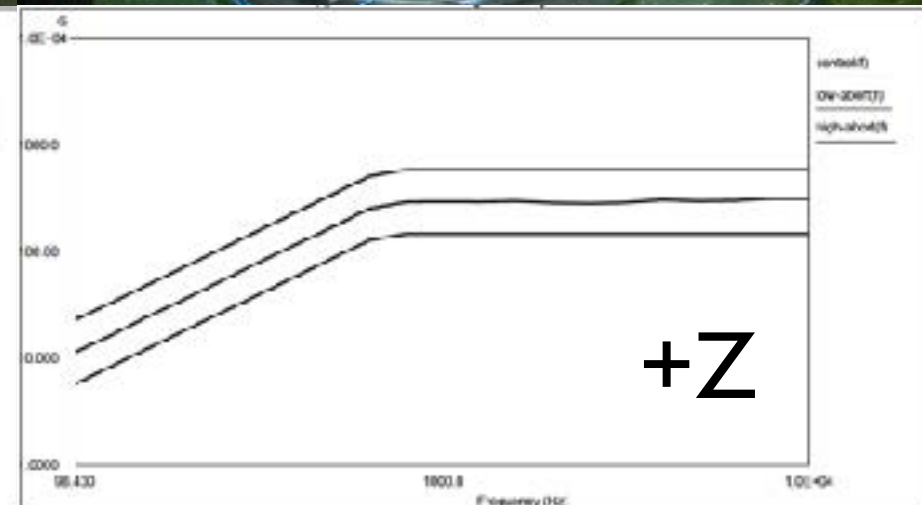
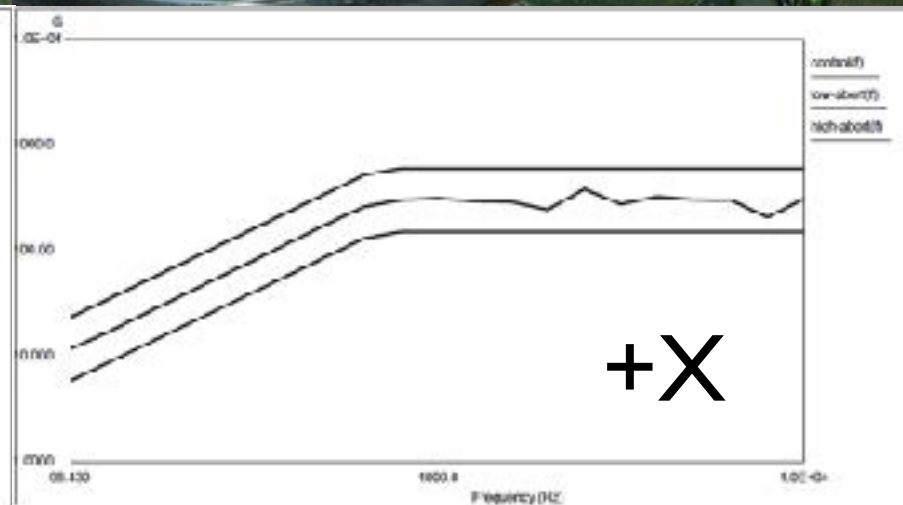
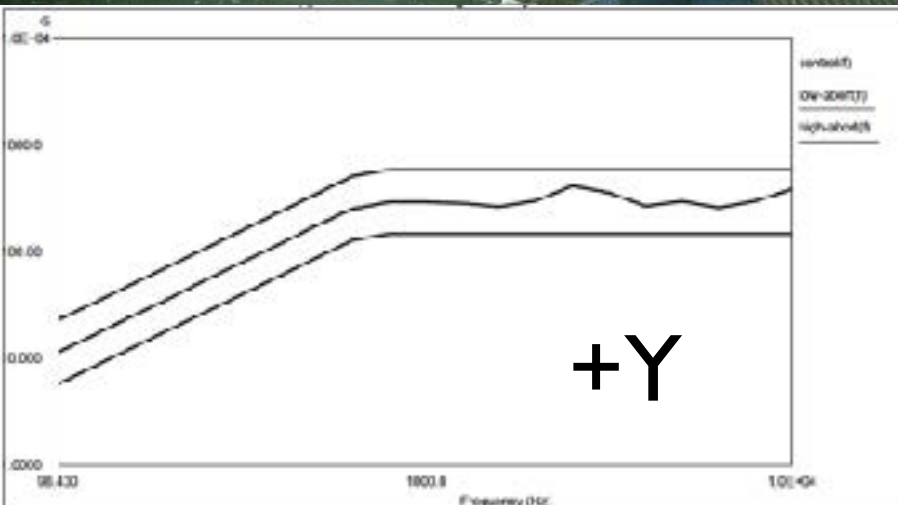
Y-axis



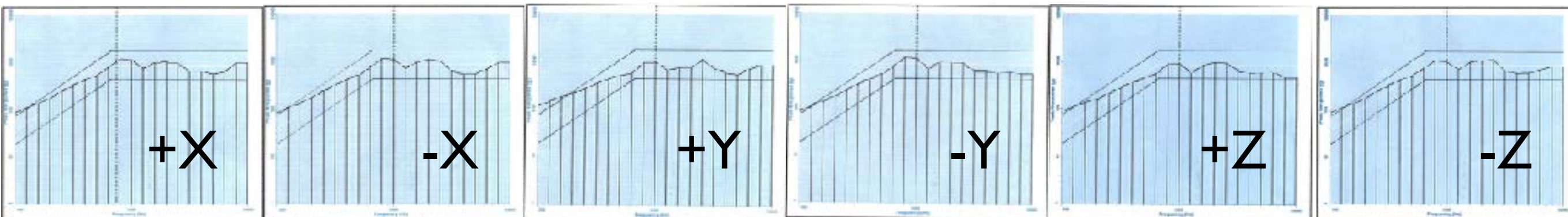
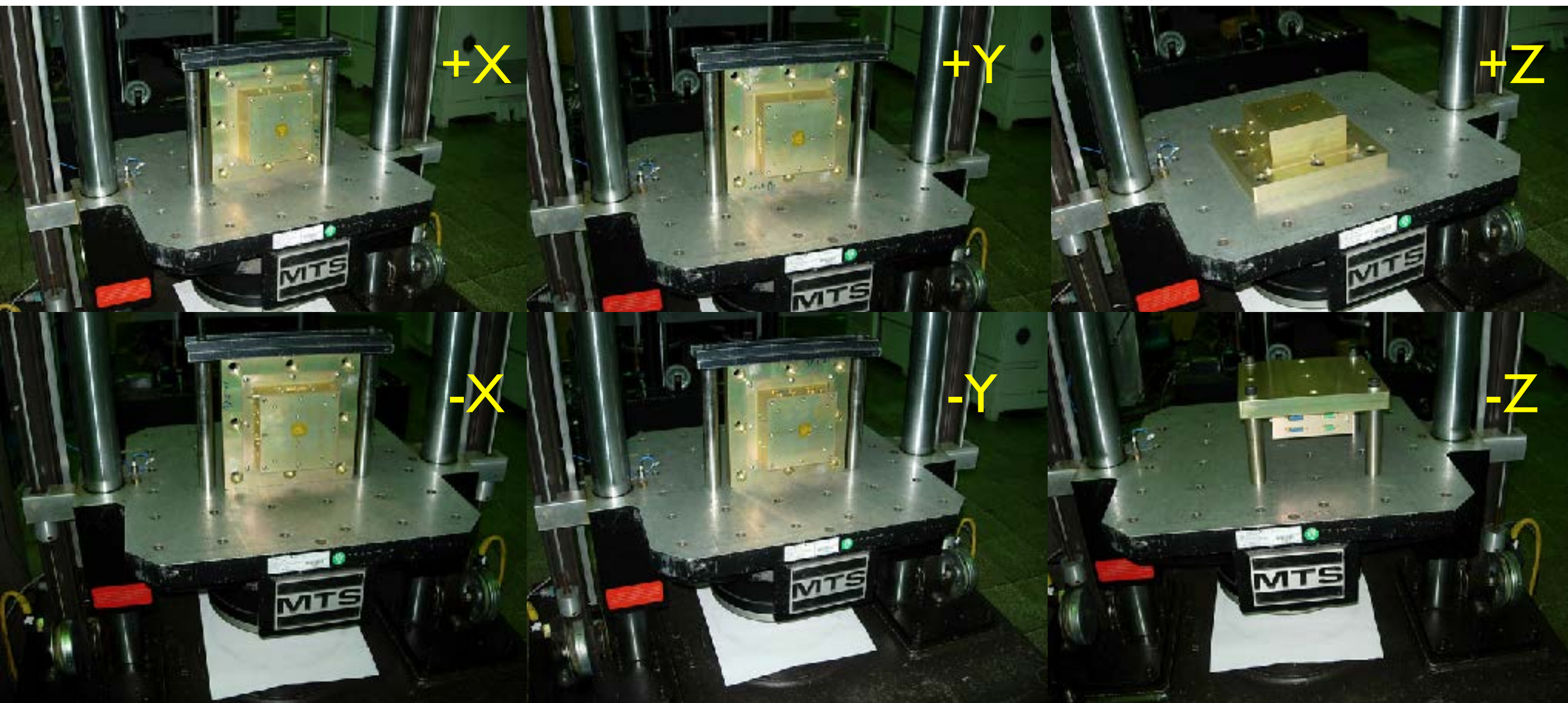
X-axis



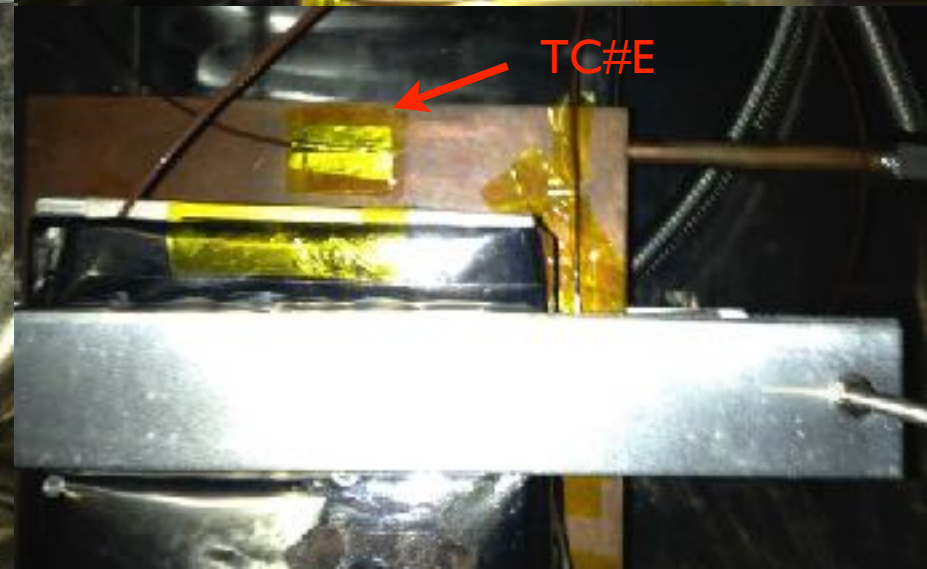
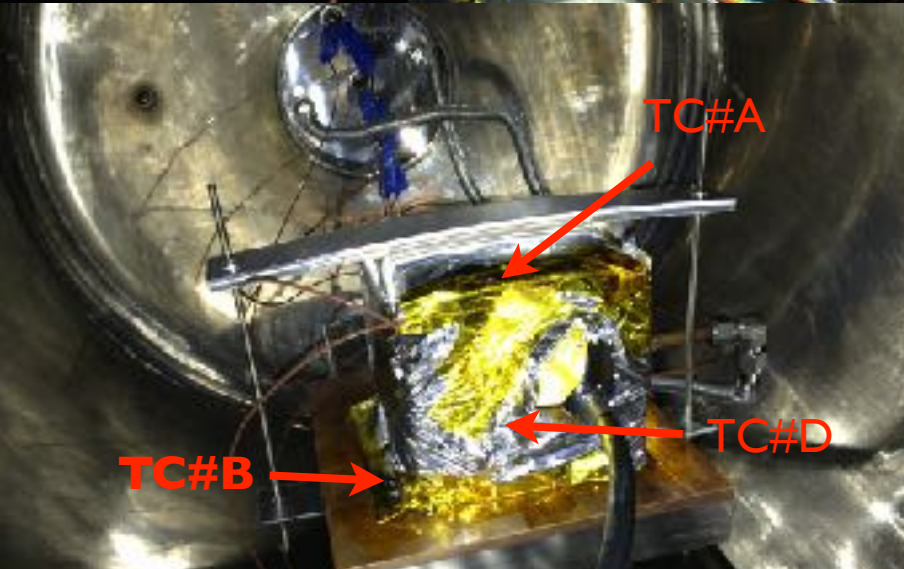
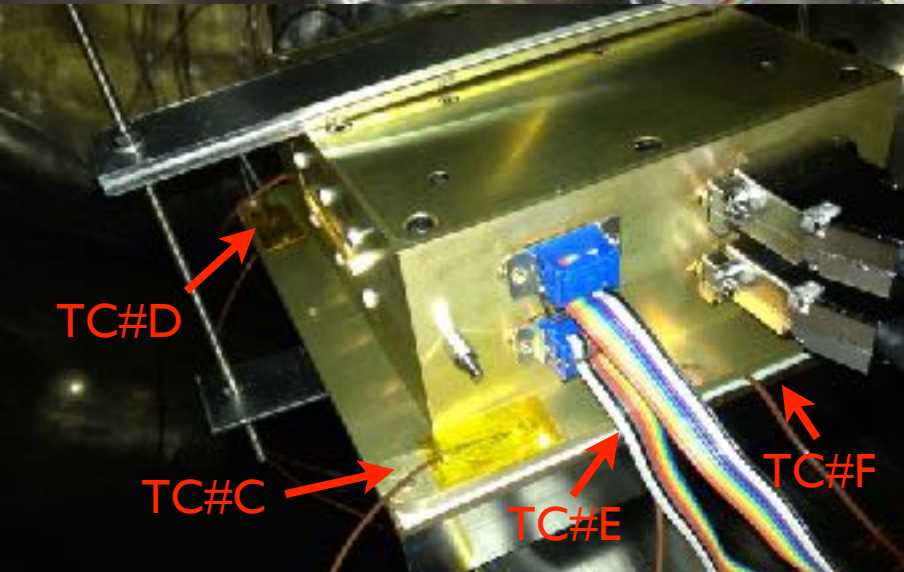
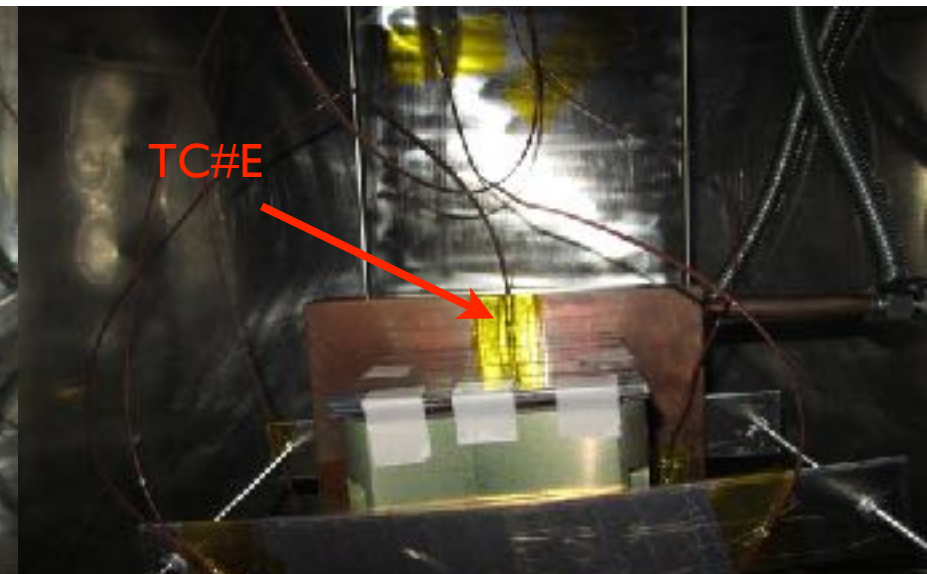
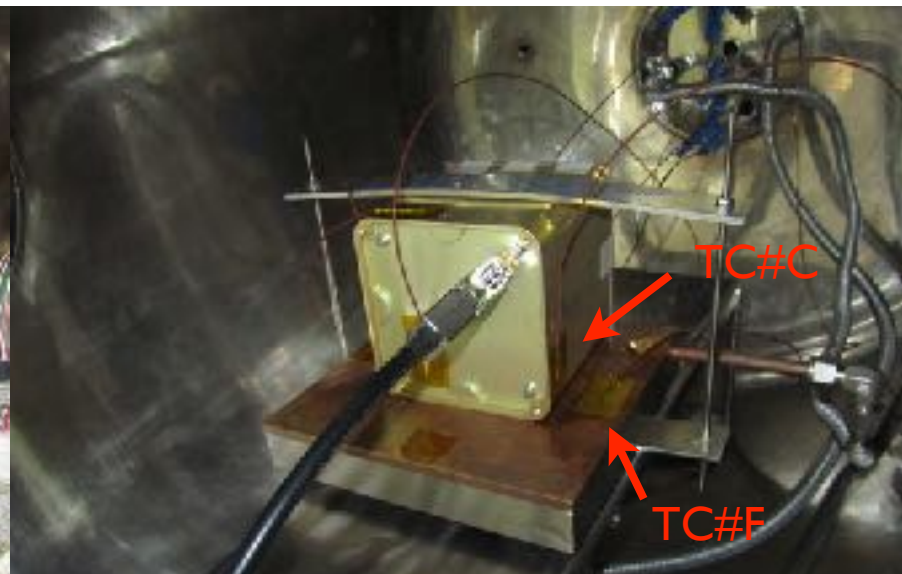
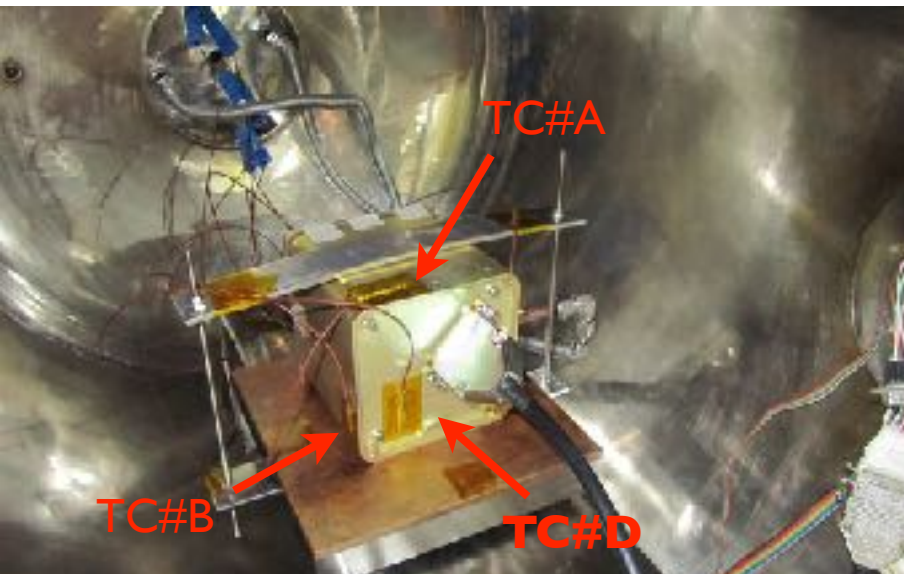
Z-axis



Shock test for SPEU

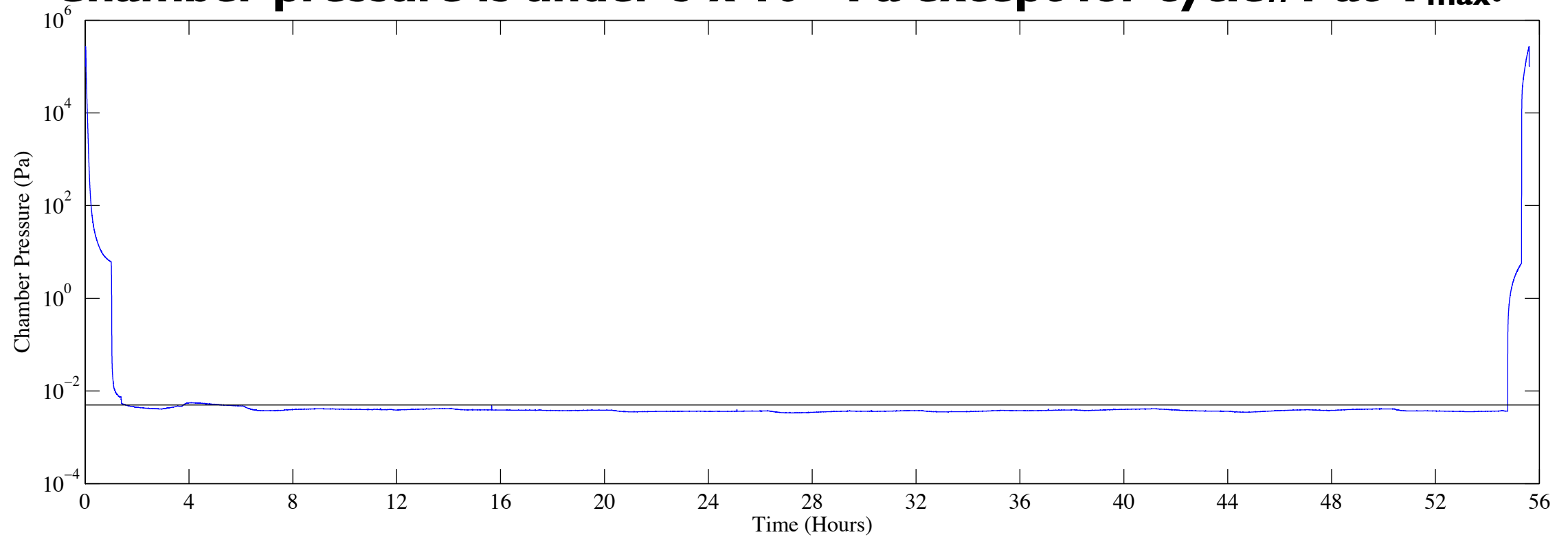


Thermal vacuum test

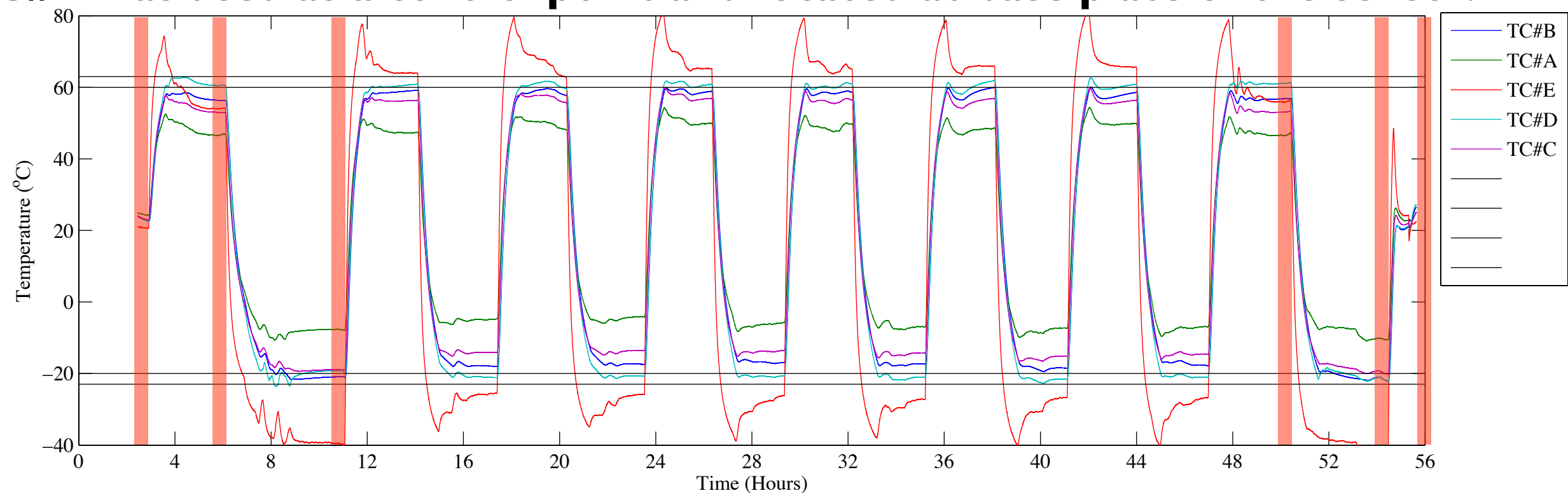


TVT for sensor

Chamber pressure is under 5×10^{-3} Pa except for cycle#1 at $T_{\max}$.

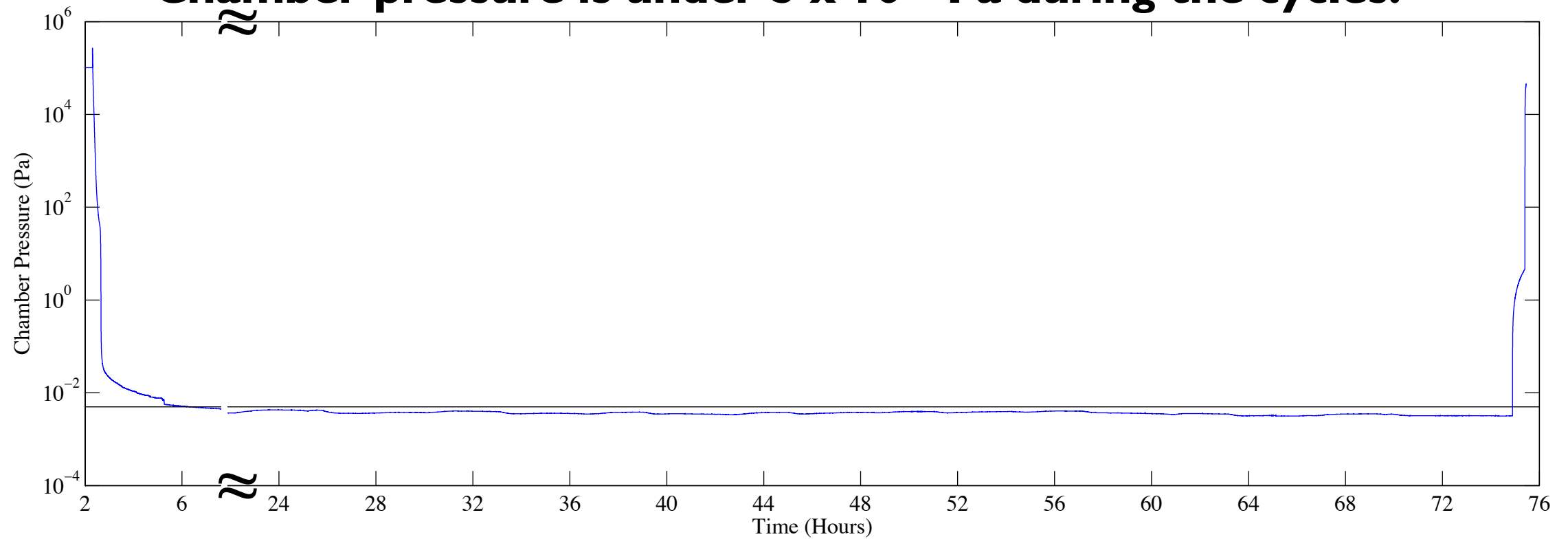


TC#D was used as a control point and located at base plate of the sensor.

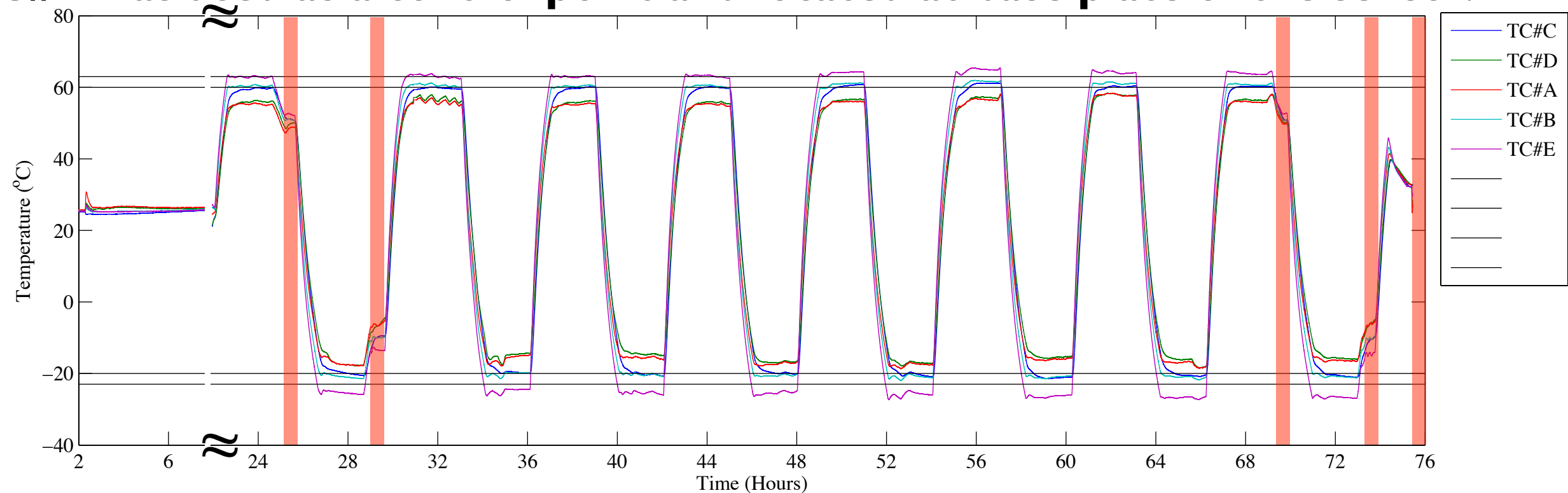


TVT for SPEU

Chamber pressure is under 5×10^{-3} Pa during the cycles.

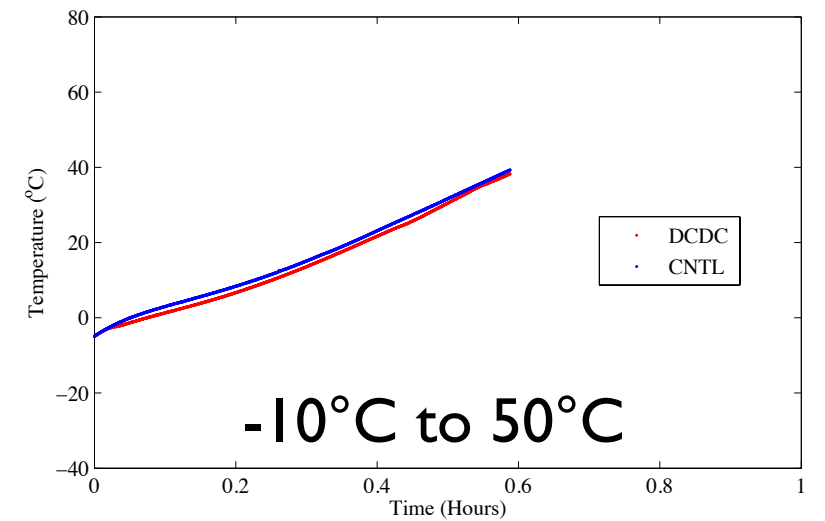
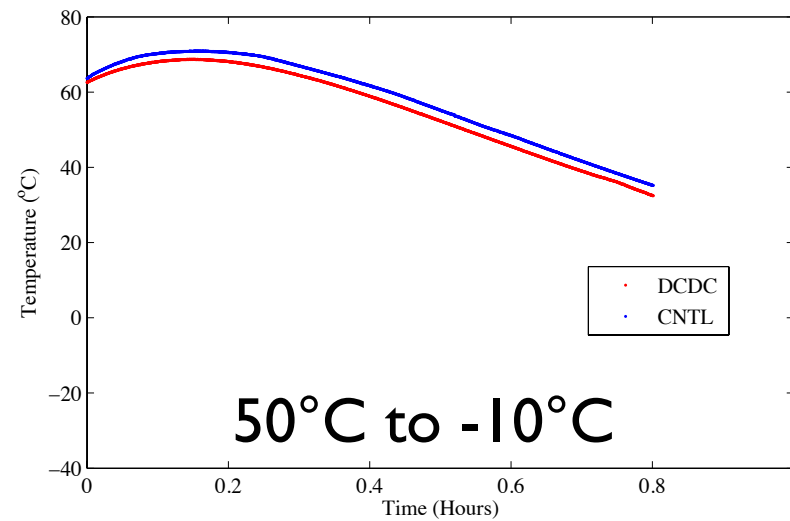
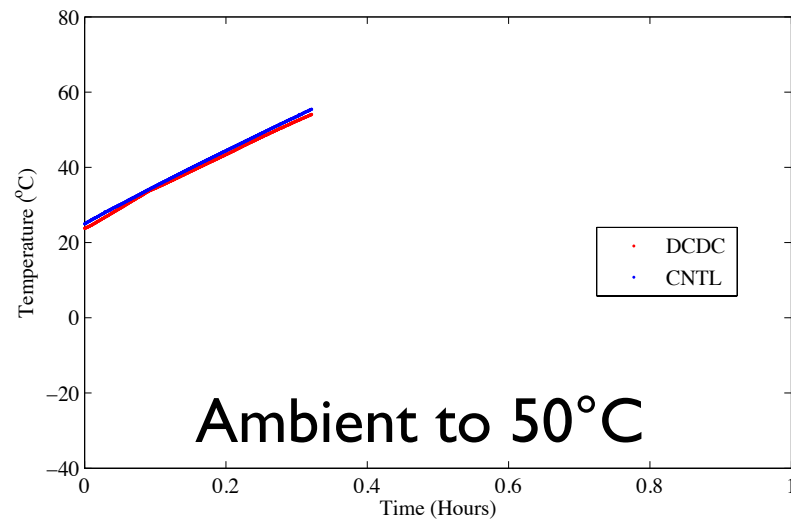


TC#B was used as a control point and located at base plate of the sensor.

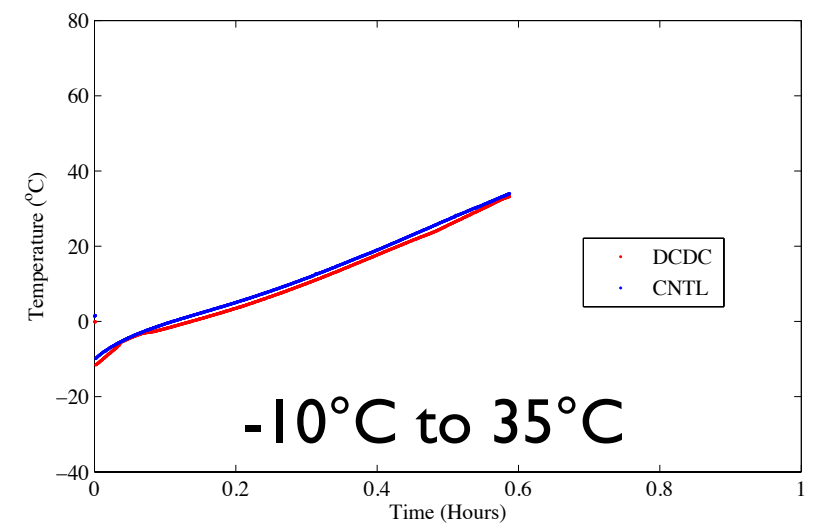
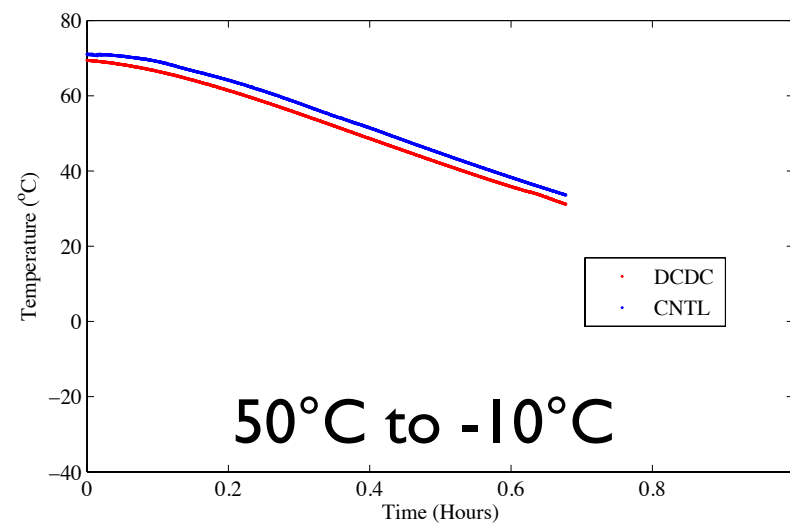
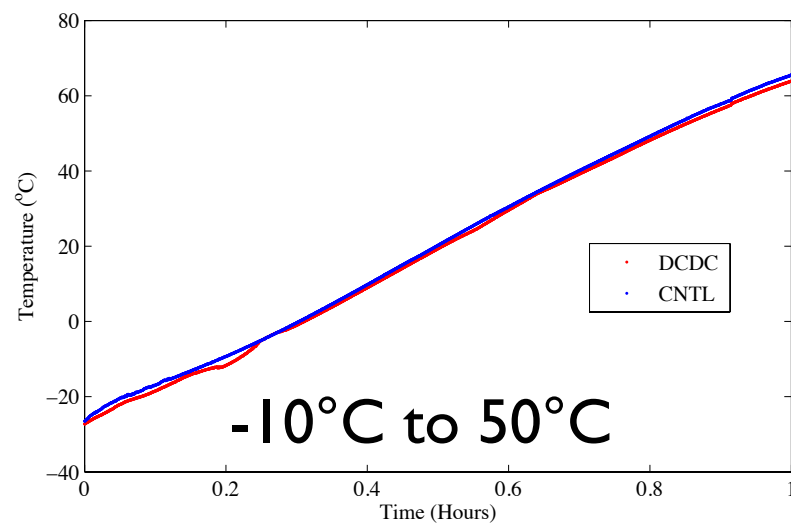


Temperature at SPEU's PCB

CYCLE#1

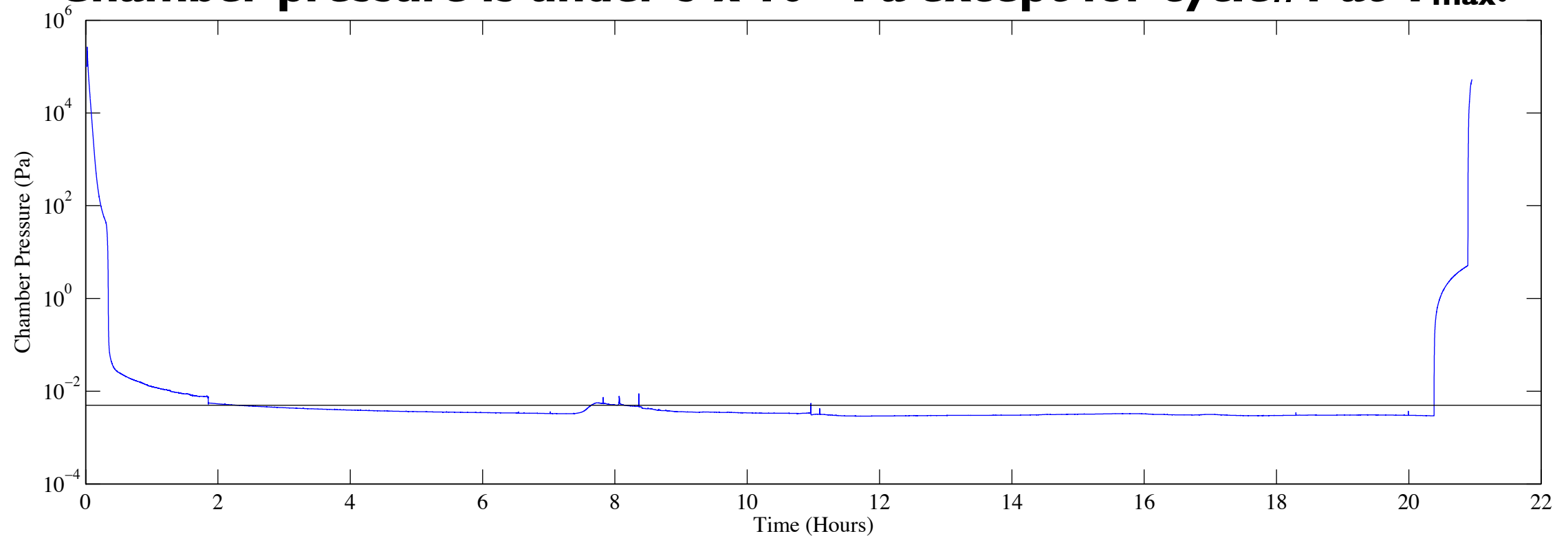


CYCLE#8

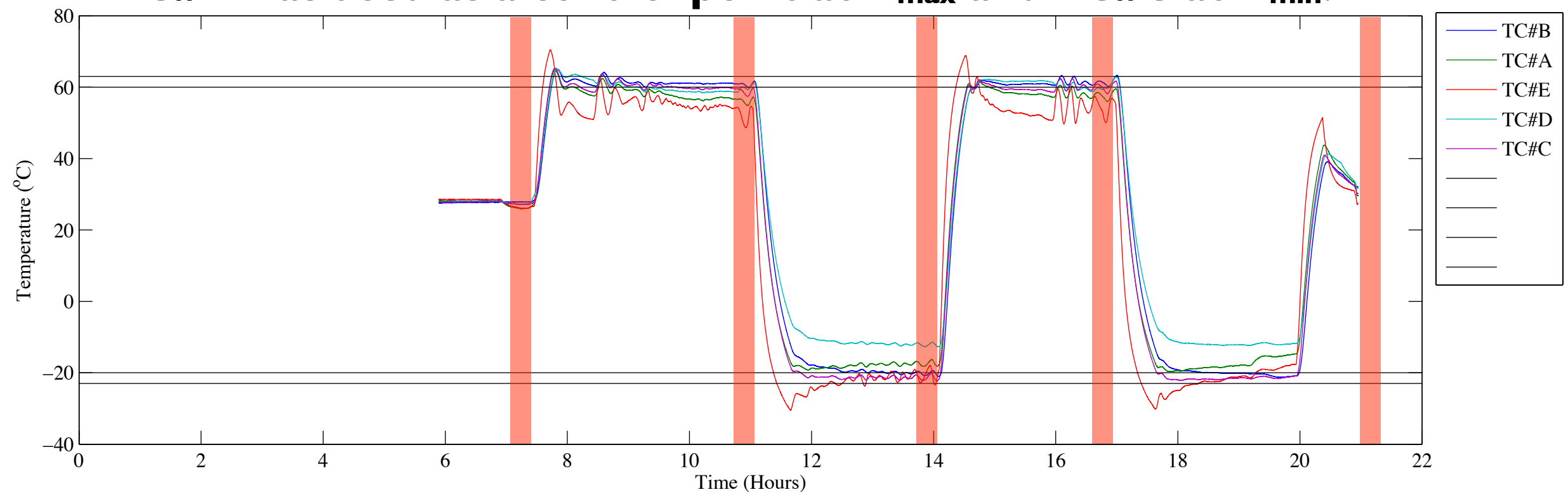


TVT for sensor with MLI

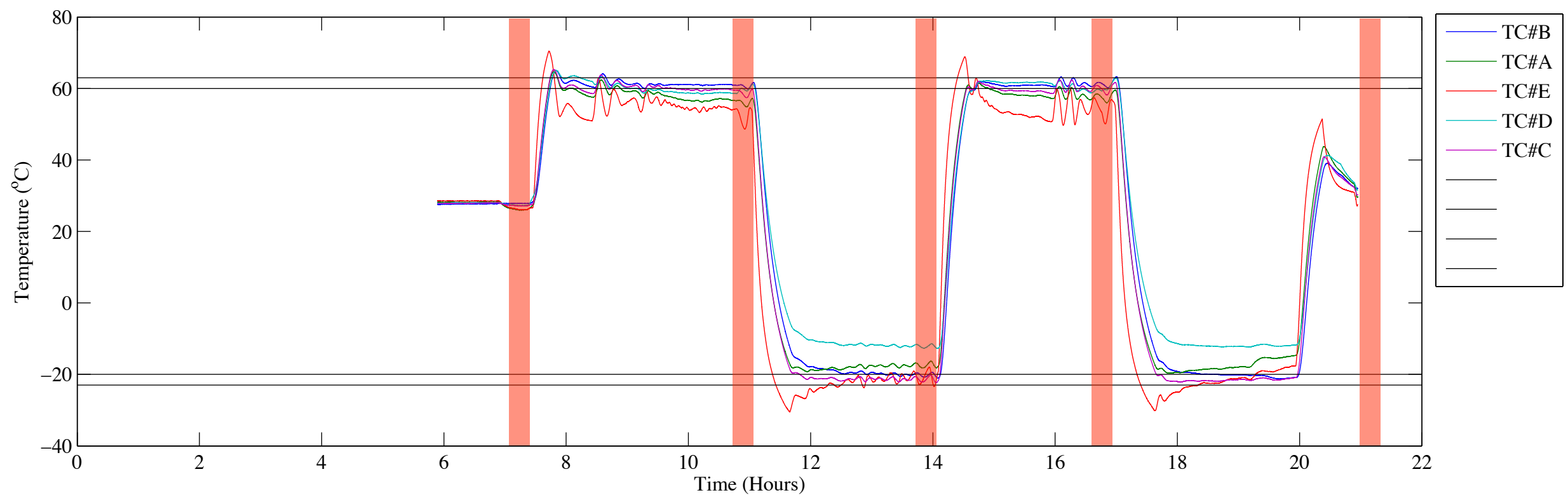
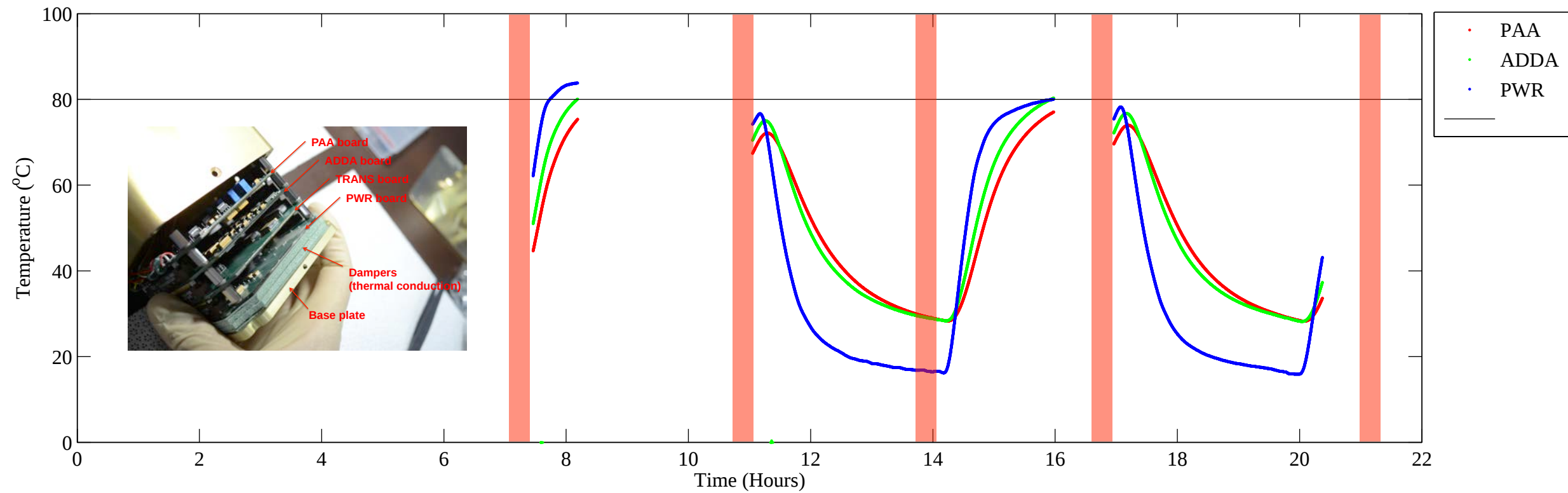
Chamber pressure is under 5×10^{-3} Pa except for cycle#1 at $T_{\max}$.



TC#B was used as a control point at $T_{\max}$ and TC#C at $T_{\min}$.



Temperature at sensor's PCB



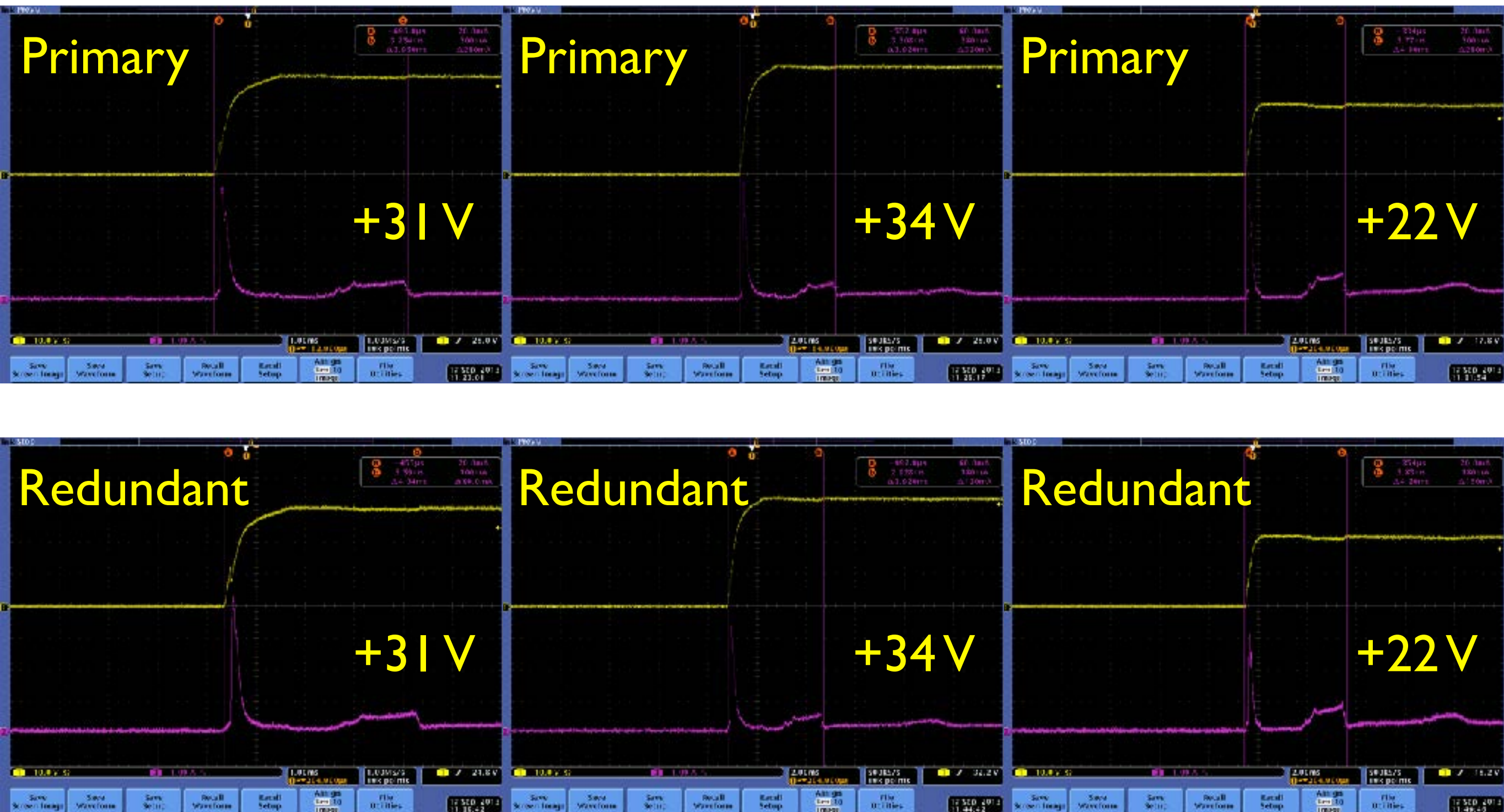
EMC test

- Conducted EMC
 - Grounding and isolation.
 - CE on transient voltage and in-rush current - time domain, on primary power lines - frequency domain, and on signal lines - time domain.
 - CS on primary power lines - sine wave and spike injection.
- Radiated EMC
 - RE - 14 KHz to 10 GHz, GPS receiver, S band receiver, and launcher receiver.
 - RS - 200 MHz to 10 GHz, local E-field by bus antennas, and launcher environment (under a conclusion of TRR meeting on EMC, 14 KHz to 200 MHz could be performed after an amplifier for this radio band returns to NSPO).

Grounding and isolation

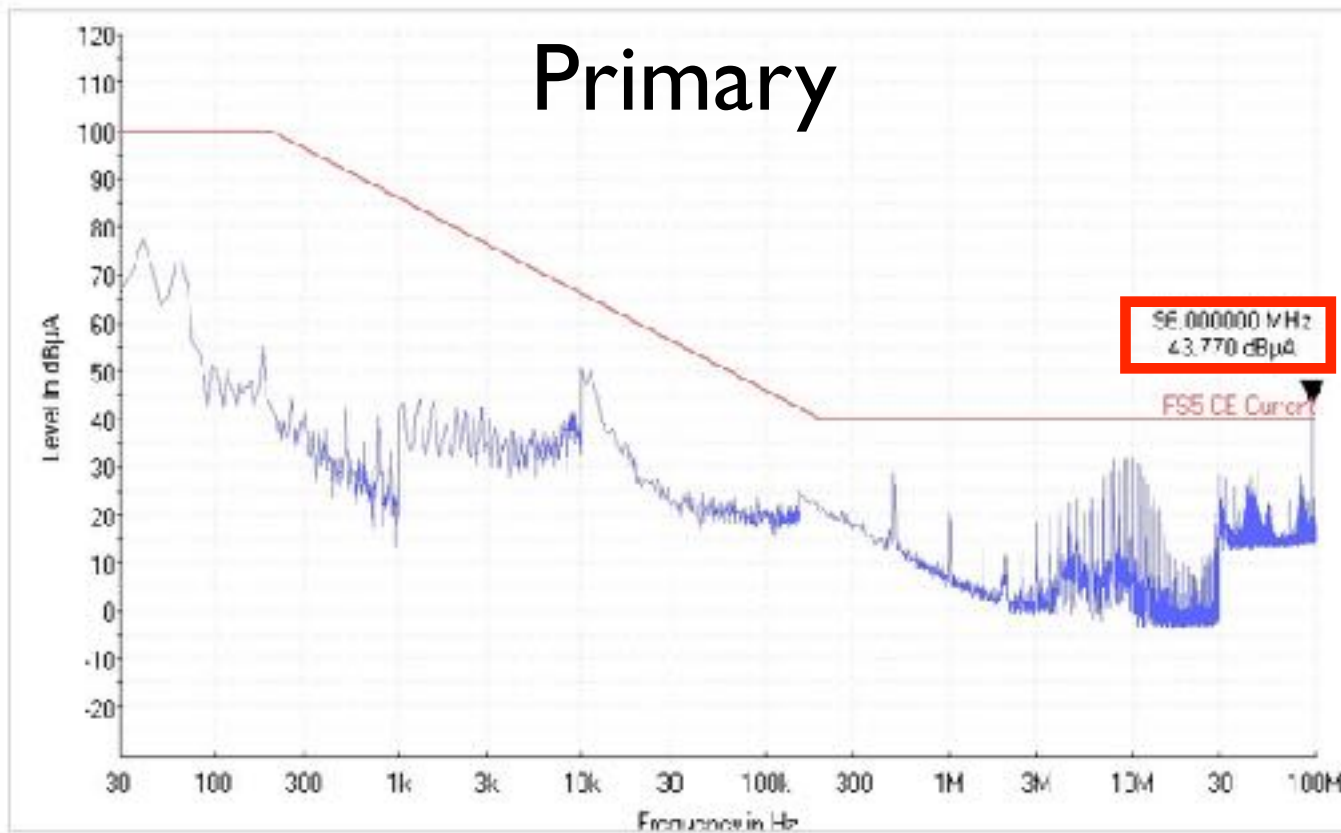
Resistance	Requirement	Measurement
Resistance between SPEU chassis and the test bench	$< 100 \text{ m}\Omega$	6.8 m Ω
Resistance between SPEU chassis and secondary ground	$\leq 100 \text{ m}\Omega$	ND
Resistance between SPEU chassis and primary power +28 V of primary controller	$> 1 \text{ M}\Omega$	OL
Resistance between SPEU chassis and primary power +28 V of redundant controller	$> 1 \text{ M}\Omega$	OL
Resistance between SPEU chassis and primary power ground of primary controller	$> 1 \text{ M}\Omega$	OL
Resistance between SPEU chassis and primary power ground of redundant controller	$> 1 \text{ M}\Omega$	OL
Resistance between primary power +28 V of primary controller and the secondary power +15 V	$> 1 \text{ M}\Omega$	OL
Resistance between primary power +28 V of redundant controller and the secondary power +15 V	$> 1 \text{ M}\Omega$	OL
Resistance between primary power ground of primary controller and the secondary power +15 V	$> 1 \text{ M}\Omega$	OL
Resistance between primary power ground of redundant controller and the secondary power +15 V	$> 1 \text{ M}\Omega$	OL

CE on transient voltage and in-rush current - time domain

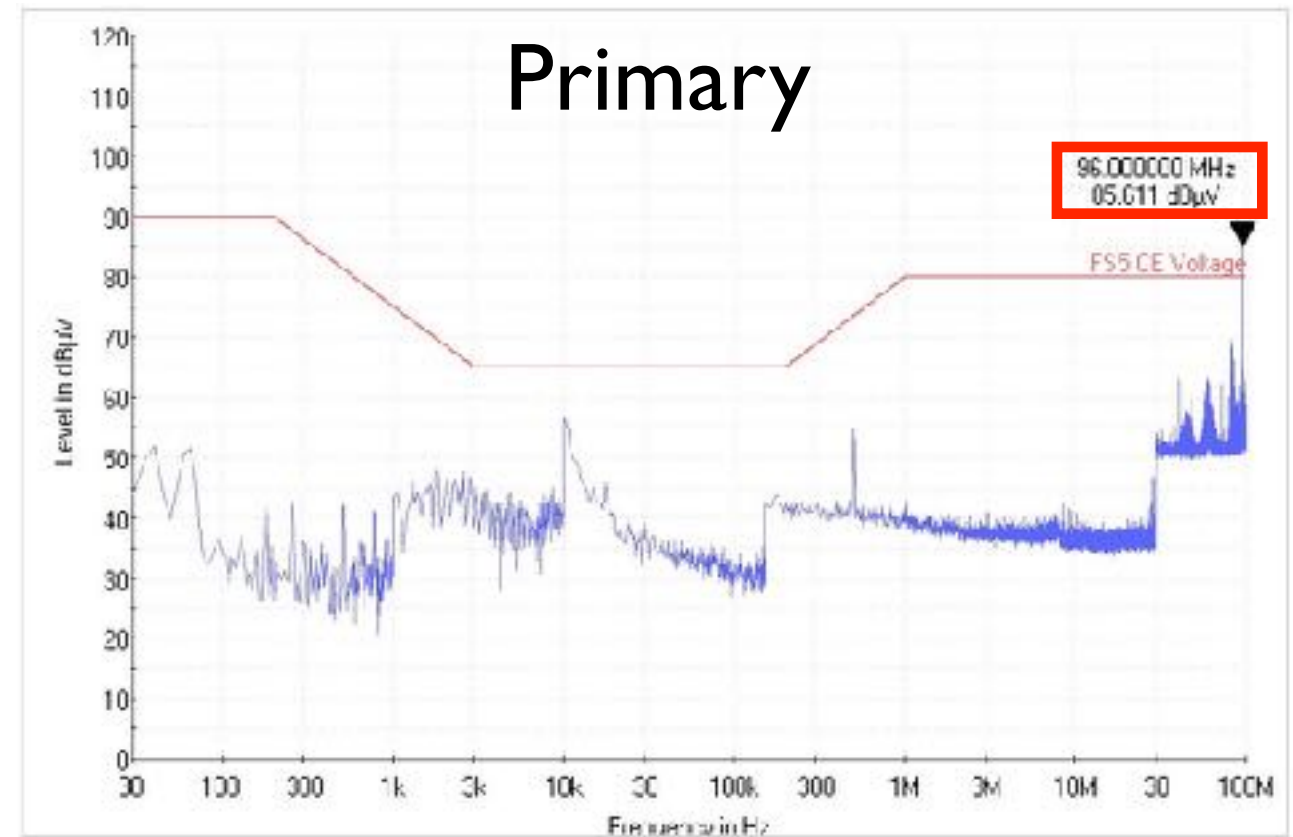


CE on primary power lines - frequency domain

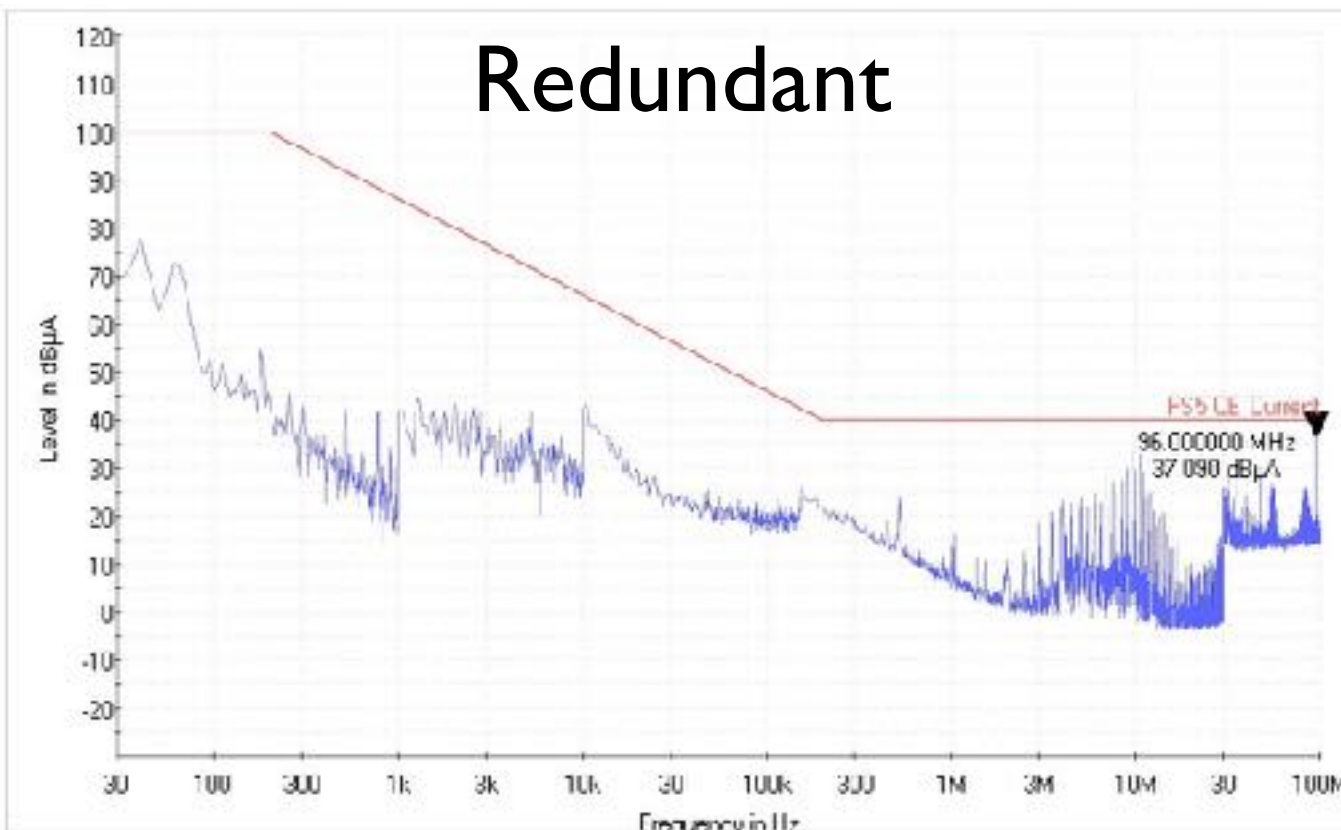
Primary



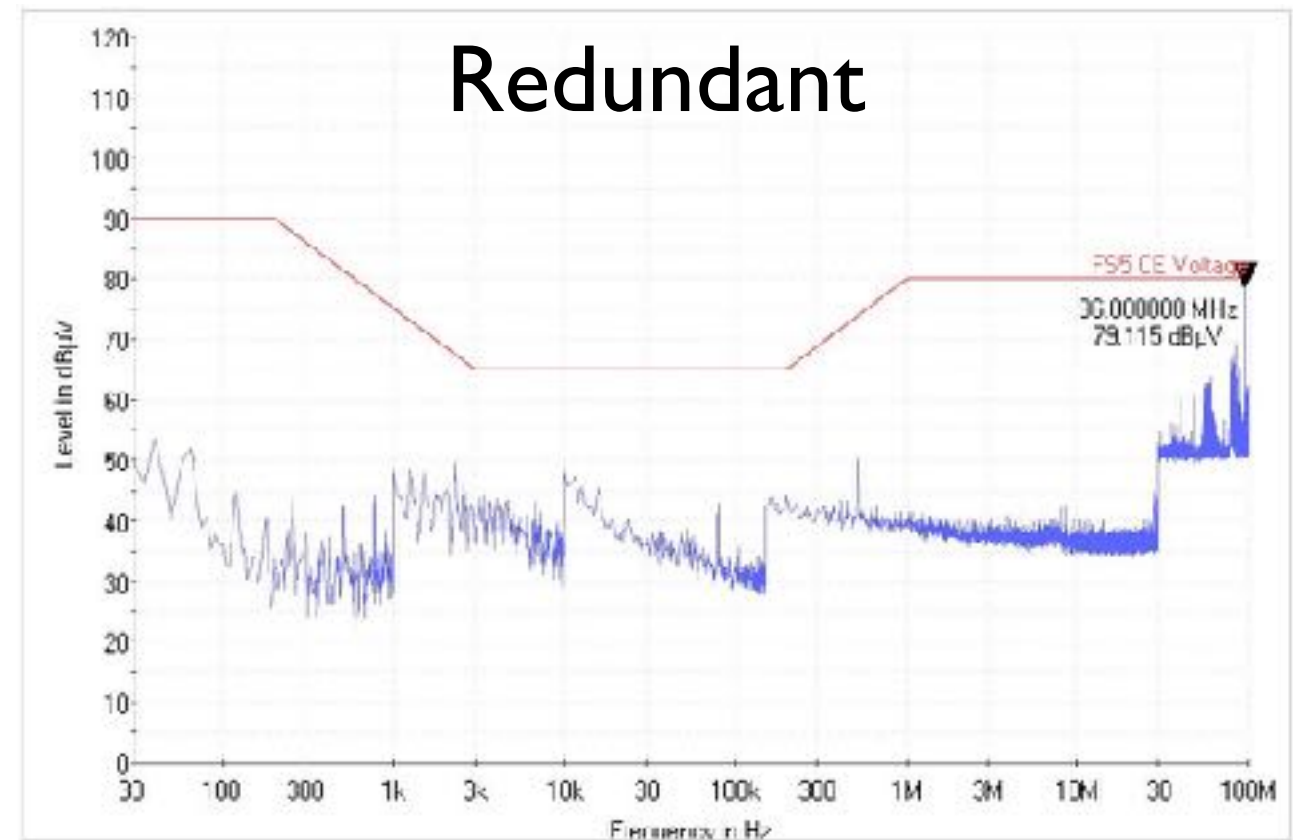
Primary



Redundant

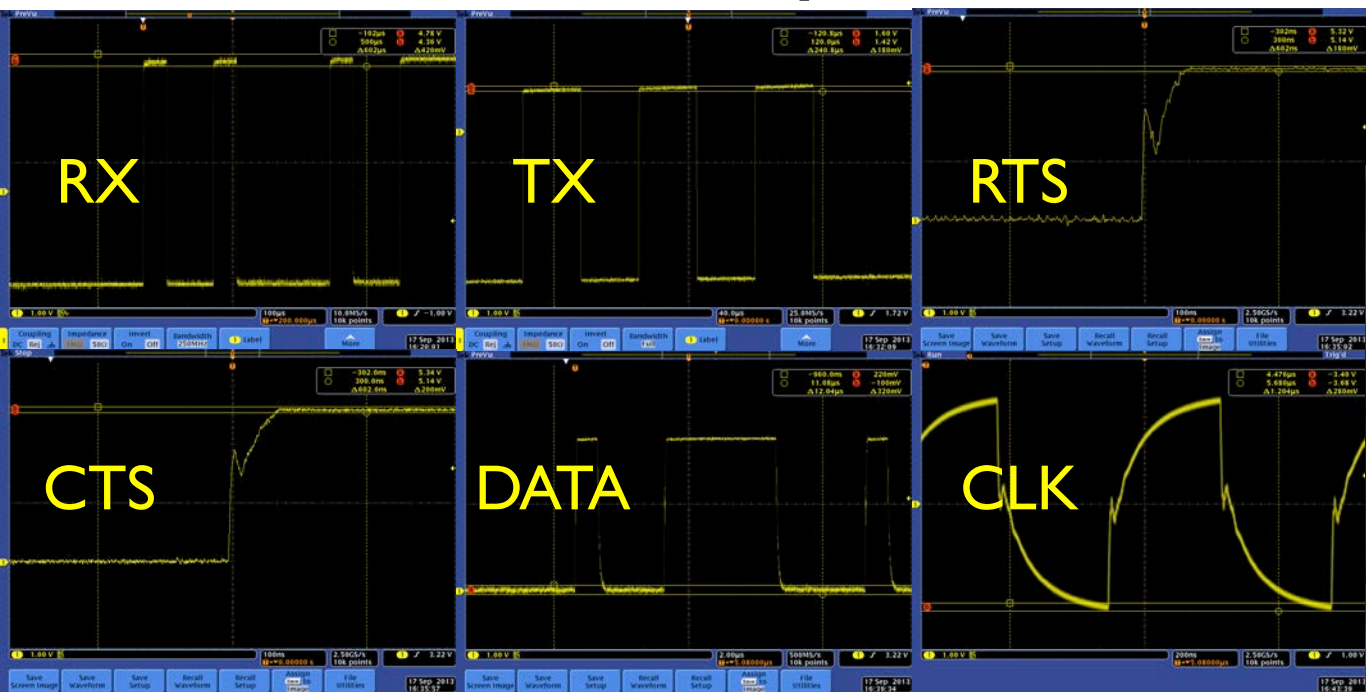


Redundant

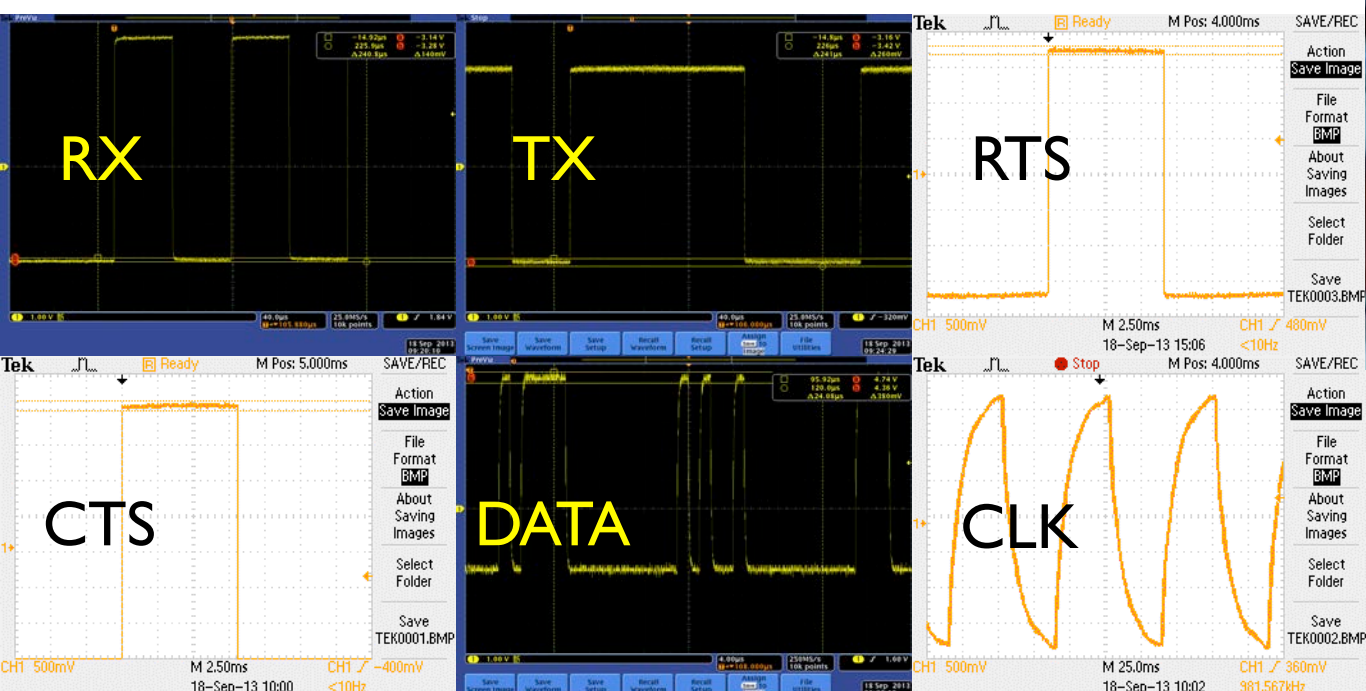


CE on signal lines - time domain

Primary

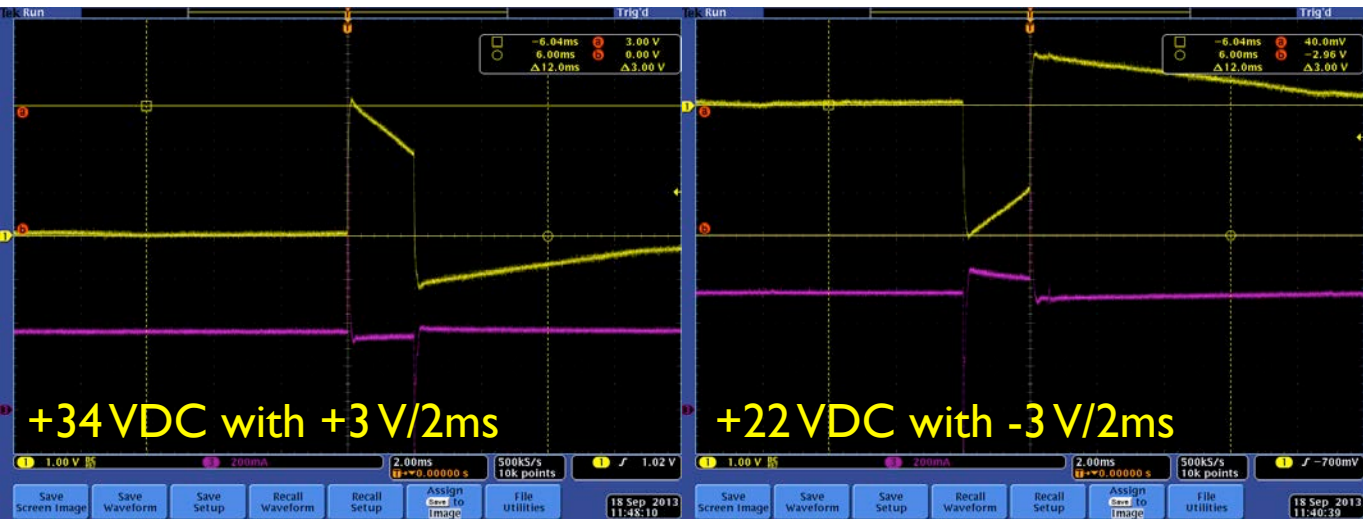


Redundant

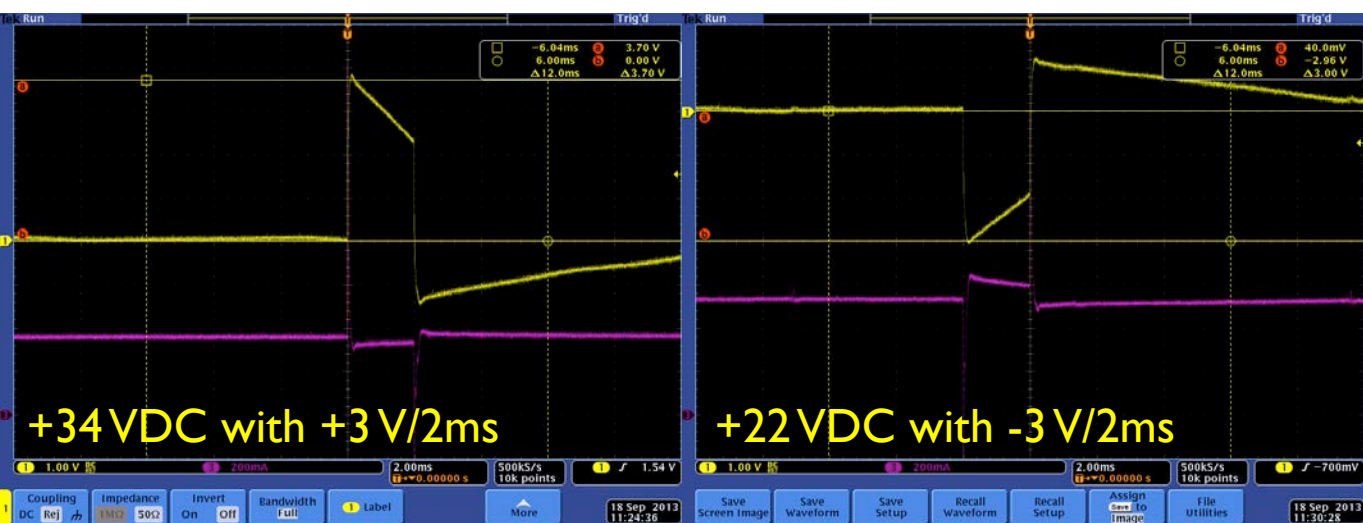


CS on primary power lines - sine wave and spike injection

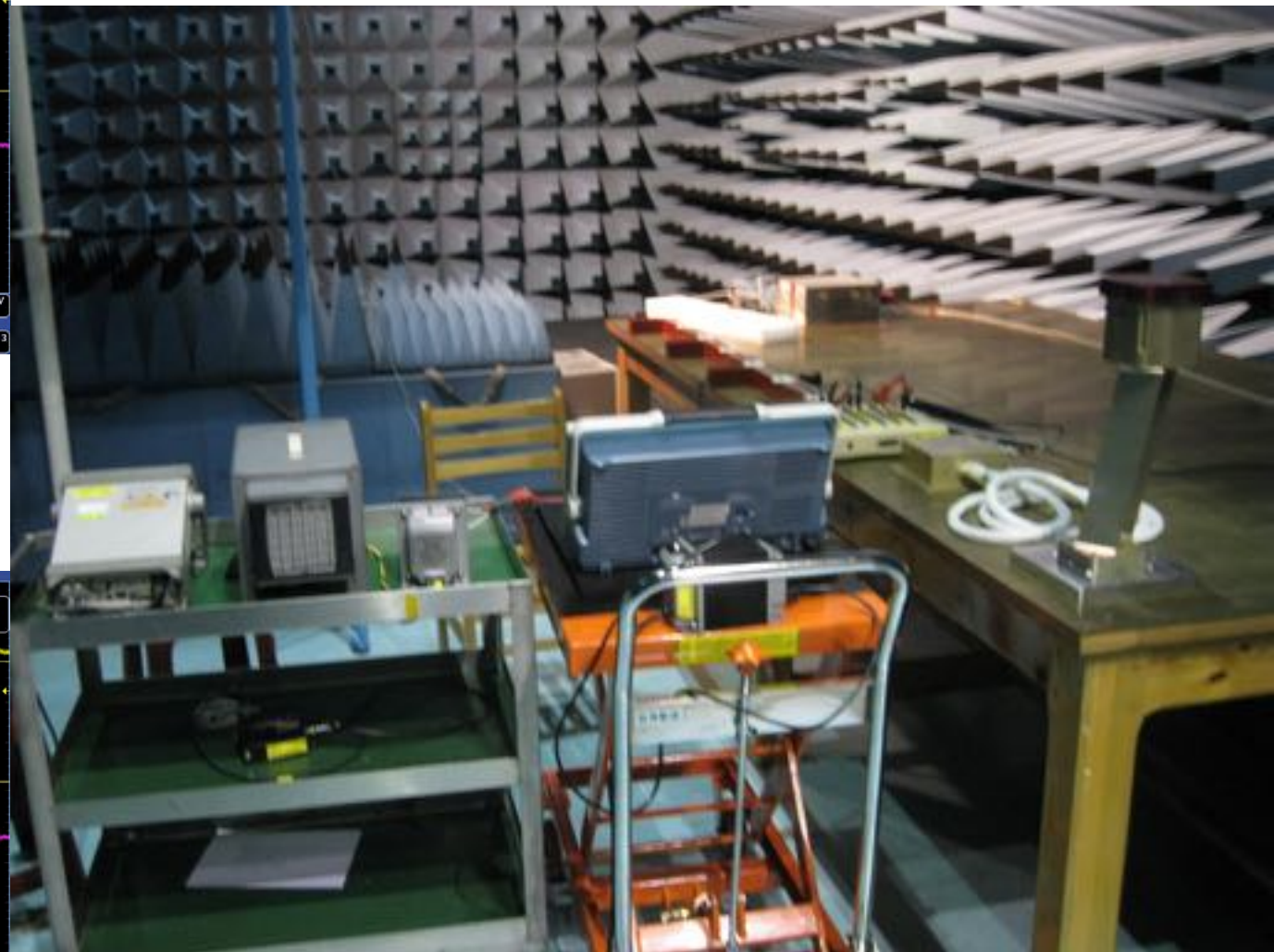
Primary



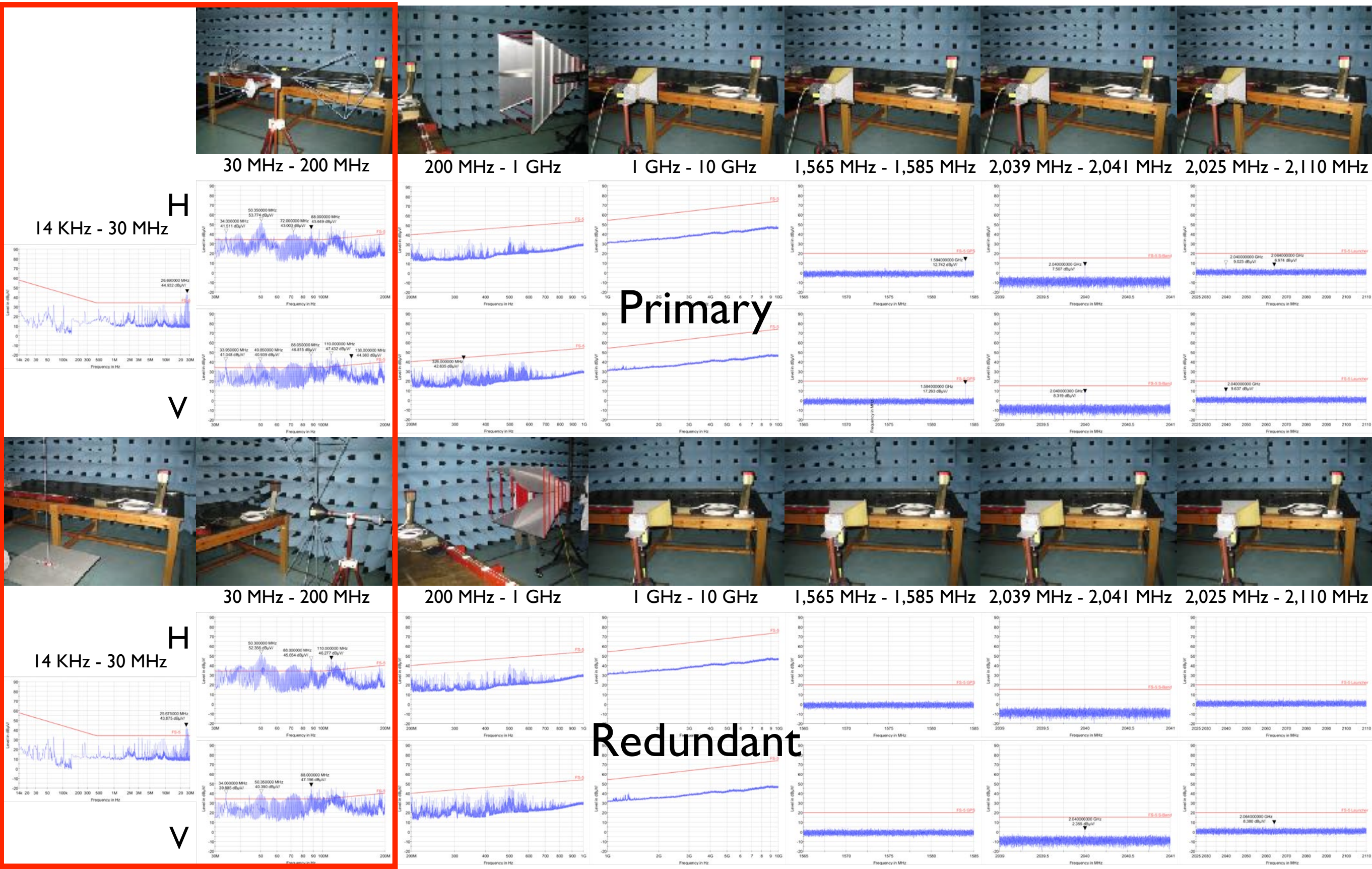
Redundant



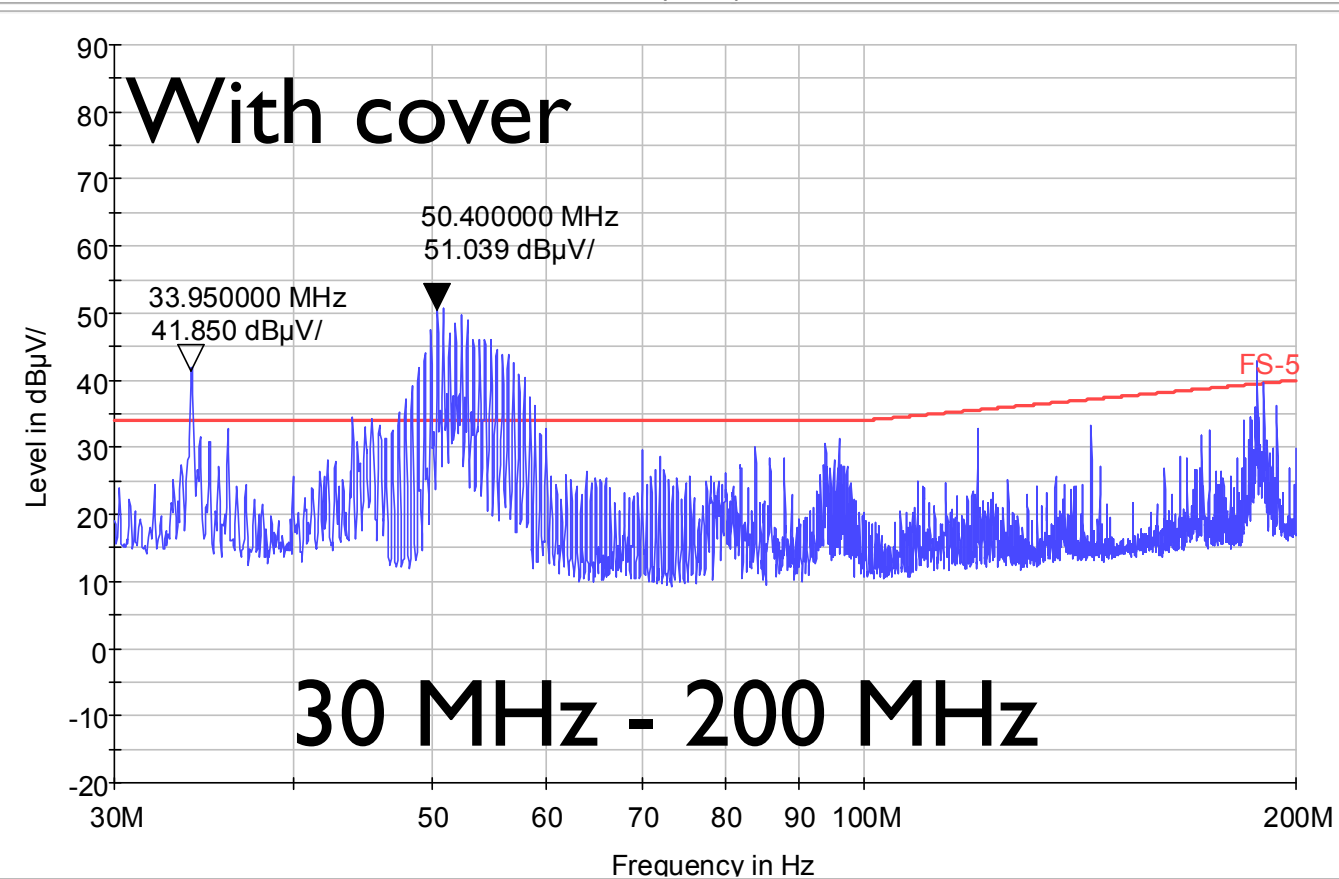
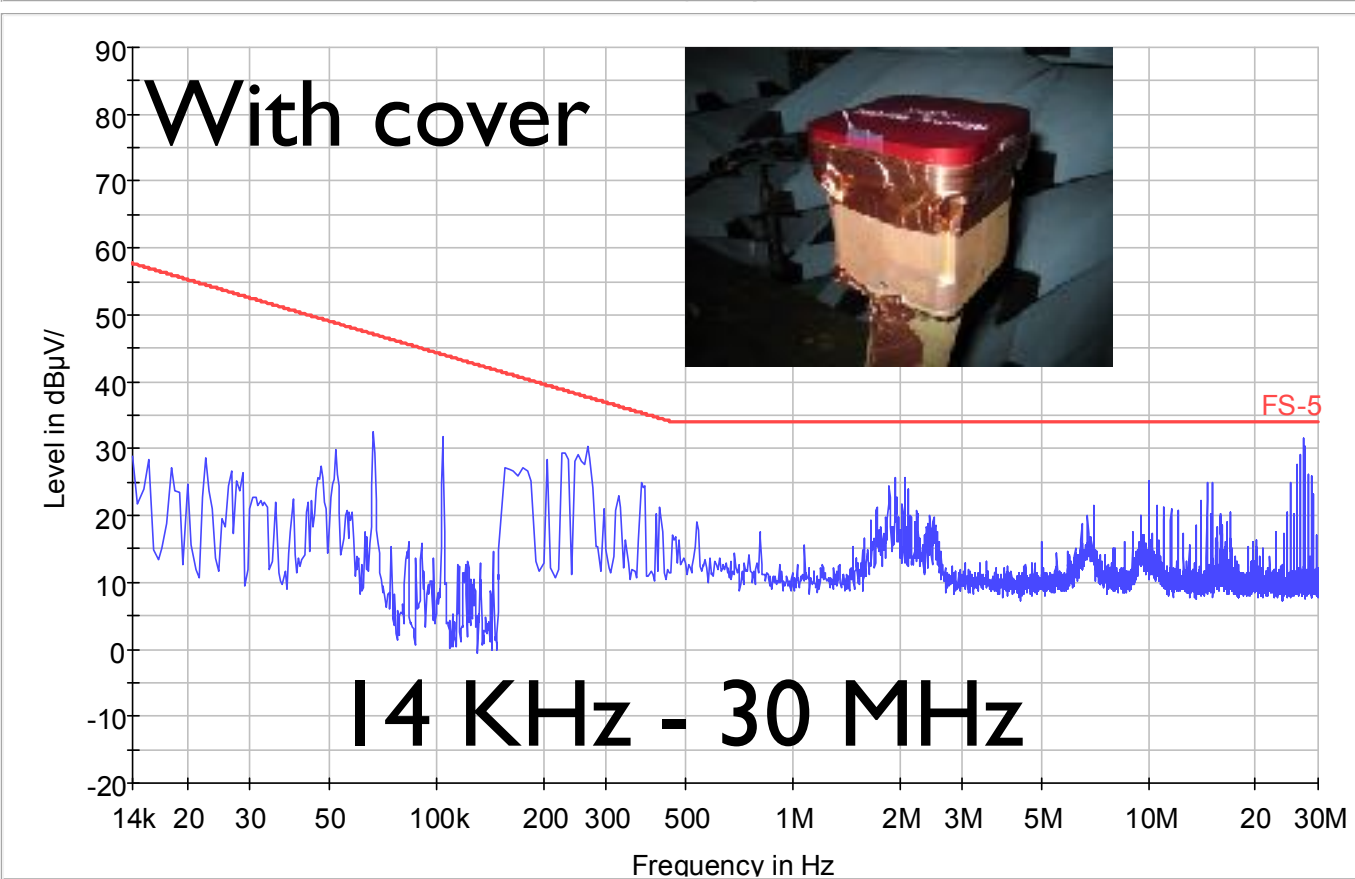
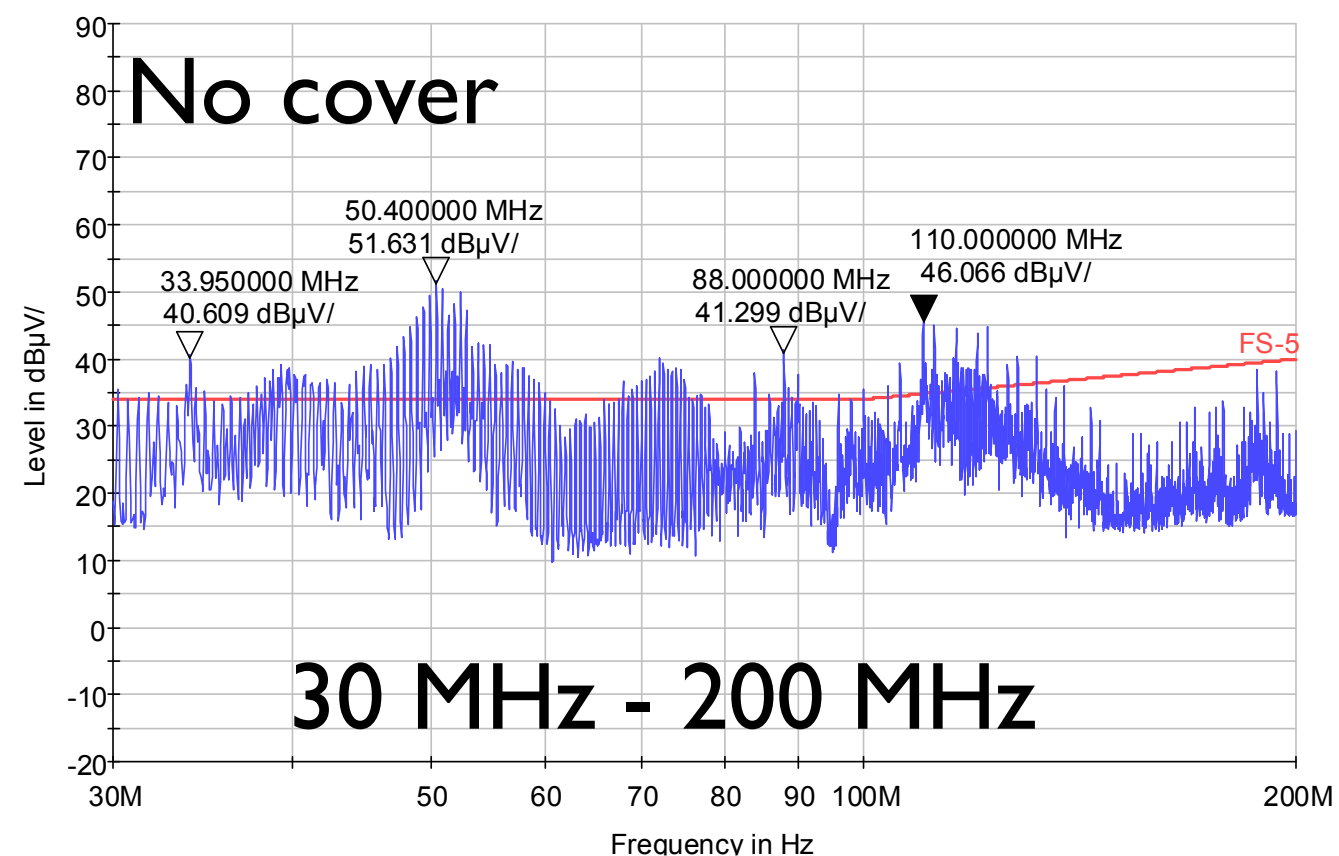
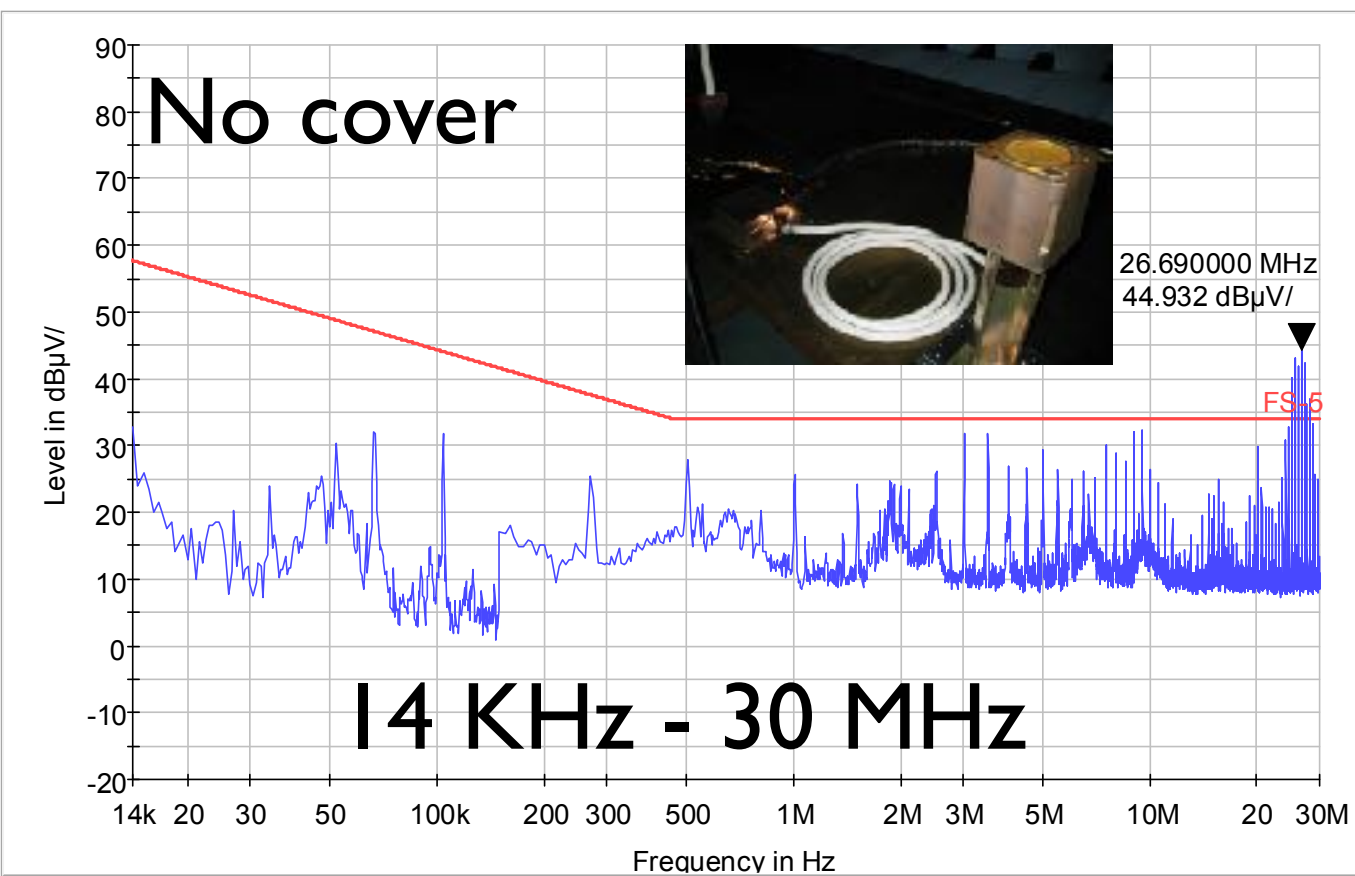
Spike injection



RE (14 KHz to 10 GHz)



With or without cover on sensor



RS (200 MHz to 10 GHz)



200 MHz - 1 GHz

1 GHz - 2 GHz

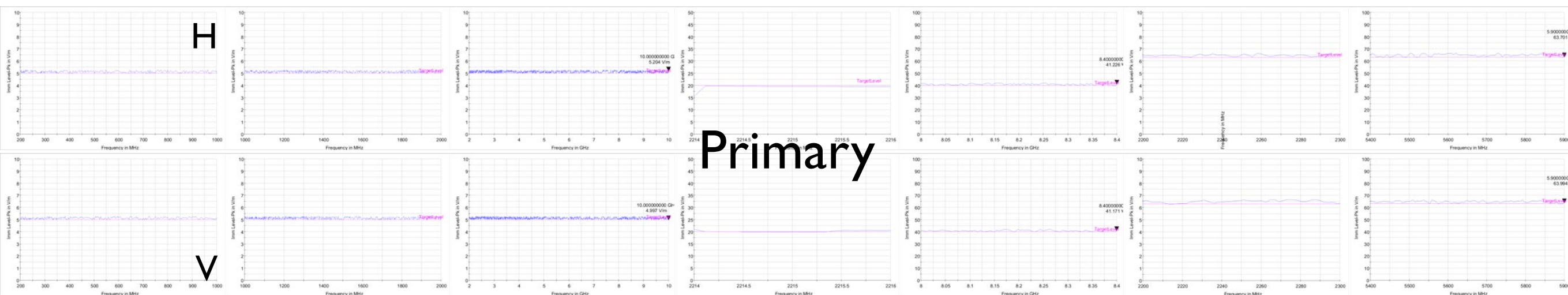
2 GHz - 10 GHz

2,214 MHz - 2,216 MHz

8.0 GHz - 8.4 GHz

2,200 MHz - 2,300 MHz

5,400 MHz - 5,900 MHz



Primary



200 MHz - 1 GHz

1 GHz - 2 GHz

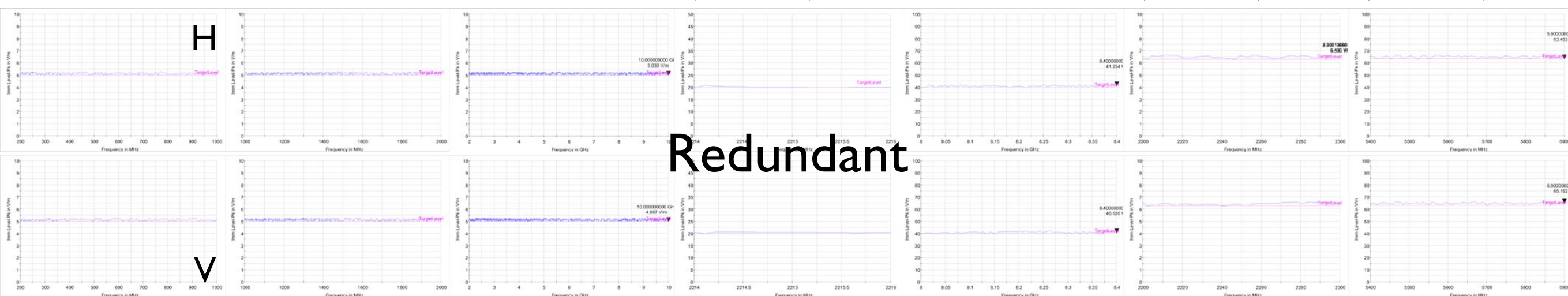
2 GHz - 10 GHz

2,214 MHz - 2,216 MHz

8.0 GHz - 8.4 GHz

2,200 MHz - 2,300 MHz

5,400 MHz - 5,900 MHz



Redundant

Burn-in test

	Sensor	Primary controller	Redundant controller
Fabrication and programming	40 hours	120 hours	40 hours
Functional tests	11 hours	6 hours	4 hours
Environmental tests	60 hours	26 hours	22 hours
Burn-in test	200 hours	149 hours	51 hours
Summation	311 (≥ 300) hours	301 (≥ 300) hours	117 (≥ 100) hours



SR-IX flight test

- Space Plasma Sensor Package (**SPSP**)
- Plasma Impedance Analyzer (**PIA**)
- Plasma sensors (**PS**)
 - Retarding Potential Analyzer (**RPA**) from **AIP**
 - Ion Drift Meter (**IDM**) from **AIP**
 - Planar Langmuir Probe (**PLP**)



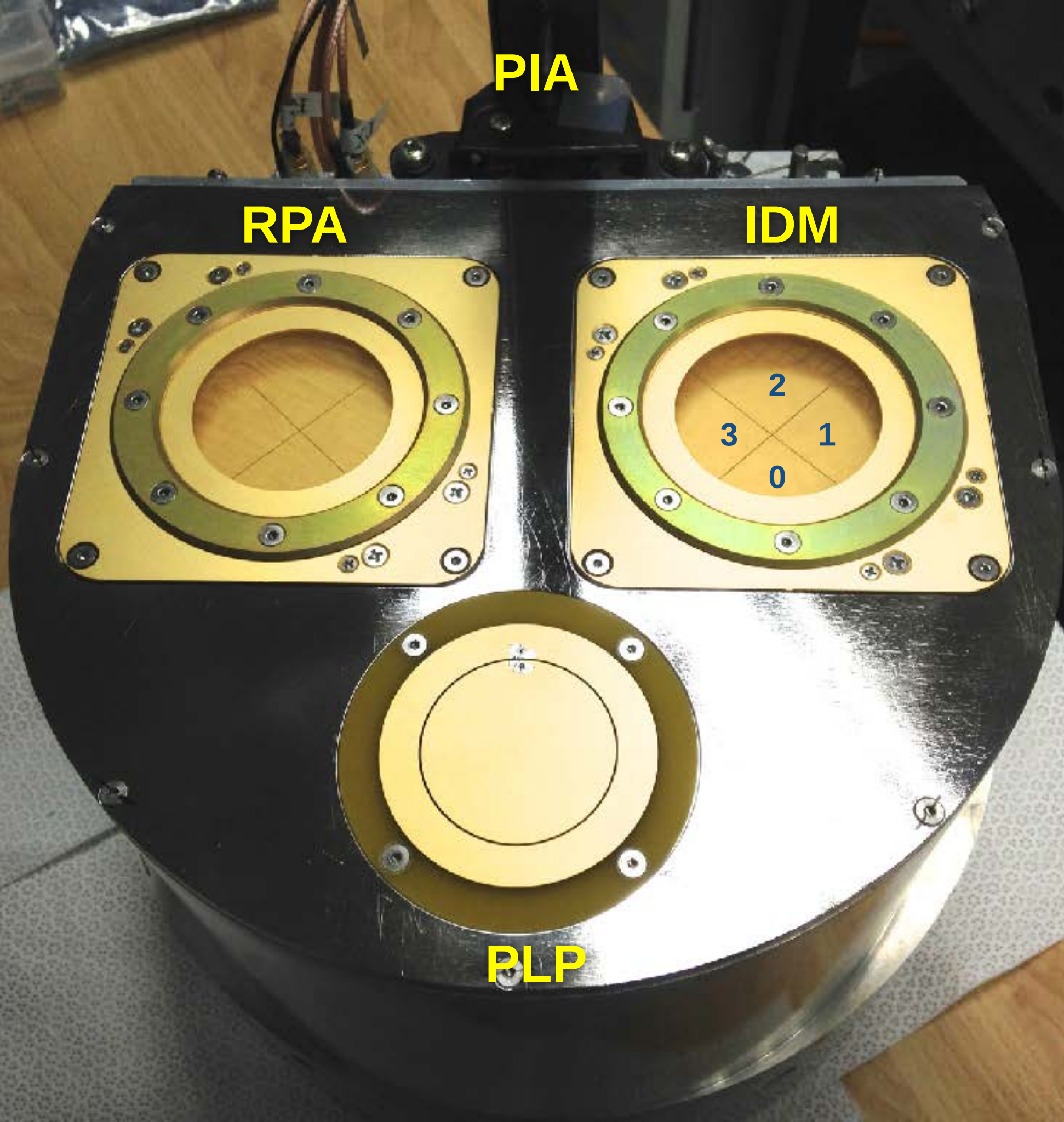
PIA

RPA

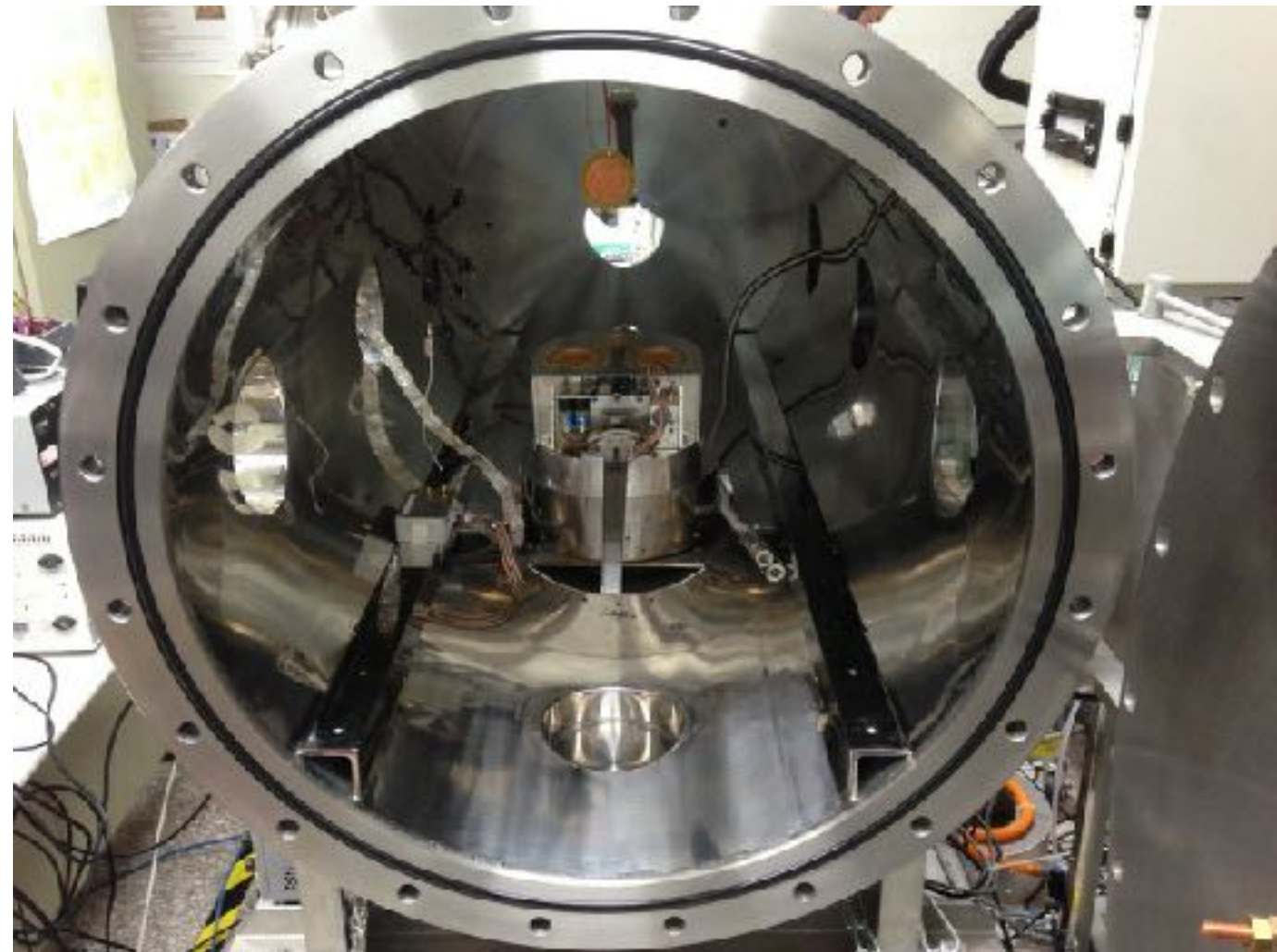
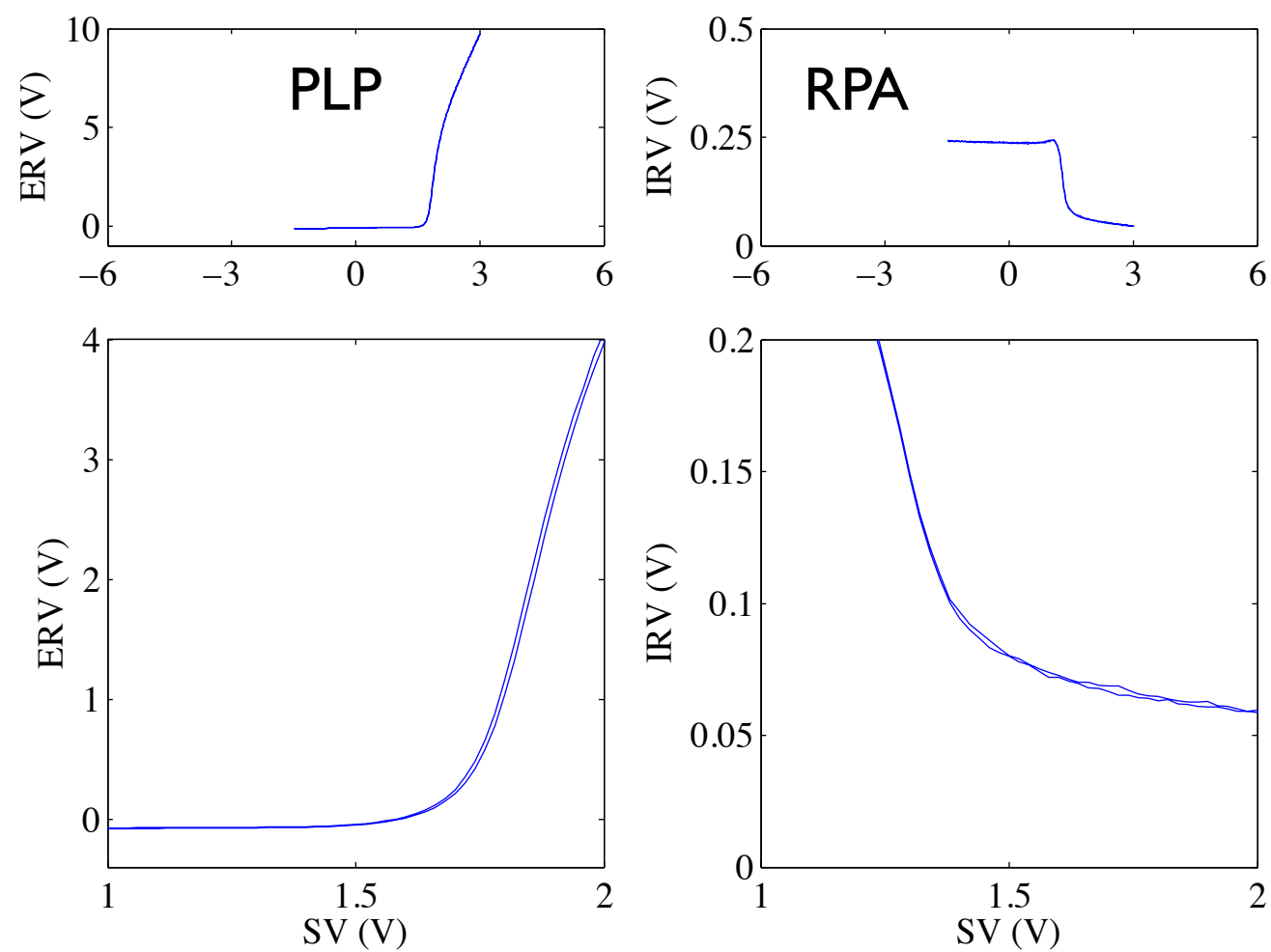
IDM

2
3 1
0

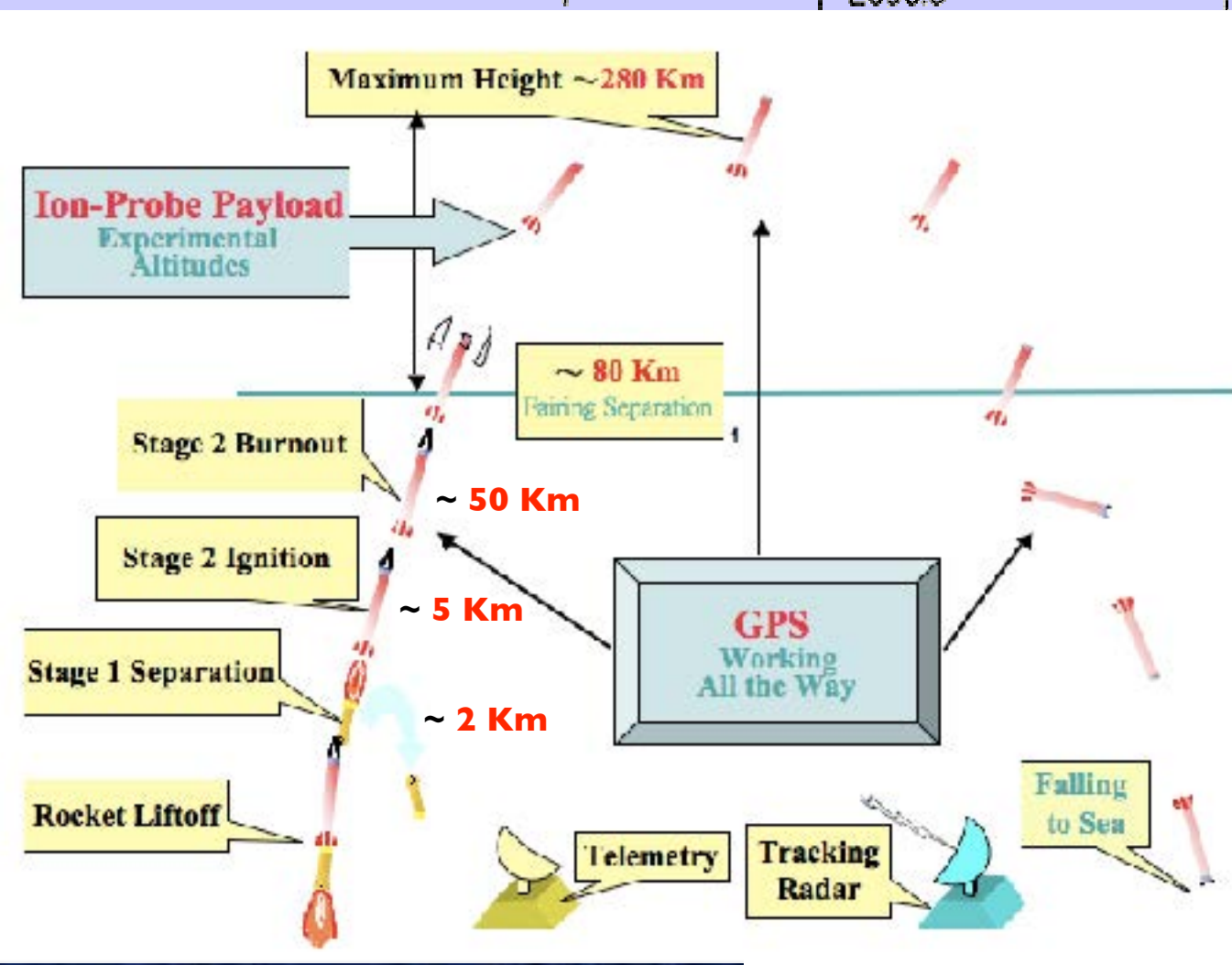
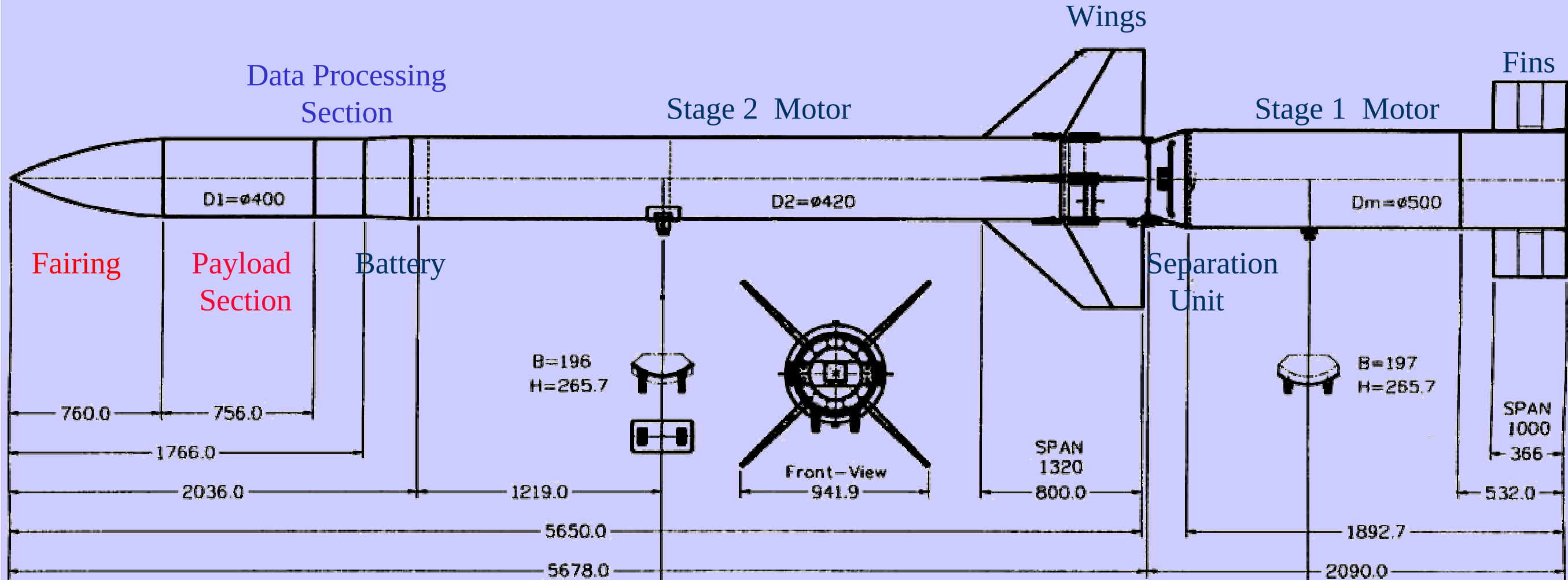
PLP

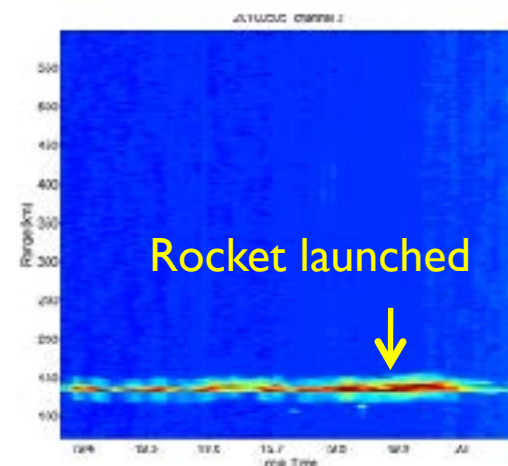
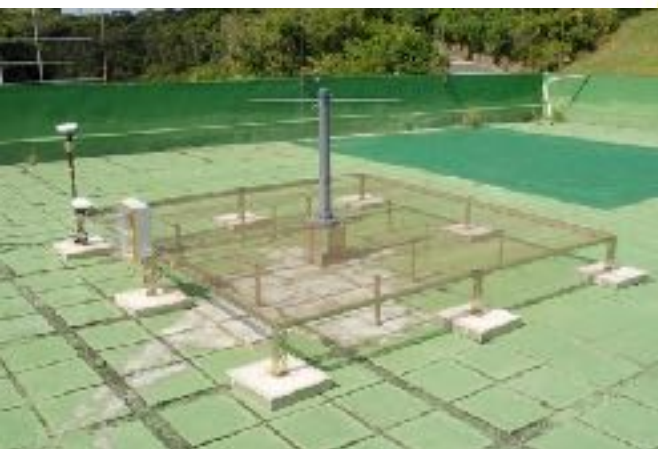


Plasma injection test in lab

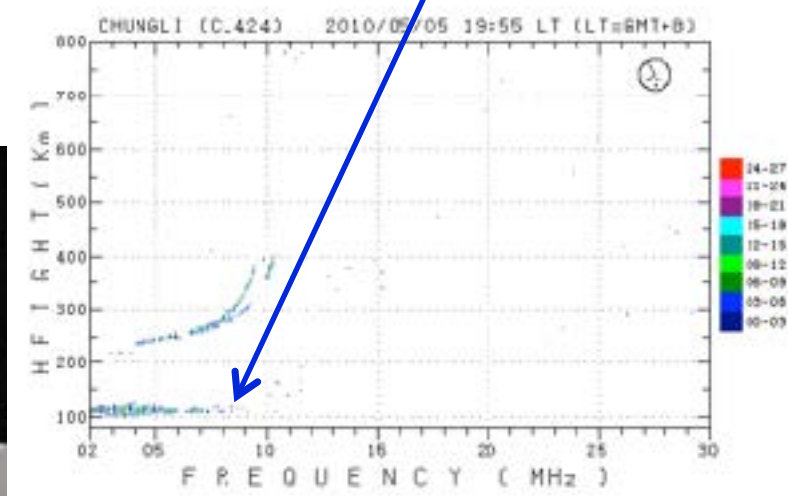
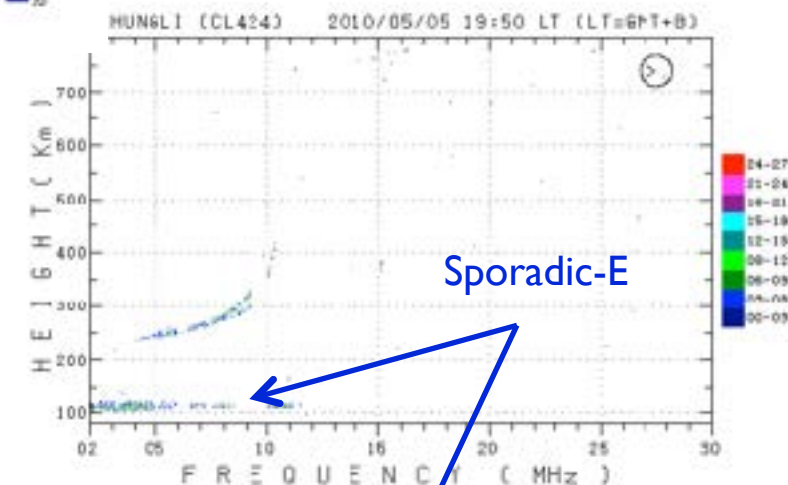


Space Plasma Simulation Chamber

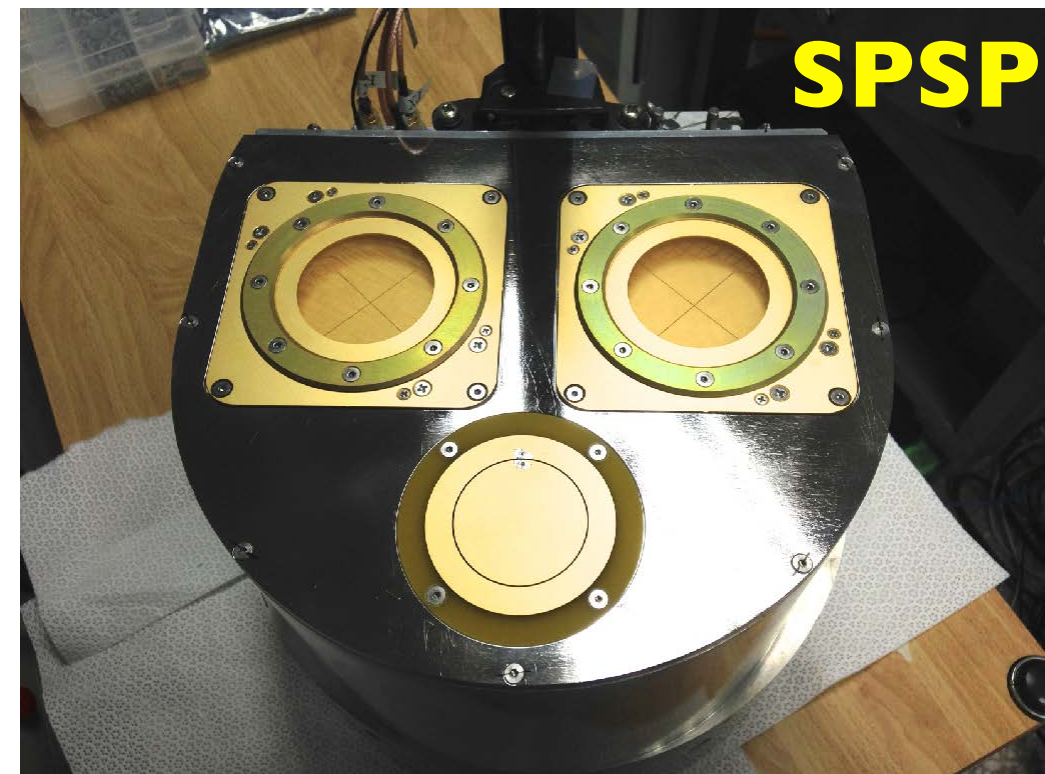
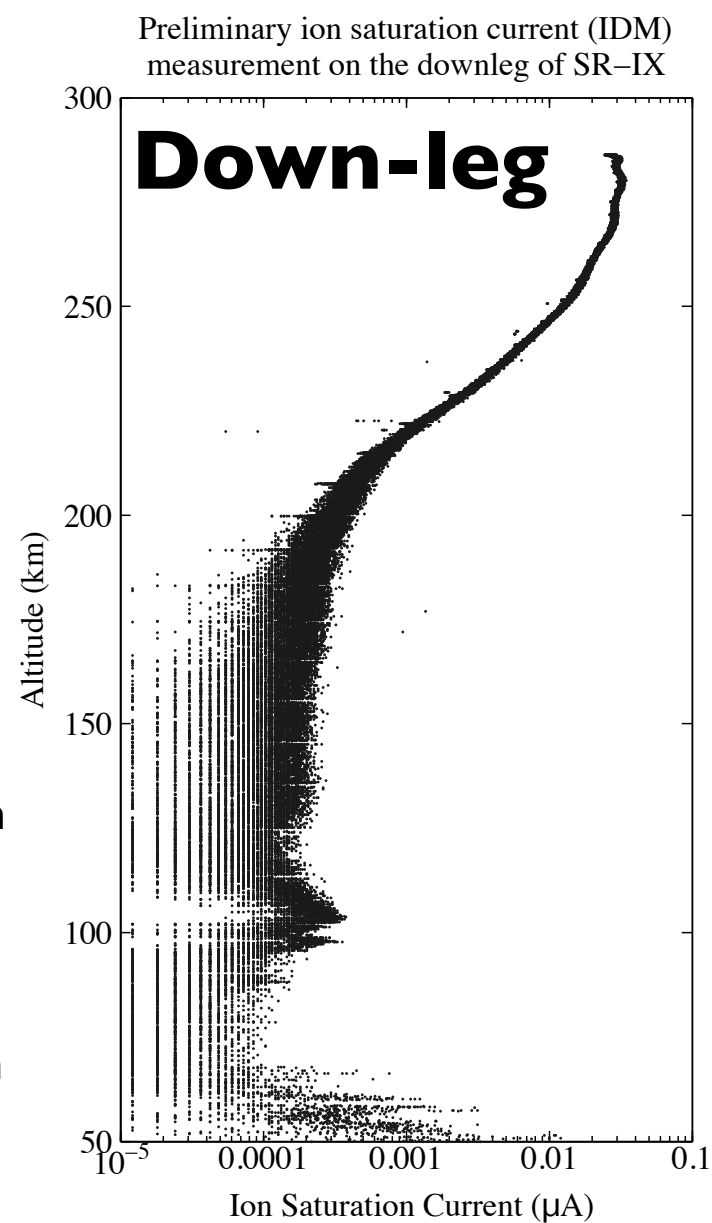
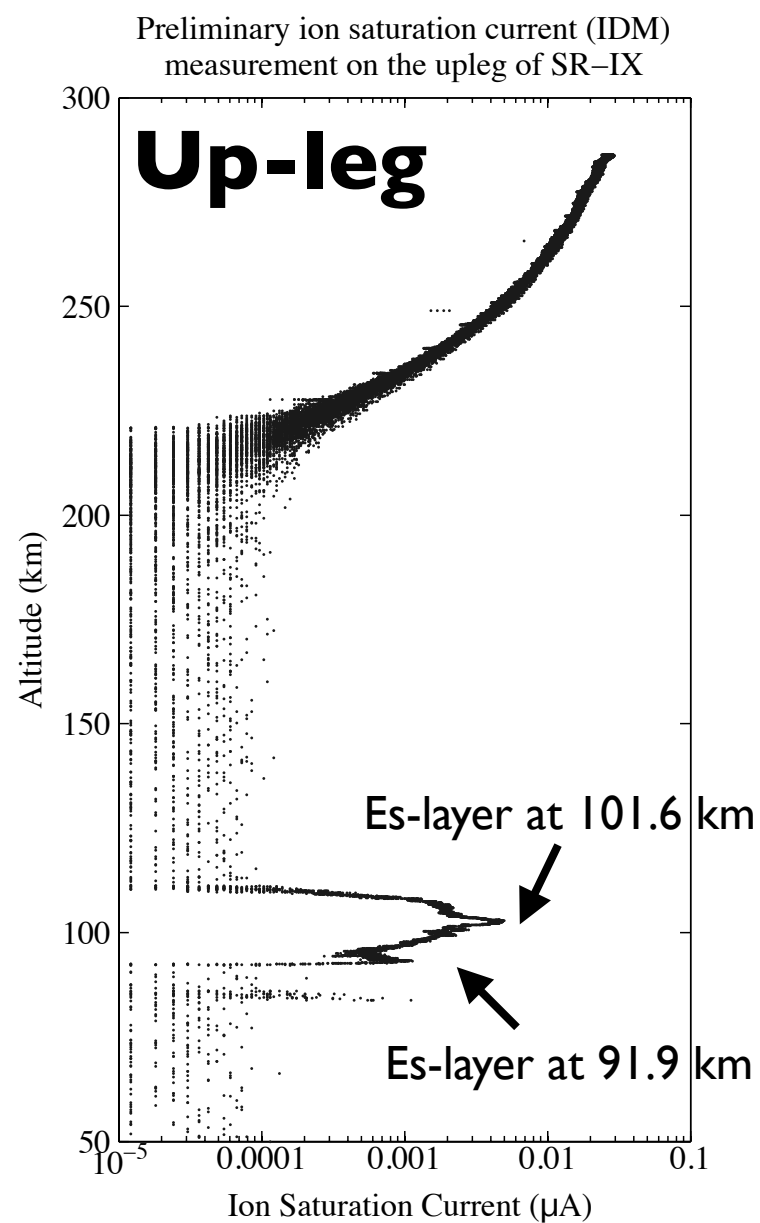




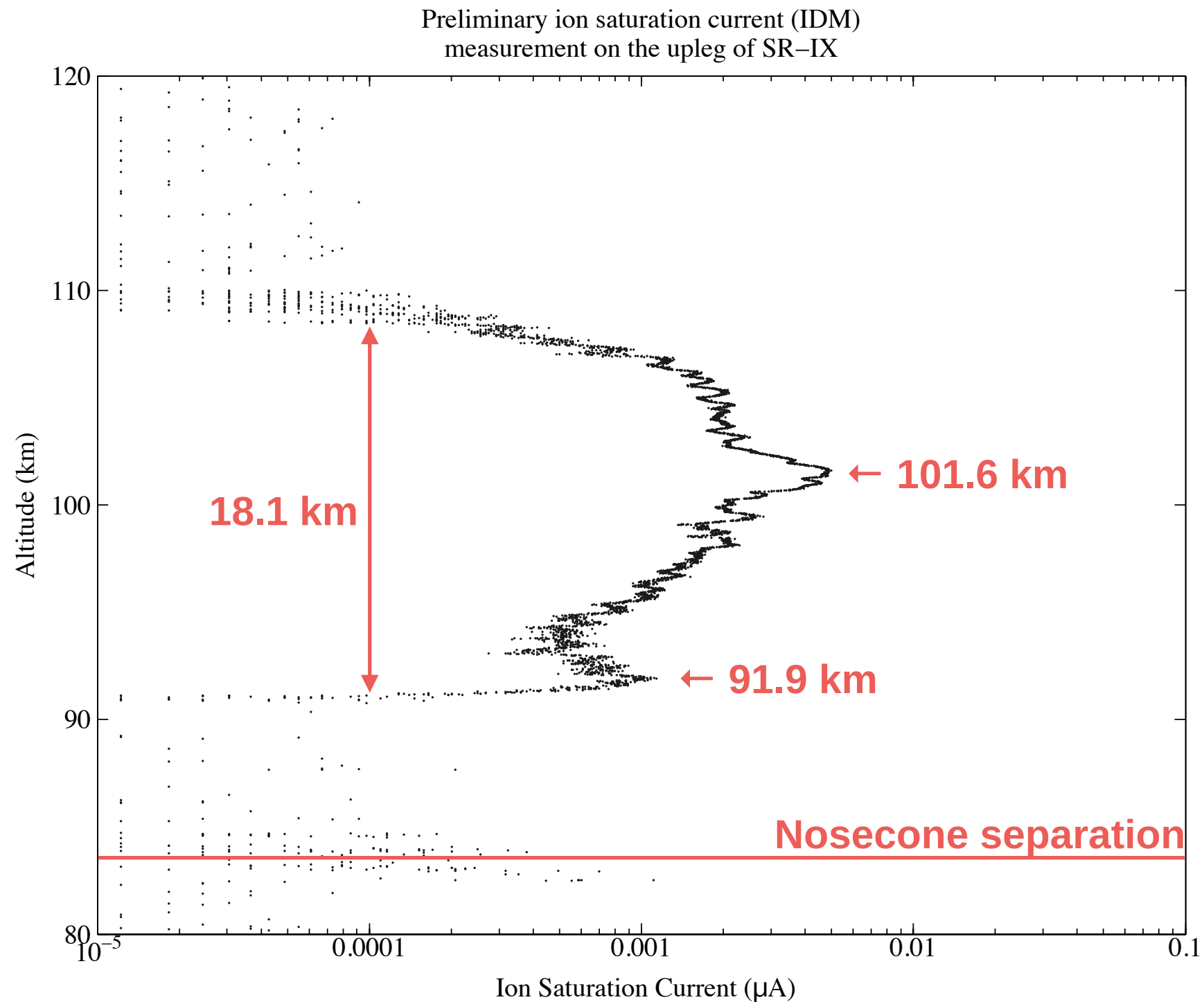
NCC lonosonde



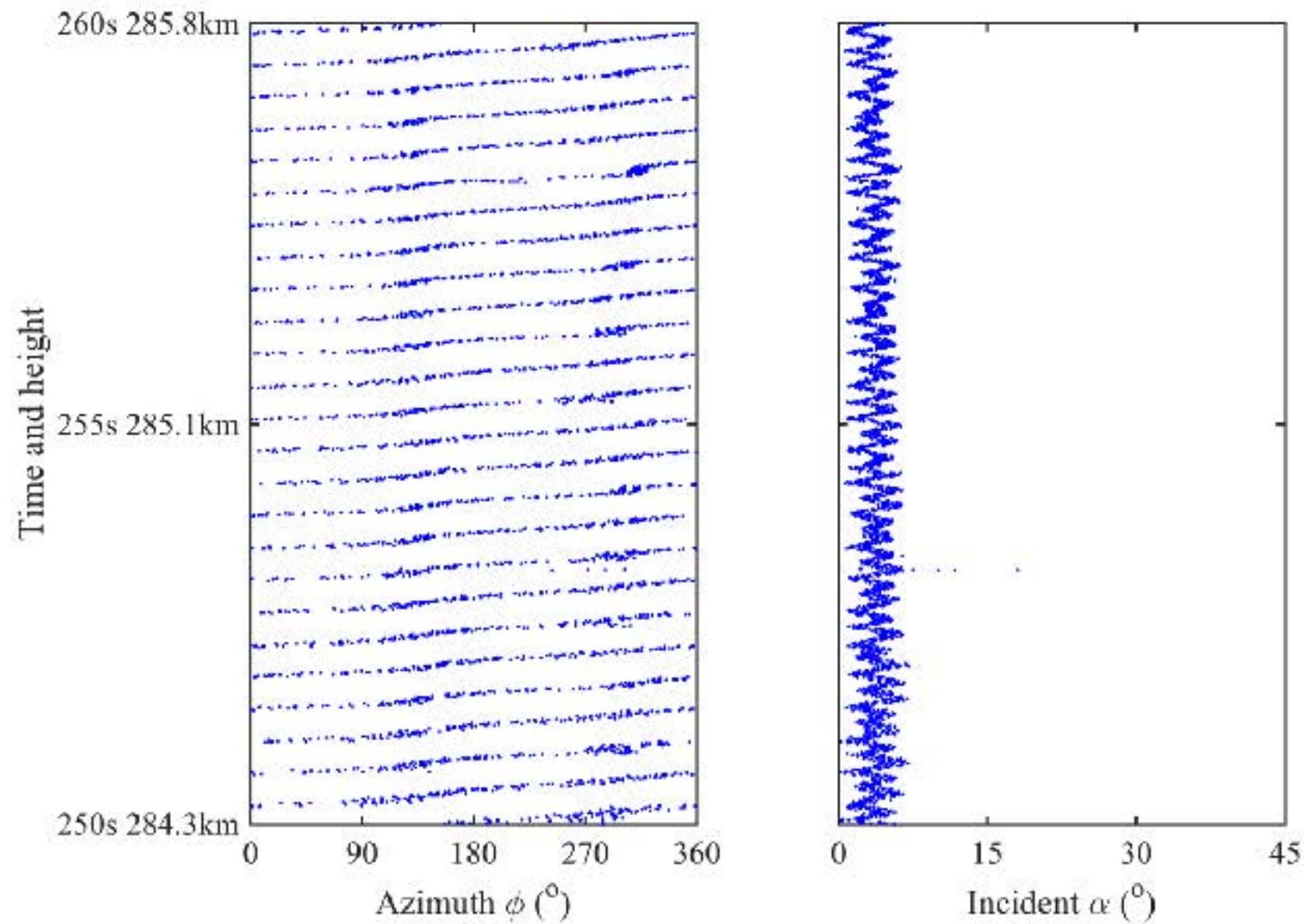
SR-IX flight test (3/26/2014)



IDM readings at E region



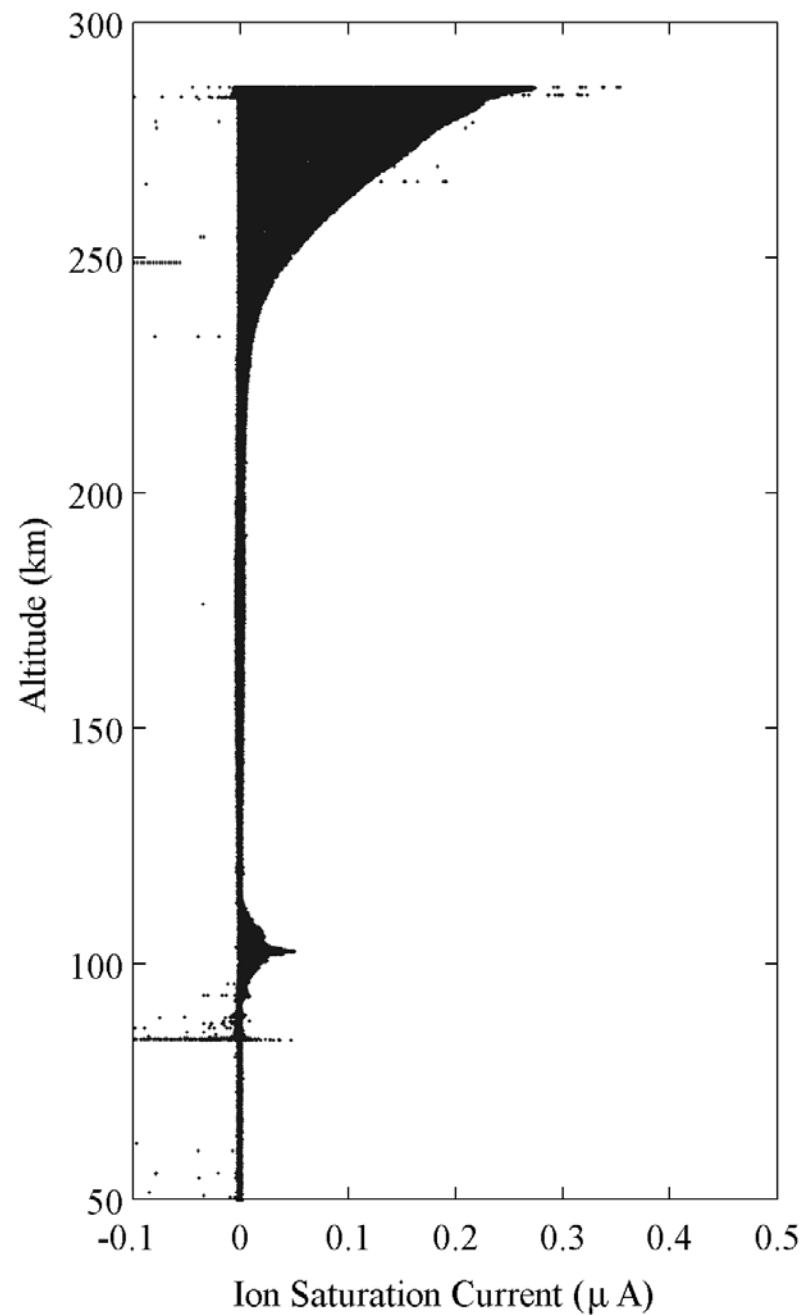
Angles of arrival of ions



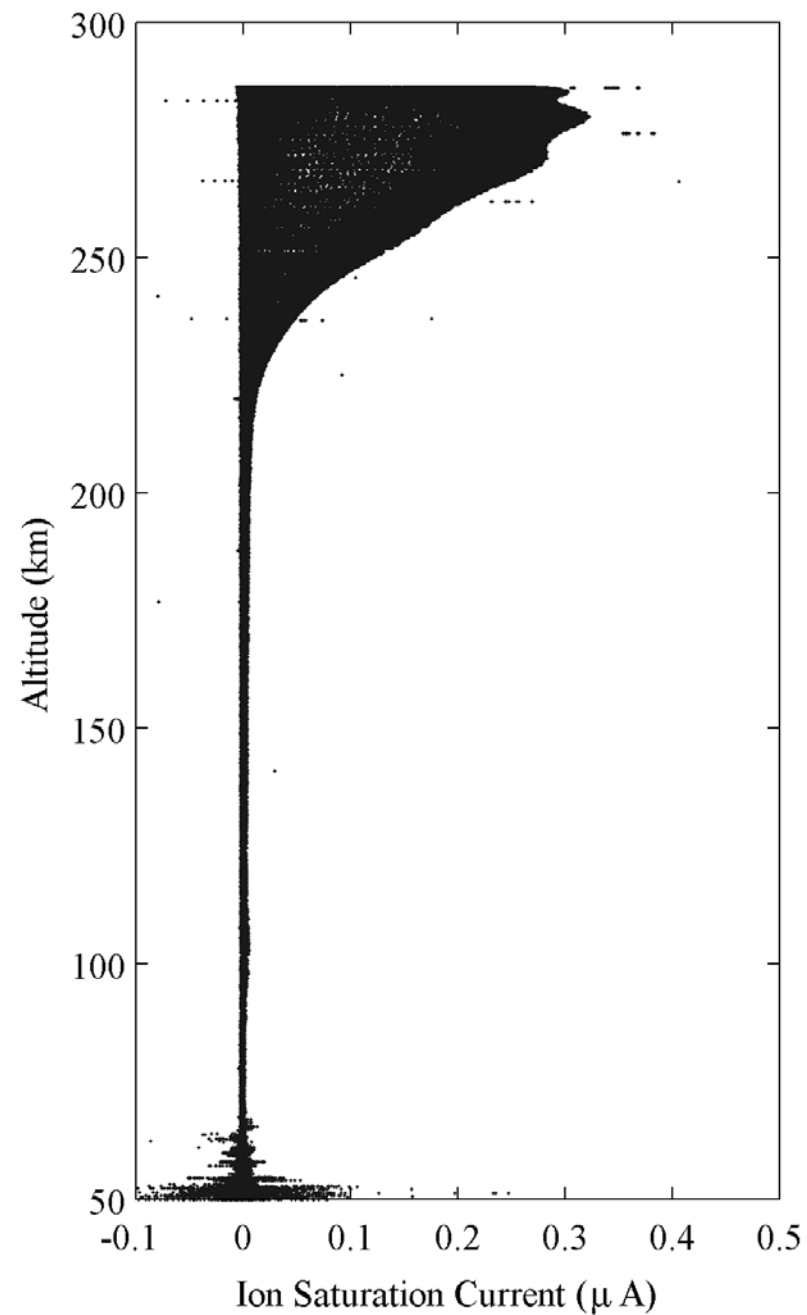
Only significant angles of arrival of ions are available ~ 280 km altitude.

RPA readings, 1,600 S/s

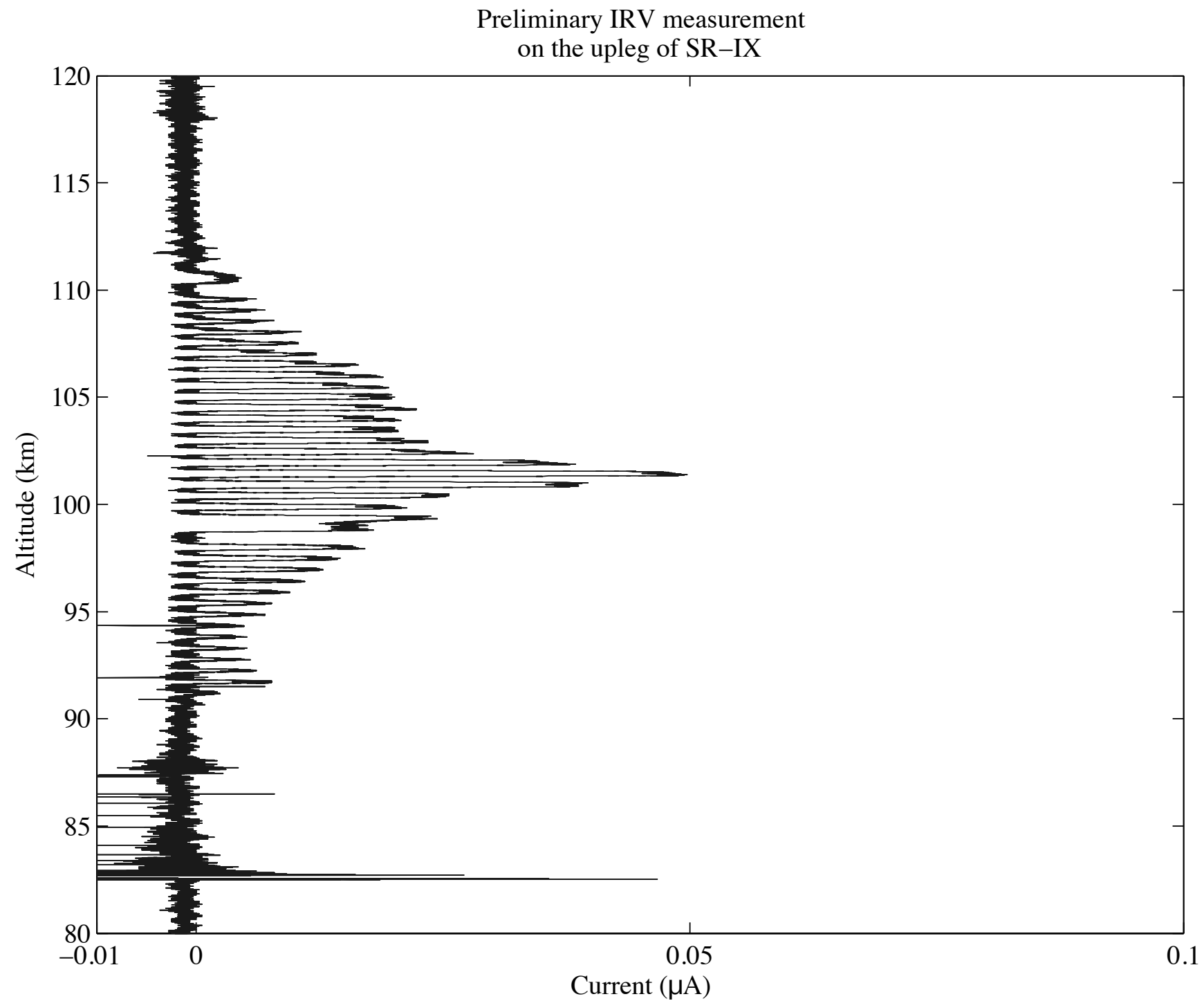
Preliminary IRV measurement
on the upleg of SR-IX



Preliminary IRV measurement
on the downleg of SR-IX

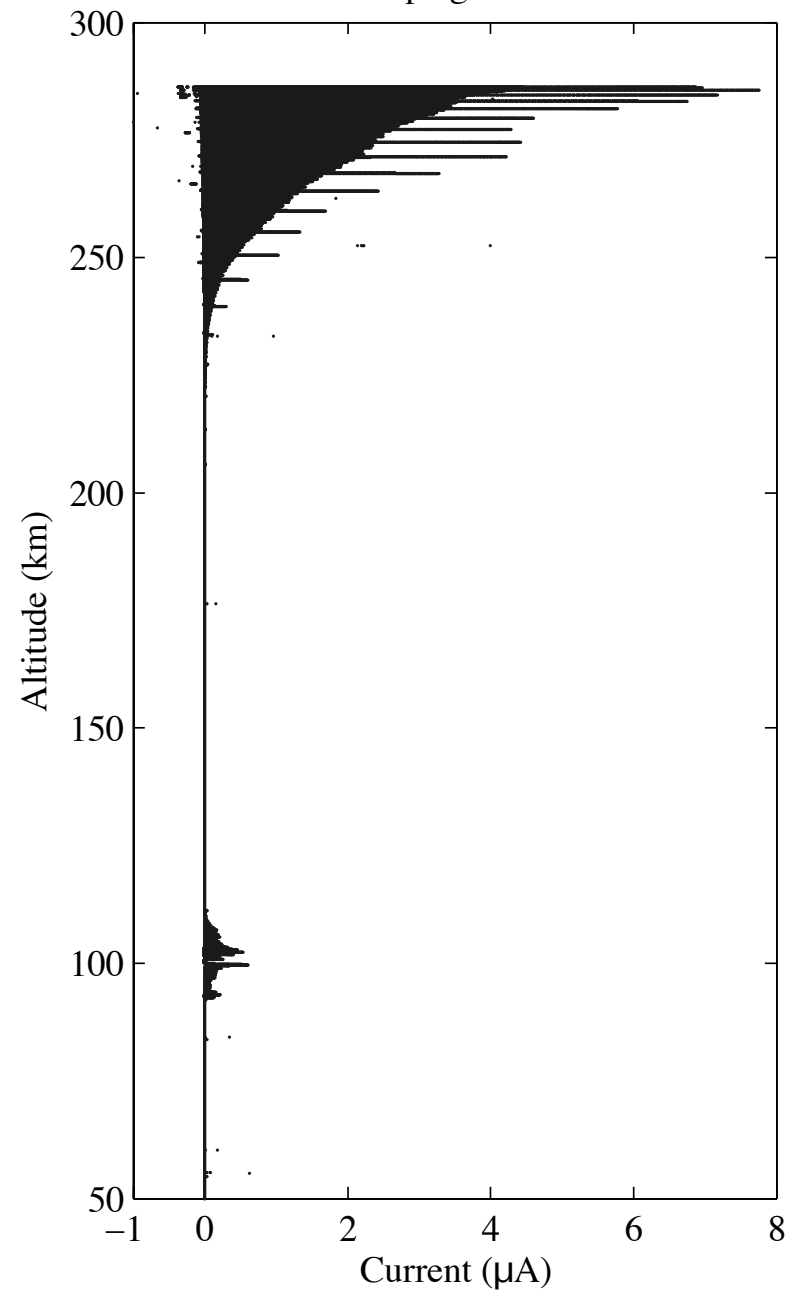


RPA readings at E region

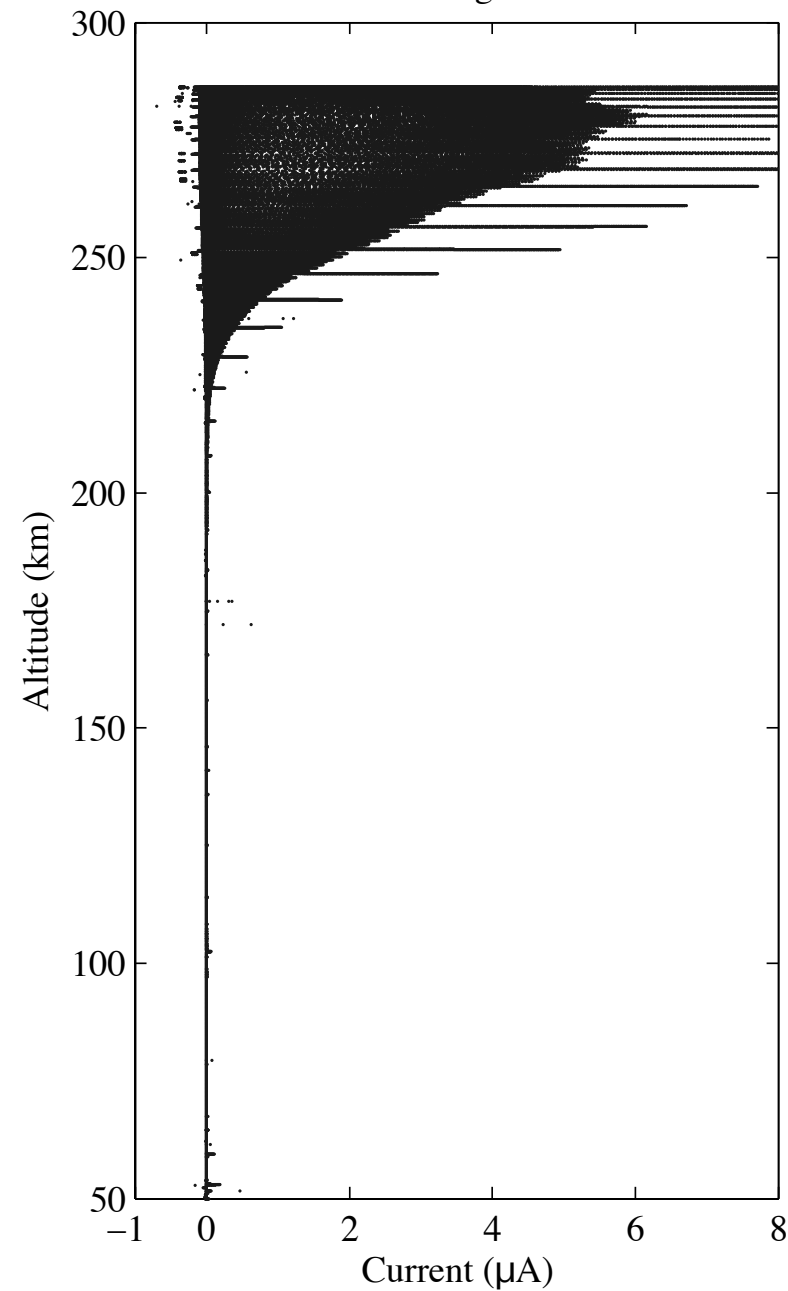


PLP readings, 1,600 S/s

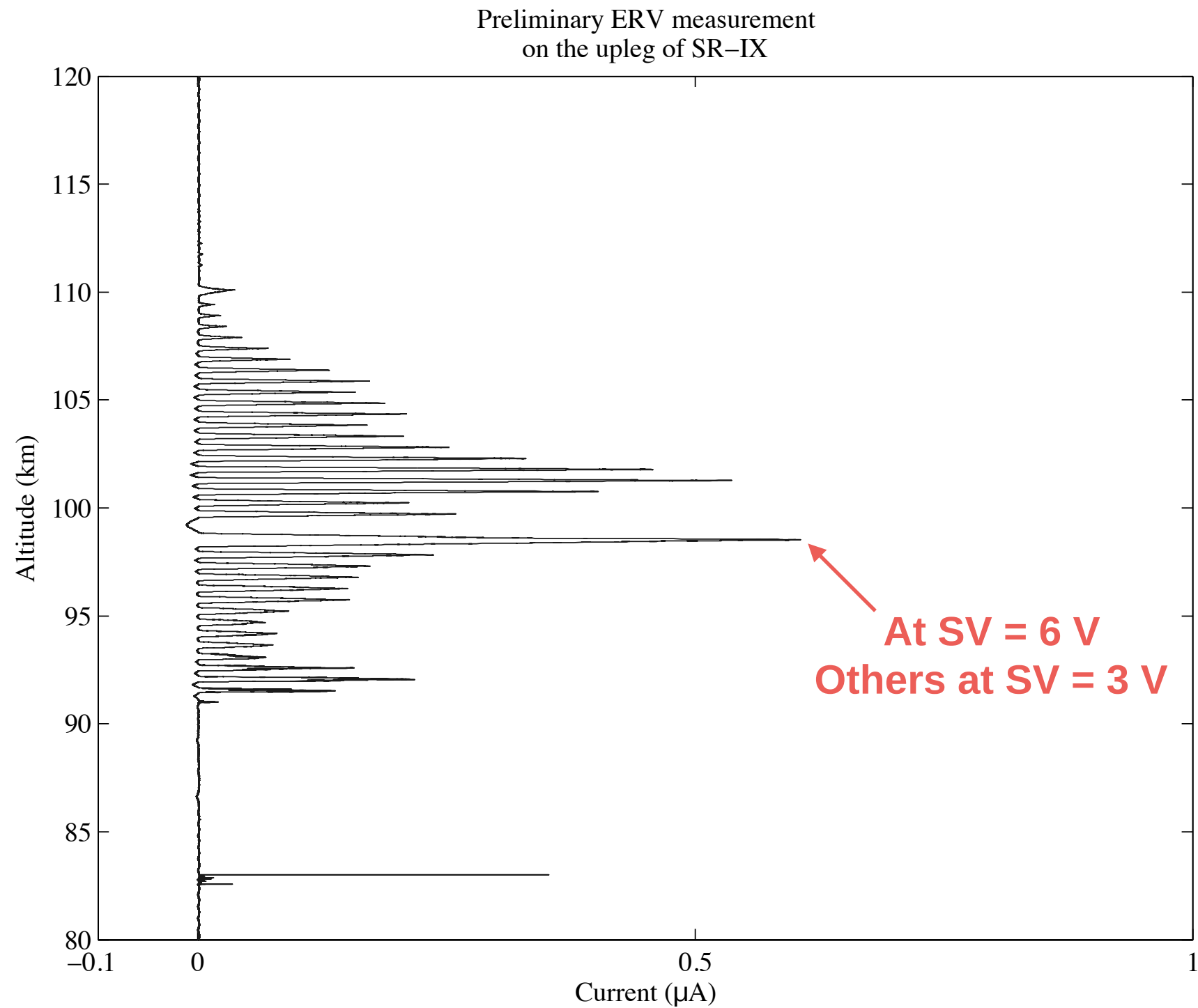
Preliminary ERV measurement
on the upleg of SR-IX



Preliminary ERV measurement
on the downleg of SR-IX



PLP readings at E region

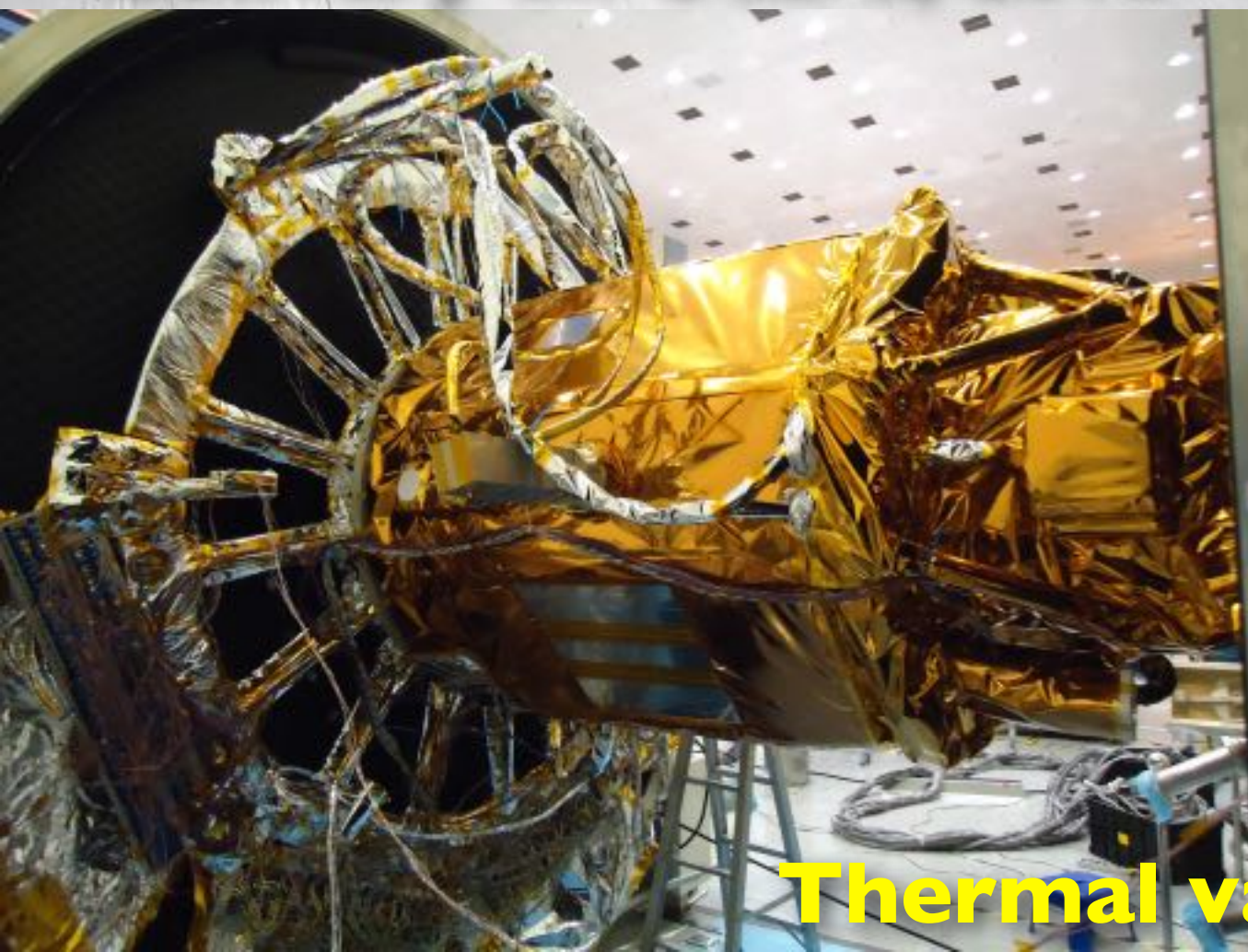




Delivery on Oct. 8, 2013



Installation

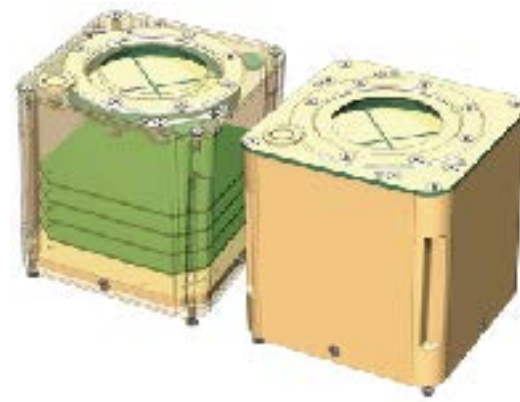


Thermal vacuum test

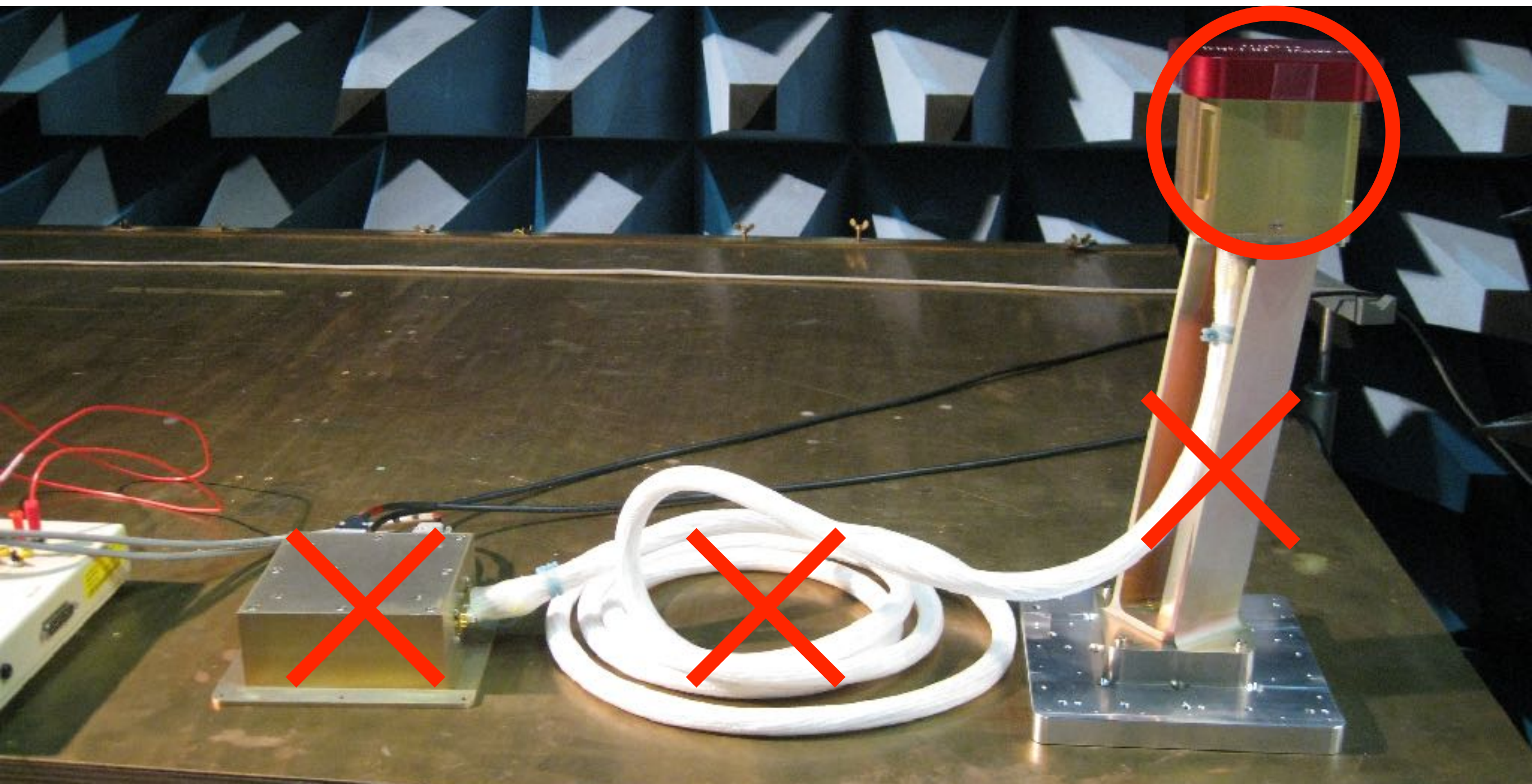


Dual Ionosphere Probe (DIP)

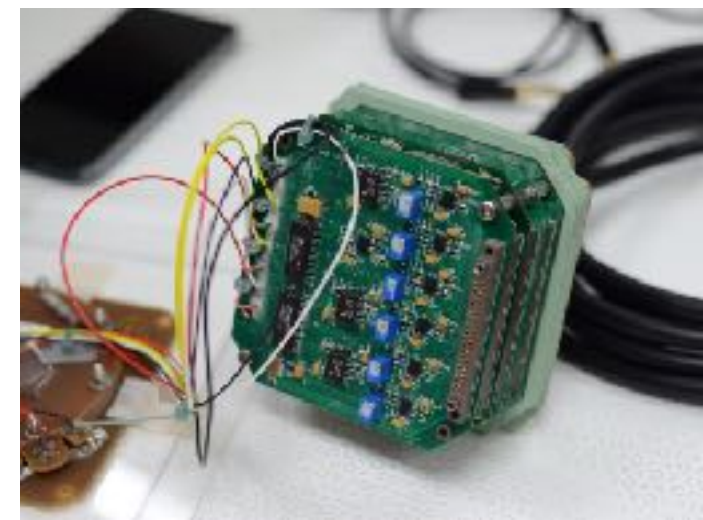
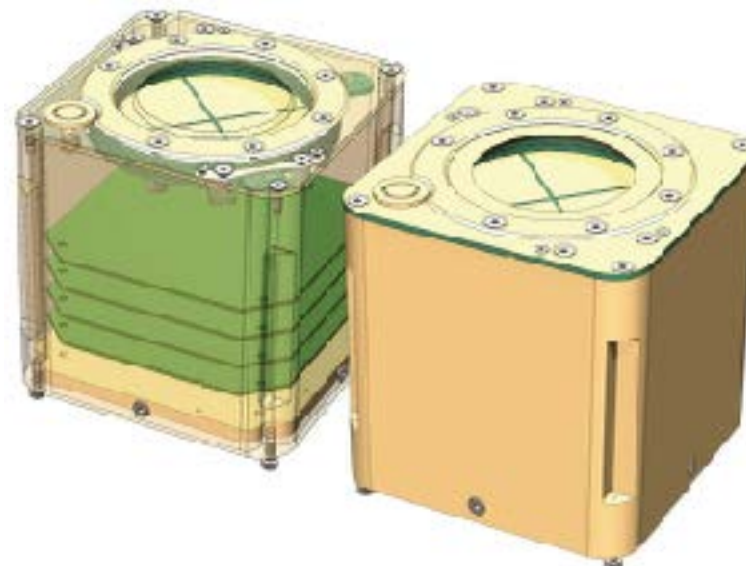
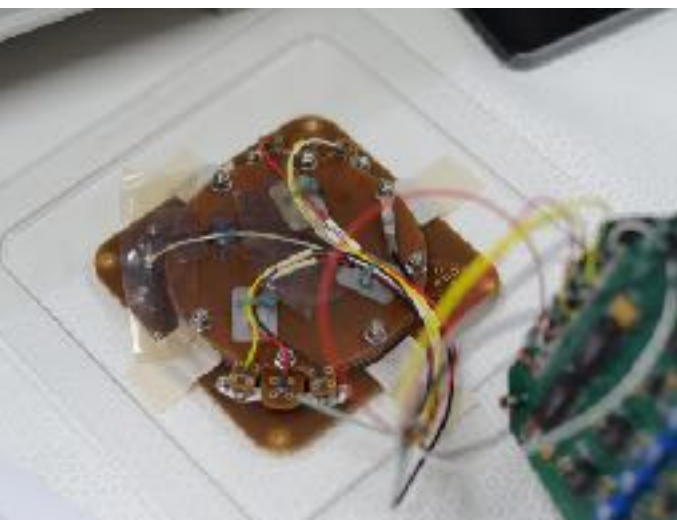
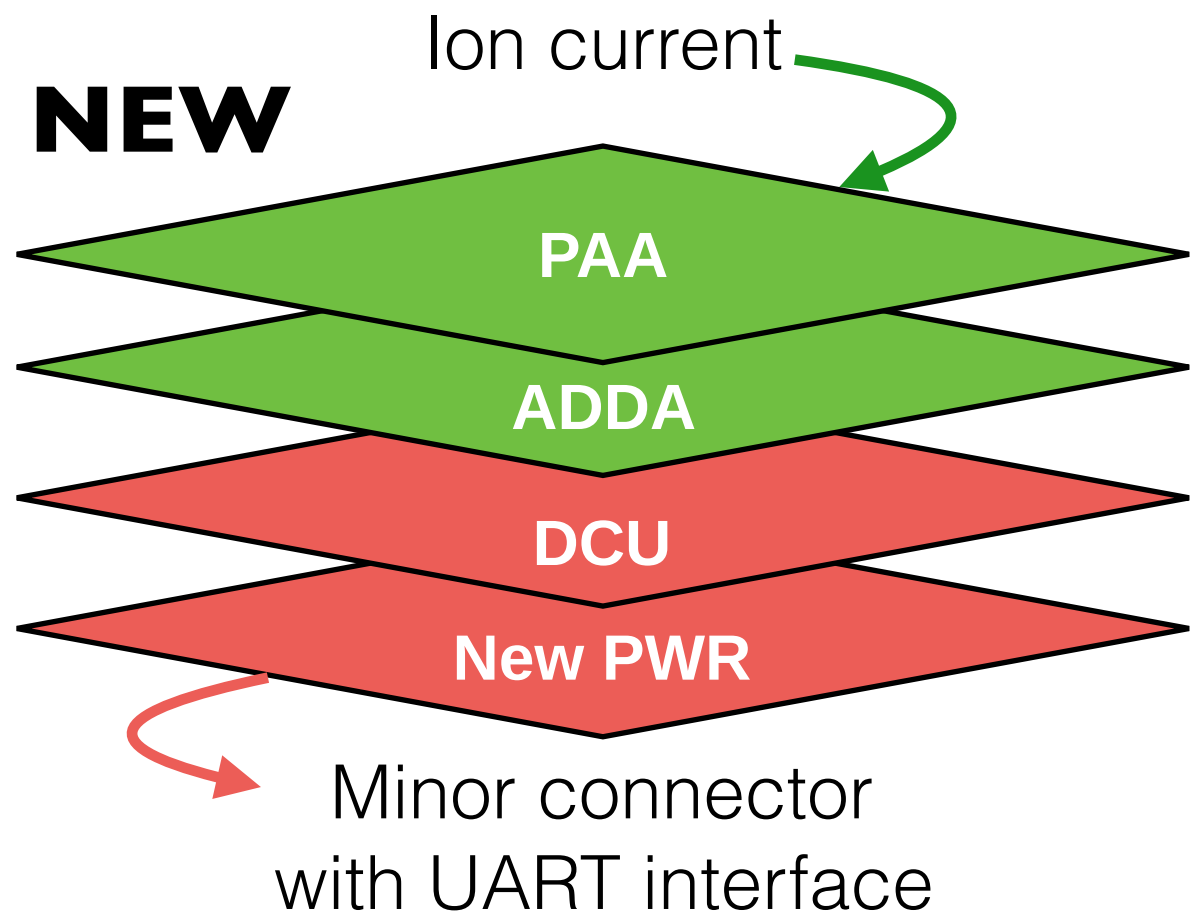
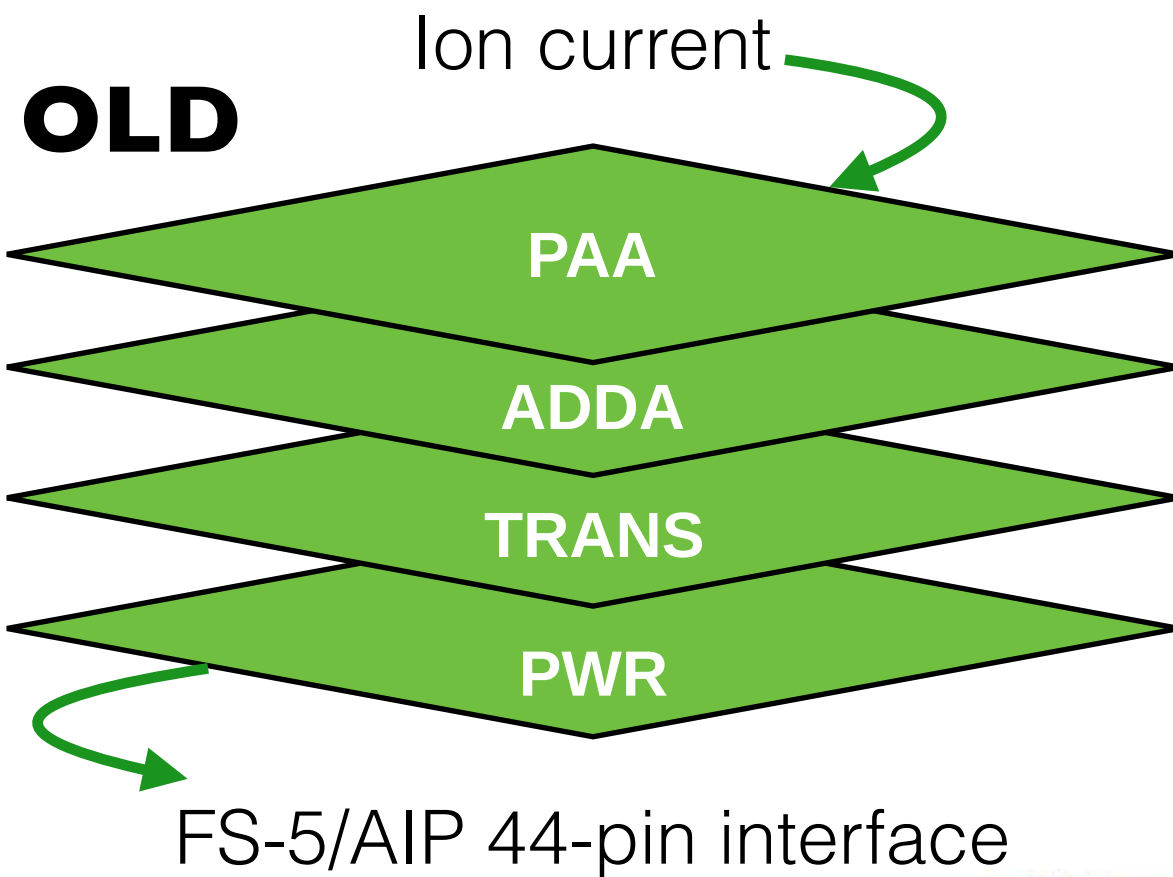
- Two miniature AIPs (a controller integrated inside the sensor cube) are daisy-chained to mount in ram direction, operate independently, and are mutually redundant for FORMOSAT-7/C2.
- Specifications (TBD)
 - Mass: 4.0-4.5 kg (< 7 kg).
 - Dimension: 100 mm L x 200 mm W x 135 mm H (< 160 mm L x 280 mm W x 135 mm H).
 - Average power: 10 W (< 14 W).
 - Data rate: 225 Mb/day (100% duty cycle) for NORMAL mode.



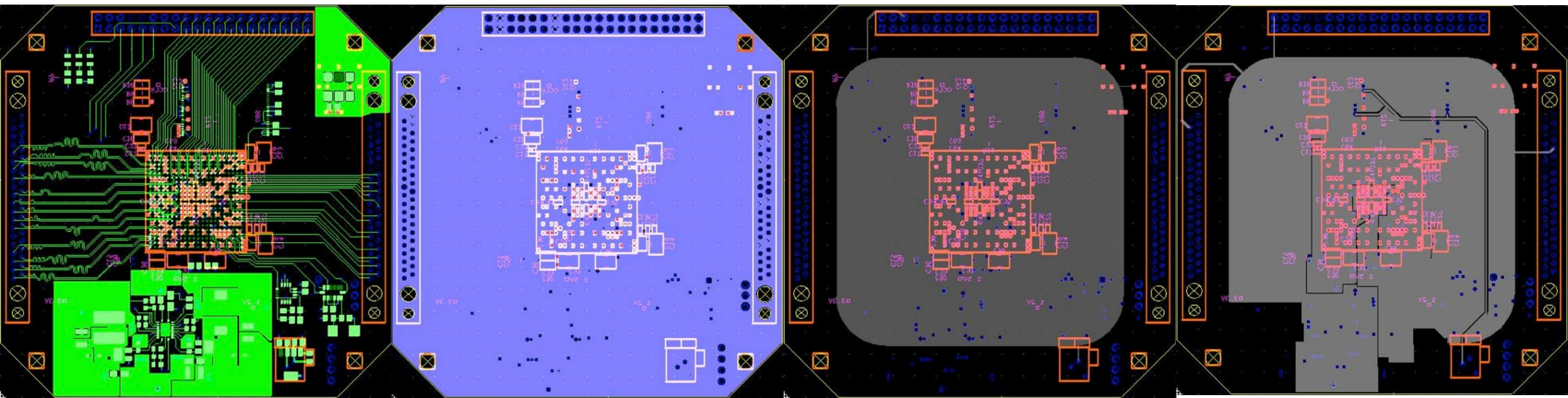
AIP miniaturization



PCBs inside the sensor head



Digital Control Unit (DCU)

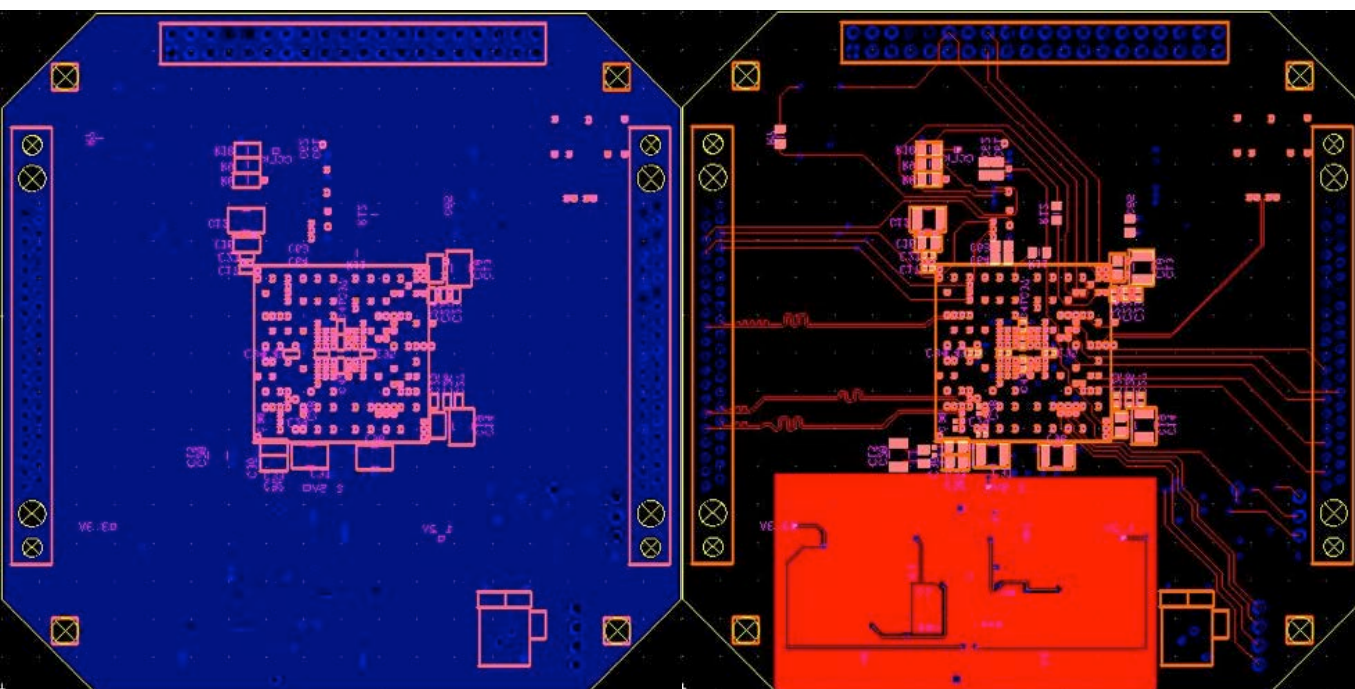


1st layer - signal

2nd layer - ground

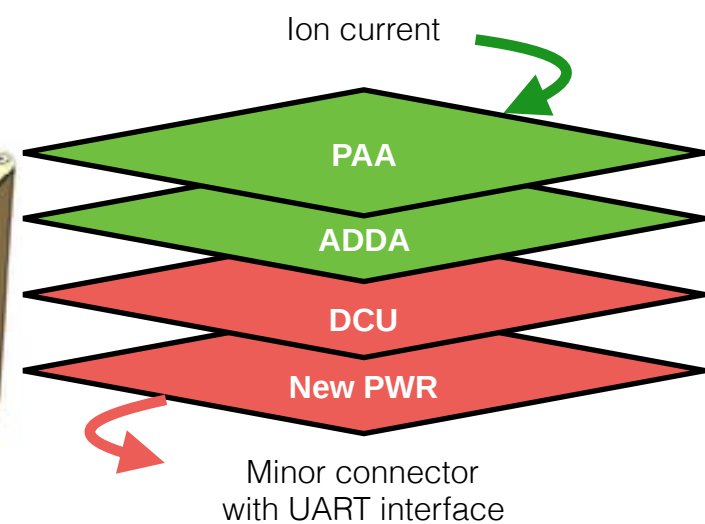
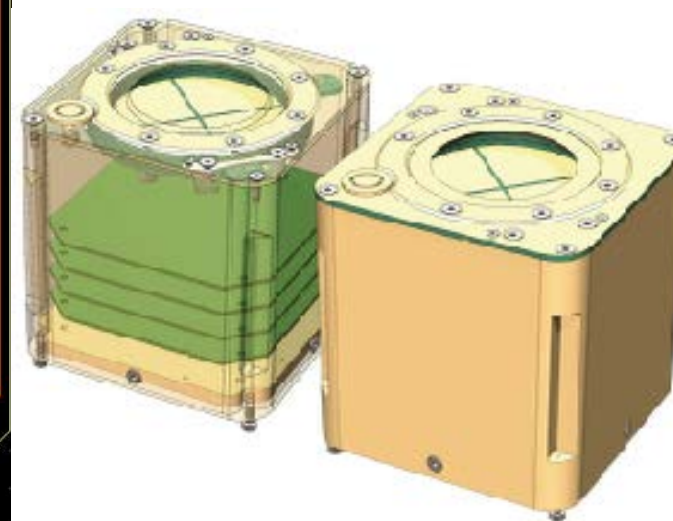
3rd layer - 3.3V power

4th layer - 1.2 & 2.5V power

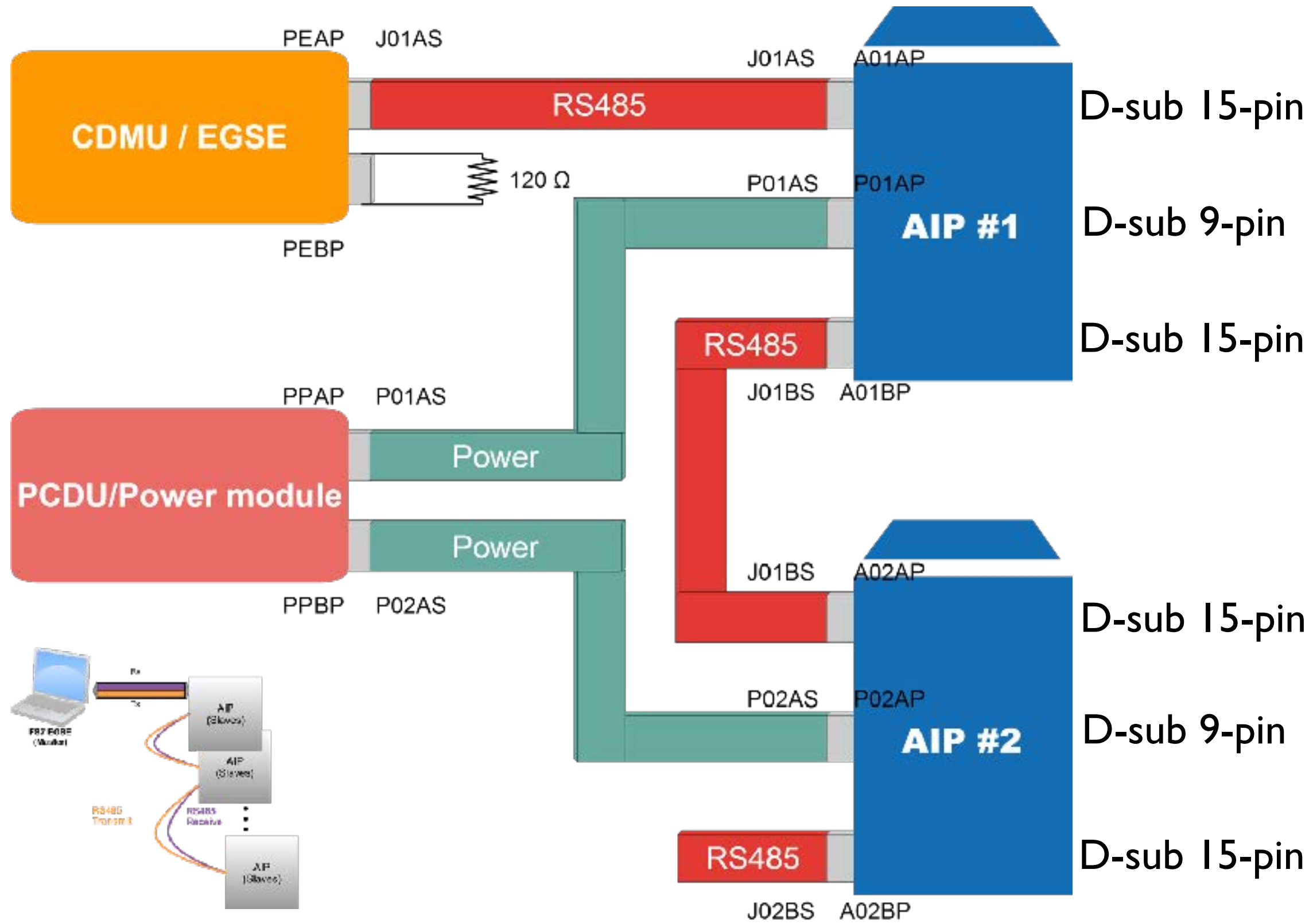


5th layer - ground

6th layer - signal



Communication interface



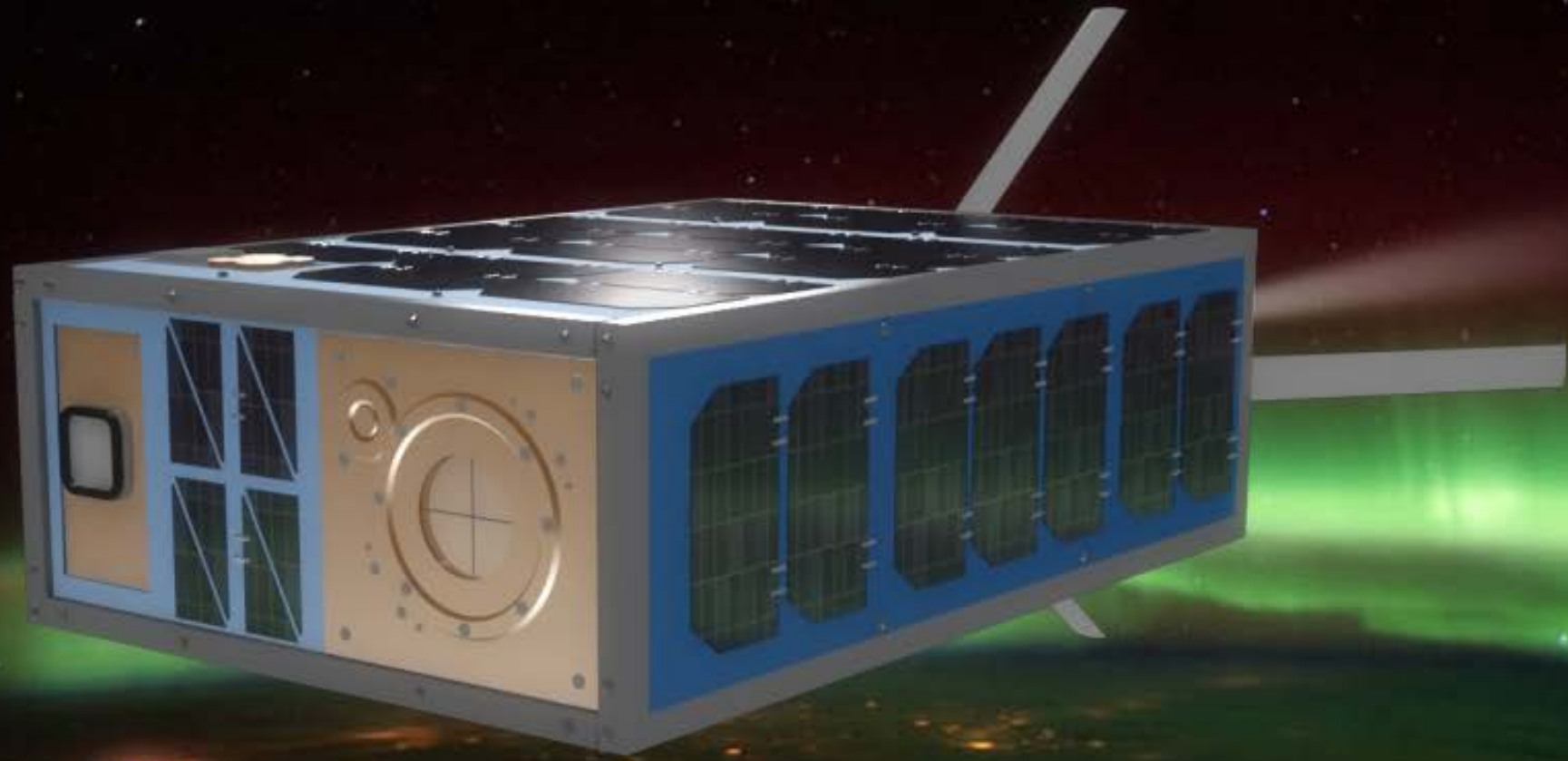
Comparison of FS-7 plasma sensors

S/C & P/L	FS-7C1/IVM	FS-7C2/DAIP
Manufacturers	UTD	NCU
Orbits	520-550 km altitude with 24°-28.5° inclination	720-750 km altitude with 71°-73° inclination
Sensors	2 (RPA/IT + DM)	2 (PLP, RPA, or IDM/IT)
Sampling rates	32 Hz (N_i) 32 Hz ($V_{y,z}$) 1 Hz (others)	128/1,024/8,192 Hz (N_i) 32/256/2,048 Hz ($V_{y,z}$) 1 Hz (others)
Functions	Fixed	Software programmable
Geophysical parameters	N_i , $\mathbf{V}$, and T_i	N_i , $\mathbf{V}$, T_i , and T_e
Mass	3.3 kg (< 4.2 kg)	4-4.5 kg (< 7 kg)
Dimension (mm)	300 mm L × 400 mm W × 135 mm H	100 mm L × 200 mm W × 135 mm H
Power	3 W (< 4.5 W)	10 W (< 14 W)

Compact Ionosphere Probe (CIP)

- Current missions
 - CIP for a 6U **Ionosphere Trawler**TM by DSI.
 - CIP for a 3U **INSPIRESat-2** by CU and NCU.
 - CIP for a 12U CubeSat by ExoTerra.
- Schedule: **PDR** in **December 2016**, **CDR** and **EM** in **June 2017**, and **PAR** for **FM** delivery in **December 2017**.
- Specifications (TBD)
 - Mechanical specification (**1U**): < **1** kg in mass and **90° x 90°** FOV without obstacle in ram direction.
 - Electrical specification: **+12VDC** input voltage, < **5 W** in average power, PC/104, URAT, and 225 Mb/day (100% duty cycle) data rate for NORMAL mode.

AIP-C for a 6U Ionosphere Trawler™



CIP for a 3U INSPIRESat-2

